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ELECTROSTATIC DISCHARGE SUSCEPTIBILITY DATA

Volume I

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Reliability Analysis Center

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ELECTROSTATIC DISCHARGE SUSCEPTIBILITY DATA OF MICROCIRCUIT DEVICES

Volume I

1989

Prepared by:

William H. Crowell
Reliability Analysis Center

Under contract to:

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19. ABSTRACT (Continue on reverse if necessary and identify by block number)

This publictaion contains Electrostatic Discharge (ESD) susceptibility data of electronic devices and is an update to the VZAP-1, the 1983 RAC ESD data compendium. Detailed susceptibility data is presented along with the ESD classification in accordance with MIL-HDBK-263 and MIL-STD-1686A for approximately 4,300 devices. This data is useful in the establishment of an ESD control program. The data contained in this publication is a product of the Reliability Analysis Center's VZAP data base, which is intended to be a central repository of ESD Susceptibility Data.

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Steven J. Flint, RAC Technical Director

22b. TELEPHONE (Include Area Code)
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PREFACE

The purpose of this document is to make available electrostatic discharge (ESD) susceptibility test and classification data. This data is much needed by industry and government equipment designers to enable them to assess their equipments' vulnerability to the ESD threat, to assist in the establishment of ESD control programs, and to comply with such requirements as MIL-STD-1686A, "Electrostatic Discharge Control Program for Protection of Electrical and Electronic Parts Assemblies and Equipment (Excluding Electrically Initiated Explosives Devices)."

This document was prepared as part of the Reliability Analysis Center's efforts to provide its user community with new and needed information in the field of electronic device reliability.

Contributing to this effort were William Denson, David Mahar, John Puleo and Shawn Gentile.

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INTRODUCTION

1.0 INTRODUCTION

This databook makes available ESD susceptibility test data that the RAC has collected from a variety of sources over the past few years on integrated circuits, discrete semiconductors and resistors.

The introductory material of this publication is not intended to provide a tutorial on ESD testing or the physics of ESD failures, but rather to provide enough information to allow the user of this document to effectively interpret the presented data. This information will also give the user some insight into the usefulness and limitations of the data.

1.1 BACKGROUND

When VZAP-1 was published in 1983, ESD was a relatively immature field with a serious lack of standardization, especially in the area of ESD susceptibility testing. Much of the VZAP-1 data was taken with non-standard ESD simulator circuits that deviated from the use of a 100 pF, 1500 ohm discharge model. Additionally, it was discovered subsequent to VZAP-1 that many of these simulators, either commercially available or built in-house, have low degrees of repeatability, due to many uncontrolled variables. Although many of the reasons for this nonrepeatability have been studied, understood, and corrected, there potentially still exists sources for large degrees of variation in the test results. A discussion of typical variability that exist in test results is given in Section 1.5

VZAP-2 is intended to be an update to VZAP-1, and presents more data of higher quality. These improvements are possible because much has been learned in the field of electrostatic discharge since VZAP-1 was issued.

1.2 USE OF THIS DATA

MIL-STD-1686A covers the requirements for the establishment and implementation of an ESD control program, including identification of ESD Sensitive (ESDS) parts, assemblies, and equipments. Any organization that designs, tests, inspects, services, manufacturers, processes, assembles, installs, packages, labels, or otherwise handles electronic parts, assemblies, and equipment susceptible to ESD damage should consider implementation of an ESD control program.

The first consideration in establishing an ESD control program in a specific application is the identification of the susceptibility levels of the specific parts being used. This is true whether the program is being implemented as a result of MIL-STD-1686A or not. Based on this information, an effective program can then be designed and implemented without expensive overkill.

MIL-STD-1686A, Paragraph 5.2 states, "The contractor shall identify each ESD Sensitive (ESDS) part, assembly, and equipment applicable to the contract as Class 1 or 2." In some cases Class 3 parts must also be identified. Paragraph 5.2.1.1 further states "ESD sensitivity classification for parts shall be determined as follows:

(a) ESD sensitivity as specified in the applicable part specification, or

(b) ESD sensitivity in accordance with Appendix A test data contained in the Reliability Analysis Center (RAC) ESD Sensitive Items List (ESDSIL), or

(c) Classified in accordance with Appendix B, or,

(d) When specified, or at the option of the contractor, determine sensitivity by test (See Appendix A). ESD sensitivity test data reporting shall be in accordance with the data ordering document included in the contract or order (See 6.2)."

The data contained in this databook is essentially a compilation of ESD test data taken from a wide variety of sources. The ESDSIL database referred to in item (b) above is entitled the "Electrostatic Discharge Sensitive Items List." The intent of the ESDSIL database is to be a central repository of data taken as a result of the requirements of MIL-STD-1686A and Data Item Description (DID-RELI-80670). The classification test procedure of MIL-STD-1686A, Appendix A, requires the use of the test circuit of MIL-STD-883, Method 3015. At the time MIL-STD-1686A was issued the MIL-STD-883 test method in effect was Method 3015.6. Since there is no data in this publication which resulted from testing as required by Method 3015.6 or later, the data contained herein does not fulfill the requirements of (b) above.

However, the data in this publication is more desirable than the use of (c) above which generically classifies components based on part type. Since 3015.6 was the first MIL-STD-883 ESD test method to ensure reasonable confidence in test waveform characteristics, it is the most desirable test data available. The data types, in order of preference, can be summarized as follows:

1) MIL-STD-883, Method 3015.6 or later
2) MIL-STD-883, Method 3015.5 or earlier, or other 100pF, 1500 ohm Human Body Model (HBM) tests, such as DOD-STD-1686
3) Non 100pF, 1500 ohm HBM tests converted to an ESD susceptibility level consistent with the 100 pF, 1500 ohm model
4) Electromagnetic Pulse (EMP) data converted to an ESD susceptibility level.

The data contained in this document are from items 2, 3 and 4. This is also the order of preference which was used in determining the ESD classification of each part listed.

A more detailed description of the test method used for each data entry is given in the remarks field of Section 3 and also in Section 5 (Volume II) of this document.

Before the updates of DOD-STD-1686 to MIL-STD-1686A and MIL-STD-883 Method 3015.5 to 3015.6, there were inconsistencies between DOD-STD-1686 and the MIL-STD-883 method of reporting ESD test results. Specifically, the voltage susceptibility ranges were different, making it impossible to cross-correlate test data. Both MIL-STD-1686A and MIL-STD-883, Method 3015.6 have been coordinated, thereby making data taken from either useable for either purpose. In fact MIL-STD-1686A invokes the procedure of MIL-STD-883 Method 3015.6. The classification ranges in these documents are as follows:

Class 1	0-1999
Class 2	2000-3999
Class 3	4000-15999

This is the classification scheme that is used in this publication. In addition to these, RAC has defined Class N to mean devices susceptible to levels above 15999 volts.

Since much of the data in this publication was obtained from tests performed not in accordance with MIL-STD-1686A or MIL-STD-883, classification in accordance with these standards becomes difficult. For example, if testing was performed that yielded devices passing a test at 1000 volts but failing the test at 3000, although it is known that the susceptibility level is 1000-3000 volts, the MIL-STD-1686A classification cannot be precisely determined. In this example it is not known whether the device is Class 1 or 2. The classification criteria used in this publication was to use the lowest failure voltage or the highest voltage at which the device passed if no failure data existed. For example, if a device was observed to fail when tested at 2000 volts only, it was classified as Class 1 since the actual threshold voltage is between 1 and 2000 volts.

As stated previously, all data present in this document was not taken from specific test methods, such as method 3015 of MIL-STD-883 but rather from a variety of test methods. Contained in this document are the results of tests done in accordance with MIL-STD-883, test method 3015; tests similar to MIL-STD-883 Method 3015 but not strictly in accordance with it; tests using nonstandard simulation models and methods; and EMP data that was converted to reflect ESD susceptibility levels. The EMP data was only used for classification purposes in the cases in which there was no other empirical ESD susceptibility data. The methodology used to convert EMP data to ESD susceptibility levels is given in Section 1.5.

In future revisions to this publication, it will be interesting to note the differences in ESD susceptibility data between Method 3015.6 and earlier versions in which the waveform was not tightly controlled. However, in general data taken from circuits in which the high frequency (i.e. > 100 MHz) performance has not been characterized will lower failure thresholds. This potential exists due to the fact that there can exist high frequency, high amplitude oscillations in some circuits which yield higher stressing amplitudes than that of the ideal RC discharge waveform.

Additionally, there is a limited amount of Charged Device Model (CDM) test results. Even though CDM tests are not yet incorporated into the ESD testing standards, there has been some data included which were taken using this model. Although the device classification schemes are only applicable for the HBM, the CDM data that was available is included for completeness, considering that conventional classifications with CDM data cannot be done.

Individuals or firms testing devices for ESD susceptibility are encouraged to submit the resulting data to the Reliability Analysis Center for inclusion into the database. If desired, the source of data will be held proprietary by RAC. This data does not need to be taken in accordance with the MIL-STD-883 test method, but can be any empirical ESD susceptibility data. A recommended format for this data is given in Appendix B (Volume II). Also given in Appendix B, for information purposes only, is the Data Item Description (DID) DI-RELI-80670 called out in MIL-STD-1686A for submission of ESD sensitivity data.

1.3 INTERPRETATION OF DATA

The data contained herein is intended to present the results of empirical tests performed. Ideally, in addition to voltage susceptibility levels, one would like to know specific failure mechanisms that caused the device to fail. While manufacturers typically know the manner in which their part will fail when exposed to an ESD transient, this data is not normally available to outside organizations. Therefore, the specific failure mechanisms are not known. What is usually known is the failure mode (that is, the measurable effect of damage), since in any ESD test there must be a means of detecting failure. Examples of typical failure modes (or failure criteria) included excessive input leakage, input stuck high, functional failure, etc.

The failure criterion used in establishing an ESD failure is critical to the outcome of the testing. This may be illustrated by the use of two examples. In the first example, let us assume that the failure criterion for a bipolar device is defined as a certain percentage change in leakage current. This may be a difficult failure criterion to implement, because the relationship of leakage current versus stress voltage itself is not well-defined. In the second example, let us assume that the leakage current specification limits are used as the failure criterion for the same parts. The device which we are testing is relatively tolerant to ESD and remains within the specification limits when stressed with a pulse well below the damage threshold. Nevertheless, there is a measurable change in the leakage current, i.e., the device has been degraded; however, it does not exceed the specification until it is subsequently pulsed with a much higher energy pulse. Since we know that some degradation has occurred, we can measure the degradation, but, because of the failure criterion, the device is not considered susceptible to ESD damage at the lower level. For this reason, the criterion used to detect device failure must also be selected in accordance with the device operating characteristics and the manner in which the device is designed into a circuit; that is, if a certain circuit configuration can tolerate a parameter shift or even an out-of-specification condition of this component. Since it is impractical to require unique failure criteria based on the manner in which the part is used in the circuit, MIL-STD-883, Method 3015.6 states the devices shall be tested for failure following stressing by performing room temperature DC parametric and functional tests. Performing both parametric and functional tests should identify any degradation or failure of the device.

It is also recognized that failure modes and mechanisms are highly dependent on the simulation circuit used to stress the device. There are various circuits being used in industry to simulate different ESD scenarios. The most standard of these is the Human Body Model, in which a charged capacitance is discharged through a resistor to the device under test. This Human Body

Model is the most commonly used simulation model and is specified in MIL-STD-1686A and MIL-STD-883 Method 3015. The resistance and capacitance values specified in these standards are 100 pF and 1500 ohms, respectively. Other values are often used and some data in this publication use these values. The values used are listed in the detailed data (Section 3.0). It should be noted that devices can exhibit different susceptibility characteristics depending on the values used. Since there is a need to classify devices in a consistent manner, the RAC derived a conversion method for data that was taken using a Human Body Model with resistance and capacitance values other than 100 pF, 1500 ohms.

Using semi-empirical methods, the RAC has established the following formula for the conversion:

$$V_1 = V_2\,(3.87)\sqrt{\frac{C_2}{R_2}}$$

where:

V_1 = standard human body model damage threshold
R_2 = nonstandard value of resistance used (in ohms)
C_2 = nonstandard value of capacitance used (in pF)
V_2 = measured damage threshold using C_2 and R_2

The derivation of this equation may be found in Appendix A.

This method is only used so that a classification in accordance with the susceptibility levels of MIL-STD-1686A can be made. The data in Section 3.0 presents both the classification of each part and the data as it was obtained, i.e., the failure voltages of the actual model used during testing.

Other ESD simulation models sometimes used are the charged device model and the machine model. The charged device model simulates the situation in which a device, after being charged, contacts a conductive object, thereby causing a high amplitude, short duration discharge pulse. The machine model simulates a situation in which a device is contacted with a charged capacitance through a very low resistance. This model is intended to simulate a conductive object, like parts of a machine, that contact the device.

The purpose of this book is not to provide background on the physics of ESD failures, as this has been done extensively in the literature, but rather to present the data collected by RAC and give the reader enough information so that the limitations of the data are fully understood. If further information is required, DOD-HDBK-263, "Electrostatic Discharge Control Handbook for the Protection of Electrical and Electronic Parts, Assemblies, and Equipment (Excluding Electrically Initiated Explosive Devices)" and the proceedings of the Annual EOS/ESD Symposium provide much information on all aspects of ESD.

1.4 CONVERSION OF EMP OVERSTRESS TEST DATA TO THE ESD HUMAN BODY MODEL

A vast amount of electrical overstress data has been compiled from Electromagnetic Pulse (EMP) studies. It would be negligent to disregard this potential data source. By knowing certain parameters of a device, a theoretical ESD failure can be calculated using the Wunsch-Bell model (Reference 28) as the starting point. The following equation has been established to convert EMP overstress data to the ESD human body model equivalent:

$$V = \left[\frac{-2V_D + \sqrt{4V_D^2 + 1200\ K_1\ (7.675 \times 10^{-7})^{-K_2}}}{60} \right] 1530 + V_D$$

where:

V = ESD threshold voltage
V_D = measured overstress breakdown voltage
K_1 = failure constant 1
K_2 = failure constant 2

The derivation of this equation may be found in Appendix A (Volume II).

To further verify the validity of the calculated ESD levels presented in this book, data was compared for specific devices which had both empirical ESD threshold data and ESD threshold levels calculated from EMP data. The log of the ratio of ESD to EMP failure voltages was plotted such that a given percentage of discrepancy (i.e., if the EMP level was the same percentage higher or lower than the ESD level) would be equidistant from the 0 line. Figure 1 is a histogram illustrating the relationship between the log $(\frac{EMP}{ESD})$ and frequency of occurrence. If the datapoints were randomly distributed about the 0 line and the data did not show a shift in distribution against any parameter, it could be concluded that the failure levels obtained from EMP data were a fairly good indication of the actual susceptibility levels of the devices (not taking into account random variations and noise in the data for any given device). Analysis of this data however, indicated that the log $(\frac{EMP}{ESD})$ datapoints were not randomly distributed but rather correlated to the susceptibility level. This indicates that the conversion algorithm is not perfectly accurate.

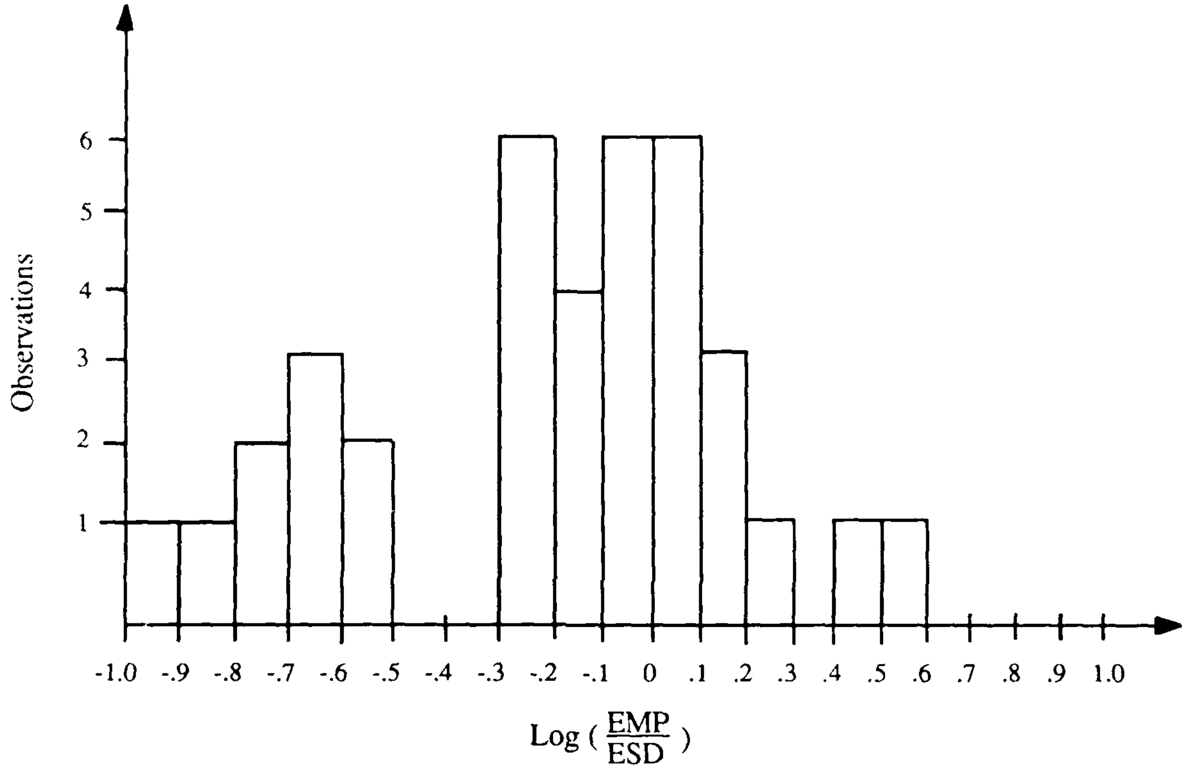


FIGURE 1: EMP VS. ESD DATA

Based on this information it should be emphasized that the ESD susceptibility levels obtained from EMP data are necessarily only approximate values. It can be seen from Figure 1 that the EMP to ESD levels can differ by as much as a factor of 10. There are various sources of error in converting EMP data to ESD data. Two of these error sources are the uncertainty in the damage constants and the uncertainty in the device parameters (bulk resistance and breakdown voltage). These uncertainties can stem from normal lot to lot variations and differences among manufacturers. Additionally, it is known that damage from EMP test pulses may manifest itself as different failure mechanisms than damage from an ESD pulse. This is due to the fact that an ESD pulse may be a shorter duration, higher current pulse relative to an EMP event. These variations can easily cause a factor of 10 difference in the susceptibility levels. For this reason, EMP data is used in this publication for classification purposes only in those cases where ESD data is not available. The EMP data is identified as such in the remarks field (field no. 18) of the detailed data section.

1.5 VARIABILITY ASSOCIATED WITH CONVENTIONAL TEST METHODS

Since ESD testing began, it has been recognized that there was a certain degree of variability in test results due to the test apparatus itself. These variations were attributed to:

- Arcing of the high voltage switching relay.
- Errors in calibration of the test voltages.
- Leakage of the capacitor.
- Parasitic inductances and capacitances.
- Inconsistencies in the criteria used to detect failure.
- Incomplete characterization of worst case pin combinations.

Conventional ESD simulators probably effectively simulate a real ESD event from a charged person or object, since a real ESD would have many of the parasitic R, L, and C values similar to that of the simulator (Reference 8). The problem is, however, that the discharge waveform produced is uncontrolled and cannot be used to obtain repeatable results.

To illustrate the repeatability of tests using a conventional circuit, Figures 2 and 3 present the data RAC has taken from two different conventional ESD simulators. A sampling of 74LS08 devices were obtained of the same date code, attempting to minimize variations in the device under test population. The most susceptible pin was found by step stressing a small sample of devices on each pin until failure. Failures were detected with a curve tracer indicating a change in reverse breakdown voltage characteristics between the pin under test and the substrate of the device.

Once the most susceptible pin was found, a sampling of 30 devices were step stressed to failure on this pin for each of the two simulators. Voltage step increments of 25 volts were used to maximize the resolution of failure voltage distributions. The intent of the study was to:

(1) Determine the failure voltage distribution of a typical device stressed with a conventional test apparatus.

(2) Identify differences in these distributions between two typical simulators.

Another study (Reference 26) with similar objectives yielded even a higher degree of variability. In this study, a sampling of 74F04 and 74F175 devices were tested by three independent test labs. Figures 4 and 5 summarize these results.

These results were taken when ESD testing technology was less mature and testers were being built with little regard for the subtleties involved in making an accurate and repeatable test circuit. Since the data contained in this publication was obtained from a variety of testers, it is apparent that this inherent variability is present in it.

In addition to the inherent variation in test apparatus and devices themselves, there can also exist large variations between manufacturers. This is due to the fact that each manufacturer employs their own unique methodologies and circuitry to protect devices, each with their own protection capability. If the manufacturer was known, it is reported in the detailed data section of this publication.

1.6 SUMMARY AND CONCLUSIONS

This publication presents the most comprehensive compendium of electrostatic discharge susceptibility test data currently available. This data is useful (and mandated by MIL-STD-1686A) for the establishment of ESD control procedures based on the susceptibility of devices being handled, assembled, stored, etc. It is important for the users of this information to understand the limitations of the data contained herein. To accomplish this, previous discussions have addressed the different types of data included in this publication as well as the variation inherent in it.

RAC also strongly encourages any one performing ESD susceptibility tests to submit the results of those tests to RAC for inclusion in the database and dissemination in future editions of this publication. If tests are performed in accordance with MIL-STD-1686A, the results are required to be submitted to RAC as outlined in the Data Item Description DI-RELI-80670 (given in Appendix B, Volume II). Also, given in Appendix B is a format for submitting data if not done in accordance with a specific test method.

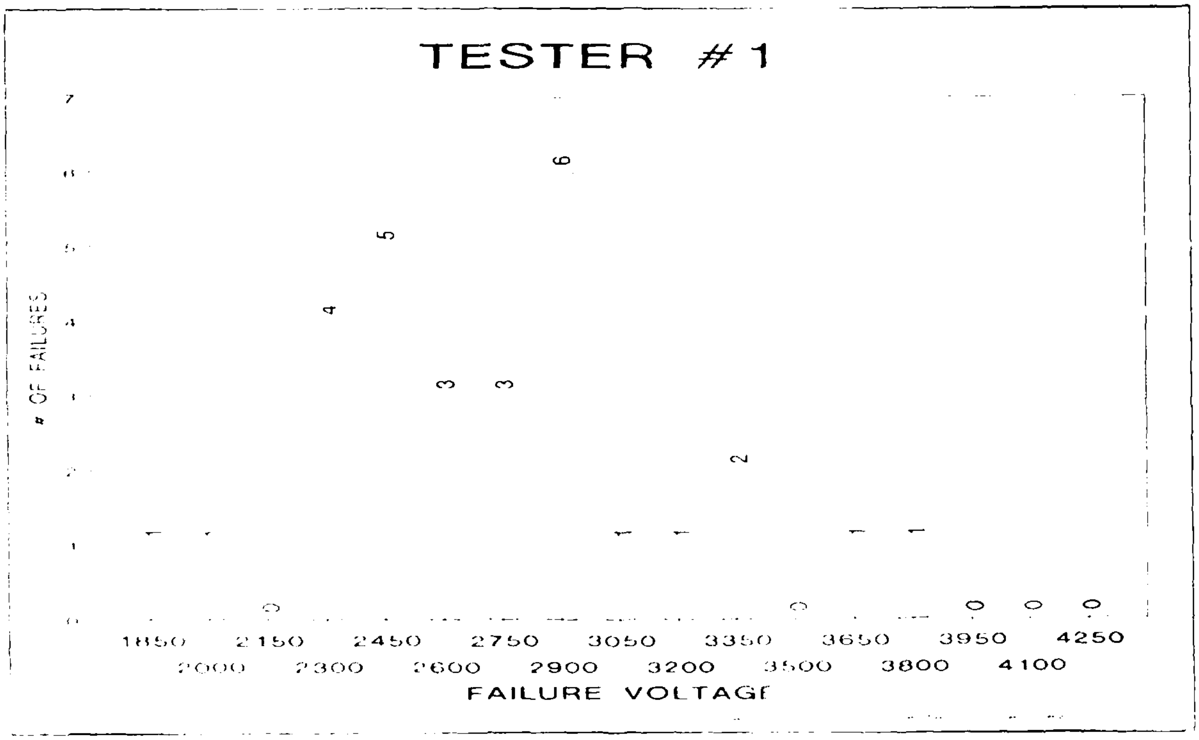


FIGURE 2: FAILURE DISTRIBUTION FOR TESTER #1

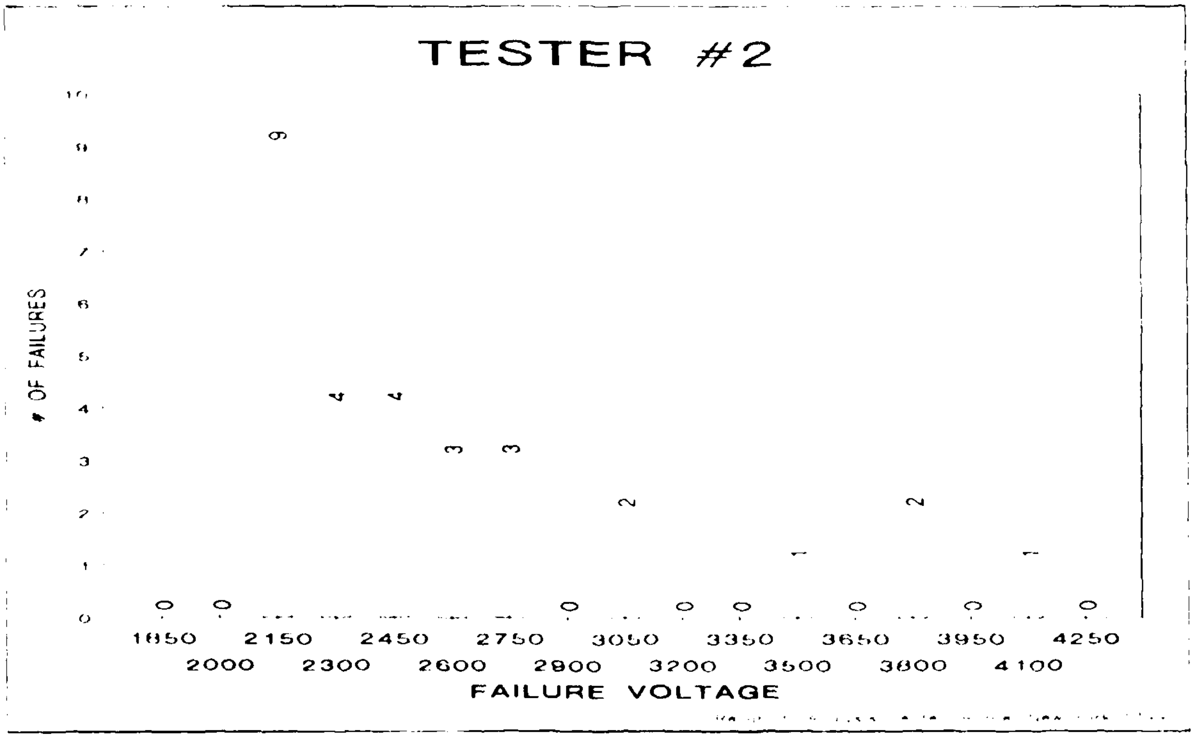


FIGURE 3: FAILURE DISTRIBUTION FOR TESTER #2

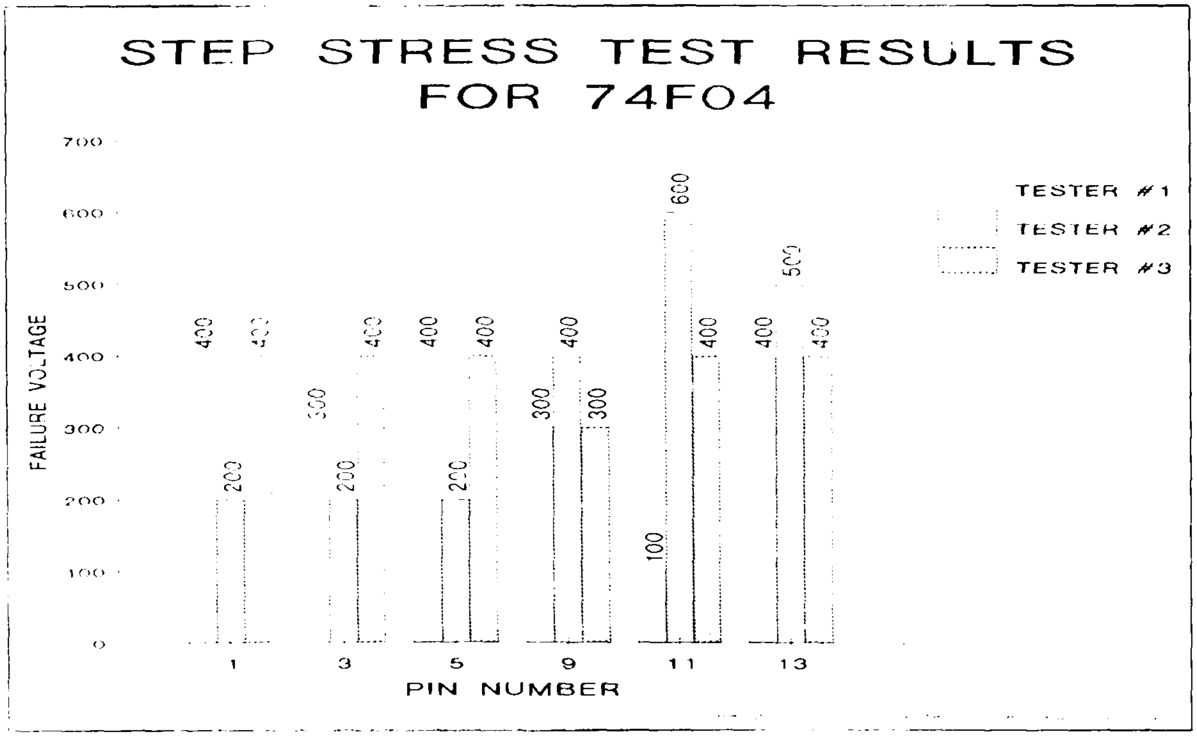


FIGURE 4: STEP-STRESS RESULTS FOR 74F04

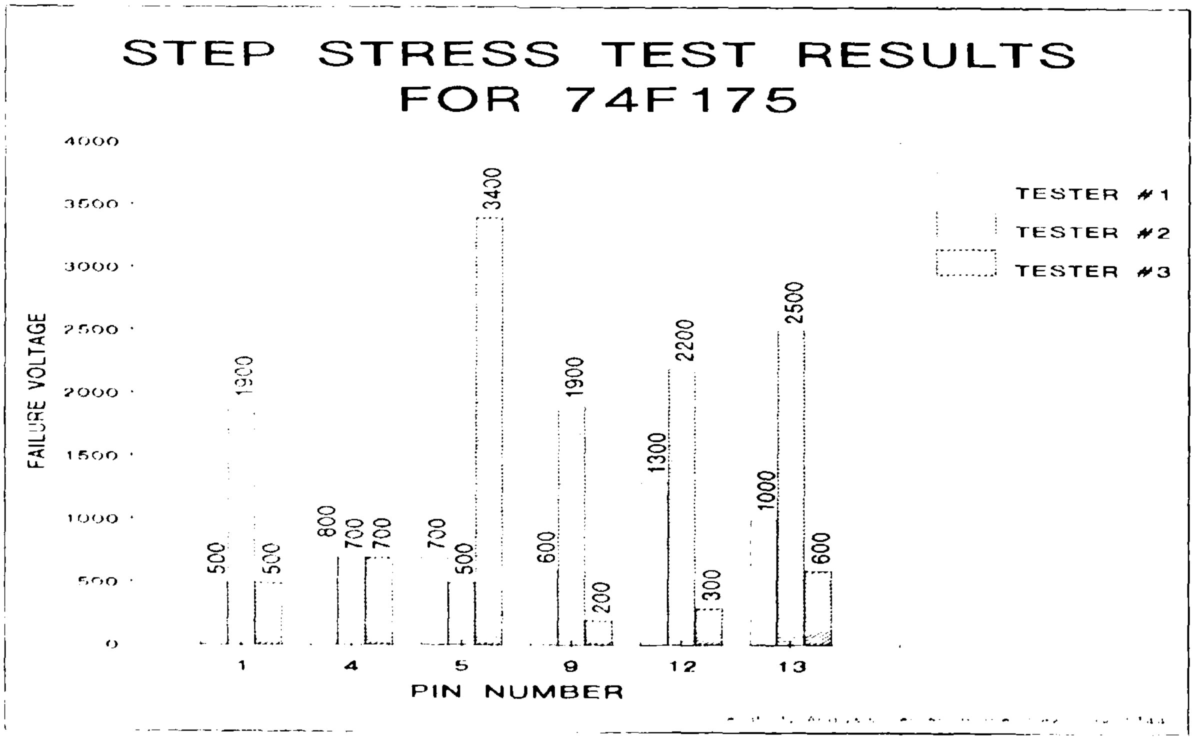


FIGURE 5: STEP-STRESS RESULTS FOR 74F175

SECTION 2.0

FAILURE VOLTAGE PROFILE

2.1 SUSCEPTIBILITIES OF VARIOUS TECHNOLOGIES

The relative susceptibilities of various technologies can be seen from the following histograms (Figure 6 through 35). Cases where there are large peaks in the histogram are indicative of a particular data source or test method. For example, the peaks at 1000-1499 volts for CMOS, 2000-2499 volts for TTL, 1000-1499 volts for STTL, etc., were primarily from data contained in Source Code 030 (Section 5.0). However, when observing the histogram (Figure 19) for failure voltages of all microcircuit technologies combined, a much larger sample size was available and a fairly well-defined curve was obtained.

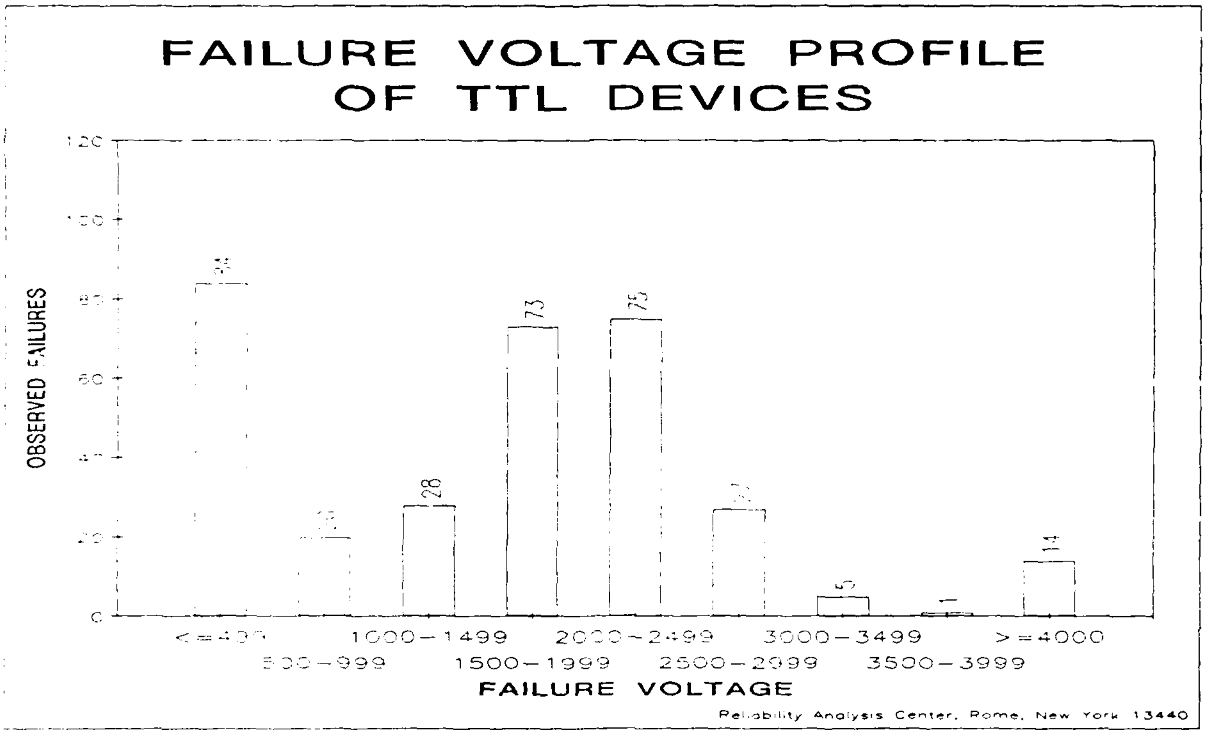


FIGURE 6

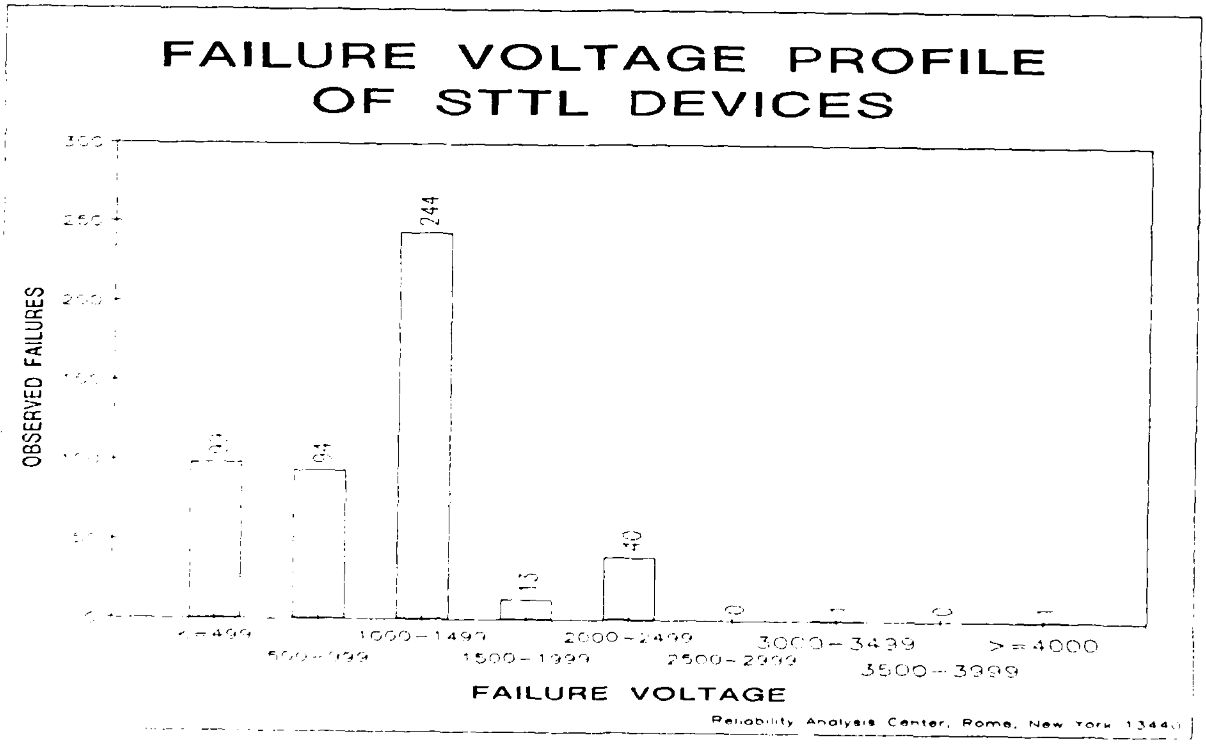


FIGURE 7

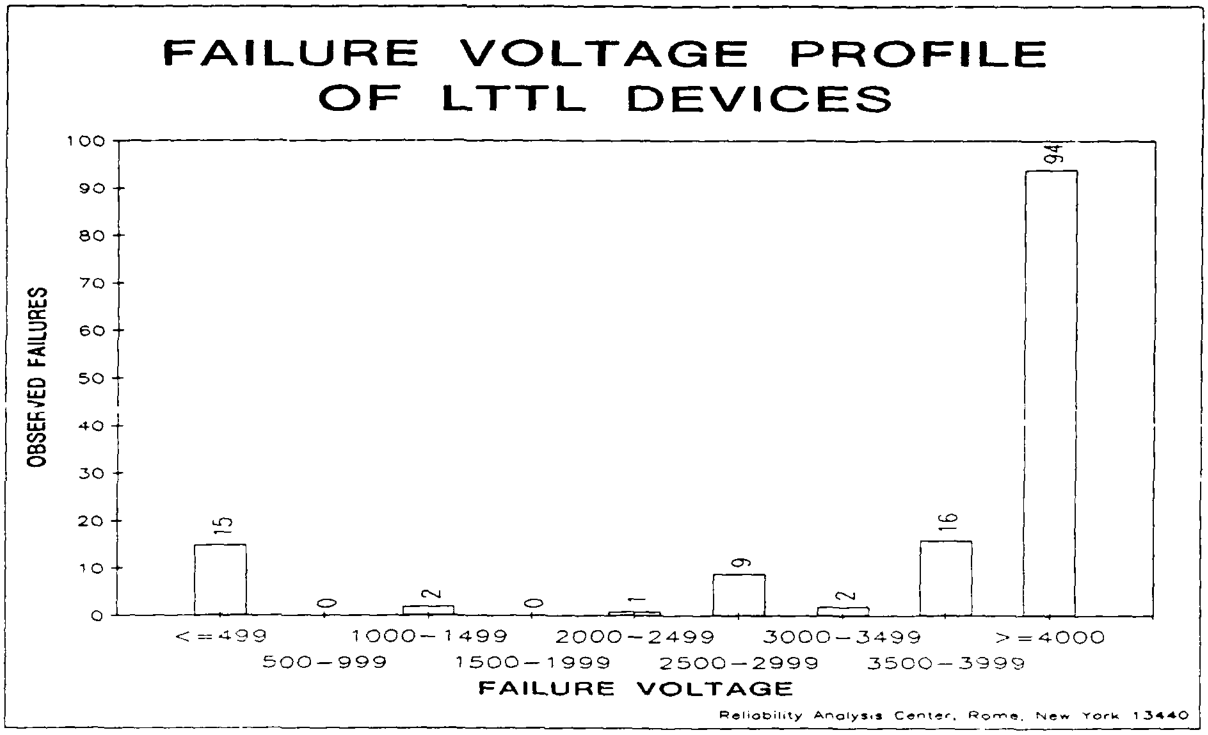


FIGURE 8

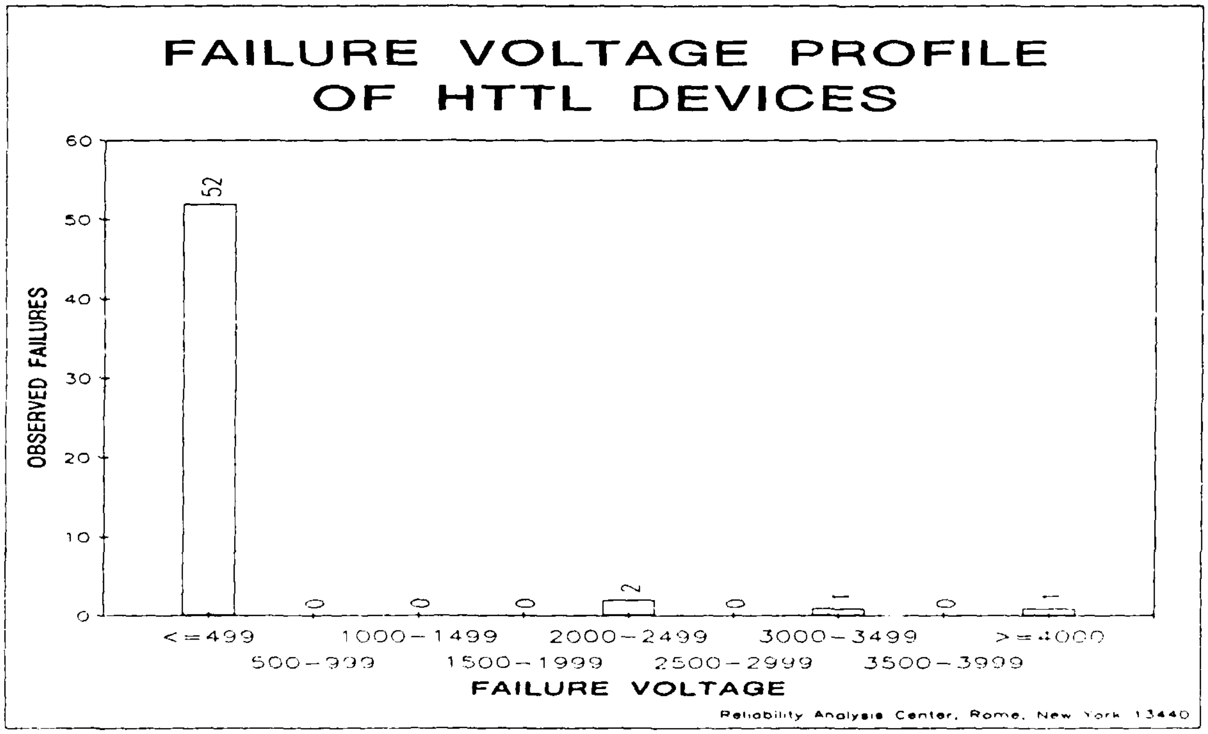


FIGURE 9

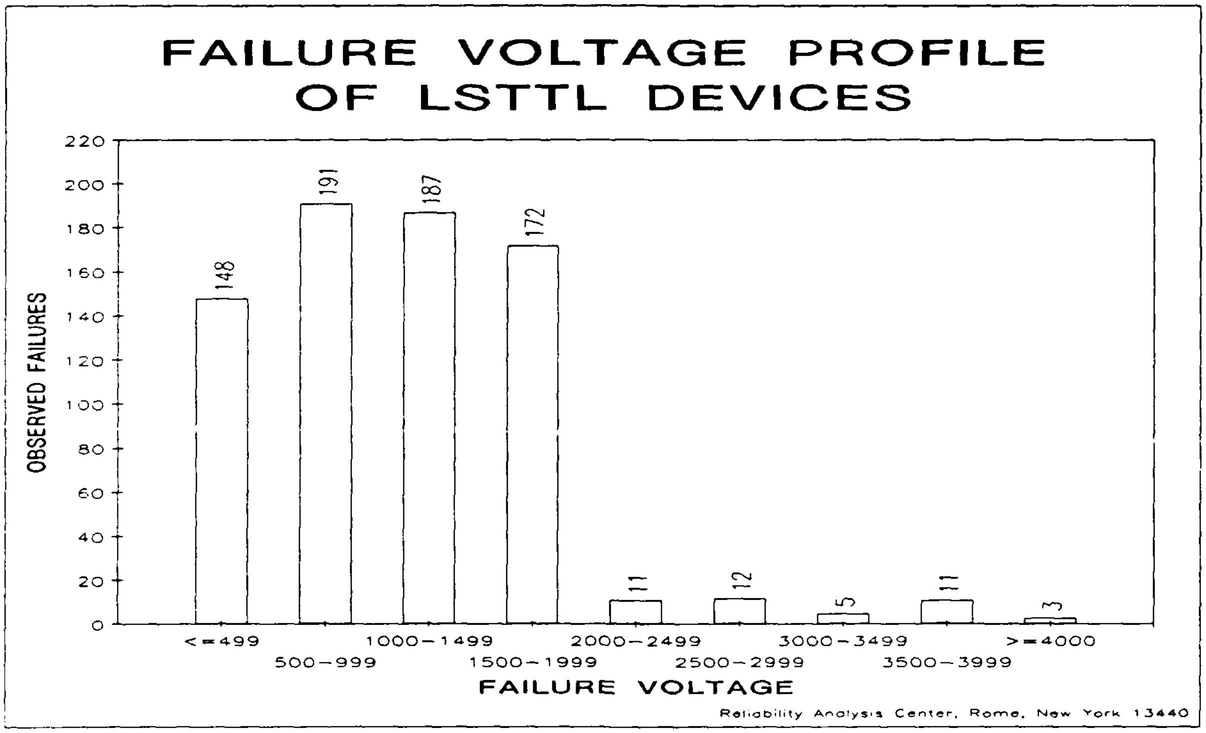


FIGURE 10

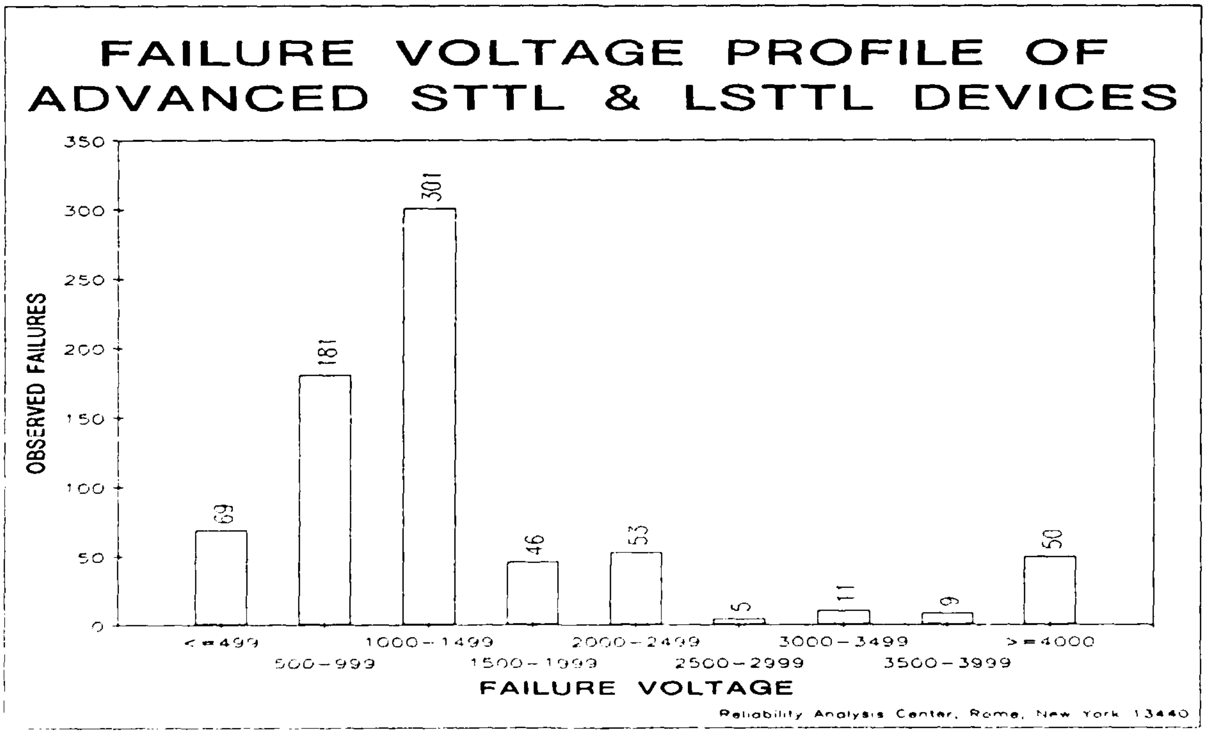


FIGURE 11

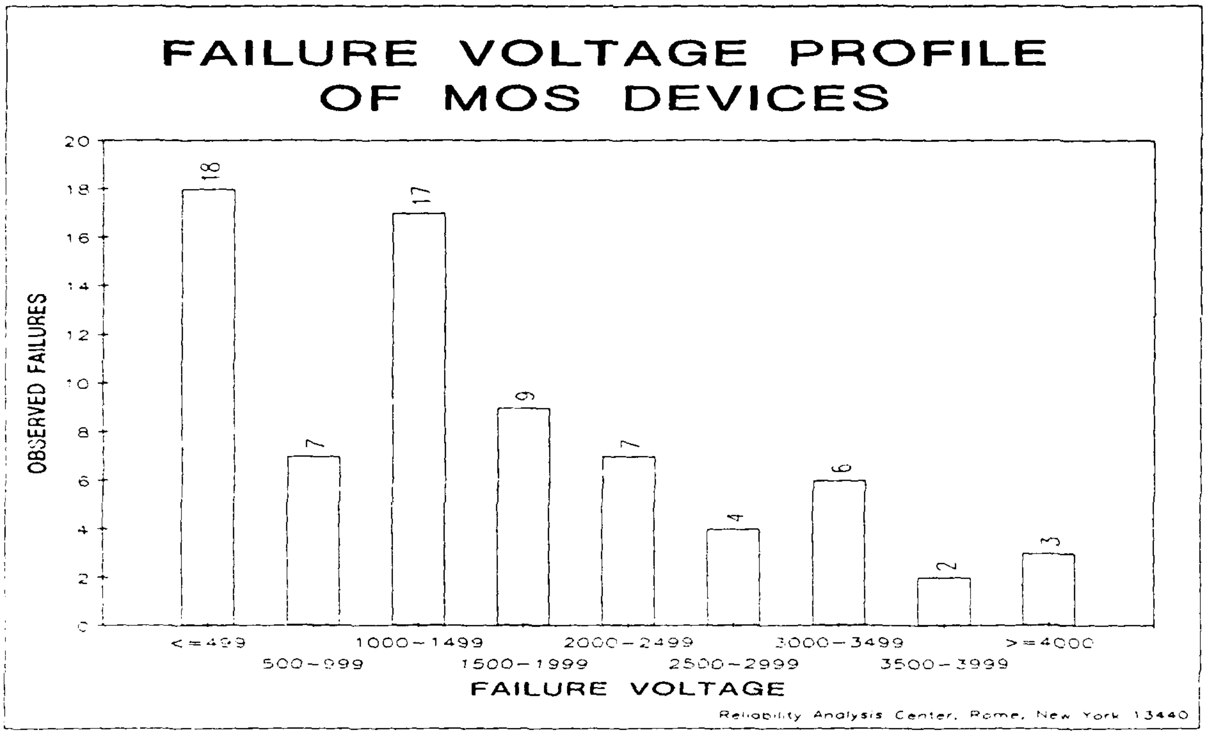


FIGURE 12

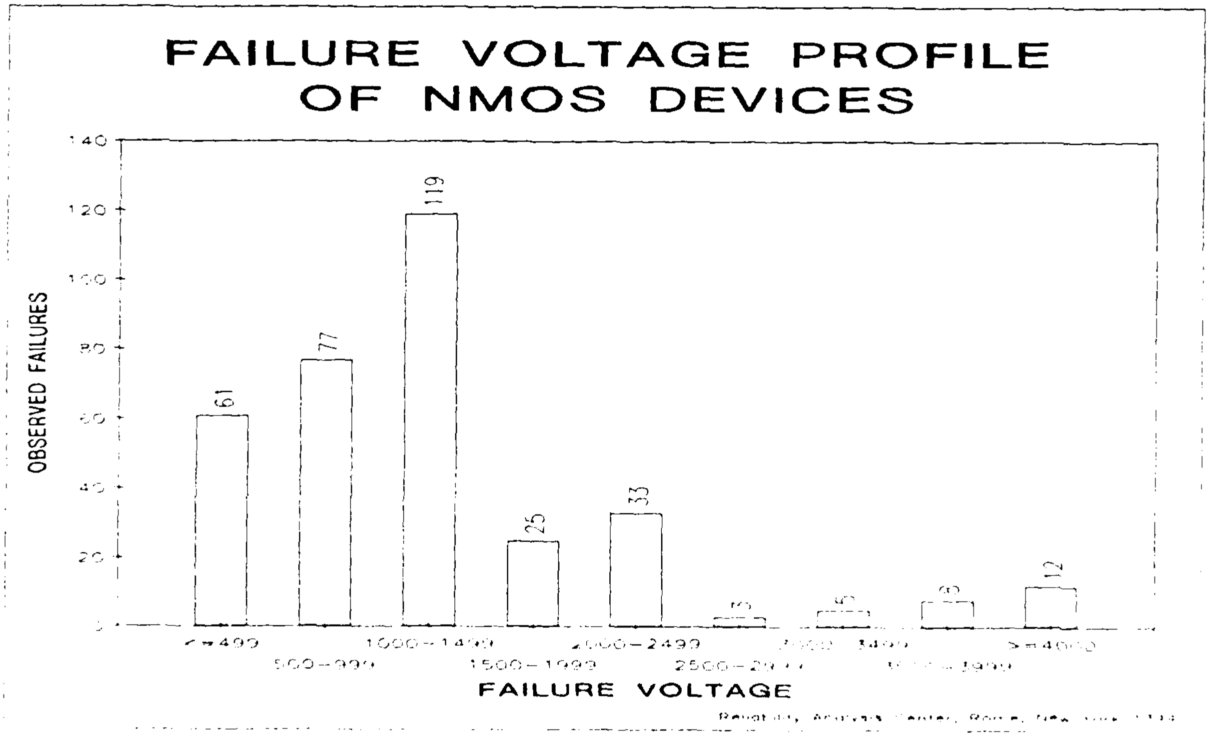
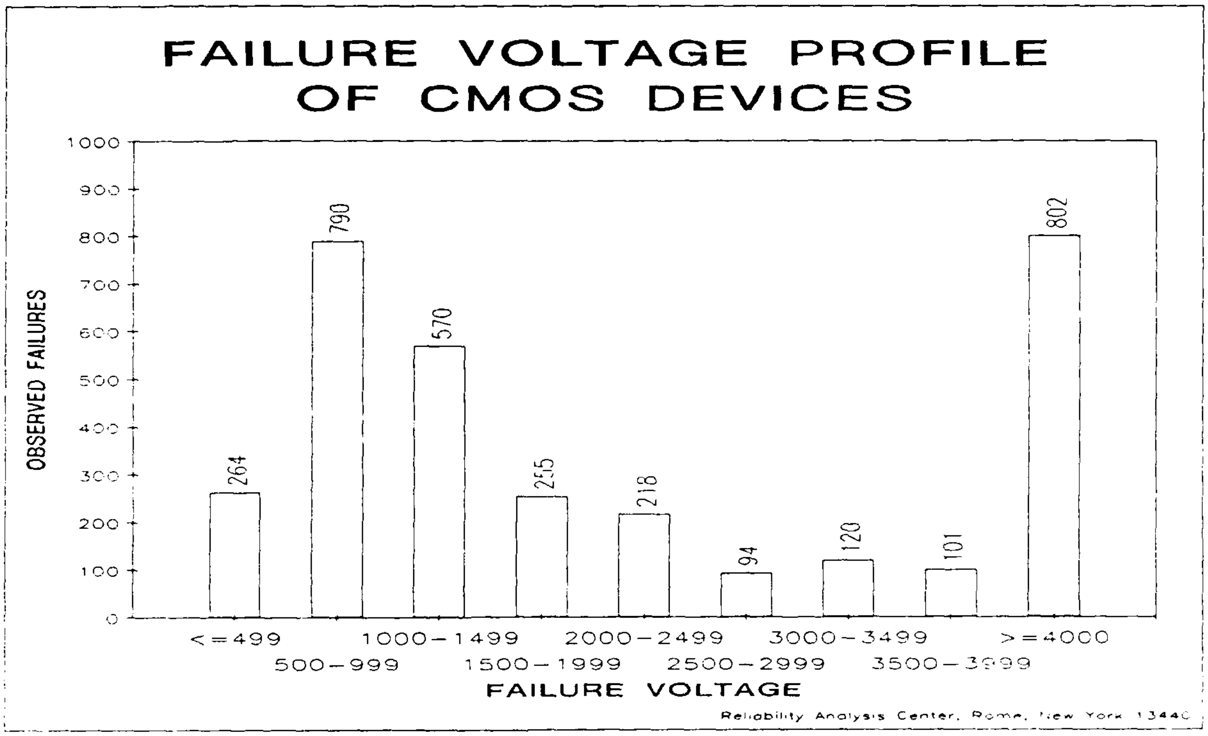
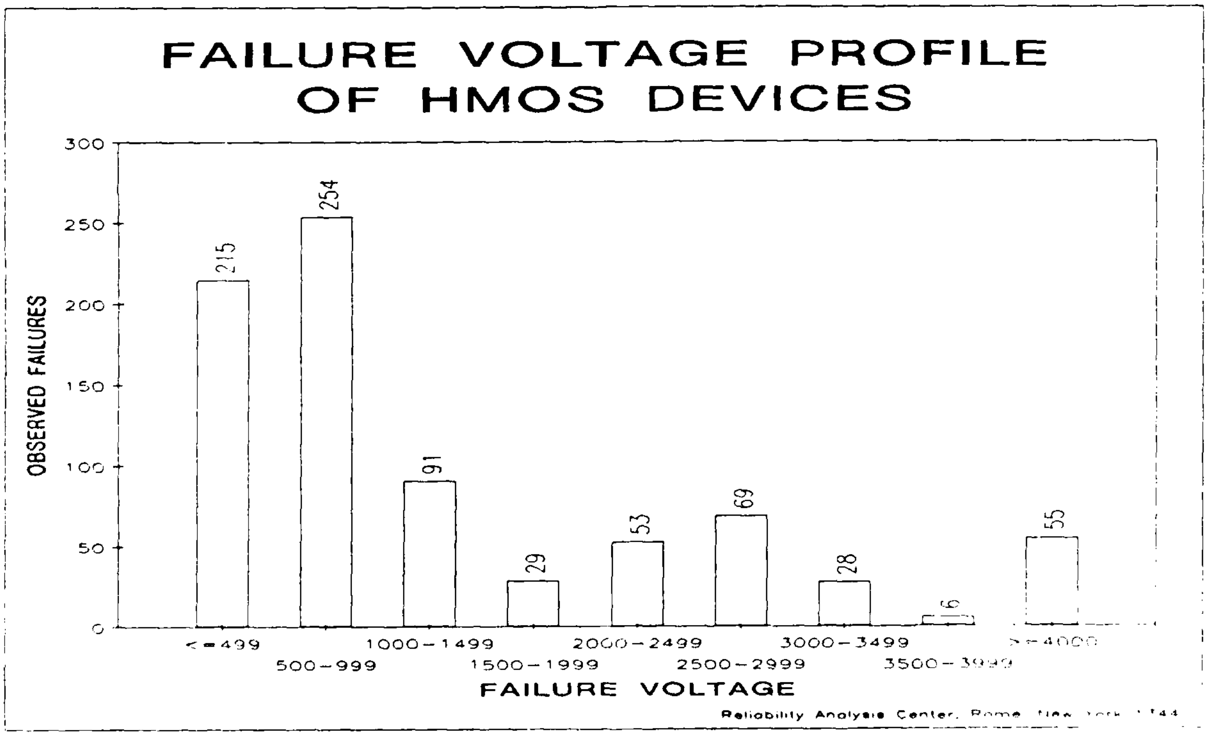


FIGURE 13



Reliability Analysis Center, Rome, New York 13440

FIGURE 14



Reliability Analysis Center, Rome, New York 1344

FIGURE 15

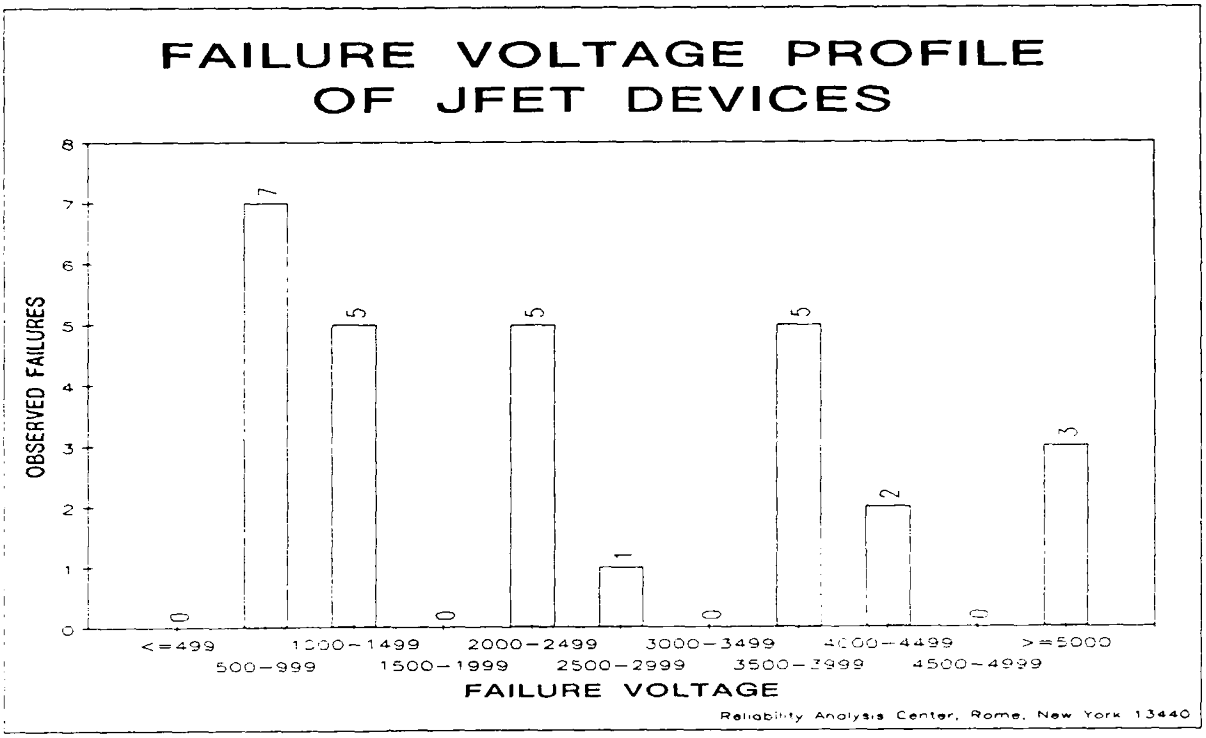


FIGURE 16

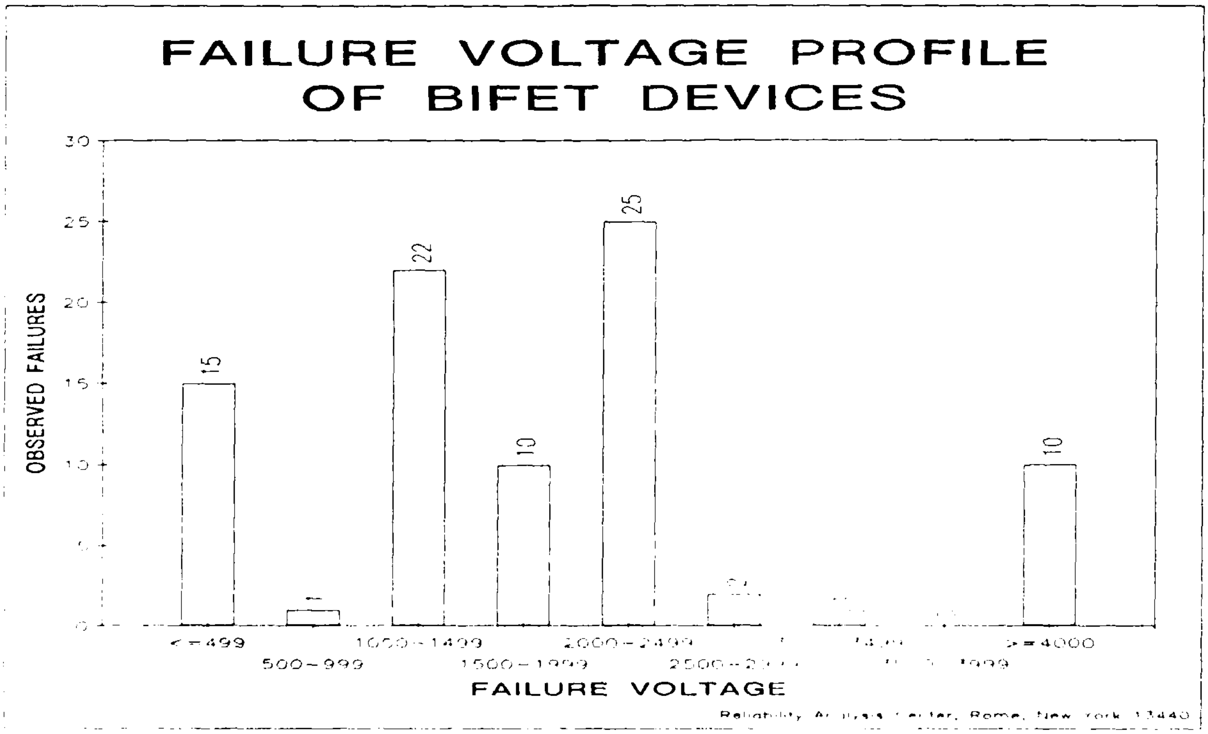


FIGURE 17

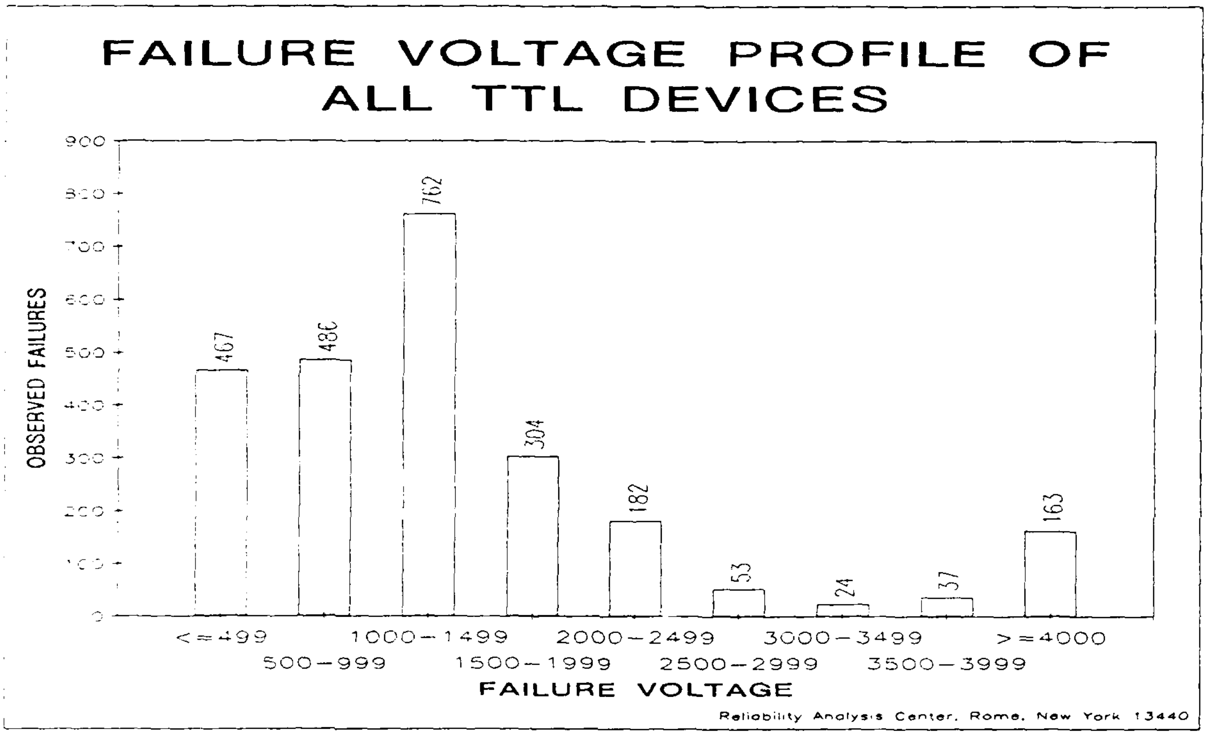


FIGURE 18

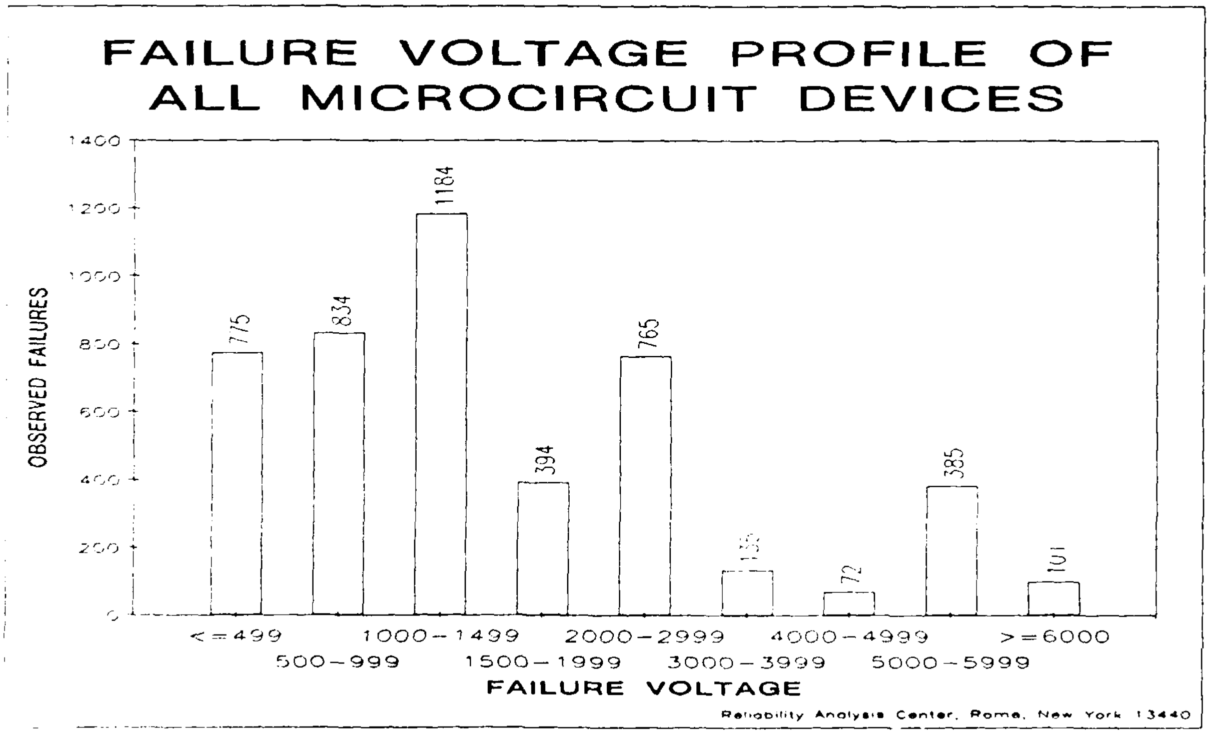


FIGURE 19

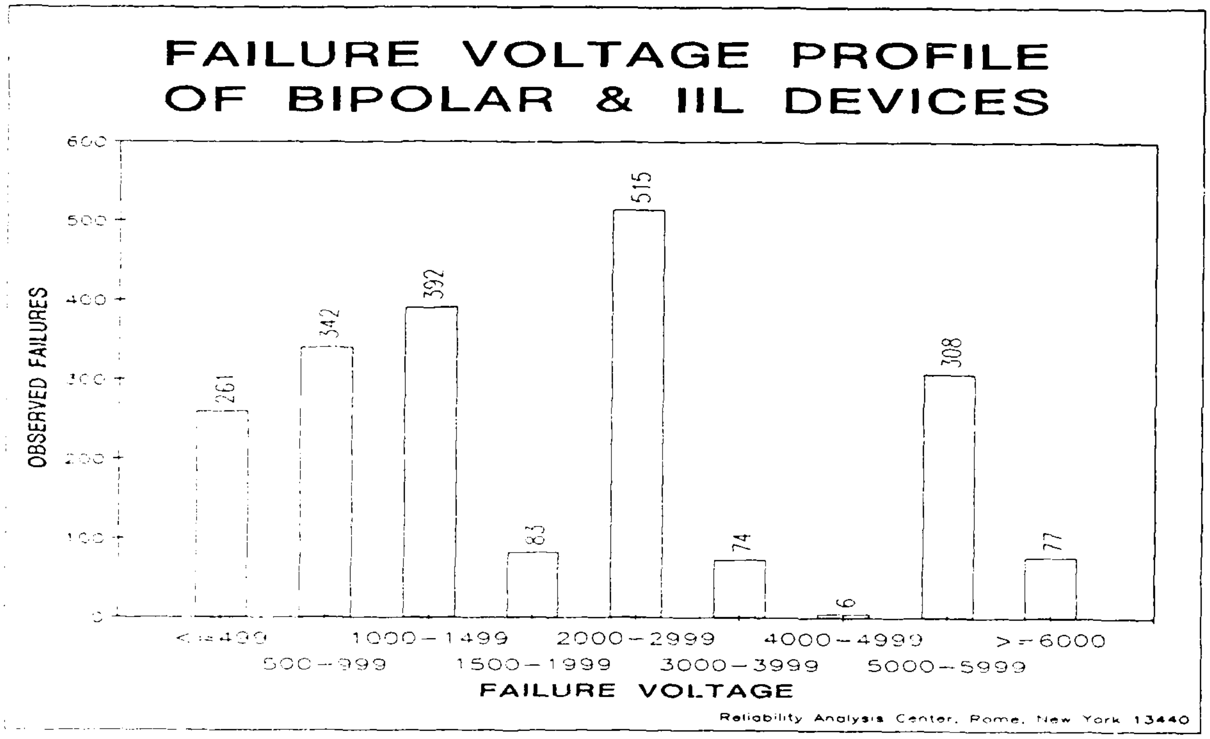


FIGURE 20

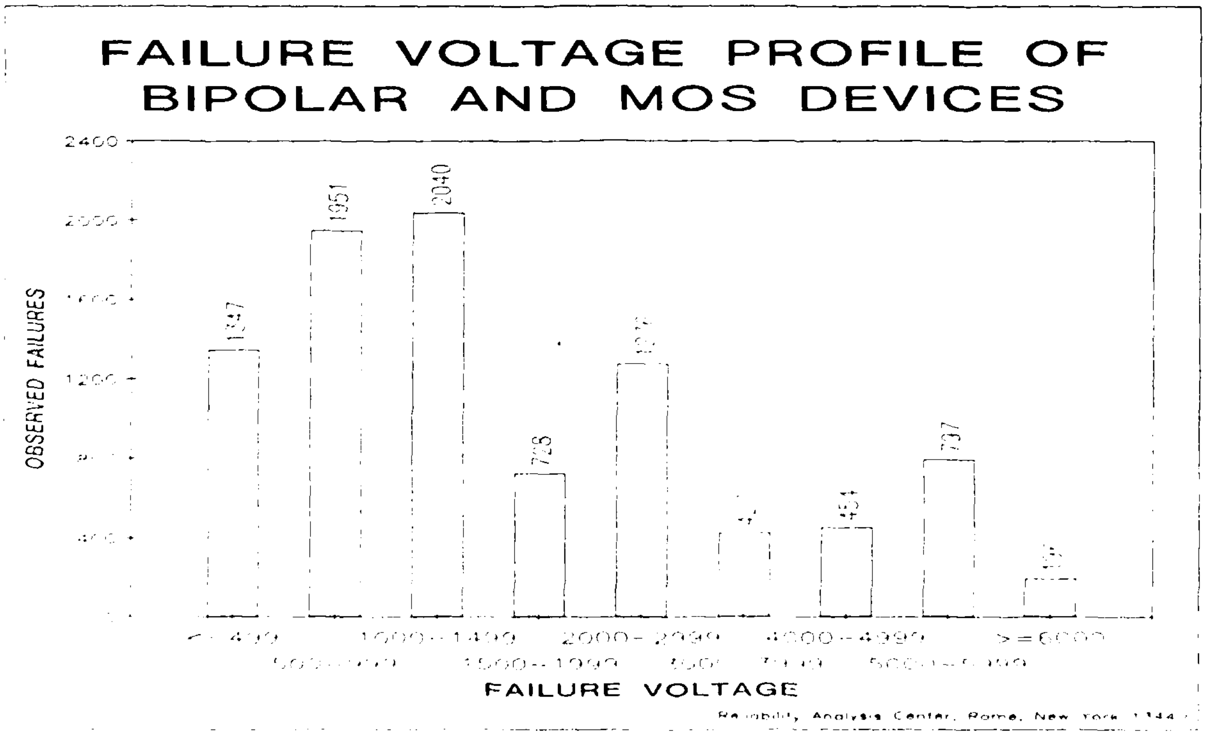


FIGURE 21

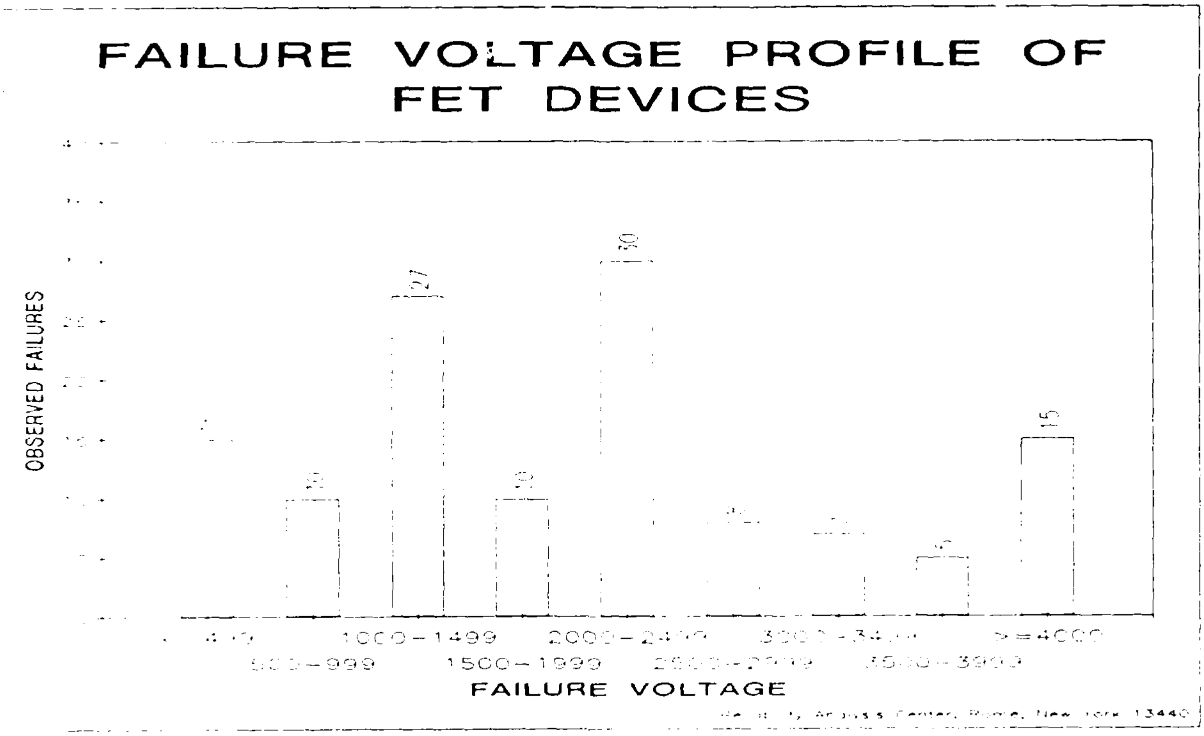


FIGURE 22

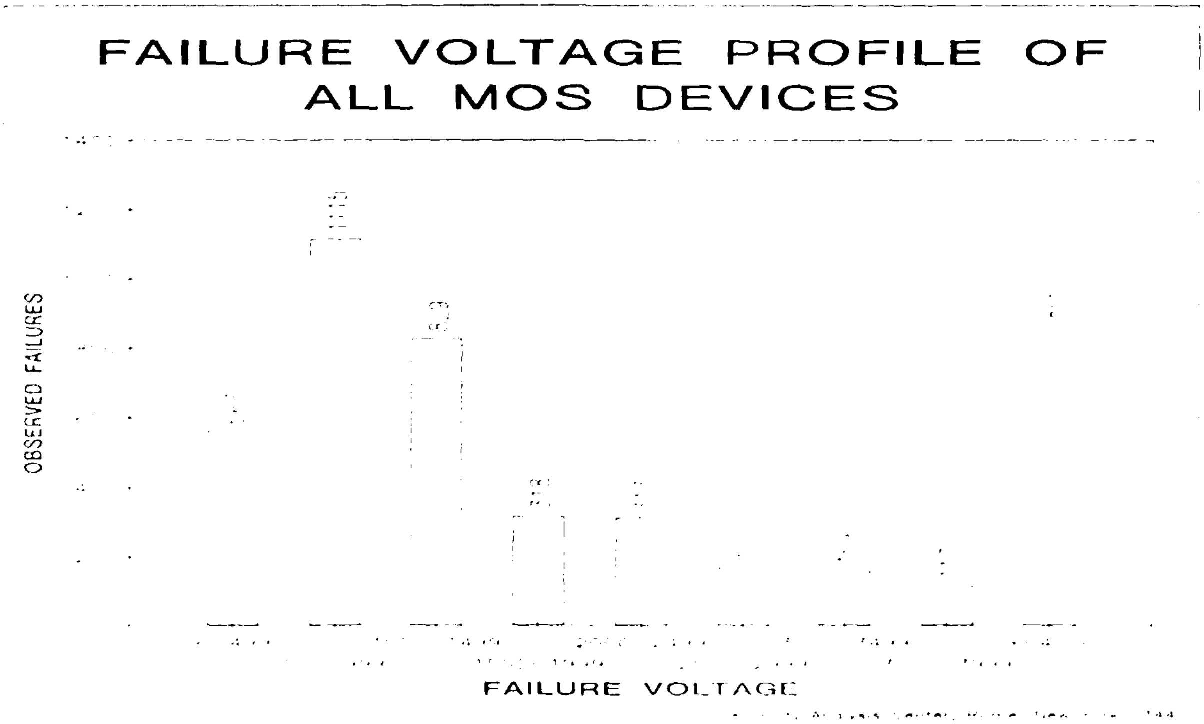


FIGURE 23

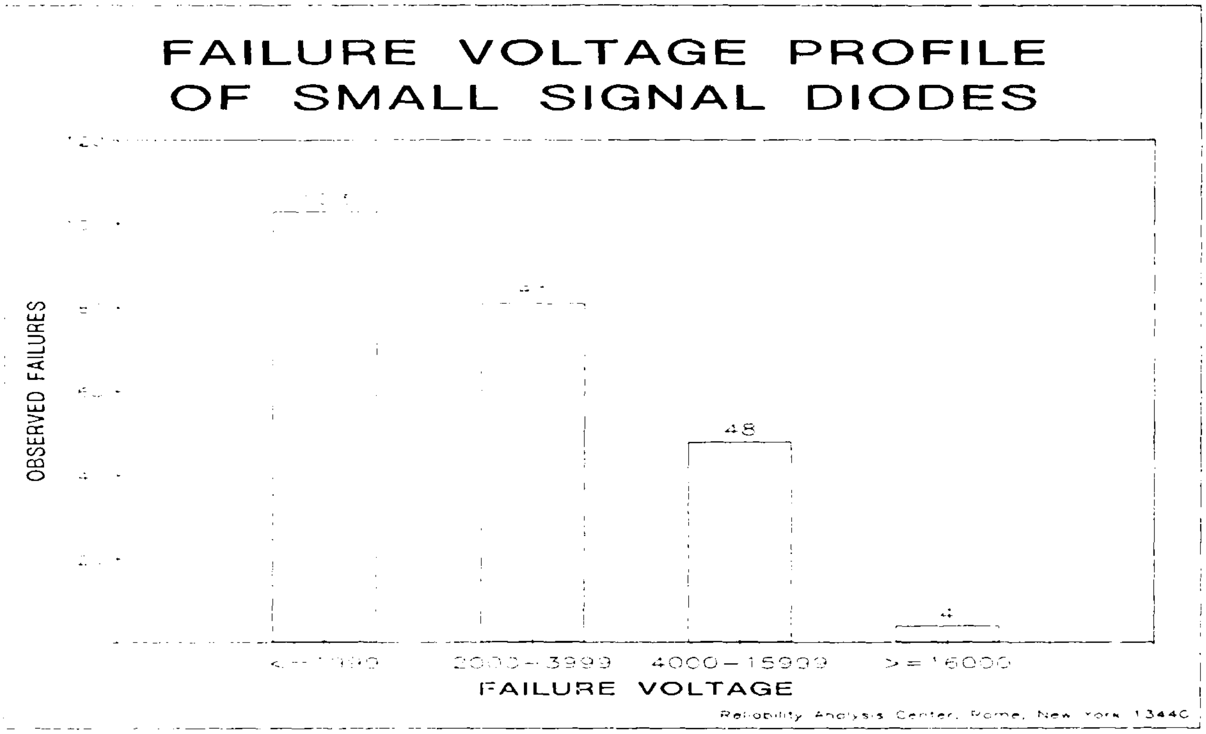


FIGURE 24

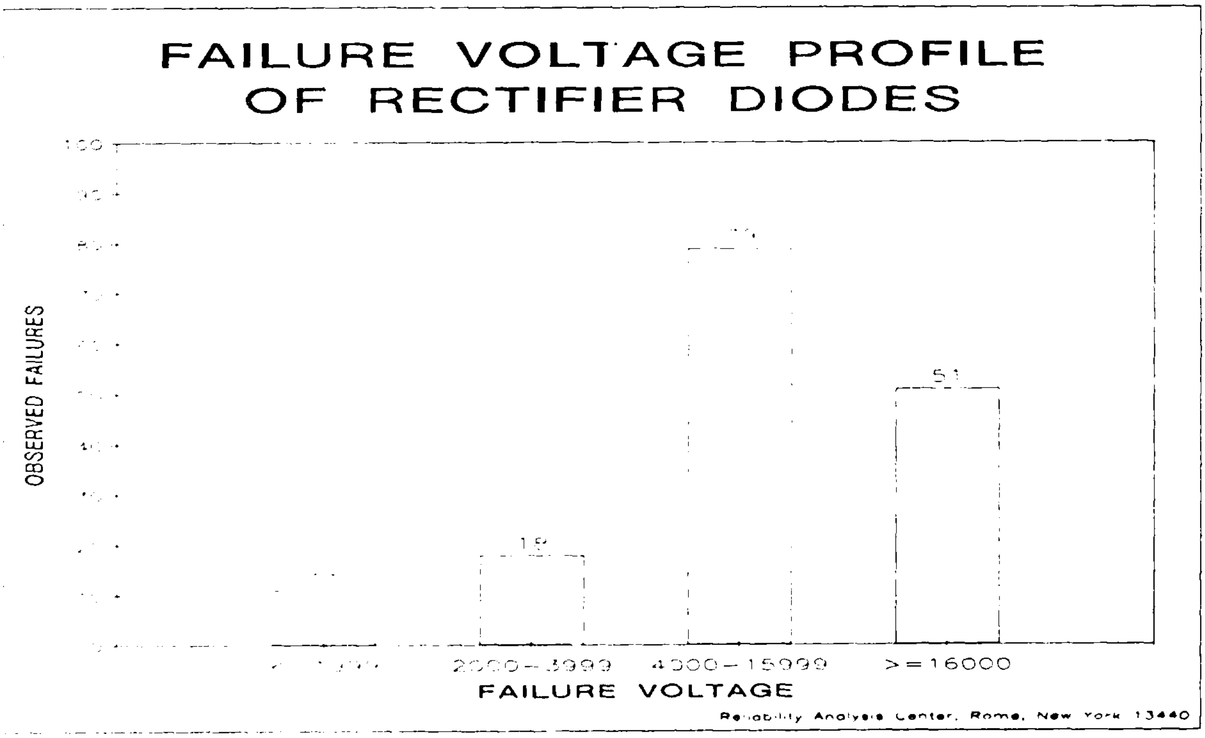
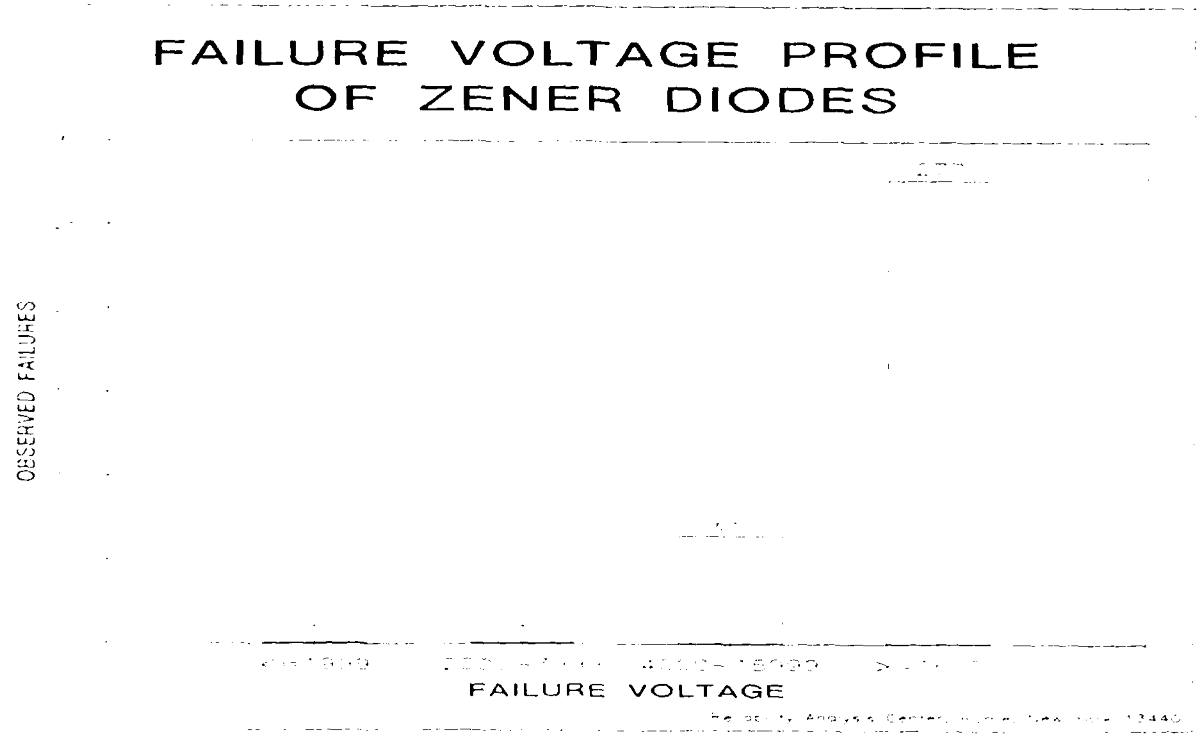
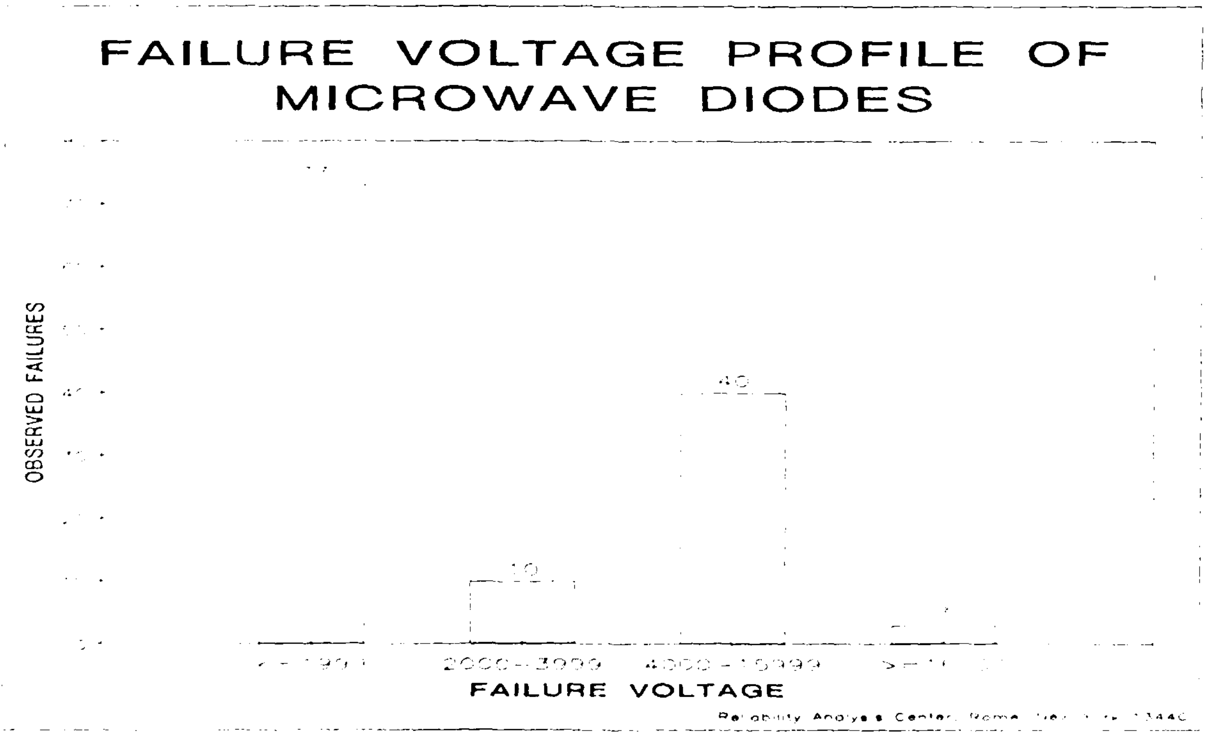


FIGURE 25



FAILURE VOLTAGE PROFILE OF ZENER DIODES

FIGURE 26



FAILURE VOLTAGE PROFILE OF MICROWAVE DIODES

FIGURE 27

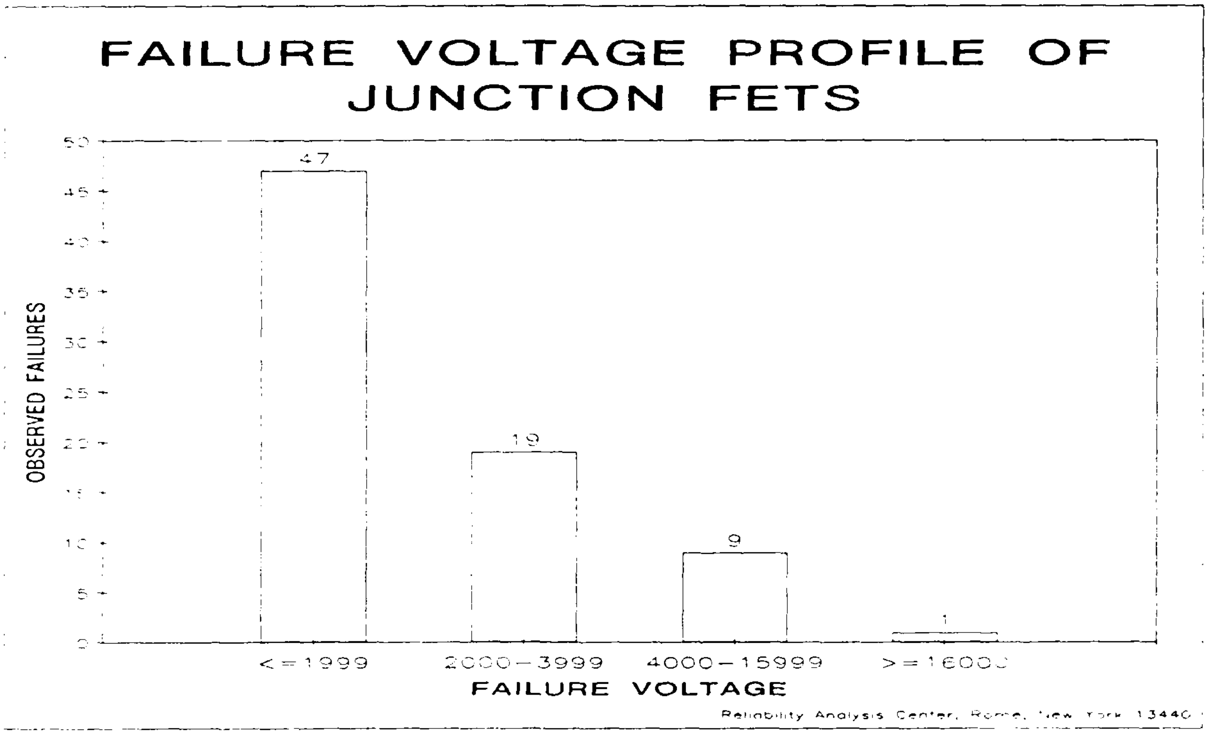


FIGURE 28

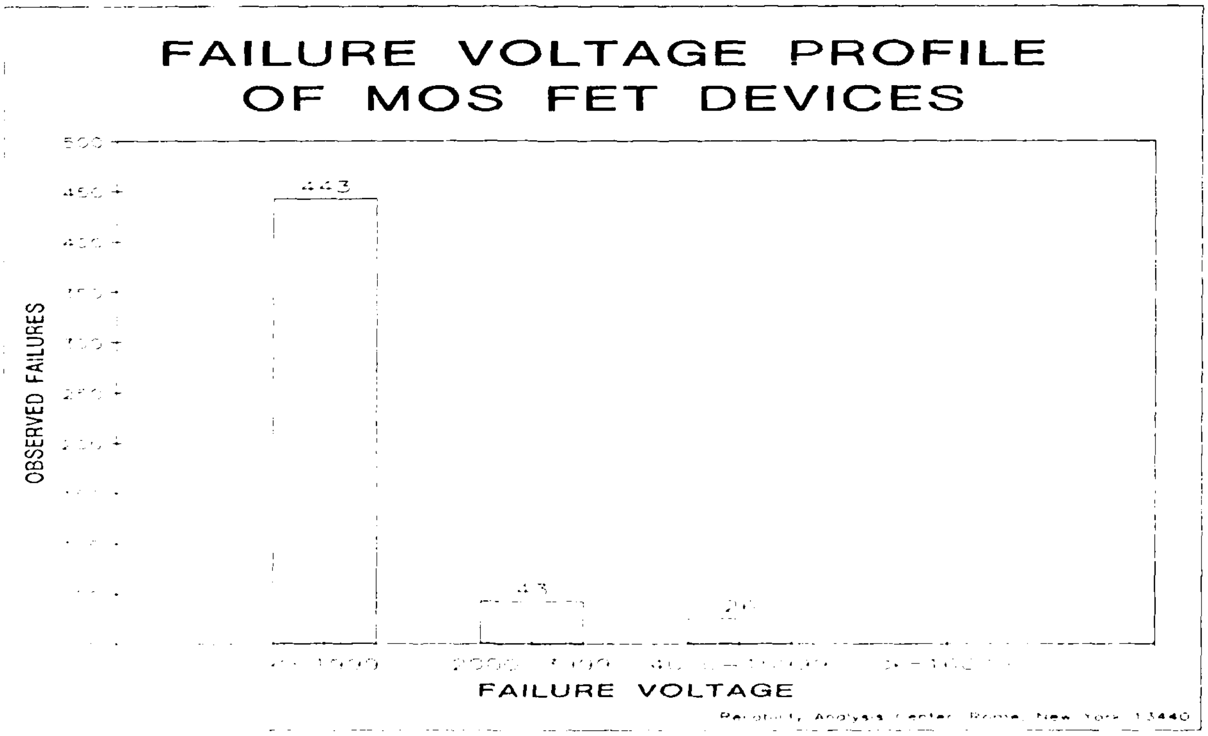


FIGURE 29

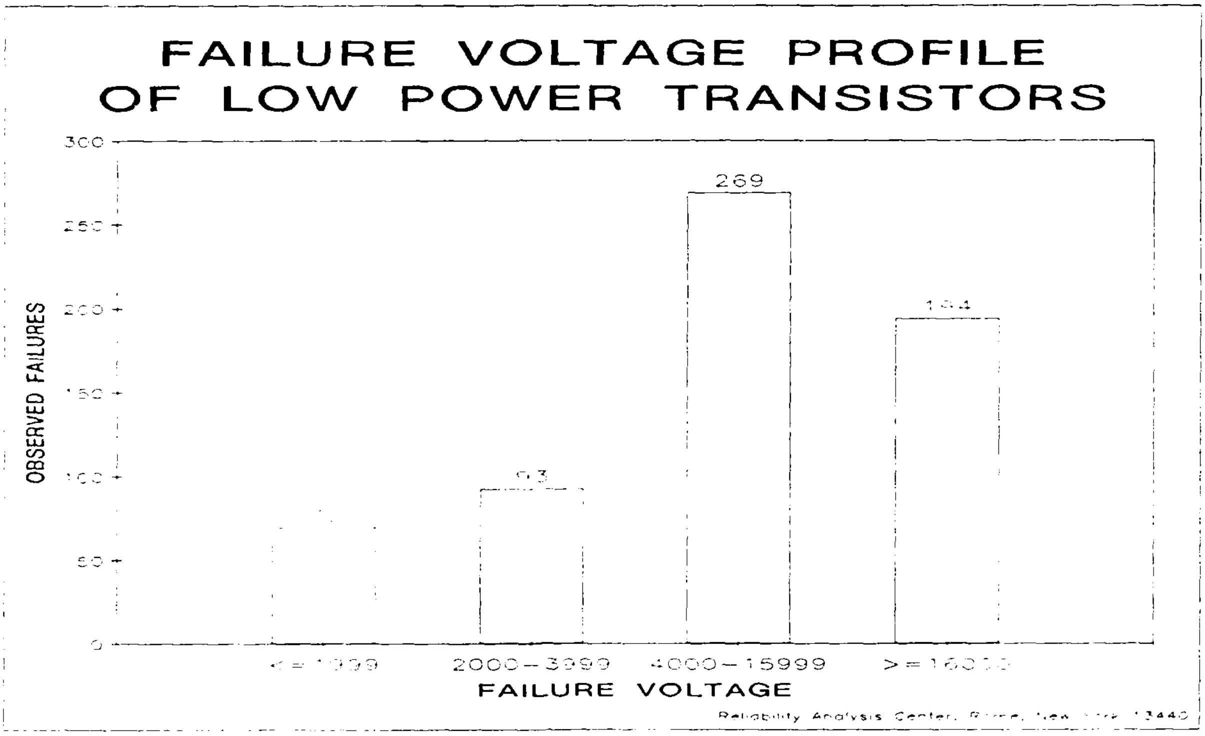


FIGURE 30

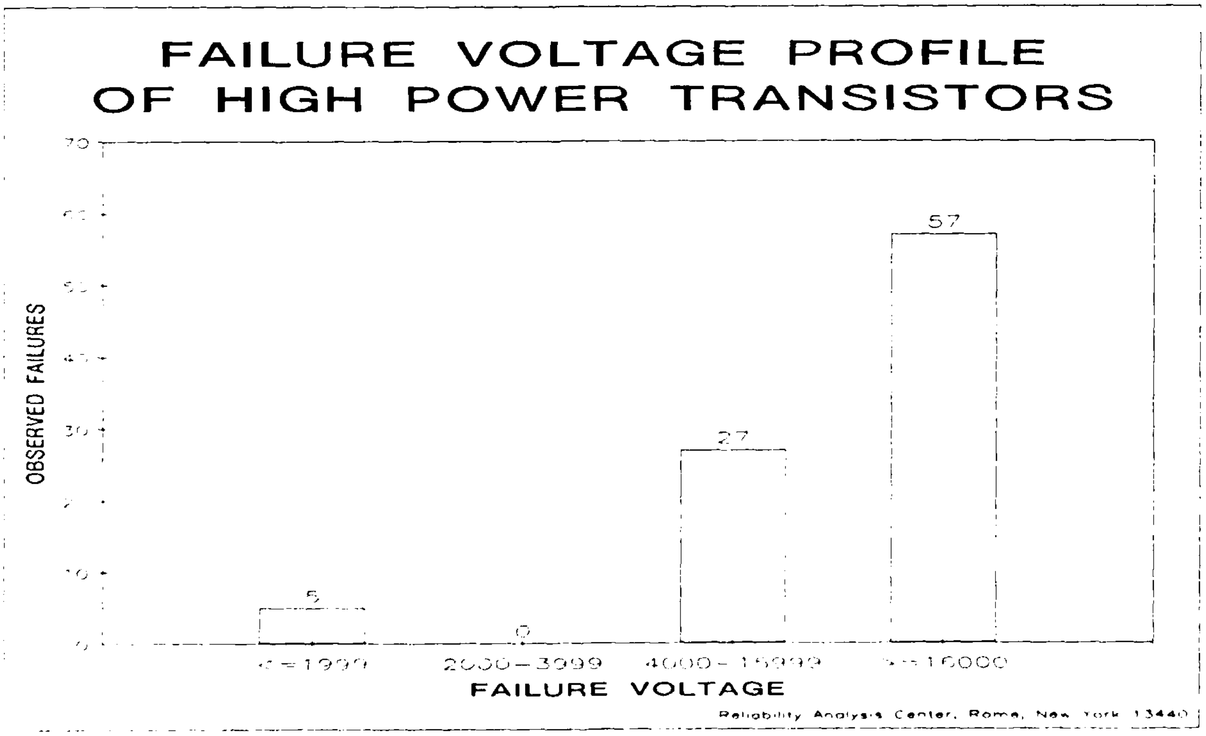


FIGURE 31

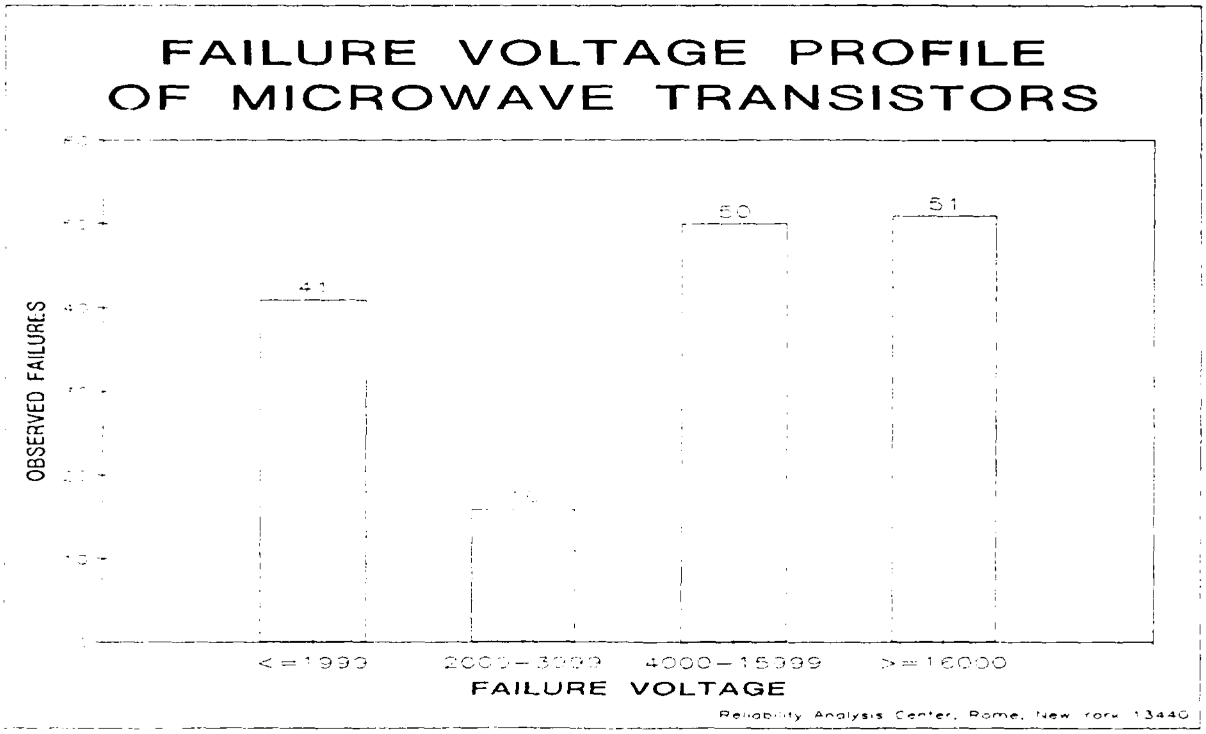


FIGURE 32

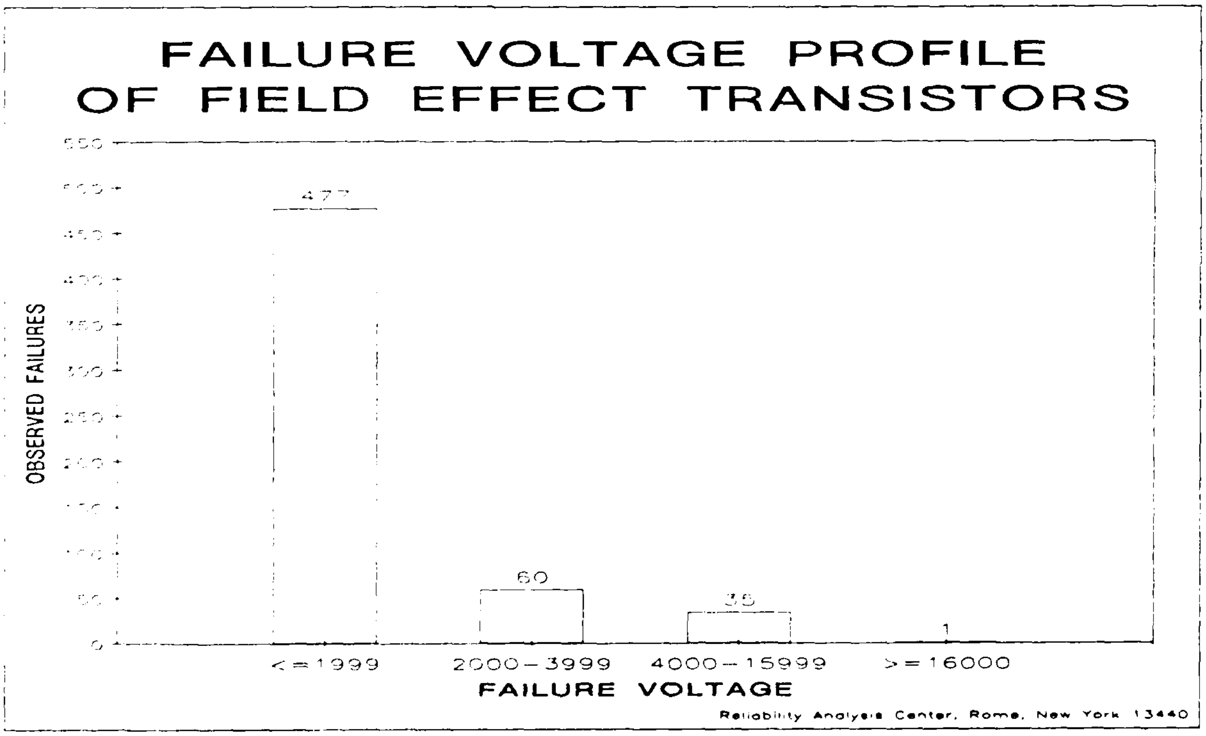


FIGURE 33

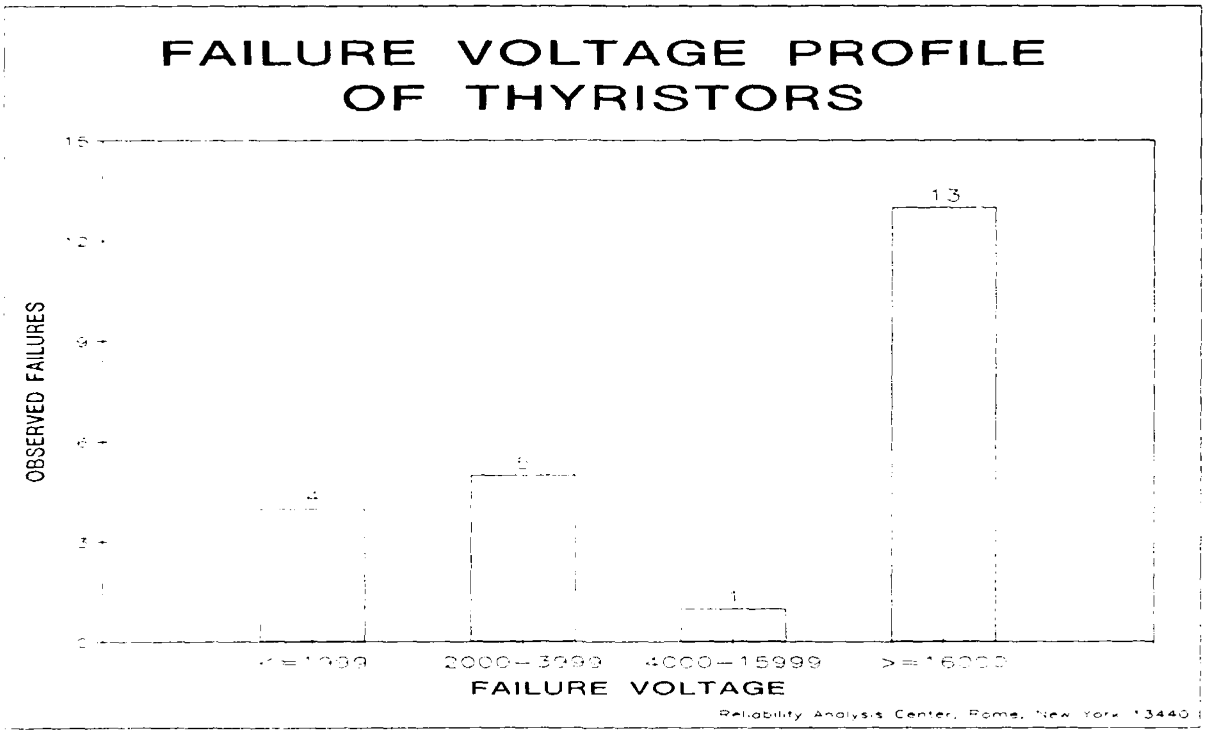


FIGURE 34

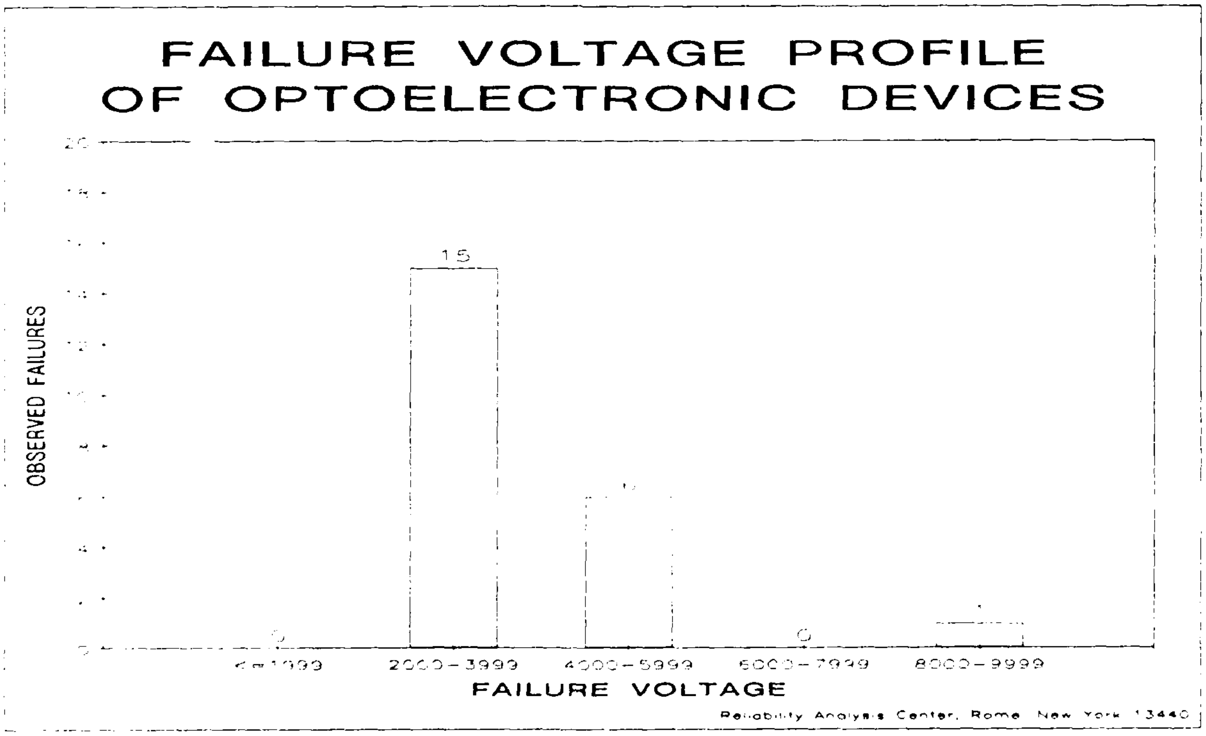


FIGURE 35

2.2 SUMMARIZED DATA - VOLTAGE VS. TECHNOLOGY

The data in this section was generated from the failure voltages of each entry in the Detailed Device Susceptibility Test Data of Section 3.0. Where necessary, the actual test voltages were converted to levels consistent with the widely recognized 100 pF, 1500 ohm human body model since mixing failure voltages of data obtained with different resistor-capacitor values and different discharge models would confound the data significantly. This data conversion methodology was discussed in Section 1.4.

It should be noted that data was also included which represents an approximate upper bound of threshold voltages (i.e., one test at one voltage was carried out on a device and a failure resulted). Thus, although exact damage threshold voltage of the device could not be determined from that one data point, it is known that the threshold is equal to or less than the test voltage.

The data as presented in this section may be somewhat biased since all data entries from the detailed data section were used. This bias comes from the fact that where one data source may have included all of the data (on all pins, for example) another may have only presented the worst-case failures (i.e., the most sensitive pin).

2.3 PERCENTAGE OF FAILURES PER TECHNOLOGY

A total of 5,501 device records were categorized during the preparation of this databook. Table 1 and 2 summarizes the percentages of each technology family, (integrated circuits and discrete semiconductors respectively) in each category of ESD classification. Section 3.0 contains the complete categorization data by part numbers.

TABLE 1: PERCENTAGE OF FAILURE RECORDS PER TECHNOLOGY-IC

	1				2				3
TECHNOLOGY	(<=499)	(500-999)	(1000-1499)	(1500-1999)	(2000-2499)	(2500-2999)	(3000-3499)	(3500-3999)	(>=4000)
TTL	25.7% (84)	6.1% (20)	8.6% (28)	22.3% (73)	22.9% (75)	8.3% (27)	1.5% (5)	0.3% (1)	4.3% (14)
STTL	20.1% (99)	19.1% (94)	49.6% (244)	2.7% (13)	8.1% (40)	0.0% (0)	0.2% (1)	0.0% (0)	0.2% (1)
LTTL	10.8% (15)	0.0% (0)	1.4% (2)	0.0% (0)	0.7% (1)	6.5% (9)	1.4% (2)	11.5% (16)	67.7% (94)
HTTL	92.8% (52)	0.0% (0)	0.0% (0)	0.0% (0)	3.6% (2)	0.0% (0)	1.8% (1)	0.0% (0)	1.8% (1)
LSTTL	20.0% (148)	25.8% (191)	25.3% (187)	23.2% (172)	1.5% (11)	1.6% (12)	0.7% (5)	1.5% (11)	0.4% (3)
Advanced STTL and LSTTL	9.5% (69)	25.0% (181)	41.6% (301)	6.3% (46)	7.3% (53)	0.7% (5)	1.4% (10)	1.2% (9)	7.0% (50)
MOS	24.7% (18)	9.6% (7)	23.3% (17)	12.3% (9)	9.6% (7)	5.5% (4)	8.2% (6)	2.7% (2)	4.1% (3)
NMOS	17.8% (61)	22.4% (77)	34.7% (119)	7.3% (25)	9.6% (33)	0.9% (3)	1.5% (5)	2.3% (8)	3.5% (12)
CMOS	8.2% (264)	24.4% (790)	18.6% (601)	7.9% (240)	6.7% (218)	2.9% (94)	3.7% (120)	3.1% (101)	24.5% (792)
HMOS	26.9% (215)	31.7% (254)	11.4% (91)	3.6% (29)	6.6% (53)	8.6% (69)	3.5% (28)	0.8% (6)	6.9% (55)
JFET	0.0% (0)	26.0% (7)	14.8% (4)	0.0% (0)	18.5% (5)	3.7% (1)	0.0% (0)	18.5% (5)	18.5% (5)
BIFET	17.4% (15)	1.2% (1)	25.6% (22)	11.6% (10)	29.1% (25)	2.3% (2)	1.2% (1)	0.0% (0)	11.6% (10)
All TTL's	18.8% (467)	19.6% (486)	30.8% (762)	12.3% (304)	7.3% (182)	2.1% (53)	1.0% (24)	1.5% (37)	6.6% (163)
Bipolar Microcircuits	16.0% (726)	18.3% (828)	25.4% (1154)	8.5% (387)	13.6% (618)	2.9% (132)	1.9% (85)	1.1% (50)	12.3% (556)
Bipolar and IIL	12.6% (259)	16.6% (342)	19.1% (392)	4.0% (83)	21.2% (436)	3.8% (79)	3.0% (61)	0.6% (13)	19.1% (393)
Bipolar and MOS	14.3% (1284)	21.8% (1956)	22.0% (1982)	7.8% (705)	10.3% (929)	3.4% (302)	2.7% (244)	1.9% (167)	15.8% (1418)
All FET's	13.3% (15)	7.1% (8)	23.0% (26)	8.9% (10)	26.5% (30)	2.6% (3)	0.9% (1)	4.4% (5)	13.3% (15)
All MOS's	12.5% (558)	25.3% (1128)	18.6% (828)	7.1% (318)	7.0% (311)	3.8% (170)	3.6% (159)	2.7% (117)	19.4% (862)

TABLE 2: PERCENTAGE OF FAILURE RECORDS PER CIRCUIT TYPE-DISCRETE

	1	2	3	N
CIRCUIT TYPE	< = 1999	2000-3999	4000-15999	> = 16000
Small Signal Diode	43.7% (103)	34.3% (81)	20.3% (48)	1.7% (4)
Rectifier	6.9% (11)	11.3% (18)	49.7% (79)	32.1% (51)
Zener	0.3% (1)	0.3% (1)	18.9% (65)	80.5% (277)
Microwave Diode	57.9% (73)	7.9% (10)	31.8% (40)	2.4% (3)
Junction FET	61.8% (47)	25.1% (19)	11.8% (9)	1.3% (1)
MOS FET	86.5% (443)	8.4% (43)	5.1% (26)	0.0% (0)
Low Power Transistor	11.4% (70)	15.1% (93)	42.0% (259)	31.5% (194)
High Power Transistor	5.6% (5)	0.0% (0)	30.3% (27)	64.1% (57)
Microwave Transistor	25.9% (41)	10.1% (16)	31.7% (50)	32.3% (51)
Field Effect Transistor	83.5% (497)	10.4% (62)	5.9% (35)	0.2% (1)
Thyristor	17.4% (4)	21.7% (5)	4.4% (1)	56.5% (13)
Optoelectronic Device	0.0% (0)	68.2% (15)	31.8% (7)	0.0% (0)

SECTION 3.0

DETAILED DEVICE SUSCEPTIBILITY TEST DATA

RAC ESD DATABASE

(1) Part Number	(2) Part Mfr	(3) ESD Class		(4) Part Description							(5) Technology			
	(6) Test Source	(7) Test Date	(8) Test Type	(9) Test Resistance	(10) Test Capacitance	(11) Number Pulses	(12) Date Code	(13) Number Devices	(14) Test Result	(15) Test Voltage	(16) Pin Combination	(17) Failure Criteria	(18) Test Remarks	(19) General Remarks

(1) BASIC PART NUMBER. The part number of the device.

(2) MANUFACTURER. Manufacturer of the device (see Table 3).

(3) ESD CLASSICATION. The classification per MIL-STD-1686A and MIL-STD-883 based on the best available data.

(4) DESCRIPTION. Basic function of the device.

(5) TECHNOLOGY. The basic technology of the device.

(6) TEST SOURCE. Source code - identifies the data source (see Section 5.0).

(7) TEST DATE. Date (month and year) the test was performed.

(8) TEST TYPE. SS = Step Stress, i.e., the device was stressed in incremental voltages and tested for failure between each one. GN = Go/No-Go, i.e., one voltage level only applied to the device and then tested for failure.

(9) RES. Resistance (in ohms) used in the discharge circuit.

(10) CAP. Capacitance used in the discharge circuit (10^{-6} = microfarads, 10^{-12} = picofarads).

(11) NUMBER PULSES. The total number of pulses applied to the device at the voltage (field no. 15) before failure (if result = fail) or before testing for failure (if result = pass).

(12) DATE CODE. Date code as it appeared on the device.

(13) NUM. DEV. The number of devices which were tested to the same stresses results (i.e., all other fields the same).

(14) RESULT. Whether the device passed or failed testing at the given test conditions.

RAC ESD DATABASE

(1) Part Number (2) Part Mfr. (3) ESD Class (4) Part Description (5) Technology

(6) Test Source (7) Test Date (8) Test Type (9) Test Resistance (10) Test Capacitance (11) Number Pulses (12) Date Code (13) Number Devices (14) Test Result (15) Test Voltage (16) Pin Combination (17) Failure Criteria (18) Test Remarks (19) General Remarks

(15) VOLTAGE. The voltage applied to the device (if the device was step-stressed and it failed during stepping, the failure voltage is given).

(16) PIN COMBINATION. The pin combination tested: function, pin number, and polarity (if known).

(17) FAILURE CRITERIA. Criteria used to detect device failure (see Table 4).

(18) TEST REMARK. Any comment which clarifies the data with respect to the specific test record (see Table 5).

(19) GENERAL REMARK. Any comment which clarifies the test procedures or results (see Table 6).

RAC ESD DATABASE

Table 3 - MANUFACTURER LISTING

CODE	MANUFACTURER NAME
ALP	Alpha Industries
AM	American Microcircuits
AMD	Advanced Micro Devices
AMP	Amperex Electronics
ANA	Analog Devices
ANZ	Anzac Electronics
ATM	ATMEL
BEC	Beckman Instruments
BEN	Bendix
CCL	Croven Crystal Ltd.
CEN	Centralab
CMP	Component Device Inc.
COD	Codi Semiconductor
CSI	Continental Semi. Inc.
CYP	Cypress Semiconductor
DAL	Dale Electronics
DCC	Dynamic Control Corp
DEL	Delco Electronics
DIC	Dickson Elec. Corp.
ETC	Elec. Transistor Corp.
FSC	Fairchild
GE	General Electric
GEN	General Semiconductor
GI	General Instruments
GTL	Gilway Technical Lamp
HAR	Harris
HAU	Haufman
HEW	Hewlett Packard
HIT	Hitachi
HON	Honeywell
HYB	Hybrid Systems
HYC	Hycomp Inc.
IDT	International Device Technologies
ITT	ITT Semiconductor
INM	INMOS
INS	Inselek
INT	Intel
IRC	Intl. Rectifier Corp.
ISL	Intersil
ITE	Intech
KSC	KSC Semiconductor Corp.
LEA	Lear Siegler
LTC	Linear Technology Corp.
MAC	MACOM
MAS	Microwave Associates
MCC	McCoy Electronics
MIT	Micro Power Systems
MON	Monolithic Memories
MOS	Mostek

CODE	MANUFACTURER NAME
MOT	Motorola Semi
MPI	Micropac Industries
MSC	Microwave Semi Corp
MSI	Microsystems International
N/R	Not Reported
NCR	National Cash Register
NEC	Nippon Electric Company (NEC)
NIT	Nitron
NSC	National Semi
NUC	Nucleonic Prod
PLE	Plessey
PPC	PPC Products
PPI	Precision Products Inc.
PRE	Precision Monolithics
RAY	Raytheon
RCA	RCA
RI	Rockwell Intl (Includes Collins)
SCN	Semicon
SEM	Semtech Corp.
SEN	Sensitron Semi.
SEQ	SEEQ
SGS	SGS ATES
SIE	Siemans
SIG	Signetics
SIL	Silicon General
SIX	Siliconix
SOL	Solitron Devices
SPR	Sprague Electric
SSD	Solid State Devices
SSS	Solid State Scientific
SUP	Supertex
SYN	Syntron
TEC	Teledyne Crystalonics
TEK	Tektronix
TEL	Teledyne
TEX	Texas Instruments
THC	Thermometrics
TRC	Transition Elec. Corp.
TRW	TRW
UDT	United Detector Technology
ULT	Ultronix Inc.
UNI	Unitrode
VAR	Various
VIS	Vishay
WES	Westinghouse
XIC	Xicor
ZIL	Zilog

RAC ESD DATABASE

Table 4 - FAILURE CRITERIA LISTING

CODE	FAILURE CRITERIA
1	1 UA LEAKAGE AT 10V.
2	1 UA LEAKAGE AT 20V.
3	10 UA INPUT LEAKAGE PREVIOUSLY MEASURED TO BE 1 UA.
4	10% CHANGE IN ELECTRICAL PARAMETERS.
5	10% CHANGE IN LEAKAGE CURRENT.
6	10% PARAMETER CHANGE.
7	110= 4 UA.
8	2 MA LEAKAGE CURRENT OR OPEN CONDUCTOR LINES.
9	2 UA LEAKAGE CURRENT OR OPEN CONDUCTOR LINES.
10	2% CHANGE OF VOUT AT IL= 50UA.
11	20 UA LEAKAGE CURRENT OR OPEN CONDUCTOR LINES.
12	200 NA LEAKAGE CURRENT OR OPEN CONDUCTOR LINES.
13	25% LEAKAGE, 1uA LEAKAGE, FUNCTION FAILS.
14	50% DROP IN REVERSE VOLTAGE AT IR= 5UA.
15	50% DROP IN V(BR) CBO AT IB= 5UA.
16	50% DROP IN V(BR) GSS AT IG= 5UA.
17	50% INCREASE IN GATE LEAKAGE CURRENT.
18	A 10% CHANGE IN INPUT OFFSET VOLTAGE AND INPUT BIAS CURRENT.
19	A 10% OR > CHANGE IN ANY MEASURED ELECTRICAL PARAMETER WAS CONSIDERED A FAILURE.
20	A 10% OR > INC. IN MEAS. LEAKAGE CURRENT @OR < A VOLT 10% < THE INITIAL BRKDWN VOLT.
21	A CHANGE OF 0.5% OR GREATER TOLERANCE.
22	A SHIFT OF 10% OF INPUT OFFSET VOLTAGE AND INPUT BIAS CURRENT.
23	ANY MEASURABLE CHANGE IN AN ELECTRICAL PARAMETER.
24	BVBE AT IR= 100NA.
25	CATASTROPHIC FAILURE (INPUT CURRENT).
26	CATASTROPHIC.
27	CHANGE IN IGSS.
28	CHANGE IN IIH OF 10%.
29	CHANGE IN IIH OF 20NA AT VCC= 5.5V AND VIN= 2.4V.
30	CHANGE IN IIH OF 500% AT VIN= 2.7V.
31	CHANGE IN IIL OF +500% AT VIN= .45V.
32	CHANGE IN IIL OF 500% AT VIN= 5V.
33	CHANGE IN IIO OF 500%.
34	CHANGE IN IL OF +500% AT VIN= 1V.
35	CHANGE IN IR OF +500% AT VBR= 30V.
36	CHANGE IN IR OF +500% AT VR= 50V.
37	CHANGE IN IR OF 500% AT VBR= 10V.
38	CHANGE IN IR OF 500% AT VR= 35V.
39	CHANGE IN IS OF 500% AT VS= -10V.
40	CHANGE IN RESISTANCE OF .1%.
41	CHANGE IN RESISTANCE OF 2%.
42	CHANGE IN VOL OF .050V AT VCC= 4.5V,IOL= 2MA AND VIN= 2 0V.
43	CHANGE OF 0.5% OR GREATER TOLERANCE.
44	CHANGED IN IV CHARACTERISTICS WITH INPUTS HIGH.
45	CHECK FOR ANY CHANGE IN FORWARD VOLTAGE AND REVERSE LEAKAGE CURRENT.
46	CUMULATIVE LEAKAGE CURRENT.
47	D.C. PARAMETER OUT OF SPEC.
48	DAMAGE TO INPUT DIODE.
49	DEGRADATION OF V-I CURVE OR FUNCTIONAL FAILURE.
50	DEVICE CONSIDERED ESD SENSITIVE WHEN A 10%CHANGE IN ELECT. CHAR. WAS OBSERVED.
51	ELECTRICAL PARAMETERS OUT OF SPEC.
52	EXCESSIVE LEAKAGE CURRENT OR OPEN CONDUCTOR LINES.
53	FAILED THE DC ELECTRICAL PARAMETERS TEST LIMITS.

RAC ESD DATABASE

Table 4 - FAILURE CRITERIA LISTING (Cont'd)

CODE	FAILURE CRITERIA
54	FAILED VOLTAGE IS THE AVERAGE OF PARTS SAMPLED.
55	FAILS TO MEET ELECTRICAL SPECIFICATION.
56	FUNCTION FAILURE OR D.C. PARAMETER OUT OF SPEC.
57	FUNCTIONAL FAILURE.
58	GATE CURRENT GREATER THAN 5UA AT A GATE/SOURCE VOLTAGE OF 22 VOLTS.
59	GREATER THAN .5UA INPUT AT 10V.
60	GREATER THAN 1uA LEAKAGE CURRENT AT 1.5 VOLTS.
61	GREATER THAN 5uA LEAKAGE CURRENT AT 0.5 VOLTS.
62	ID= SHORT.
63	IDSS OUT OF SPEC.
64	IEB AT VEB= +6V +1000% CHANGE.
65	IEBO AT VEB= -6V +1000% CHANGE.
66	IEBO AT VEB= 2.5V +1000% CHANGE.
67	IEBO AT VEB= 3.5V 1000% CHANGE.
68	IF AC,DC,OR FUNCTIONAL PARAMETERS FAILS THE MIN. OR MAX. LIMITS.
69	IGSS AND V(BR)GSS OUT OF SPEC.
70	IGSS AT VGS= -20V +1000% CHANGE.
71	IGSS OUT OF SPEC.
72	IGSSR >25PA AT VGS= 8V AND VDS= 0V.
73	IGSSR AND IDSS OUT OF SPEC.
74	IGSSR AND VGS(TH) OUT OF SPEC.
75	IGSSR OUT OF SPEC.
76	IGSSR,VGS(TH) OR IDSS OUT OF SPEC.
77	IIH AND VR OUT OF SPEC.
78	IIH AND/OR VOL OUT OF SPEC.
79	IIH AND/OR VR OUT OF SPEC.
80	IIH OUT OF SPEC.
81	IIH, IIL, OR ISS OUT OF SPEC AT VDD=15V.
82	IIH,IIL,ISS OUT OF SPEC.
83	IIH,IIL,OR ISS OUT OF SPEC.
84	IIH,VF,OR VR OUT OF SPEC.
85	IIH= 10MA.
86	IIH= 16MA.
87	IIH= 97UA.
88	IIL OUT OF SPEC.
89	IL AT VR= .5V +300%.
90	IL AT VR= 50V +1000% CHANGE.
91	INPUT BREAKDOWN OF 5MV.
92	INPUT SHORTED TO VCC.
93	INPUTS SHORTED TO GROUND.
94	IR AND VB OUT OF SPEC.
95	IR GREATER THAN 100% CHANGE.
96	IR OUT OF SPEC.
97	IR= 300UA AT 50 VOLTS.
98	IZ AT VR= 5V +1000% CHANGE.
99	IZ AT VR= 6.5V +1000% CHANGE.
100	LEAKAGE CURRENT.
101	LIGHT OUTPUT DEGRADATION AT CONSTANT CURRENT.
102	N/R.
103	PARAMETER CHANGE OF GREATER THAN 10%.
104	PARAMETER SHIFT OF GREATER THAN 10%.
105	PASSED FUNCTIONALLY OR DC ELECTRICAL PARAMETERS.
106	RESISTANCE CHANGE OF 1%.

Table 4 - FAILURE CRITERIA LISTING (Cont'd)

CODE	FAILURE CRITERIA
107	RESISTANCE OUT OF SPEC.
108	SIGNIFICANT AMOUNT OF DEGRADATION TO V-I CURVE.
109	SIGNIFICANT CHANGE IN THE +INPUT -GROUND V-I CURVE.
110	STUDY OF BREAKDOWN CHARACTERISTIC OF INPUT AND OUTPUT PINS.
111	TEST LEAKAGE CURRENT.
112	TESTED TO 2000 VOLTS PER METHOD 3015.2 OF MIL-STD-883.
113	V(BR)GSS OUT OF SPEC.
114	VB OUT OF SPEC.
115	VEBO= IV. TYPICALLY 5 VOLTS.
116	VGS(OFF) OUT OF SPEC AND IGSSR >25PA AT VGS= 8V AND VDS= 0V.
117	VGS(OFF) OUT OF SPEC AND/OR IGSSR >25PA AT VGS= 8V AND VDS= 0V.
118	VGS(OFF) OUT OF SPEC AT VDS= 15V AND ID= 50UA.
119	VGS(TH) AND IDSS OUT OF SPEC.
120	VGS(TH) OUT OF SPEC.
121	VR OUT OF SPEC.
122	WHEN ONE PULSE RESULTED IN DECREASE REV. LEAKAGE OR DECREASE IN JUNC. BRKDWN. VOLT.
123	WHEN ONE PULSE RESULTED IN INCREASE REV. LEAKAGE OR DECREASE IN JUNC. BRKDWN. VOLT.

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Table 5 - TEST REMARKS LISTING

CODE	TEST REMARKS
1	1-DEV. IR SHORT, 3-100% CHANGE, 1-25% CHANGE, 5- NO CHANGE. 5 PULSES FWD & REV.
2	1.13M OHM MODEL.
3	1.1M OHM MODEL.
4	1.21M OHM MODEL.
5	1.58M OHM MODEL.
6	1.69M OHM MODEL.
7	1.78M OHM MODEL.
8	10 MHZ CRYSTAL OSCILLATOR.
9	10 OHM MODEL.
10	10000 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
11	107 OHM MODEL.
12	11.8 OHM MODEL.
13	12 MHZ CRYSTAL OSCILLATOR.
14	133K OHM MODEL.
15	1400 VOLTS IS AN AVERAGE OF 3 DEVICES.
16	140K OHM MODEL.
17	15 MHZ CRYSTAL OSCILLATOR.
18	150K OHM MODEL.
19	16 MHZ CRYSTAL OSCILLATOR.
20	1625 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
21	16300 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
22	1900 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
23	1M OHM MODEL.
24	2 DEVICES INCREASED IR FROM .09, .095 TO .85, .65uA. 5 PULSES FWD & REVERSE.
25	2 OUT OF 9 DEVICES TESTED FAILED.
26	2.1M OHM MODEL.
27	2.49M OHM MODEL.
28	2.6% OF TOTAL NUMBER OF PINS FAILED.
29	2.94M OHM MODEL.
30	20.5 OHM MODEL.
31	220 OHM MODEL.
32	232K OHM MODEL.
33	24.9 OHM MODEL.
34	240K OHM MODEL.
35	250 OHM MODEL.
36	250K OHM MODEL.
37	27.2% OF TOTAL NUMBER OF PINS FAILED.
38	270K OHM MODEL.
39	294K OHM MODEL.
40	297K OHM MODEL.
41	3.01M OHM MODEL.
42	301 OHM MODEL.
43	3200 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
44	330 OHM MODEL.
45	360.1K OHM MODEL.
46	38/PIN DEVICE CMOS, GATE ARRAY, SEMICUSTOM, MONOLITHIC.
47	383 OHM MODEL.
48	392K OHM MODEL.
49	4.37 OHM MODEL.
50	4.7% OF TOTAL NUMBER OF PINS FAILED.
51	400K OHM MODEL.
52	450 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
53	47.5 OHM MODEL.

Table 5 - TEST REMARKS LISTING (Cont'd)

CODE	TEST REMARKS
54	475 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
55	475K OHM MODEL.
56	49.9 OHM MODEL.
57	499 OHM MODEL.
58	5 PULSES APPLIED AT BOTH FORWARD AND REVERSE POLARITIES.
59	5 PULSES FORWARD, 5 PULSES REVERSE.
60	5 PULSES PER POLARITY. DEVICES HAD METAL LID.
61	50 OHM MODEL.
62	50% FAILURE RATE WITH ARCING BETWEEN LEADS.
63	5000 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
64	511K OHM RESISTOR.
65	5500 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
66	57.6 OHM MODEL.
67	590 OHM MODEL.
68	600 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
69	604K OHM MODEL.
70	665K OHM MODEL.
71	7 OUT OF 10 DEVICES FAILED COLLECTOR TO BASE.
72	768K OHM MODEL.
73	7800 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
74	850 VOLTS IS AN AVERAGE OF AN UNKNOWN NUMBER OF DEVICES.
75	ALL 10 INPUTS FAILED TO VSS AT 800 VOLTS.
76	ALL UNUSED INPUTS AT 5.5 VOLTS.
77	ALL UNUSED INPUTS AT GROUND.
78	ALSO DEGRADATION FROM COMMON TO OUTPUT OF 4000 VOLTS.
79	ALSO FAILED 4,5,7-13 TO VDD AT 500 VOLTS.
80	ALSO FAILED FROM 5,6 & 7 TO VSS AT 800 VOLTS.
81	ALSO FAILED FROM ALL OTHER INPUTS TO VSS AT 800 VOLTS.
82	ALSO FAILED FROM INPUT PINS 5,6,8-13 TO VSS AT 800 VOLTS.
83	ALSO FAILED FROM PIN 7 TO OUTPUT AT 1000 VOLTS.
84	ALSO FAILED FROM PINS 4-8 AND 11-13 TO VSS AT 800 VOLTS.
85	ALSO FAILED FROM PINS 5,6,7,11 TO VDD AT 1000 VOLTS.
86	ALSO FAILED FROM PINS 5-13 TO VSS AT 800 VOLTS.
87	ALSO FAILED FROM PINS 8-13 TO VSS AT 800 VOLTS.
88	ALSO FAILED PIN 12 TO VDD AT 500 VOLTS.
89	ALSO FAILED PIN 4 TO VDD, 5-7,9-13 TO OUTPUT AT 500 VOLTS
90	ALSO FAILED PIN 9 TO OUTPUT AT 800 VOLTS.
91	ALSO FAILED PIN 9 TO VDD AND 8 TO OUTPUT AT 1000 VOLTS.
92	ALSO FAILED PIN 9 TO VSS AT 800 VOLTS.
93	ALSO FAILED PINS 4,5 & 9 TO VSS AT 800 VOLTS.
94	ALSO FAILED PINS 5 AND 10 TO VDD AT 800 VOLTS.
95	ALSO FAILED PINS 5-13 TO OUTPUT AT 500 VOLTS
96	ALSO FAILED PINS 5-13 TO VSS AT 800 VOLTS
97	ALSO INPUT TO GND DEGRADED AT 1800 VOLTS.
98	ALSO SHOWED DEGRADATION ON INPUT TO INPUT AT 2000 VOLTS.
99	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1000V.
100	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1020V.
101	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1025V.
102	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1060V.
103	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1070V.
104	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1080V.
105	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1100V.
106	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1125V.

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Table 5 - TEST REMARKS LISTING (Cont'd)

CODE	TEST REMARKS
107	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1170V.
108	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1200V.
109	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1310V.
110	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1325V.
111	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1350V.
112	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1360V.
113	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1600V.
114	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1675V.
115	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1700V.
116	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 1750V.
117	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2300V.
118	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2400V.
119	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2450V.
120	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2500V.
121	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2600V.
122	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2700V.
123	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 2900V.
124	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3000V.
125	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3200V.
126	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3444V.
127	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3500V.
128	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3550V.
129	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3700V.
130	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3760V.
131	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3800V.
132	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 3900V.
133	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 4550V.
134	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 5200V.
135	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 550V.
136	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 600V.
137	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 700V.
138	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 725V.
139	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 750V.
140	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 800V.
141	AVERAGE FAILURE VOLTAGE FOR ALL PINS IS 850V.
142	AVG OF ALL INPUTS 940V, PINS 1,2,15 MOST SUSCEPTIBLE.
143	AVG OF ALL INPUTS 960V, PIN 15 MOST SUSCEPTIBLE.
144	AVG OF ALL INPUTS 960V, PINS 11,14 MOST SUSCEPTIBLE.
145	BOTH POLARITIES WERE TESTED.
146	BREAKDOWN VOLTAGE CHARACTERISTICS WERE DEGRADED.
147	CARRY LOOK AHEAD GENERATOR.
148	CATASTROPHIC FAILURES OBSERVED ARE DUE TO EMIT. CONTACT PENETRATING THE SILICON.
149	CHARGED DEVICE MODEL.
150	COLLECTOR TO BASE FOUND TO BE MOST SENSITIVE (BOTH POLARITIES).
151	COMMON TO OUTPUT SHOWED DEGRADATION AT 4000 VOLTS.
152	CRYSTAL (4 Mhz).
153	DAMAGE OBSERVED AT -700 VOLTS, FAILED AT 1100 VOLTS.
154	DAMAGE OBSERVED AT 1000 VOLTS, ALL PINS FAILED AT OR BEFORE 3500 VOLTS.
155	DAMAGE OBSERVED AT 1050 VOLTS, ALL INPUT PINS FAILED AT OR BEFORE 2000 VOLTS.
156	DAMAGE OBSERVED AT 150 VOLTS, ALL DEVICES FAILED AT OR BEFORE 400 VOLTS.
157	DATE CODE TESTED WERE BETWEEN 8134 TO 8715.
158	DEGRADATION OCCURRED AT 1000V.
159	DEGRADATION OCCURRED AT 1500V.

Table 5 - TEST REMARKS LISTING (Cont'd)

CODE	TEST REMARKS
160	DEGRADATION OCCURRED AT 2000V.
161	DEGRADATION OCCURRED AT 3000V.
162	DEGRADATION OCCURRED AT 3500V.
163	DEGRADATION OCCURRED AT 4500V.
164	DEGRADATION OCCURRED AT THE APPLIED VOLTAGE.
165	DELAY LINE, PULSE, ELECTROMAGNETIC, LUMPED CONSTANT, 16 PIN DIP.
166	DEVICE PASSED THE REVERSE V-I CURVE AFTER TESTING.
167	DIFFERENT PIN COMB. TESTED AT EACH VOLTAGE STEP.
168	DRIVER / RECEIVER.
169	DUAL PNP TRANSISTOR.
170	EACH PIN STRESSED WITH ALL OTHER PINS CONNECTED TO GROUND.
171	EACH PIN TESTED TO ALL OTHERS TIED TOGETHER.
172	EMITTER TO BASE FAILED AT 3500 VOLTS.
173	FAILED FROM PINS 4,8,13 TO VDD AND 10 TO OUTPUT AT 500 V.
174	FAILED INPUTS TO GND. VOLT IS AVG. OF 4 DEV. MEAN ENGY=16UJ.
175	FAILED PIN 13 TO VDD AT 500 V, 8 TO VSS, 6 TO VDD AT 800 V.
176	FAILED PIN 16 TO VDD AT 500 V & PIN 5 TO VSS AT 800 V.
177	FAILED PINS 13 TO VDD AND PIN 4 TO OUTPUT AT 800 VOLTS.
178	FAILED PINS 5-6,11-13 TO VSS 7 TO VDD & 8-10 TO OUTPUT 500V.
179	FAILED PINS 5-7,9,11 TO VSS 8,10,12 TO VDD AT 500 VOLTS.
180	FAILED PINS 5-8 & 10-13 TO VSS & PIN 9 TO VDD AT 500 VOLTS.
181	FAILED PINS 5-8 & 10-13 TO VSS AT 500V & 9 TO VSS AT 800 V.
182	FAILED PINS 8,13 TO VSS, 15 TO VSS AND 6 TO VDD, ALL AT 800V.
183	FAILED PINS 8-13 TO VSS AT 300V & PINS 4,6 TO OUTPUT AT 500V
184	FAILURE VOLTAGE FROM EMP DATA & WUNSCH MODEL. (SUPERSAP 2).
185	FAILURE VOLTAGE GIVEN IS APPROXIMATE VALUE ONLY.
186	FAILURE VOLTAGE IS AN AVERAGE OF 15 DEVICES.
187	FAILURE VOLTAGE IS AN AVERAGE.
188	FAILURE VOLTAGE OBTAINED FROM EMP DATA AND EXPONENTIAL MODEL.
189	FAILURE VOLTAGE OBTAINED FROM EMP DATA AND WUNSCH MODEL.
190	FAILURE VOLTAGE OBTAINED FROM EMP DATA.
191	FAILURES WERE DUE TO INCREASED CONTACT RESISTANCE.
192	FIVE PULSES BOTH POLARITY ACROSS EACH PIN COMBINATION.
193	FREQUENCY SYNTHESIZER.
194	HEX SCHMIDTT TRIGGER.
195	HYBRID, OSCILLATOR.
196	IMCS TO >17.5KV, PAL TESTER TO >43KV. PAL IS A MOTOROLA IN HOUSE BUILT TESTER.
197	IN MOST FAILURES, Vos STARTS FAILING FIRST. THEN, Ios,IB,AND Icc.
198	INITIAL IGSS IS 0.1uA AND FINAL IGSS IS 10uA.
199	INITIAL IGSS IS 3.8uA AND FINAL IGSS IS 10uA.
200	INITIAL IGSS WAS 0.1uA AND FINAL IGSS WAS 1.0uA.
201	INITIAL IGSS WAS 0.1uA AND THE FINAL IGSS WAS 0.7uA.
202	INITIAL IGSS WAS 1.0uA AND FINAL IGSS WAS 3.4uA.
203	INITIAL IGSS WAS 1uA AND FINAL IGSS WAS 10uA.
204	INPUT AND CLAMPING DIODES WERE TYPICAL FAILURES.
205	INPUT FAILED AT 2500 AND 3000 VOLTS, OUTPUT DID NOT FAIL.
206	INPUT PIN 1 FAILED AT 200V AND INPUT PIN 8 FAILED AT 300V.
207	INPUT PIN 1 FAILED AT 200V AND INPUT PIN 8 FAILED AT 400V.
208	INPUT PIN 1 FAILED AT 200V.
209	INPUT PIN 1 FAILED AT 300V.
210	INPUT PIN 1 FAILED AT 400V AND INPUT PIN 8 FAILED AT 500V.
211	INPUT PIN 1 FAILED AT 500V.
212	INPUT PIN 10 FAILED AT 300V.

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Table 5 - TEST REMARKS LISTING (Cont'd)

CODE	TEST REMARKS
213	INPUT PIN 2 FAILED AT 200V.
214	INPUT PIN 2 FAILED AT 300V.
215	INPUT PIN 2 FAILED AT 400V.
216	INPUT PIN 2 FAILED AT 500V.
217	INPUT PIN 7 FAILED AT 200V.
218	INPUT PIN 8 FAILED AT 400V.
219	INPUT PIN 9 FAILED AT 400V.
220	INPUT PINS 1 AND 8 FAILED AT 300V.
221	INPUT PINS 1 AND 8 FAILED AT 400V.
222	INPUT PINS 1 AND 8 FAILED AT 500V.
223	INPUT PINS 1 AND 9 FAILED AT 200V.
224	INPUT PINS 11 AND 15 FAILED AT 200V.
225	INPUT PINS 2 AND 10 FAILED AT 200V.
226	INPUT PINS 2 AND 6 FAILED AT 200V.
227	INPUT PINS 2 AND 6 FAILED AT 300V.
228	INPUT PINS 7 AND 15 FAILED AT 300V.
229	INPUT TO COM. 3000 V, OUTPUT TO COMMON FAIL AT 1600 VOLTS.
230	INPUT TO OUTPUT DEGRADATED AT 600 VOLTS.
231	INPUTS STRESSED NO PINS GND CAP. OF PACKAGE TO GND IS 290PF.
232	INPUTS STRESSED NO PINS GND CAP. OF PACKAGE TO GND IS 3.5PF.
233	INPUTS STRESSED NO PINS GND CAP. OF PACKAGE TO GND IS 37PF.
234	INPUTS STRESSED NO PINS GND CAP. OF PACKAGE TO GND IS 3PF.
235	INPUTS STRESSED NO PINS GND CAP. OF PACKAGE TO GND IS 6.5PF.
236	INTEL METHOD.
237	INTEL MODEL.
238	IR CHANGED FROM .045uA TO 22.JuA ON ONE DEVICE. 5 PULSES FORWARD AND REVERSE.
239	IR CHANGED FROM .103uA, 200V TO .4uA, 80 VOLTS. 5 PULSES FORWARD & REVERSE.
240	IR DOUBLED AFTER 400 VOLTS, SHORTED AFTER 500 VOLTS.
241	IR INCREASED FROM .05uA TO 148uA. 5 PULSES FORWARD, 5 PULSES REVERSE.
242	IR INCREASED FROM .19MA TO .23MA. 5 PULSES FORWARD, 5 PULSES REVERSE.
243	IR INCREASED ON 3 DEVICES; 5.4 TO 6.2uA, 3.7 TO 4.1uA, AND 4.6 TO 5.6uA.
244	JUNCTION IS DAMAGED BEFORE DEVICE FAILS ELECTRICALLY.
245	LED DEVICES WHICH HAVE REV BRKDWN DAMAGE CAUSED BY ESD MAY FUNC NORM IN FWD DIR.
246	MICROCONTROLLER.
247	MIL-STD-883B METHOD 3015 (CAT B), DEVICE PASSED 2000V TEST.
248	MIMIMUM OBSERVED DAMAGE WAS 200 VOLTS ALL DEVICES FAILED AT OR BELOW 300 VOLTS.
249	MIMIMUM OBSERVED DAMAGE WAS 500 VOLTS ALL INPUT PINS FAILED AT OR BEFORE 700 V.
250	MINIMUM OBSERVED WAS 2600 VOLTS, ALL DEVICES FAILED AT OR BEFORE 3000 VOLTS.
251	MODULATOR.
252	N/R.
253	NO DEGRADATION TO OUTPUT AT 4000 VOLTS.
254	NO DEGRADATION TO OUTPUT PINS.
255	NO FAILURES OBSERVED GATE TO CATHODE.
256	OF 4 DEVICES FAILURE VOLTAGE WAS FROM 1400V TO 6000 VOLTS.
257	OF THE FOUR DEVICES TESTED TWO DEVICE DATE CODES WERE GIVEN AS 8615 AND 8501.
258	ONE DEVICE IR SHORTED. 5 PULSES FORWARD, 5 PULSES REVERSE.
259	OTHER PINS OPEN.
260	OTHER PINS TIED TO GND.
261	PAL TESTER IS A MOTOROLA IN HOUSE BUILT IMCS TO >17.5KV, PAL TO >43KV.
262	PIN UNDER TEST STRESSED WITH ALL OTHERS TIED TOGETHER FLOATING.
263	PINS 1 AND 2 FAILED AT 1100 VOLTS.
264	PINS 11-14 TO VSS,15 TO VDD AT 800V,8,13 TO OUTPUT AT 1000V.
265	PINS 13 TO VSS, 9 TO VSS AT 1000V, 8 TO VDD AT 1000 VOLTS.

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Table 5 - TEST REMARKS LISTING (Cont'd)

CODE	TEST REMARKS
266	PINS 3,4,5, AND 22 FAILED AT 1200 VOLTS.
267	PINS 8-15 TO VSS AT 500V, 11 TO OUTPUT AT 500 VOLTS.
268	PINS THAT FAILED 3,6-8,11,14,15,17-21, AND 23.
269	PRECISION MOTION CONTROLLER.
270	PROGRAMMABLE BAND PASS FILTER.
271	PROGRAMMABLE INTERVAL TIMER.
272	QUAD DEVICE, ONE DIODE PER DEVICE TESTED.
273	SEMI-CUSTOM GATE ARRAY.
274	SERIAL INPUT PLL FREQUENCY SYNTHESIZER.
275	TEST PREPARED AT 25 DEGREES C.
276	THE MOST SENSITIVE PIN TESTED IS B.
277	THE MOST SENSITIVE PIN TESTED IS G.
278	THE MOST SENSITIVE PINS TESTED ARE C TO B.
279	THE MOST SENSITIVE PINS TESTED ARE C TO E.
280	THE MOST SENSITIVE PINS TESTED ARE E TO B.
281	THE MOST SENSITIVE PINS TESTED ARE G AND D TO S.
282	THE MOST SENSITIVE PINS TESTED ARE S AND D TO G.
283	THE MOST SENSITIVE PINS TESTED ARE S AND G TO D.
284	VOLTAGE IS AN AVERAGE OF 12 RESISTORS. MEAN ENERGY OF 48UJ.
285	VOLTAGE IS AN AVERAGE OF 4 DEVICES.
286	VOLTAGE IS AN AVERAGE OF ALL INPUTS.
287	WORST CASE PINS (+) 1-4,9,10,20,23-27(-)1,10.LOT # (413,410-1).
288	WORST CASE PINS (+) 4-6,22,23,25-27 (-) 20,21. LOT # (284/006,285/008,416-3).
289	ZERO OHMS MODEL.

Table 6 - GENERAL REMARKS LISTING

CODE	GENERAL REMARKS
1	5 PULSES +/-.
2	ALL PINS BUT PIN UNDER TEST CONNECTED TO GND VIA RESISTOR. VDD AND VSS GROUNDED.
3	BEGIN WITH 200V, INCR. 100V TO 1000V, INCR. 200V TO 2000V, INCR 500V TO 4000V.
4	CHARGED DEVICE MODEL.
5	DATA OBTAINED FROM WEIBULL PLOTS. STEPS WERE 20% OF AN UNKNOWN STARTING VOLTAGE.
6	DEVICE PASSED REVERSE V-I CURVE. FORWARD AND REVERSE POLARITY TESTED.
7	FAILED VOLTAGE IS THE AVERAGE OF PARTS SAMPLED.
8	FAILURE VOLTAGE OBTAINED FROM EMP DATA AND EXPONENTIAL MODEL.
9	FAILURE VOLTAGES GIVEN ARE VOLTAGE TO CAUSE 30% FAILURE. DETAILS UNKNOWN.
10	IMCS TESTER TO >17.5KV, PAL TESTER TO >43KV. ONE PULSE PER VOLTAGE INCREMENT.
11	IN ACCORDANCE WITH MIL-STD-883B METHOD 3015 (CAT B), DEVICE PASSED 2000V TESTING.
12	MODEL 900.
13	N/R.
14	PIN COMBINATIONS AND POLARITY DIFFER FOR EACH OF THE FOUR PULSES.
15	PIN UNDER TEST STRESSED WITH ALL OTHER PINS TIED TOGETHER GROUNDED.
16	PIN UNDER TEST STRESSED WITH ALL OTHER PINS.
17	START 100V WITH INCREMENTS OF 100V TO 1000V. THEN INCREMENTS OF 250V TO FAILURE.
18	STEP STRESS TEST WAS PERFORMED HOWEVER ACTUAL VOLTAGE STEPS WERE UNKNOWN.
19	STEPPED FROM 1800 VOLTS TO FAILURE IN 25 VOLT INCREMENTS.
20	STEPPED IN 100 VOLT INCREMENTS STARTING AT 400 VOLTS.
21	STEPPED IN 2.5 VOLT INCREMENTS.
22	STEPPED IN 25 VOLT INCREMENTS.
23	STRESSED IN INCREMENTS OF 20% STARTING AT 16V FOR MOS DEVICES AND 70V FOR OTHERS.
24	TEST VOLTAGE WAS INCREMENTED FROM 100V TO 5500V IN 100V STEPS.
25	TESTED TO 2000 VOLTS PER METHOD 3015.2 OF MIL-STD-883.
26	TESTER IS A MARTIN MARIETTA IN HOUSE BUILT.
27	THERE WERE ALSO 100V INCREMENTS STEPPED FROM 100V TO 800V.
28	VOLT INCREMENTS AS FOLLOWS:100V TO 1KV,250V TO 3KV,500V TO 6KV,AND 1KV TO 16KV.
29	VOLTAGE STEP LEVELS 100 VOLT INCREMENTS UP TO 4000 VOLTS.

SECTION 3.1

MICROCIRCUIT SUSCEPTIBILITY TEST DATA

RAC ESD Database

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
0042	INT	1	Linear, Operational Amplifier												Bipolar			
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R		13	236	13
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1100	N/R		13	252	13
04580	RCA	3	Digital												PMOS			
				029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5958	N/R		102	189	13
072	TEX	2	Linear, Operational Amplifier												JFET			
				393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4000	N/R		102	252	13
084	TEX	2	Linear, Operational Amplifier												JFET			
				393	0183	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R		102	252	13
100	N/R	2	Digital, Converter, A/D-D/A												CMOS			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R		103	252	13
10078119	UDT	3	Digital												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	18	N/R	6	PASSED	4000	N/R		5	252	3
10082603	HON	2	Linear, Comparator												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	17	N/R	2	FAILED	3500	INPUT AND GROUND		5	252	3

RAC ESD Database

Part Number (Cont'd)	Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
[illegible]	HON	2	Linear, Comparator	Bipolar														
					435	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	INPUT TO INPUT	5	252	3
10082603-101	HON	2	Linear, Comparator	Bipolar														
					435	1186	SS	1500 Ohms	100E-12 F	17	8526	1	FAILED	3500	INPUT TO INPUT	5	252	3
												2	FAILED	3500	VCC TO OUTPUT	5	252	3
[illegible]	N/R	1	Linear, Operational Amplifier	Bipolar														
					232	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	N/R	103	252	13
												1	FAILED	2500	N/R	103	252	13
					228	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	750	N/R	7	252	13
10102	N/R	3	Digital, Gate	ECL														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	59	OUTPUT(+) INPUT(-)	47	186	21
10130	N/R	N	Digital, Latch	ECL														
					245	N/R	SS	100 Ohms	N/R	1	7634	15	FAILED	131	OUTPUT(+) INPUT(-)	47	186	21
10146	MOT	1	Digital, Memory, RAM	ECL														
					027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	15	FAILED	1000	N/R	47	252	12
101A	FSC	1	Linear, Operational Amplifier	Bipolar														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	293	OFF NULL(5)(+) V(-)(4)	33	285	13

RAC ESD Database

Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
105		NSC	3	Linear, Voltage Regulator								Bipolar		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6767	N/R	102	188	13
105		N/R	2	Linear, Voltage Regulator								Bipolar		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4000	N/R	103	252	13
10501		MOT	2	Digital, Gate								ECL		
	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	440	N/R	32	285	13
10502		MOT	1	Digital, Gate								ECL		
	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1250	EACH PIN TO 4 & 12 (+ -)	19	252	13
								5	FAILED	1250	EACH PIN TO 8 & 16 (+ -)	19	252	13
10503		MOT	1	Digital, Flip-Flop								ECL		
	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1500	EACH PIN TO 4 & 12 (+ -)	19	252	13
10505		MOT	1	Digital, Gate								ECL		
	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	850	EACH PIN TO 8 & 16 (+ -)	19	252	13
10507		MOT	1	Digital, Gate								ECL		
	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1000	EACH PIN TO 4 & 12 (+ -)	19	252	13
10513		N/R	1	Digital, Gate								ECL		
	028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	1500	N/R	85	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
10524	MOT	1	Digital, Gate	ECL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 4,12 & 13 (+ -)	19	252	13
												5	FAILED	2000	EACH PIN TO 8 & 9 THAN 16	19	145	13
10525	MOT	1	Digital, Gate	ECL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 8 & 9 THEN 16	19	145	13
108	N/R	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	N/R	103	252	13
												1	FAILED	1250	N/R	103	252	13
												1	FAILED	1250	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	214	INPUT(+) INPUT(-)	47	186	21
109	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
109	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
11011	INT	2	Digital, Memory, RAM, Static	PMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2109	N/R	102	189	13
11201	N/R	3	Linear, Switch	JFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
11331	N/R	3	Linear, Switch	JFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
117	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
118	N/R	3	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13
119	N/R	1	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
												1	FAILED	1500	N/R	103	252	13
120	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
124	N/R	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
												1	FAILED	1500	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	164	INPUT(+) GND(-)	47	186	21

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
13201	N/R	3	Linear, Switch	JFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
139	N/R	1	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
												1	FAILED	2000	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	102	V+(+) INPUT(-)	47	186	21
14000	MOT	2	Digital, Gate	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3301	N/R	102	188	13
												1	FAILED	2856	N/R	102	188	13
14001A	MOT	1	Digital, Gate	CMOS														
					111	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	850	INPUT A(+) INPUT B(-)	56	252	5
												10	FAILED	1450	INPUT A(+) INPUT B(-)	56	252	5
												10	FAILED	2060	INPUT A(+) INPUT B(-)	56	252	5
												2	PASSED	2060	INPUT A(+) INPUT B(-)	56	252	5
14001B	MOT	1	Digital, Gate	CMOS														
					112	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1630	INPUT A(+) INPUT B(-)	56	252	5
												10	FAILED	2400	INPUT A(+) INPUT B(-)	56	252	5
												10	FAILED	3100	INPUT A(+) INPUT B(-)	56	252	5
												2	PASSED	3100	INPUT A(+) INPUT B(-)	56	252	5
14006B	MOT	2	Digital, Register, Shift	CMOS														
					436	1'86	SS	1500 Ohms	100E-12 F	16	8640	3	FAILED	3000	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
14013A	MOT	1	Digital, Flip-Flop	CMOS	113	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1200	RESET(+) CLOCK(-)	56	252	5
												10	FAILED	1560	RESET(+) CLOCK(-)	56	252	5
												10	FAILED	2150	RESET(+) CLOCK(-)	56	252	5
												2	PASSED	2150	RESET(+) CLOCK(-)	56	252	5
14013B	MOT	1	Digital, Flip-Flop	CMOS	114	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1550	DATA(+) RESET(-)	56	252	5
												10	FAILED	2100	DATA(+) RESET(-)	56	252	5
												10	FAILED	2500	DATA(+) RESET(-)	56	252	5
												2	PASSED	2500	DATA(+) RESET(-)	56	252	5
14018	MOT	1	Digital, Counter/Divider	CMOS	007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1000	N/R	82	252	13
14021	INT	3	Digital, Register, Shift	CMOS	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4733	N/R	102	189	13
14046	MOT	1	Linear, Phase Lock Loop	CMOS	007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	400	N/R	82	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
14046	MOT	1	Linear, Phase Lock Loop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	600	N/R	82	252	13
009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	800	N/R	82	252	13
010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	N/R	82	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
14049	MOT	1	Digital, Inverter, Buffer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
098	0278	GN	1500 Ohms	150E-12 F	15	N/R	1	FAILED	4500	ALL LEADS(+) GATE(-)	56	252	13
098	0278	GN	1500 Ohms	150E-12 F	40	N/R	29	PASSED	4500	ALL LEADS(+) GATE(-)	56	252	13
099	0278	GN	1500 Ohms	150E-12 F	5	N/R	2	FAILED	6000	ALL LEADS(+) GATE(-)	56	252	13
099	0278	GN	1500 Ohms	150E-12 F	15	N/R	4	FAILED	6000	ALL LEADS(+) GATE(-)	56	252	13
099	0278	GN	1500 Ohms	150E-12 F	25	N/R	1	FAILED	6000	ALL LEADS(+) GATE(-)	56	252	13
099	0278	GN	1500 Ohms	150E-12 F	40	N/R	3	FAILED	6000	ALL LEADS(+) GATE(-)	56	252	13
							15	PASSED	6000	ALL LEADS(+) GATE(-)	56	252	13
100	0278	GN	1500 Ohms	150E-12 F	5	N/R	4	FAILED	7000	ALL LEADS(+) GATE(-)	56	252	13
100	0278	GN	1500 Ohms	150E-12 F	15	N/R	10	FAILED	7000	ALL LEADS(+) GATE(-)	56	252	13
100	0278	GN	1500 Ohms	150E-12 F	25	N/R	5	FAILED	7000	ALL LEADS(+) GATE(-)	56	252	13
100	0278	GN	1500 Ohms	150E-12 F	40	N/R	9	FAILED	7000	ALL LEADS(+) GATE(-)	56	252	13
							2	PASSED	7000	ALL LEADS(+) GATE(-)	56	252	13
101	0278	GN	1500 Ohms	150E-12 F	15	N/R	2	FAILED	7000	GATE(+) ALL LEADS(-)	56	252	13
101	0278	GN	1500 Ohms	150E-12 F	40	N/R	10	PASSED	700	GATE(+) ALL LEADS(-)	56	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
14049	MOT	1	Digital, Inverter, Buffer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
102	0278	GN	1500 Ohms	150E-12 F	5	N/R	5	FAILED	900	GATE(+) ALL LEADS(-)	56	252	13
102	0278	GN	1500 Ohms	150E-12 F	40	N/R	2	FAILED	900	GATE(+) ALL LEADS(-)	56	252	13
							5	PASSED	900	GATE(+) ALL LEADS(-)	56	252	13
103	0278	GN	1500 Ohms	150E-12 F	5	N/R	10	FAILED	1100	GATE(+) ALL LEADS(-)	56	252	13
103	0278	GN	1500 Ohms	150E-12 F	25	N/R	1	FAILED	1100	GATE(+) ALL LEADS(-)	56	252	13
103	0278	GN	1500 Ohms	150E-12 F	40	N/R	1	PASSED	1100	GATE(+) ALL LEADS(-)	56	252	13
007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	800	N/R	82	252	13
010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	N/R	82	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
14049A	MOT	1	Digital, Inverter, Buffer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
115	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	790	INPUT(+) VCC(-)	56	252	5
							10	FAILED	900	INPUT(+) VCC(-)	56	252	5
							10	FAILED	980	INPUT(+) VCC(-)	56	252	5
							2	PASSED	980	INPUT(+) VCC(-)	56	252	5

Part Number	Part Mfr	ESD Class	Part Description	Technology
14049B	MOT	1	Digital, Inverter, Buffer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
093	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	860	GATE(+) VSS(-)	56	252	5
							10	FAILED	1030	GATE(+) VSS(-)	56	252	5
								PASSED	1150	GATE(+) VSS(-)	56	252	5

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
14049B	MOT	1	Digital, Inverter, Buffer	CMOS														
					116	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	730	INPUT(+) VCC(-)	56	252	5
												10	FAILED	920	INPUT(+) VCC(-)	56	252	5
												10	FAILED	1070	INPUT(+) VCC(-)	56	252	5
												2	PASSED	1070	INPUT(+) VCC(-)	56	252	5
					093	0278	SS	1500 Ohms	150E-12 F	1	N/R	10	FAILED	1150	GATE(+) VSS(-)	56	252	5
14050	MOT	1	Digital, Inverter, Buffer	CMOS														
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	N/R	82	252	13
												1	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	N/R	82	252	13
14053B	MOT	1	Linear, Switch	CMOS														
					117	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1360	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	2000	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	2510	VEE(+) SELECT A(-)	56	252	5
												2	PASSED	2510	VEE(+) SELECT A(-)	56	252	5
[illegible]	MOT	1	Digital, Inverter, Buffer	CMOS														
					087	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	700	VDD(+) GATE(-)	56	252	5
												10	FAILED	1370	VDD(+) GATE(-)	56	252	5
												10	FAILED	1720	VDD(+) GATE(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
14049B	MOT	1	Digital, Inverter, Buffer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
087	0278	SS	1500 Ohms	150E-12 F	1	N/R	2	PASSED	1720	VDD(+) GATE(-)	56	252	5
091	0278	GN	1500 Ohms	150E-12 F	1	N/R	18	FAILED	1125	VDD(+) GATE(-)	56	252	13
							7	PASSED	1125	VDD(+) GATE(-)	56	252	13
094	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	760	VDD(+) GATE(-)	56	252	5
							10	FAILED	1380	VDD(+) GATE(-)	56	252	5
							10	FAILED	1800	VDD(+) GATE(-)	56	252	5
							2	PASSED	1800	VDD(+) GATE(-)	56	252	5
095	0278	GN	1500 Ohms	150E-12 F	1	N/R	25	PASSED	600	VDD(+) GATE (-)	56	252	13
096	0278	GN	1500 Ohms	150E-12 F	1	N/R	7	FAILED	1125	VDD(+) GATE(-)	56	252	13
							18	PASSED	740	VDD(+) GATE(-)	56	252	13
097	0278	GN	1500 Ohms	150E-12 F	1	N/R	14	FAILED	920	VDD(+) GATE(-)	56	252	13
							11	PASSED	920	VDD(+) GATE(-)	56	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
1408	N/R	3	Digital, Converter, A/D-D/A	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5000	N/R	103	252	13
							1	FAILED	5000	N/R	103	252	13
							1	FAILED	5000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
141	FSC	2	Linear, Voltage Regulator	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
							1	PASSED	2000	S/R	105	247	11

Part Number	Part Mfr	ESD Class	Part Description	Technology
14511	MOT	2	Digital, Decoder	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	INPUT(1)(+) OUT(15)(-)	81	167	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
14511	MOT	2	Digital, Decoder	CMOS														
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3500	INPUT(3)(+) OUT(13)(-)	81	167	13
												1	FAILED	2500	INPUT(1)(+) OUT(15)(-)	81	167	13
145155	MOT	1	Digital, Transceiver	CMOS														
					393	0984	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	600	6(INPUT) 5(VDD)	102	274	13
14519	MOT	1	Digital, Gate	CMOS														
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1000	N/R	82	252	13
14524	MOT	2	Digital, Memory, PROM	CMOS														
					393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	3000	15(INPUT) 16(VDD)	102	252	13
												3	FAILED	4000	2(INPUT) 16(VDD)	102	252	13
14568	MOT	2	Digital, Counter/Divider	CMOS														
					393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	102	252	13
1458	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
1458	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
1463	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
148	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
148	FSC	2	Linear, Operational Amplifier	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
1488	MOT	3	Digital, Line/Bus Driver	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5546	N/R	102	188	13
1488	N/R	3	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
												1	FAILED	6000	N/R	103	252	13
1489	MOT	3	Digital, Line/Bus Receiver	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4491	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
1489	N/R	3	Digital, Line/Bus Receiver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
												1	FAILED	6000	N/R	103	252	13
1494	N/R	1	Linear	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
												1	FAILED	2000	N/R	103	252	13
1496	N/R	2	Linear	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
1506	MOT	2	Digital, Converter, A/D-D/A	Bipolar														
					026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	520	INPUT(5)(+)GND(2)(-)	37	174	13
1508	N/R	3	Digital, Converter, A/D-D/A	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5000	N/R	103	252	13
												1	FAILED	5000	N/R	103	252	13
1524	SIL	2	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	15	8631	5	FAILED	2500	INPUT TO OUTPUT	5	252	3
1530	MOT	1	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2159	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
1530	MOT	1	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1887	N/R	102	188	13
1533	MOT	1	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1413	N/R	102	188	13
155	N/R	3	Linear, Operational Amplifier	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
												1	FAILED	6000	N/R	103	252	13
15530-8	HAR	2	Digital, Decoder	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	2	FAILED	2500	INPUT TO OUTPUT	5	78	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	FAILED	4000	INPUT TO COMMON	5	252	3
1558	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
156	N/R	3	Linear, Operational Amplifier	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
156	SIG	2	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3945	N/R	102	188	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
155	AMD	2	Linear, Operational Amplifier	Bipolar	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	636	INPUT(2)(+) V(-)(4)(-)	33	285	13
1563	N/R	2	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
156A	N/R	3	Linear, Operational Amplifier	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
1590	N/R	3	Linear, Operational Amplifier	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7000	N/R	103	252	13
1594	N/R	1	Linear	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
15946	TEX	N	Digital, Gate	DTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	342741	N/R	102	188	13
1596	N/R	2	Linear	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
1678	MOT	3	Digital, Counter/Divider	ECL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11934	N/R	102	189	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology
180	SIG	3	Digital, Gate	DTL
1802	N/R	1	Digital, Processing Unit, Central	CMOS
1822	RCA	2	Digital, Memory, RAM, Static	CMOS
1852	N/R	1	Digital, Transceiver, Input-Output Port	CMOS
193	SIX	3	Linear, Switch	JFET
198	N/R	2	Linear	BIFET
2001	TEX	3	Digital, Register, Shift	TTL
201	SIX	1	Linear, Switch	CMOS

Part Number	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
180	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7274	N/R	102	188	13
1802	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
1822	383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2018	OUT.(8)(+) APTT(-)	49	188	8
1852	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
								1	FAILED	1000	N/R	103	252	13
193	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	750	V(-)(14)(+) INPUT(-)	39	285	13
198	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
2001	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7583	N/R	102	189	13
201	436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3

Part Number (Cont'd)	Part Mfr	Part ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
201	SIX	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	5	FAILED	400	INPUT TO OUTPUT	5	252	3
201	SIL	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO OUTPUT	5	252	3
2051	N/R	1	Digital, Memory, EAROM	MNOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
20LID	MON	1	Digital	TTL														
					436	1186	SS	1500 Ohms	100E-12 F	7	8649	1	FAILED	800	INPUT TO OUTPUT	5	252	3
2102	INT	1	Digital, Memory, RAM, Stat c	NMOS														
					041	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	700	N/R	1	252	20
												1	FAILED	2000	N/R	1	252	20
					045	N/R	SS	1000 Ohms	200E-12 F	4	N/R	3	FAILED	1400	N/R	1	15	13
					046	N/R	GN	1000 Ohms	200E-12 F	200	N/R	1	PASSED	500	N/R	1	252	13
					047	N/R	GN	1000 Ohms	200E-12 F	25	N/R	1	FAILED	1000	N/R	1	252	13
					026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	535	INPUT(1)(+) GND(9)(-)	32	285	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
2102	FSC	1	Digital, Memory, RAM, Static	NMOS														
					001	0980	SS	1500 Ohms	100E-12 F	3	N/R	2	FAILED	300	N/R	48	252	13
												1	FAILED	400	N/R	48	252	13
2102	SIG	1	Digital, Memory, RAM, Static	NMOS														
					046	N/R	GN	1000 Ohms	200E-12 F	20	N/R	1	FAILED	500	N/R	1	252	13
2102	N/R	3	Digital, Memory, RAM, Static	NMOS														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	45	INPUT(+) GND(-)	47	186	21
211	N/R	3	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13
2111	N/R	1	Digital, Memory, RAM, Static	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
2114	N/R	1	Digital, Memory, RAM, Static	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
2141	N/R	1	Digital, Memory, RAM, Static	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
2147	N/R	1	Digital, Memory, RAM, Static	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
2255	MOT	1	Digital, Gate	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	268	N/R	102	189	13
2401	N/R	1	Digital, Memory, EPROM	NMOS														
					028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	750	N/R	91	252	13
2516	N/R	1	Digital, Memory, EPROM	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	300	EACH PIN(+)	52	140	24
												1	FAILED	700	EACH PIN(+)	52	117	24
2520HA	HAR	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	11	8625	1	FAILED	1400	INPUT TO INPUT	5	229	3
2622	HAR	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
2622	ISL	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
2622	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
2650	N/R	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
26LS31	N/R	1	Digital, Line/Bus Driver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
26LS31	NSC	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO COMMON	5	252	3
26LS31	AMD	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	2	FAILED	400	INPUT TO OUTPUT	5	252	3
26LS32	N/R	1	Digital, Line/Bus Receiver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
26LS32	AMD	1	Digital, Line/Bus Receiver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	2	FAILED	500	INPUT TO COMMON	5	230	3
26LS33	AMD	1	Digital, Line/Bus Receiver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	8420	2	FAILED	500	INPUT TO OUTPUT & COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	8420	2	FAILED	700	OUTPUT TO COMMON	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
26LS33	NSC	1	Digital, Line/Bus Receiver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO COMMON	5	252	3
2702	N/R	1	Linear, Voltage Reference	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
2708	N/R	1	Digital, Memory, EPROM	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	EACH PIN(+)	52	121	24
												1	FAILED	400	EACH PIN(+)	52	135	24
												1	FAILED	1500	EACH PIN(+)	52	121	24
												1	FAILED	500	EACH PIN(+)	52	136	24
27128	INT	2	Digital, Memory, EAROM	NMOS														
					393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3500	N/R	102	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
2716	N/R	1	Digital, Memory, EPROM	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	600	EACH PIN(+)	52	117	24
												1	FAILED	3000	EACH PIN(+)	52	132	24
27256	INT	1	Digital. Memory, EPROM	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
27256	INT	1	Digital, Memory, EPROM	HMOS														
					429	N/R	"	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
2732	INT	2	Digital, Memory, EPROM	NMOS														
					393	0383	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	102	252	13
2732	N/R	1	Digital, Memory, EPROM	NMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1500	EACH PIN(+)	52	122	24
												1	FAILED	500	EACH PIN(+)	52	99	24
27512	INT	1	Digital, Memory, EPROM	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
2764	INT	1	Digital, Memory, EPROM	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
27S13	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
27S19C	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
27S20		N/R	1	Digital, Memory, PROM								STTL		
	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	263	N/R	31	285	13
27S291		AMD	1	Digital, Memory, PROM								STTL		
	393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	5(INPUT) 12(GND)	102	252	13
28C256		SEQ	2	Digital, Memory, PROM								MOS		
	436	1186	SS	1500 Ohms	100E-12 F	16	8718	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
								1	FAILED	3000	INPUT TO COMMON	5	252	3
2901		AMD	1	Digital, Processing Unit, Central								LSTTL		
	383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	774	CP(+) APTT(-)	49	188	8
								1	FAILED	183	F=0(+) APTT(-)	49	188	8
								1	FAILED	57286	VCC(+) APTT(-)	49	188	8
2901		N/R	1	Digital, Processing Unit, Central								LSTTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
2909		N/R	1	Digital, Processing Unit, [illegible]								[illegible]		
	030	N/R	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]		[illegible]
2910		N/R	[illegible]	Digital, [illegible]										
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	[illegible]	N/R	[illegible]	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
2930	N/R	1	Digital, Processing Unit, Central	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
3001	INT	1	Digital	Bipolar	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	412	PINS 23 AND 24	13	252	13
3002	INT	1	Digital	Bipolar	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	425	PINS 16,24,26, AND 27	13	252	13
3003	INT	1	Digital	Bipolar	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	512	PINS 2 AND 17	13	252	13
301	N/R	1	Linear, Operational Amplifier	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	N/R	103	252	13
301	MOT	N	Linear, Operational Amplifier	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	82092	N/R	102	188	13
3015	RCA	1	Linear, Operational Amplifier	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1958	N/R	102	189	13
302	NSC	3	Linear, Operational Amplifier	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10899	N/R	102	188	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
304	MOT	3	Digital, Line/Bus Driver	ECL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	13991	N/R	102	188	13
308	MOT	3	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6257	N/R	102	188	13
308	N/R	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	N/R	103	252	13
												1	FAILED	1250	N/R	103	252	13
309	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
3101	INT	3	Digital, Memory, RAM, Static	STTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	8060	N/R	102	189	13
311	FSC	1	Linear, Comparator	Bipolar														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	295	IN.(+) APTT(-)	49	188	8
												1	FAILED	23485	CLOCK(+) APTT(-)	49	188	8
311	N/R	3	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
311	N/R	3	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
3158	HON	1	Linear, Comparator	Bipolar														
					436	0688	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	COMMON TO OUTPUT	5	252	3
												1	FAILED	3000	INPUT TO COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	VCC TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	VCC TO GND	5	252	3
317	MOT	3	Linear, Voltage Regulator	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6253	N/R	102	188	13
317	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
318	N/R	3	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13
319	N/R	1	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
320	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks	Technology
320	N/R	3	Linear, Voltage Regulator															Bipolar
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
324	N/R	1	Linear, Operational Amplifier															Bipolar
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13	
331	HYB	1	Digital, Converter, A/D-D/A															CMOS
				005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	INPUT(6)(+) VSS(3)(-)	04	79	13	
											1	FAILED	800	INPUT(4)(+) VSS(3)(-)	104	96	13	
											1	FAILED	500	INPUT(8)(+) VSS(3)(-)	104	89	13	
											1	FAILED	300	INPUT(7)(+) VSS(3)(-)	104	183	13	
											1	FAILED	500	INPUT(4)(+) OUTPUT(-)	104	95	13	
											1	FAILED	800	INPUT(4)(+) VSS(3)(-)	104	96	13	
339	N/R	1	Linear, Comparator															Bipolar
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13	
342	N/R	3	Linear, Voltage Regulator															Bipolar
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
											1	FAILED	10000	N/R	103	252	13	
3400	GI	1	Digital, Memory, EAROM															CMOS
				383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	81	VCC(+) APTT(-)	49	188	8	

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
3400	GI	1	Digital, Memory, EAROM	CMOS														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	144	VDD(+) APTT(-)	49	188	8
												1	FAILED	14024	A5(9)(+) APTT(-)	49	188	8
34001	MOT	1	Linear, Operational Amplifier	BIFET														
					027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	8	FAILED	1000	N/R	47	252	12
												7	PASSED	1000	N/R	47	252	12
34001	FSC	1	Linear, Operational Amplifier	BIFET														
					123	0478	SS	1500 Ohms	150E-12 F	1	N/R	10	FAILED	1800	INPUT B(+) INPUT A(-)	56	252	5
												10	FAILED	1450	INPUT B(+) INPUT A(-)	56	252	5
												3	FAILED	1150	INPUT B(+) INPUT A(-)	56	252	5
												2	PASSED	1800	INPUT B(+) INPUT A(-)	56	252	5
3403	MOT	1	Linear, Operational Amplifier	Bipolar														
					027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	6	FAILED	1000	N/R	47	252	12
												9	PASSED	1000	N/R	47	252	12
34049B	FSC	1	Digital, Inverter, Buffer	CMOS														
					125	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1100	INPUT(+) OUTPUT(-)	56	252	5
												10	FAILED	1280	INPUT(+) OUTPUT(-)	56	252	5
												10	FAILED	1480	INPUT(+) OUTPUT(-)	56	252	5
												2	PASSED	1480	INPUT(+) OUTPUT(-)	56	252	5
34050941-001	HYC	1	Digital, Converter, A/D-D/A	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT-GND AND GND-OUTPUT	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
34054597	HON	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	12	8702	1	FAILED	1500	INPUT TO GND	5	252	3
34054597-001	HON	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1500	INPUT TO GND	5	252	3
34056230-001	LTC	3	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
34069508-100	IDT	1	Digital, Memory, RAM, Static	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	8641	1	FAILED	600	INPUT AND COMMON TO GND	5	252	3
34371	HAR	1	Digital, Memory, PROM	Bipolar														
					392	0886	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	1000	EACH PIN TO GND & VCC	19	154	13
344	NSC	1	Linear, Operational Amplifier	Bipolar														
					052	0681	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	400	EACH PIN	51	171	13
												1	FAILED	500	EACH PIN	51	171	13
												3	FAILED	600	EACH PIN	51	171	13
					053	0681	SS	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1500	EACH PIN	51	171	13
					420	0581	SS	0 Ohms	125E-12 F	12	N/R	1	FAILED	600	N/R	18	170	13
348	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
351	MOT	1	Digital, Gate	ECL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1576	N/R	102	189	13
355	N/R	3	Linear, Operational Amplifier	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
356	N/R	3	Linear, Operational Amplifier	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
												1	FAILED	6000	N/R	103	252	13
357	N/R	3	Linear, Operational Amplifier	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
3600	TEX	3	Digital, Converter, A/D-D/A	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	12930	N/R	102	188	13
373	VAR	2	Digital, Latch	Bipolar														
					424	1083	SS	1500 Ohms	100E-12 F	7	N/R	2	FAILED	1000	PINS 1 AND 11	46	149	13
					424	1083	SS	1500 Ohms	100E-12 F	9	N/R	8	FAILED	1250	PINS 1 AND 11	46	149	13
					424	1083	SS	1500 Ohms	100E-12 F	12	N/R	4	FAILED	1500	PINS 1 AND 11	46	149	13
					423	1083	SS	0 Ohms	0 F	6	N/R	2	FAILED	750	PINS 1 AND 11	46	252	4

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
373	VAR	2	Digital, Latch	Bipolar														
					423	1083	SS	0 Ohms	0 F	18	N/R	2	FAILED	2250	PINS 1 AND 11	46	252	4
					423	1083	SS	0 Ohms	0 F	20	N/R	4	FAILED	2500	PINS 1 AND 11	46	252	4
					423	1083	SS	0 Ohms	0 F	22	N/R	4	FAILED	2750	PINS 1 AND 11	46	252	4
3870	MOS	1	Digital, Micro Computer	NMOS														
					134	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	PIN(23)(+) APTT(-)	102	252	13
												4	PASSED	1000	EACH PIN(+) APTT(-	102	252	13
					138	N/R	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN(+) APTT(-	102	252	13
					139	N/R	GN	1500 Ohms	100E-12 F	1	N/R	4	FAILED	3500	EACH PIN(+) APTT(-)	102	252	13
3873	MOS	1	Digital, Micro Computer	NMOS														
					140	0780	SS	1300 Ohms	100E-12 F	1	N/R	24	FAILED	300	EACH PIN(+) APTT(-)	102	28	13
					140	0780	SS	1300 Ohms	100E-12 F	3	N/R	15	FAILED	300	EACH PIN(+) APTT(-)	102	50	13
					140	0780	SS	1300 Ohms	100E-12 F	1	N/R	1	FAILED	1000	EACH PIN(+) APTT(-)	102	37	13
398	N/R	2	Linear	BIFET														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
4000	HAR	3	Digital, Gate	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7119	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4000	N/R	1	Digital, Gate	CMOS														
					028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	1000	INPUT VCC	92	252	13
4001	NSC	1	Digital, Gate	CMOS														
					118	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1220	VSS(+) INPUT A(-)	56	252	5
												10	FAILED	1530	VSS(+) INPUT A(-)	56	252	5
												10	FAILED	1750	VSS(+) INPUT A(-)	56	252	5
												2	PASSED	1750	VSS(+) INPUT A(-)	56	252	5
4001	RCA	1	Digital, Gate	CMOS														
					048	N/R	SS	100 Ohms	218E-12 F	1	N/R	1	FAILED	250	N/R	59	252	23
4001	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1300	N/R	103	252	13
												1	FAILED	1300	N/R	103	252	13
					244	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	950	INPUT(+) OUTPUT(-)	47	252	22
												13	PASSED	1000	INPUT(+) OUTPUT(-)	47	252	22
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	66	VSS(+) INPUT(-)	47	186	21
40014	N/R	1	Digital, Gate	CMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	900	EACH PIN(+)	52	102	24
4001A	RCA	1	Digital, Gate	CMOS														
					104	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	580	INPUT B(+) INPUT A(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	RCA	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
104	0478	SS	1500 Ohms	150E-12 F	1	N/R	10	FAILED	780	INPUT B(+) INPUT A(-)	56	252	5
							10	FAILED	980	INPUT B(+) INPUT A(-)	56	252	5
							2	PASSED	980	INPUT B(+) INPUT A(-)	56	252	5
293	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	750	VDD(14)(+) IN.(1)(-)	88	252	13
294	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	775	VDD(14)(+) IN.(1)(-)	88	252	13
295	N/R	GN	1500 Ohms	100E-12 F	200	N/R	2	PASSED	790	VDD(14)(+) IN.(1)(-)	88	252	13
296	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	795	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	500	N/R	5	PASSED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	300	N/R	1	FAILED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	80	N/R	1	FAILED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	800	VDD(14)(+) IN.(1)(-)	88	252	13
297	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	800	VDD(14)(+) IN.(1)(-)	51	252	13
299	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	805	VDD(14)(+) IN.(1)(-)	88	252	13
300	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	810	VDD(14)(+) IN.(1)(-)	88	252	13
301	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	815	VDD(14)(+) IN.(1)(-)	88	252	13
302	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	825	VDD(14)(+) IN.(1)(-)	88	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	RCA	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
303	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	830	VDD(14)(+) IN.(1)(-)	88	252	13
304	N/R	GN	1500 Ohms	100E-12 F	500	N/R	3	PASSED	833	VDD(14)(+) IN.(1)(-)	88	252	13
304	N/R	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	833	VDD(14)(+) IN.(1)(-)	88	252	13
304	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	833	VDD(14)(+) IN.(1)(-)	88	252	13
304	N/R	GN	1500 Ohms	100E-12 F	4	N/R	1	FAILED	833	VDD(14)(+) IN.(1)(-)	88	252	13
305	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	840	VDD(14)(+) IN.(1)(-)	88	252	13
306	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	845	VDD(14)(+) IN.(1)(-)	88	252	13
307	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	850	VDD(14)(+) IN.(1)(-)	88	252	13
307	N/R	GN	1500 Ohms	100E-12 F	200	N/R	3	PASSED	850	VDD(14)(+) IN.(1)(-)	88	252	13
307	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	850	VDD(14)(+) IN.(1)(-)	88	252	13
307	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	850	VDD(14)(+) IN.(1)(-)	88	252	13
308	N/R	GN	1500 Ohms	100E-12 F	1	N/R	6	FAILED	865	VDD(14)(+) IN.(1)(-)	88	252	13
308	N/R	GN	1500 Ohms	100E-12 F	200	N/R	3	PASSED	865	VDD(14)(+) IN.(1)(-)	88	252	13
308	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	865	VDD(14)(+) IN.(1)(-)	88	252	13
							8	PASSED	865	VDD(14)(+) IN.(1)(-)	88	252	13
309	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	870	VDD(14)(+) IN.(1)(-)	88	252	13
310	N/R	GN	1500 Ohms	100E-12 F	4	N/R	1	FAILED	875	VDD(14)(+) IN.(1)(-)	88	252	13
310	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	875	VDD(14)(+) IN.(1)(-)	88	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	RCA	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
311	N/R	GN	1500 Ohms	100E-12 F	25	N/R	1	FAILED	880	VDD(14)(+) IN.(1)(-)	88	252	13
312	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	890	VDD(14)(+) IN.(1)(-)	88	252	13
313	N/R	GN	1500 Ohms	100E-12 F	1	N/R	7	FAILED	898	VDD(14)(+) IN.(1)(-)	88	252	13
313	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	898	VDD(14)(+) IN.(1)(-)	88	252	13
313	N/R	GN	1500 Ohms	100E-12 F	200	N/R	2	PASSED	898	VDD(14)(+) IN.(1)(-)	88	252	13
313	N/R	GN	1500 Ohms	100E-12 F	1	N/R	6	FAILED	898	VDD(14)(+) IN.(1)(-)	88	252	13
							4	PASSED	898	VDD(14)(+) IN.(1)(-)	88	252	13
314	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	900	VDD(14)(+) IN.(1)(-)	88	252	13
314	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	900	VDD(14)(+) IN.(1)(-)	88	252	13
315	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	910	VDD(14)(+) IN.(1)(-)	88	252	13
316	N/R	GN	1500 Ohms	100E-12 F	3	N/R	1	FAILED	915	VDD(14)(+) IN.(1)(-)	88	252	13
316	N/R	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	915	VDD(14)(+) IN.(1)(-)	88	252	13
316	N/R	GN	1500 Ohms	100E-12 F	200	N/R	3	PASSED	915	VDD(14)(+) IN.(1)(-)	88	252	13
317	N/R	GN	1500 Ohms	100E-12 F	1	N/R	3	FAILED	920	VDD(14)(+) IN.(1)(-)	88	252	13
317	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	920	VDD(14)(+) IN.(1)(-)	88	252	13
318	N/R	GN	1500 Ohms	100E-12 F	1	N/R	13	FAILED	930	VDD(14)(+) IN.(1)(-)	88	252	13
318	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	930	VDD(14)(+) IN.(1)(-)	88	252	13
326	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	VDD(14)(+) IN.(1)(-)	88	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	RCA	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
330	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1500	VDD(14)(+) IN.(1)(-)	88	252	13
330	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	1500	VDD(14)(+) IN.(1)(-)	88	252	13
346	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2000	VDD(14)(+) IN.(1)(-)	88	252	13
308	N/R	GN	1500 Ohms	100E-12 F	500	N/R	1	PASSED	865	VDD(14)(+) IN.(1)(-)	88	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	N/R	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
143	N/R	SS	100 Ohms	250E-12 F	1	N/R	1	FAILED	300	N/R	102	185	13
							1	FAILED	400	N/R	102	185	13
144	N/R	SS	250 Ohms	250E-12 F	1	N/R	1	FAILED	300	N/R	102	185	13
							1	FAILED	600	N/R	102	185	13
145	N/R	SS	500 Ohms	250E-12 F	1	N/R	1	FAILED	400	N/R	102	185	13
							1	FAILED	800	N/R	102	185	13
146	N/R	SS	1000 Ohms	250E-12 F	1	N/R	1	FAILED	600	N/R	102	185	13
							1	FAILED	1000	N/R	102	185	13
147	N/R	SS	2000 Ohms	250E-12 F	1	N/R	1	FAILED	1200	N/R	102	185	13
148	N/R	SS	3000 Ohms	250E-12 F	1	N/R	1	FAILED	2000	N/R	102	185	13
							1	FAILED	2500	N/R	102	185	13
149	N/R	SS	5000 Ohms	250E-12 F	1	N/R	1	FAILED	3000	N/R	102	185	13
							1	FAILED	4000	N/R	102	185	13
150	N/R	SS	500 Ohms	N/R	1	N/R	1	FAILED	2000	N/R	102	185	13
							1	FAILED	2500	N/R	102	185	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001A	N/R	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
151	N/R	SS	500 Ohms	N/R	1	N/R	1	FAILED	1750	N/R	102	185	13
							1	FAILED	2000	N/R	102	185	13
152	N/R	SS	500 Ohms	N/R	1	N/R	1	FAILED	1000	N/R	102	185	13
							1	FAILED	1500	N/R	102	185	13
153	N/R	SS	500 Ohms	100E-12 F	1	N/R	1	FAILED	700	N/R	102	185	13
							1	FAILED	950	N/R	102	185	13
154	N/R	SS	500 Ohms	250E-12 F	1	N/R	1	FAILED	600	N/R	102	185	13
							1	FAILED	700	N/R	102	185	13
155	N/R	SS	500 Ohms	500E-12 F	1	N/R	1	FAILED	300	N/R	102	185	13
							1	FAILED	400	N/R	102	185	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001B	NSC	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
119	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1220	VSS(+) INPUT A(-)	56	252	5
							10	FAILED	1570	VSS(+) INPUT A(-)	56	252	5
							10	FAILED	1830	VSS(+) INPUT A(-)	56	252	5
							2	PASSED	1830	VSS(+) INPUT A(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001B	RCA	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
105	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1300	INPUT B(+) INPUT A(-)	56	252	5
							10	FAILED	3100	INPUT B(+) INPUT A(-)	56	252	5
							10	FAILED	4050	INPUT B(+) INPUT A(-)	56	252	5
							2	PASSED	4050	INPUT B(+) INPUT A(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4001B	N/R	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1300	N/R	103	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology		
															Failure Criteria	Test Remarks	General Remarks
4001B	N/R	1	Digital, Gate												CMOS		
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1300	N/R	103	252	13
4002B	N/R	1	Digital, Gate												CMOS		
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
											1	FAILED	1000	N/R	103	252	13
4006	MOT	2	Digital, Register, Shift												CMOS		
				029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4951	N/R	102	188	13
				436	1186	SS	1500 Ohms	100E-12 F	17	N/R	3	FAILED	3500	OUTPUT TO GND	5	252	3
4006A	NSC	1	Digital, Register, Shift												CMOS		
				436	1186	SS	1500 Ohms	100E-12 F	14	8552	1	FAILED	2000	INPUT TO OUTPUT	5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	11	8552	1	FAILED	1400	INPUT TO OUTPUT	5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	7	8552	1	FAILED	800	INPUT TO GND	5	252	3
4006B	N/R	1	Digital, Register, Shift												CMOS		
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
											1	FAILED	1000	N/R	103	252	13
4006B	RCA	2	Digital, Register, Shift												CMOS		
				436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4007	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4007B	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4008B	N/R	1	Digital, Arithmetic, Adder, Full	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
40101B	N/R	1	Digital, Arithmetic, Parity Gen. & Check	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4011	MOT	1	Digital, Gate	CMOS														
					141	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	1000	VDD(+) INPUT(-)	102	252	13
												1	FAILED	4000	INPUT(+) VDD(-)	102	252	13
												1	FAILED	1000	VSS(+) INPUT(-)	102	252	13
												1	FAILED	2000	INPUT(+) VSS(-)	102	252	13
												1	FAILED	2000	INPUT(+) OUTPUT(-)	102	252	13
												1	FAILED	500	OUTPUT(+) INPUT(-)	102	252	13
												1	FAILED	2000	VDD(+) OUTPUT(-)	102	252	13
												1	FAILED	5000	OUTPUT(+) VDD(-)	102	252	13
												1	FAILED	4500	VSS(+) OUTPUT(-)	102	252	13
												1	FAILED	3000	OUTPUT(+) VSS(-)	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
4011	MOT	1	Digital, Gate												CMOS			
				141	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	4000	VDD(+) VSS(-)		102	252	13
											1	FAILED	5000	VSS(+) VDD(-)		102	252	13
4011	RCA	1	Digital, Gate												CMOS			
				141	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	3500	VDD(+) INPUT(-)		102	252	13
											1	FAILED	5000	INPUT(+) VDD(-)		102	252	13
											1	FAILED	2500	VSS(+) INPUT(-)		102	252	13
											1	FAILED	3000	INPUT(+) VSS(-)		102	252	13
											1	FAILED	3000	INPUT(+) OUTPUT(-)		102	252	13
											1	FAILED	1000	OUTPUT(+) INPUT(-)		102	252	13
											1	FAILED	1500	VDD(+) OUTPUT(-)		102	252	13
											1	FAILED	2500	OUTPUT(+) VDD(-)		102	252	13
											1	FAILED	2000	VSS(+) OUTPUT(-)		102	252	13
											1	FAILED	2000	OUTPUT(+) VSS(-)		102	252	13
											1	FAILED	2000	VDD(+) VSS(-)		102	252	13
											1	FAILED	5000	VSS(+) VDD(-)		102	252	13
4011	NSC	1	Digital, Gate												CMOS			
				141	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	500	VDD(+) INPUT(-)		102	252	13
											1	FAILED	5000	INPUT(+) VDD(-)		102	252	13
											1	FAILED	500	VSS(+) INPUT(-)		102	252	13
											1	FAILED	2500	INPUT(+) VSS(-)		102	252	13
											1	FAILED	2500	INPUT(+) OUTPUT(-)		102	252	13
											1	FAILED	500	OUTPUT(+) INPUT(-)		102	252	13
											1	FAILED	3000	VDD(+) OUTPUT(-)		102	252	13
											1	FAILED	1500	OUTPUT(+) VDD(-)		102	252	13
											1	FAILED	5000	VSS(+) OUTPUT(-)		102	252	13
											1	FAILED	2000	OUTPUT(+) VSS(-)		102	252	13
											1	FAILED	1000	VDD(+) VSS(-)		102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4011	NSC	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
141	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	5000	VSS(+) VDD(-)	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4011	N/R	1	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1300	N/R	103	252	13
							1	FAILED	1300	N/R	103	252	13
142	0575	SS	560 Ohms	100E-12 F	1	N/R	1	FAILED	500	VDD(+) INPUT(-)	102	252	13
							1	FAILED	1000	INPUT(+) VDD(-)	102	252	13
							1	FAILED	1000	VSS(+) INPUT(-)	102	252	13
							1	FAILED	1000	INPUT(+) VSS(-)	102	252	13
							1	FAILED	1000	INPUT(+) OUTPUT(-)	102	252	13
							1	FAILED	1000	OUTPUT(+) INPUT(-)	102	252	13
							1	FAILED	4000	VDD(+) OUTPUT(-)	102	252	13
							1	FAILED	4500	OUTPUT(+) VDD(-)	102	252	13
							1	FAILED	5000	VSS(+) OUTPUT(-)	102	252	13
							1	FAILED	2000	OUTPUT(+) VSS(-)	102	252	13
							1	FAILED	4000	VDD(+) VSS(-)	102	252	13
							1	FAILED	5000	VSS(+) VDD(-)	102	252	13
384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	500	EACH PIN(+)	52	103	24
							1	FAILED	500	EACH PIN(+)	52	140	24
							1	FAILED	800	EACH PIN(+)	52	130	24
							1	FAILED	2300	EACH PIN(+)	52	126	24
							1	FAILED	2900	EACH PIN(+)	52	134	24
							1	FAILED	500	EACH PIN(+)	52	119	24

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4011	SSS	2	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	600	INPUT(+) PR. SUPPLY(-)	102	252	13
004	1175	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	4000	INPUT	102	232	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4011A	RCA	2	Digital, Gate	CMOS														
					163	N/R	SS	610 Ohms	100E-12 F	1	N/R	1	PASSED	4000	VSS(7)(+)	57	252	2
												1	FAILED	2500	VSS(7)(-)	57	160	2
												1	FAILED	2000	INPUT(1)(+)	57	159	2
												1	FAILED	4000	INPUT(1)(-)	57	159	2
												1	FAILED	4000	OUTPUT(4)(+)	57	252	2
												1	FAILED	3500	OUTPUT(4)(-)	57	252	2
												1	FAILED	1500	VDD(14)(+)	57	252	2
												1	PASSED	4000	VDD(14)(-)	57	252	2
4011B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1300	N/R	103	252	13
												1	FAILED	1300	N/R	103	252	13
4012	INS	2	Digital, Gate	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2428	N/R	102	189	13
4012B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4013	FSC	1	Digital, Flip-Flop	CMOS														
					124	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1240	VDD(+) SET(-)	56	252	5
												10	FAILED	1570	VDD(+) SET(-)	56	252	5
												10	FAILED	1830	VDD(+) SET(-)	56	252	5
												2	PASSED	1830	VDD(+) SET(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4013	FSC	1	Digital, Flip-Flop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14

Part Number	Part Mfr	ESD Class	Part Description	Technology
4013	RCA	1	Digital, Flip-Flop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	OUTPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	OUTPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
4013A	RCA	2	Digital, Flip-Flop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
106	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	710	RESET(+) CLOCK(-)	56	252	5
							10	FAILED	900	RESET(+) CLOCK(-)	56	252	5
							10	FAILED	1000	RESET(+) CLOCK(-)	56	252	5
							2	PASSED	1000	RESET(+) CLOCK(-)	56	252	5
164	N/R	SS	610 Ohms	100E-12 F	1	N/R	1	FAILED	3500	OUTPUT(1)(+)	57	252	2
							1	FAILED	3000	OUTPUT(1)(+)	57	252	2
							1	FAILED	3500	INPUT(5)(+)	57	158	2
							1	FAILED	2500	INPUT(5)(-)	57	252	2
							1	PASSED	4000	VSS(7)(+)	57	252	2
							1	FAILED	3000	VSS(7)(+)	57	160	2
							1	FAILED	2500	VDD(14)(+)	57	252	2
							1	PASSED	4000	VDD(14)(-)	57	252	2
026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	373	INPUT(5)(+) VSS(7)(-)	6	285	13
026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	205	VDD(14)(+) INPUT(3)(-)	34	285	13
393	1284	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	3500	11(INPUT) 7(VSS)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
4013B	NSC	1	Digital, Flip-Flop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
120	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	980	DATA(+) CLOCK(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4013B	NSC	1	Digital, Flip-Flop	CMOS														
					120	0478	SS	1500 Ohms	150E-12 F	1	N/R	10	FAILED	1350	DATA(+) CLOCK(-)	56	252	5
												10	FAILED	1620	DATA(+) CLOCK(-)	56	252	5
												2	PASSED	1620	DATA(+) CLOCK(-)	56	252	5
4013B	RCA	1	Digital, Flip-Flop	CMOS														
					107	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	860	SET(+) DATA(-)	56	252	5
												10	FAILED	2200	SET(+) DATA(-)	56	252	5
												10	FAILED	4000	SET(+) DATA(-)	56	252	5
												2	PASSED	4000	SET(+) DATA(-)	56	252	5
					436	0488	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	COMMON TO OUTPUT	5	252	3
					436	0488	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1500	COMMON TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	GND TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT AND OUTPUT	5	252	3
4013B	N/R	1	Digital, Flip-Flop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4014B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4015	MOT	2	Digital, Register, Shift	CMOS														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2750	EACH PIN TO 8 & 16 (+ -)	19	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4015B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4015B	RCA	2	Digital, Register, Shift	CMOS														
					436	0788	SS	1500 Ohms	100E-12 F	18	N/R	10	FAILED	4000	COMMON TO OUTPUT	5	252	3
												10	FAILED	4000	INPUT TO COMMON	5	252	3
40160B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
40161B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
40161BC	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
40162B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
40163B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
40163B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4016A	RCA	1	Linear, Switch	CMOS														
					393	0884	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	102	252	13
40174B	N/R	1	Digital, Flip-Flop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4017A	RCA	1	Digital, Counter/Divider	CMOS														
					393	1284	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	750	13(INPUT) 16(VDD)	102	252	13
4017B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4018	FSC	1	Digital, Counter/Divider	CMOS														
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1000	N/R	82	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4018	NSC	2	Digital, Counter/Divider	CMOS	393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	102	252	13
4019	FSC	1	Digital, Gate	CMOS	165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	INPUT(3)(+) OUT(12)(-)	81	167	13
												4	FAILED	2500	INPUT(5)(+) OUT(11)(-)	81	167	13
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1000	N/R	82	252	13
												1	FAILED	1000	N/R	82	252	13
4019	NSC	1	Digital, Gate	CMOS	006	0878	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	2000	INPUT(3)(+) OUT(12)(-)	81	167	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	600	N/R	83	252	13
4019	SSS	1	Digital, Gate	CMOS	011	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	200	N/R	83	252	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4019	SSS	1	Digital, Gate	CMOS														
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	600	N/R	83	252	13
40194B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
40195B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4019A	NSC	1	Digital, Gate	CMOS														
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1200	N/R	102	252	13
4019B	RCA	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	pin 4 (input) to VDD	103	157	13
					436	0688	SS	1500 Ohms	100E-12 F	18	N/R	5	FAILED	4000	- OUTPUT TO + VSS (GROUND)	5	252	3
4019B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4020	SSS	2	Digital, Counter/Divider	CMOS														
					003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	900	INPUT(+) PR. SUPPLY(-)	102	252	13

RAC ESD Database

Part Number	Part Mfr	ESD Class	Part Description	Technology
4020B	N/R	1	Digital, Counter/Divider	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
							1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
4020B	RCA	2	Digital, Counter/Divider	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
							1	FAILED	3000	INPUT TO GND	5	252	3
							1	FAILED	3000	INPUT TO OUTPUT	5	252	3
							1	FAILED	3000	INPUT TO OUTPUT	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
4021	NSC	1	Digital, Register, Shift	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
006	0878	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	2000	INPUT(13)(+) OUT(12)	81	167	13
							1	FAILED	800	INPUT(11)(+) OUT(12)	81	167	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
4021A	RCA	1	Digital, Register, Shift	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
156	N/R	SS	610 Ohms	100E-12 F	1	N/R	2	PASSED	1500	OUTPUT(3)(+)	57	252	2
							1	FAILED	1500	OUTPUT(3)(-)	57	252	2
							1	PASSED	1500	OUTPUT(3)(-)	57	252	2
							2	PASSED	1500	VSS(8)(+)	57	252	2
							2	PASSED	1500	PSC(9)(+)	57	252	2
							2	PASSED	1500	PI7(15)(+)	57	252	2
							1	PASSED	1500	PI7(15)(-)	57	159	2
							1	PASSED	1500	VDD(16)(+)	57	159	2
							1	PASSED	1500	VDD(16)(+)	57	252	2
							2	PASSED	1500	VDD(16)(-)	57	252	2
157	N/R	GN	610 Ohms	100E-12 F	1	N/R	6	PASSED	1000	VSS(8)(-)	57	164	2

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
4021A	RCA	1	Digital, Register, Shift	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
158	N/R	GN	610 Ohms	100E-12 F	1	N/R	1	PASSED	1200	OUTPUT(3)(-)	57	252	2
							2	PASSED	1200	OUTPUT(3)(-)	57	164	2
							1	FAILED	1200	OUTPUT(3)(-)	57	252	2
159	N/R	GN	610 Ohms	100E-12 F	1	N/R	2	PASSED	1500	VSS(8)(-)	57	164	2
							2	PASSED	1500	PSC(9)(-)	57	252	2
							1	PASSED	1500	PI7(15)(-)	57	164	2
							4	PASSED	1500	VDD(16)(+)	57	164	2
							2	PASSED	1500	OUTPUT(3)(-)	57	252	2
							2	PASSED	1500	OUTPUT(3)(-)	57	164	2
							1	FAILED	1500	OUTPUT(3)(-)	57	252	2
							4	PASSED	1500	PI7(15)(-)	57	164	2
							3	PASSED	1500	VSS(8)(-)	57	164	2
							1	FAILED	1500	VSS(8)(-)	57	252	2
160	N/R	SS	610 Ohms	100E-12 F	1	N/R	6	FAILED	3208	VDD(16)(+)	57	187	2
							2	FAILED	3250	VDD(16)(-)	57	187	2
							2	FAILED	3250	OUTPUT(3)(+)	57	187	2
							14	FAILED	2104	OUTPUT(3)(-)	57	187	2
							2	FAILED	3250	VSS(8)(+)	57	187	2
							12	FAILED	2063	VSS(8)(-)	57	187	2
							2	FAILED	3250	PSC(9)(+)	57	187	[illegible]
							2	FAILED	4000	PSC(9)(-)	57	187	[illegible]
							2	PASSED	5500	PI7(15)(+)	57	187	2
							5	FAILED	4000	PI7(15)(-)	57	187	2
233	N/R	SS	610 Ohms	100E-12 F	1	N/R	2	PASSED	1000	VSS(8)(-)	57	158	2
							2	PASSED	1000	PSC(9)(-)	57	158	2
							1	PASSED	1000	PI7(15)(-)	57	158	2

Part Number	Part Mfr	ESD Class	Part Description	Technology
4021A	NSC	1	Digital, Register, Shift	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4021B	FSC	2	Digital, Register, Shift	CMOS														
					161	N/R	SS	610 Ohms	100E-12 F	1	N/R	2	PASSED	4000	VSS(+)	57	252	2
												3	PASSED	4000	VSS(-)	57	162	2
												1	FAILED	4000	VSS(-)	57	160	2
												1	FAILED	2000	VSS(-)	57	252	2
												1	FAILED	4000	PSC(+)	57	161	2
												1	FAILED	2500	PSC(+)	57	159	2
												1	FAILED	3500	PSC(-)	57	159	2
												1	FAILED	2000	PSC(-)	57	252	2
												2	FAILED	4000	VDD(+)	57	252	2
												2	PASSED	4000	VDD(-)	57	252	2
												1	FAILED	2000	PI7(+)	57	252	2
												1	FAILED	2000	PI7(+)	57	159	2
												2	FAILED	2500	PI7(-)	57	252	2
												1	FAILED	2500	OUTPUT(+)	57	252	2
												1	PASSED	4000	OUTPUT(+)	57	252	2
												5	PASSED	4000	OUTPUT(-)	57	252	2
4021B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4023A	N/R	1	Digital, Gate	CMOS														
					244	N/R	SS	1500 Ohms	100E-12 F	1	7614	1	FAILED	975	OUTPUT(+) INPUT(-)	47	252	22
												1	FAILED	1000	OUTPUT(+) INPUT(-)	47	252	22
												12	PASSED	1000	OUTPUT(+) INPUT(-)	47	252	22
					245	N/R	SS	100 Ohms	N/R	1	7614	15	FAILED	203	VSS(+) INPUT(-)	47	186	21
4023B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4023B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	232	VSS(+) INPUT(-)	47	186	21
4023D	N/R	1	Digital, Gate	CMOS														
					244	N/R	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	1000	VSS(+) INPUT(-)	47	252	22
												11	PASSED	1000	VSS(+) INPUT(-)	47	252	22
												1	FAILED	950	OUTPUT(+) INPUT(-)	47	252	22
												1	FAILED	1000	OUTPUT(+) INPUT(-)	47	252	22
												12	PASSED	1000	OUTPUT(+) INPUT(-)	47	252	22
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	61	VSS(+) INPUT(-)	47	186	21
4024	SSS	1	Digital, Counter/Divider	CMOS														
					003	1175	SS	0 Ohms	100E-12 F	1	7508	1	FAILED	400	INPUT(+) PR. SUPPLY(-)	102	252	13
4024B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4024B	RCA	2	Digital, Counter/Divider	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	5	FAILED	3000	INPUT-GND AND INPUT-OUTPUT	5	252	3
												5	FAILED	3000	INPUT TO OUTPUT	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4025B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4027B	N/R	2	Digital, Flip-Flop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2100	N/R	103	252	13
												1	FAILED	2100	N/R	103	252	13
4027B	RCA	2	Digital, Flip-Flop	CMOS														
					436	0488	SS	1500 Ohms	100E-12 F	16	N/R	5	FAILED	3000	OUTPUT TO GROUND	5	252	3
4028A	NSC	2	Digital, Decoder	CMOS														
					393	0385	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	3000	13(INPUT) 16(VCC)	102	252	13
4028B	N/R	1	Digital, Decoder	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4029	FSC	1	Digital, Counter/Divider	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	7546	2	PASSED	400	N/R	57	146	14
4029B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4029B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4030B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4030B	SPR	2	Digital, Gate	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
4030B	RCA	2	Digital, Gate	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	4000	INPUT & OUTPUT TO COMMON	5	252	3
4031B	N/R	1	Digital, Register, Shift	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4033B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4034B	N/R	1	Digital, Register, Shift, Combination	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4034B	N/R	1	Digital, Register, Shift, Combination	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4035	NSC	1	Digital, Register, Shift	CMOS	006	0878	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1200	INPUT(2)(+) OUT(1)(-)	81	167	13
												1	FAILED	2000	INPUT(3)(+) OUT(13)(-)	81	167	13
4035	SSS	1	Digital, Register, Shift	CMOS	006	0878	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1200	INPUT(2)(+) OUT(1)(-)	81	167	13
												1	FAILED	1000	IN(10)(+) OUT(15)(-)	81	167	13
4035A	NSC	1	Digital, Register, Shift	CMOS	393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	102	252	13
4035B	N/R	1	Digital, Register, Shift	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4040	FSC	1	Digital, Counter/Divider	CMOS	165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14
4040A	RCA	2	Digital, Counter/Divider	CMOS	393	1284	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4000	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4040B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4042B	N/R	1	Digital, Latch	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4043	MOT	3	Digital, Latch	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6783	N/R	102	188	13
4043B	N/R	1	Digital, Latch	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4044	NSC	1	Digital, Latch	CMOS														
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	1000	INPUT(14)(+) OUT(1)(-)	81	167	13
4044	SSS	1	Digital, Latch	CMOS														
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1200	INPUT(3)(+) OUT(13)(-)	81	167	13
												1	FAILED	2000	INPUT(7)(+) OUT(9)(-)	81	167	13
												1	FAILED	600	INPUT(6)(+) OUT(9)(-)	81	167	13
4044A	SSS	1	Digital, Latch	CMOS														
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	600	N/R	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4044A	NSC	1	Digital, Latch	CMOS														
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	102	252	13
4046B	N/R	1	Linear, Phase Lock Loop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4046B	SSS	1	Linear, Phase Lock Loop	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO COMMON	5	151	3
												1	FAILED	1000	INPUT TO COMMON	5	253	3
4047	N/R	1	Digital, Multivibrator	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4049	FSC	1	Digital, Inverter, Buffer	CMOS														
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	82	252	13
												1	PASSED	800	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	200	N/R	82	252	13
4049	SSS	1	Digital, Inverter, Buffer	CMOS														
					003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	200	INPUT(+) PR. SUPPLY(-)	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4049	SSS	1	Digital, Inverter, Buffer	CMOS														
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	1000	INPUT(9)(+) OUT(10)(-)	81	167	13
												1	FAILED	600	INPUT(5)(+) OUT(4)(-)	81	167	13
					011	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	200	N/R	83	252	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	600	N/R	83	252	13
4049	NSC	1	Digital, Inverter, Buffer	CMOS														
					090	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	900	GATE(+) VSS(-)	56	252	5
												10	FAILED	1250	GATE(+) VSS(-)	56	252	5
												10	FAILED	1520	GATE(+) VSS(-)	56	252	5
												2	PASSED	1520	GATE(+) VSS(-)	56	252	5
					091	0278	GN	1500 Ohms	150E-12 F	1	N/R	7	FAILED	1125	GATE(+) VSS(-)	56	252	13
												18	PASSED	1125	GATE(+) VSS(-)	56	252	13
					092	0278	GN	1500 Ohms	150E-12 F	1	N/R	16	FAILED	1350	GATE(+) VSS(-)	56	252	13
												9	PASSED	1350	GATE(+) VSS(-)	56	252	13
					121	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	900	INPUT(+) VSS(-)	56	252	5
												10	FAILED	1250	INPUT(+) VSS(-)	56	252	5
												10	FAILED	1520	INPUT(+) VSS(-)	56	252	5
												2	PASSED	1520	INPUT(+) VSS(-)	56	252	5
					011	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	200	N/R	83	252	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	600	N/R	83	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4049A	RCA	1	Digital, Inverter, Buffer	CMOS														
					108	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1200	INPUT(+) VCC(-)	56	252	5
												10	FAILED	1750	INPUT(+) VCC(-)	56	252	5
												10	FAILED	2200	INPUT(+) VCC(-)	56	252	5
												2	PASSED	2200	INPUT(+) VCC(-)	56	252	5
4049A	SSS	1	Digital, Inverter, Buffer	CMOS														
					393	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	102	252	13
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	102	252	13
					393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	N/R	102	252	13
4049UB	RCA	1	Digital, Inverter, Buffer	CMOS														
					109	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	980	INPUT(+) VCC(-)	56	252	5
												10	FAILED	1460	INPUT(+) VCC(-)	56	252	5
												10	FAILED	1950	INPUT(+) VCC(-)	56	252	5
												2	PASSED	1950	INPUT(+) VCC(-)	56	252	5
4049UB	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4050	FSC	1	Digital, Inverter, Buffer	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14
					007	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	82	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4050	FSC	1	Digital, Inverter, Buffer	CMOS														
					008	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	600	N/R	82	252	13
					009	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	N/R	82	252	13
					010	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	82	252	13
												1	PASSED	1000	N/R	82	252	13
4050	SSS	1	Digital, Inverter, Buffer	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1200	INPUT(11)(+) OUT(12)	81	167	13
												2	FAILED	1500	INPUT(14)(+) OUT(15)	81	167	13
												1	FAILED	2000	INPUT(14)(+) OUT(15)	81	167	13
					011	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	200	N/R	83	252	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	600	N/R	83	252	13
4050	NSC	1	Digital, Inverter, Buffer	CMOS														
					011	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	200	N/R	83	252	13
					012	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	400	N/R	83	252	13
					013	0878	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	600	N/R	83	252	13
4050	N/R	1	Digital, Inverter, Buffer	CMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	500	EACH PIN(+)	52	100	24

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4050A	SSS	1	Digital, Inverter, Buffer	CMOS														
					393	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	600	N/R	102	252	13
4050A	NSC	1	Digital, Inverter, Buffer	CMOS														
					393	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	102	252	13
4050A	LEA	1	Digital, Inverter, Buffer	CMOS														
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1200	N/R	102	252	13
4050B	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4050B	RCA	1	Digital, Inverter, Buffer	CMOS														
					436	0588	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT TO OUTPUT	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	11	N/R	5	FAILED	1400	INPUT TO COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
												1	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT TO GND	5	252	3
4051	RCA	2	Digital, Multiplexer	CMOS														
					393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4051B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4052B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4053	NSC	1	Digital, Multiplexer	CMOS														
					122	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	720	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	1070	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	1400	VEE(+) SELECT A(-)	56	252	5
												2	PASSED	1400	VEE(+) SELECT A(-)	56	252	5
4053B	RCA	1	Digital, Multiplexer	CMOS														
					110	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	435	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	740	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	1020	VEE(+) SELECT A(-)	56	252	5
												2	PASSED	1020	VEE(+) SELECT A(-)	56	252	5
4053B	FSC	1	Digital, Multiplexer	CMOS														
					126	0478	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	1610	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	1950	VEE(+) SELECT A(-)	56	252	5
												10	FAILED	2200	VEE(+) SELECT A(-)	56	252	5
												2	PASSED	2200	VEE(+) SELECT A(-)	56	252	5
4053B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4053B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4066	N/R	3	Linear, Switch	CMOS														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	76	VSS(+) INPUT(-)	47	186	21
4066	NSC	1	Linear, Switch	CMOS														
					416	0184	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
4066B	N/R	1	Linear, Switch	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4066B	RCA	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	17	N/R	1	FAILED	3500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO GND	5	252	3
4067B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4068B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4068B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	3
4069	FSC	1	Digital, Inverter, Buffer	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	4
4069	SSS	1	Digital, Inverter, Buffer	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	400	N/R	57	146	14
4069B	NSC	1	Digital, Inverter, Buffer	CMOS														
					089	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	960	VDD(+) GATE(-)	56	252	5
												10	FAILED	1300	VDD(+) GATE(-)	56	252	5
												10	FAILED	1600	VDD(+) GATE(-)	56	252	5
												2	PASSED	1600	VDD(+) GATE(-)	56	252	5
4069B	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4069UB	RCA	1	Digital, Inverter, Buffer	CMOS														
					038	0278	SS	1500 Ohms	150E-12 F	1	N/R	3	FAILED	730	VDD(+) GATE(-)	56	252	5
												10	FAILED	1080	VDD(+) GATE(-)	56	252	5
												10	FAILED	1510	VDD(+) GATE(-)	56	252	5
												2	PASSED	1510	VDD(+) GATE(-)	56	252	5

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4069UB	RCA	1	Digital, Inverter, Buffer	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
												1	PASSED	4000	N/R	5	252	3
4069UB	N/R	1	Digital, Inverter, Buffer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4070	FSC	1	Digital, Gate	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	7602	2	PASSED	400	N/R	57	146	14
4070B	SSS	2	Digital, Gate	CMOS														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
4071B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4073B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4076B	N/R	1	Digital, Flip-Flop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4076B	N/R	1	Digital, Flip-Flop	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4077B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4081B	RCA	2	Digital, Gate	CMOS														
					162	N/R	SS	610 Ohms	100E-12 F	1	N/R	2	PASSED	4500	INPUT(1)(+)	57	252	2
												2	FAILED	4500	INPUT(1)(-)	57	252	2
												2	FAILED	4500	OUTPUT(4)(+)	57	252	2
												1	PASSED	4500	OUTPUT(4)(-)	57	163	2
												1	PASSED	4500	OUTPUT(4)(-)	57	252	2
												2	PASSED	4500	VSS(7)(+)	57	252	2
												1	FAILED	4000	VSS(7)(-)	57	252	2
												1	PASSED	4500	VSS(7)(-)	57	162	2
												2	PASSED	4500	VDD(14)(+)	57	252	2
												2	PASSED	4500	VDD(14)(-)	57	252	2
					436	0488	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	INPUT TO COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	INPUT TO GND	5	252	3
4081B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4081UB	RCA	2	Digital, Inverter, Buffer	CMOS														
					436	0788	SS	1500 Ohms	100E-12 F	17	8729	5	FAILED	3500	INPUT TO VSS	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4082B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4085B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4086B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4093	NSC	1	Digital, Gate	CMOS														
					006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	INPUT(9)(+) OUT(10)(-)	81	167	13
												2	FAILED	2500	INPUT(13)(+) OUT(11)	81	167	13
												1	FAILED	1500	INPUT(5)(+) OUT(4)(-)	81	167	13
					393	0180	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	102	252	13
4093B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4094	RCA	2	Digital, Register, Shift	CMOS														
					393	1284	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	3500	1(INPUT) 16(VDD)	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology
4099B	N/R	1	Digital, Latch	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
4116	MOS	1	Digital, Memory, RAM, Dynamic	NMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
061	0978	SS	1000 Ohms	220E-12 F	1	N/R	1	FAILED	500	N/R	2	252	13
							8	FAILED	1000	N/R	2	252	13
							1	PASSED	1000	N/R	2	252	13
062	1079	GN	1000 Ohms	220E-12 F	1	N/R	6	FAILED	1000	VCC(+) VBB,VDD(-)	102	252	13
							4	PASSED	1000	VCC(+) VBB,VDD(-)	102	252	13
062	1079	GN	1000 Ohms	220E-12 F	5	N/R	3	FAILED	1000	VCC(+) VDD,VSS(-)	102	252	13
							2	PASSED	1000	VCC(+) VDD,VSS(-)	102	252	13
063	1079	SS	1000 Ohms	220E-12 F	1	N/R	4	FAILED	800	VCC(+) VBB,VDD(-)	102	252	13
							4	FAILED	1000	VCC(+) VBB,VDD(-)	102	252	13
							2	PASSED	1000	VCC(+) VBB,VDD(-)	102	252	13
064	1079	SS	100 Ohms	200E-12 F	1	N/R	1	FAILED	1000	VCC(+) VBB,VDD(-)	102	252	13
							4	FAILED	1200	VCC(+) VBB,VDD(-)	102	252	13
065	1079	GN	100 Ohms	220E-12 F	1	N/R	2	FAILED	1000	VCC(+) VBB,VDD(-)	102	252	13
065	1079	GN	100 Ohms	220E-12 F	2	N/R	7	FAILED	1000	VCC(+) VBB,VDD(-)	102	252	13
							1	PASSED	1000	VCC(+) VBB,VDD(-)	102	252	13
065	1079	GN	100 Ohms	220E-12 F	1	N/R	4	FAILED	1000	VCC(+) VDD,VSS(-)	102	252	13
							1	PASSED	1000	VCC(+) VDD,VSS(-)	102	252	13
066	1079	GN	1000 Ohms	220E-12 F	1	N/R	2	FAILED	1200	VCC(+) VDD,VSS(-)	102	252	13
							3	PASSED	1200	VCC(+) VDD,VSS(-)	102	252	13
129	0780	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	500	EACH PIN(+) APTT(-)	102	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4115	MOS	1	Digital, Memory, RAM, Dynamic	NMOS														
					131	0780	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	700	EACH PIN(+) APTT(-)	102	252	13
					133	0780	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	EACH PIN(+) APTT(-)	102	252	13
												4	PASSED	800	EACH PIN(+) APTT(-)	102	252	13
					135	0780	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1000	EACH PIN(+) APTT(-)	102	252	13
					137	0780	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1500	EACH PIN(+) APTT(-)	102	252	13
4116	TEX	1	Digital, Memory, RAM, Dynamic	NMOS														
					061	0978	SS	1000 Ohms	220E-12 F	1	N/R	5	FAILED	1000	N/R	2	252	13
4131	N/R	2	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
4136	FSC	2	Linear, Operational Amplifier	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
416	NEC	1	Digital, Memory, RAM, Dynamic	NMOS														
					061	0978	SS	1000 Ohms	220E-12 F	1	N/R	4	FAILED	500	N/R	2	252	13
												1	FAILED	1000	N/R	2	252	13
					130	0880	GN	1500 Ohms	100E-12 F	1	N/R	5	PASSED	500	EACH PIN(+) APTT(-)	102	252	13
					132	0880	GN	1500 Ohms	100E-12 F	1	N/R	3	FAILED	700	EACH PIN(+) APTT(-)	102	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
416	NEC	1	Digital, Memory, RAM, Dynamic	NMOS
4164	TEX	2	Digital, Memory, RAM, Dynamic	NMOS
420	NSC	2	Digital, Processing Unit, Central	NMOS
4502B	N/R	1	Digital, Inverter, Buffer	CMOS
4503B	N/R	1	Digital, Inverter, Buffer	CMOS
4508B	N/R	1	Digital, Latch	CMOS
4511	RCA	1	Digital, Decoder	CMOS

Part Number	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
416	132	0880	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	700	EACH PIN(+) APTT(-)	102	252	13
	136	0880	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1000	EACH PIN(+) APTT(-)	102	252	13
4164	393	0884	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	10(INPUT) 8(VCC)	102	252	13
420	393	0383	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	102	246	13
4502B	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
								1	FAILED	1000	N/R	103	252	13
4503B	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
								1	FAILED	1000	N/R	103	252	13
4508B	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
								1	FAILED	1000	N/R	103	252	13
4511	006	0878	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1500	INPUT(6)(+) OUT(10)(-)	81	167	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4511	RCA	1	Digital, Decoder	CMOS	006	0878	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	INPUT(7)(+) OUT(9)(-)	81	167	13
4511B	N/R	1	Digital, Decoder	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4512B	N/R	1	Digital, Multiplexer	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4514B	N/R	1	Digital, Decoder	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4515B	N/R	1	Digital, Decoder	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4516B	N/R	1	Digital, Counter/Divider	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4518B	N/R	1	Digital, Counter/Divider	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
45188	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4519B	N/R	1	Digital, Gate	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4520B	N/R	1	Digital, Counter/Divider	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
45288	N/R	1	Digital, Multivibrator	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4539B	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4555B	N/R	1	Digital, Decoder	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4558	N/R	1	Linear, Operational Amplifier	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1750	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4558	RAY	1	Linear, Operational Amplifier	Bipolar														
					435	0483	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	1000	PINS 5 TO 6	100	244	13
					435	0483	SS	1500 Ohms	100E-12 F	20	N/R	1	FAILED	1750	PINS 2 TO 4	100	197	13
					435	0483	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	1500	PIN 2 TO 4	100	197	13
					435	0483	SS	1500 Ohms	100E-12 F	24	N/R	1	FAILED	2000	PINS 2 TO 4	100	197	13
					435	0483	SS	1500 Ohms	100E-12 F	28	N/R	1	FAILED	2250	PINS 2 TO 4	100	197	13
					434	0483	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	INPUT TO GND	100	252	13
												3	FAILED	2000	INPUT TO INPUT	100	252	13
					435	0483	SS	1500 Ohms	100E-12 F	12	N/R	4	FAILED	1250	PINS 2 TO 4	100	197	13
					435	0483	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1250	PINS 5 TO 6	100	244	13
					435	0483	SS	1500 Ohms	100E-12 F	12	N/R	2	FAILED	1500	PINS 5 TO 6	100	244	13
					435	0483	SS	1500 Ohms	100E-12 F	16	N/R	3	FAILED	1750	PINS 5 TO 6	100	244	13
					435	0483	SS	1500 Ohms	100E-12 F	20	N/R	2	FAILED	2000	PINS 5 TO 6	100	244	13
					435	0483	SS	1500 Ohms	100E-12 F	24	N/R	1	FAILED	2250	PINS 5 TO 6	100	244	13
					434	0483	GN	1500 Ohms	100E-12 F	10	N/R	6	PASSED	2000	N/R	100	252	13
4581B	N/R	1	Digital, Arithmetic, Logic Unit	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
4585B	N/R	1	Linear, Comparator	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
4585B	N/R	1	Linear, Comparator	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
4716	HIT	1	Digital, Memory, RAM, Dynamic	NMOS														
					130	0780	GN	1500 Ohms	100E-12 F	1	N/R	4	FAILED	500	EACH PIN(+) APTT(-)	102	252	13
												1	PASSED	500	EACH PIN(+) APTT(-)	102	252	13
					132	0780	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	700	EACH PIN(+) APTT(-)	102	252	13
4724	FSC	1	Digital, Latch	CMOS														
					165	0676	GN	1500 Ohms	100E-12 F	1	7603	2	PASSED	400	N/R	57	146	14
4741	RAY	1	Linear, Operational Amplifier	Bipolar														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	850	EACE PIN TO 4 & 11 (+ -)	19	252	13
4801	VAR	3	Digital, Memory, RAM, Static	NMOS														
					424	0683	SS	1500 Ohms	100E-12 F	6	N/R	8	FAILED	750	PIN 5	46	149	13
					424	0683	SS	1500 Ohms	100E-12 F	8	N/R	7	FAILED	1000	PIN 5	46	149	13
					423	0683	SS	0 Ohms	0 F	12	N/R	2	FAILED	1500	PIN 5	46	252	4
					423	0683	SS	0 Ohms	0 F	14	N/R	5	FAILED	1750	PIN 5	46	252	4
					423	0683	SS	0 Ohms	0 F	16	N/R	7	FAILED	2000	PIN 5	46	252	4
					423	0683	SS	0 Ohms	0 F	15	N/R	1	FAILED	2000	PIN 5	46	252	4

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
506	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
507A	HAR	1	Digital, Multiplexer	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	7	8712	2	FAILED	800	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	17	8712	2	FAILED	3500	OUTPUT TO GND	5	252	3
508	N/R	1	Digital, Multiplexer	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
508/6108	SIX	1	Digital, Multiplexer	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	8651	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	16	8651	5	FAILED	3000	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	8651	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	8651	4	FAILED	400	INPUT TO OUTPUT	5	252	3
51C86	INT	1	Digital	CMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
5214	HYB	3	Digital, Converter, A/D-D/A	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	8628	5	PASSED	4000	N/R	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
52168	HYB	1	Digital, Converter, A/D-D/A	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	2	FAILED	1800	INPUT TO GND	5	252	3
52832	NCR	1	Digital, Memory, EAROM, EEPROM	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	2	FAILED	2000	INPUT TO GND	5	252	3
5309-1	MON	1	Digital, Memory, PROM	STTL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	450	EACH PIN TO 10 & 20 (+ -)	19	252	13
532	N/R	1	Linear	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	N/R	103	252	13
												1	FAILED	1250	N/R	103	252	13
												1	FAILED	1250	N/R	103	252	13
5400	FSC	1	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	2600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	2500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	2	FAILED	1600	INPUT	5	252	3
5400	TEX	3	Digital, Gate	TTL														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	763	INPUT(1)(+) GND(7)(-)	5	285	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5400	TEX	3	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5400	NSC	1	Digital, Gate	TTL														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	625	INPUT(1)(+) GND(7)(-)	6	285	13
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1500	INPUT TO OUTPUT	5	252	3
5400	N/R	3	Digital, Gate	TTL														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	99	INPUT(+) GND(-)	47	186	21
5401	TEX	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5402	FSC	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5402	NSC	1	Digital, Gate	TTL														
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	3	FAILED	1600	INPUT TO GND	5	252	3
5404	FSC	2	Digital, Inverter, Buffer	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
5404	TEX	2	Digital, Inverter, Buffer	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
5404	N/R	2	Digital, Inverter, Buffer	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
321	N/R	GN	1500 Ohms	100E-12 F	200	N/R	2	PASSED	1000	VCC(14)(+) IN.(1)(-)	79	252	13
331	N/R	GN	1500 Ohms	200E-12 F	200	N/R	1	PASSED	1500	VCC(14)(+) IN.(1)(-)	79	252	13
332	N/R	GN	1500 Ohms	N/R F	200	N/R	1	PASSED	1575	VCC(14)(+) IN.(1)(-)	79	252	13
333	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1615	VCC(14)(+) IN.(1)(-)	77	252	13
334	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1630	VCC(14)(+) IN.(1)(-)	79	252	13
[illegible]	N/R	GN	1500 Ohms	200E-12 F	2	N/R	1	FAILED	1650	VCC(14)(+) IN.(1)(-)	121	252	13
[illegible]	N/R	GN	1500 Ohms	200E-12 F	3	N/R	2	FAILED	1650	VCC(14)(+) IN.(1)(-)	121	252	13
[illegible]	N/R	GN	1500 Ohms	200E-12 F	4	N/R	1	FAILED	1650	VCC(14)(+) IN.(1)(-)	121	252	13
[illegible]	N/R	GN	1500 Ohms	200E-12 F	50	N/R	1	FAILED	1650	VCC(14)(+) IN.(1)(-)	77	252	13
[illegible]	N/R	GN	1500 Ohms	200E-12 F	150	N/R	1	FAILED	1650	VCC(14)(+) IN.(1)(-)	77	252	13
335	N/R	GN	1500 Ohms	200E-12 F	2	N/R	1	PASSED	1650	VCC(14)(+) IN.(1)(-)	121	252	13
336	N/R	GN	1500 Ohms	200E-12 F		N/R	1	PASSED	1670	VCC(14)(+) IN.(1)(-)	79	252	13
337	N/R	GN	1500 Ohms	200E-12 F	3	N/R	1	FAILED	1675	VCC(14)(+) IN.(1)(-)	121	252	13
337	N/R	GN	1500 Ohms	200E-12 F	2	N/R	1	FAILED	1675	VCC(14)(+) IN.(1)(-)	77	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
5404	N/R	2	Digital, Inverter, Buffer	TL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
337	N/R	GN	1500 Ohms	200E-12 F	200	N/R	1	PASSED	1675	VCC(14)(+) IN.(1)(-)	79	252	13
338	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1700	VCC(14)(+) IN.(1)(-)	121	252	13
338	N/R	GN	1500 Ohms	200E-12 F	2	N/R	2	FAILED	1700	VCC(14)(+) IN.(1)(-)	121	252	13
338	N/R	GN	1500 Ohms	200E-12 F	4	N/R	2	FAILED	1700	VCC(14)(+) IN.(1)(-)	77	252	13
							1	FAILED	1700	VCC(14)(+) IN.(1)(-)	121	252	13
338	N/R	GN	1500 Ohms	200E-12 F	200	N/R	1	PASSED	1700	VCC(14)(+) IN.(1)(-)	79	252	13
338	N/R	GN	1500 Ohms	200E-12 F	2	N/R	1	FAILED	1700	VCC(14)(+) IN.(1)(-)	121	252	13
339	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1730	VCC(14)(+) IN.(1)(-)	79	252	13
340	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1750	VCC(14)(+) IN.(1)(-)	79	252	13
340	N/R	GN	1500 Ohms	200E-12 F	50	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	121	252	13
							1	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	2	N/R	3	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	3	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	4	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	121	252	13
							6	PASSED	1750	VCC(14)(+) IN.(1)(-)	79	252	13
340	N/R	GN	1500 Ohms	200E-12 F	3	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	77	252	13
340	N/R	GN	1500 Ohms	200E-12 F	4	N/R	1	FAILED	1750	VCC(14)(+) IN.(1)(-)	121	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
5404	N/R	2	Digital, Inverter, Buffer	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
341	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1760	VCC(14)(+) IN.(1)(-)	77	252	13
342	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1775	VCC(14)(+) IN.(1)(-)	79	252	13
343	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1800	VCC(14)(+) IN.(1)(-)	79	252	13
							1	FAILED	1800	VCC(14)(+) IN.(1)(-)	121	252	13
343	N/R	GN	1500 Ohms	200E-12 F	2	N/R	1	FAILED	1800	VCC(14)(+) IN.(1)(-)	121	252	13
							1	FAILED	1800	VCC(14)(+) IN.(1)(-)	77	252	13
343	N/R	GN	1500 Ohms	200E-12 F	3	N/R	1	FAILED	1800	VCC(14)(+) IN.(1)(-)	77	252	13
343	N/R	GN	1500 Ohms	200E-12 F	5	N/R	1	FAILED	1800	VCC(14)(+) IN.(1)(-)	121	252	13
343	N/R	GN	1500 Ohms	200E-12 F	9	N/R	1	FAILED	1800	VCC(14)(+) IN.(1)(-)	121	252	13
343	N/R	GN	1500 Ohms	200E-12 F	200	N/R	1	PASSED	1800	VCC(14)(+) IN.(1)(-)	79	252	13
343	N/R	GN	1500 Ohms	200E-12 F	1	N/R	2	FAILED	1800	VCC(14)(+) IN.(1)(-)	80	252	13
							1	FAILED	1800	VCC(14)(+) IN.(1)(-)	77	252	13
							4	PASSED	1800	VCC(14)(+) IN.(1)(-)	79	252	13
344	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	1850	VCC(14)(+) IN.(1)(-)	79	252	13
							3	FAILED	1850	VCC(14)(+) IN.(1)(-)	121	252	13
344	N/R	GN	1500 Ohms	200E-12 F	2	N/R	2	FAILED	1850	VCC(14)(+) IN.(1)(-)	121	252	13
344	N/R	GN	1500 Ohms	200E-12 F	3	N/R	1	PASSED	1850	VCC(14)(+) IN.(1)(-)	79	252	13
344	N/R	GN	1500 Ohms	200E-12 F	6	N/R	1	FAILED	1850	VCC(14)(+) IN.(1)(-)	77	252	13
345	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1900	VCC(14)(+) IN.(1)(-)	121	252	13
346	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	2000	VCC(14)(+) IN.(1)(-)	79	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5404	N/R	2	Digital, Inverter, Buffer	TTL	347	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	2000	VCC(14)(+) IN.(1)(-)	121	252	13
5405	TEX	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S R	105	247	11
5406	TEX	2	Digital, Line/Bus Driver	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5406	NSC	2	Digital, Line/Bus Driver	TTL	436	1186	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	2500	INPUT TO GND	5	252	3
5406	N/R	2	Digital, Line/Bus Driver	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5407	N/R	2	Digital, Line/Bus Driver	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5408	FSC	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5409	FSC	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5410	NSC	1	Digital, Gate	TTL														
					436	0788	SS	1500 Ohms	100E-12 F	18	8711	5	FAILED	4000	OUTPUT TO COMMON	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	12	8711	5	FAILED	1500	INPUT TO OUTPUT	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	7	8711	5	FAILED	800	INPUT TO COMMON	5	252	3
5410	FSC	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54107	TEX	2	Digital, Flip-Flop	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5412	TEX	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54120	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
54120	TEX	1	Digital, Line/Bus Driver	TTL														
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	2	FAILED	1200	INPUT TO OUTPUT	5	252	3
54121	FSC	1	Digital, Multivibrator	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54121	FSC	1	Digital, Multivibrator	TTL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 7 & 14 (+ -)	19	252	13
54122	FSC	1	Digital, Multivibrator	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	2	FAILED	2000	INPUT TO OUTPUT	5	252	3
54123	FSC	2	Digital, Multivibrator	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54128	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
54150	FSC	1	Digital, Multiplexer	TTL														
					436	1186	SS	1500 Ohms	100E-12 F	11	8704	1	FAILED	1400	INPUT TO GND	5	252	3
54151	FSC	2	Digital, Multivibrator	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54153	FSC	2	Digital, Multiplexer	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54153	N/R	3	Digital, Multiplexer	TTL	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	78	INPUT(+) GND(-)	47	186	21
54154	N/R	2	Digital, Decoder	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5416	TEX	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5416	FSC	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54161	TEX	2	Digital, Counter/Divider	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54174	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54174	FSC	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54175	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54175	FSC	2	Digital, Flip-Flop	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54182	N/R	1	Digital, Arithmetic, Carry Generator	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	2500	N/R	103	252	13
5420	FSC	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5420	TEX	2	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2230	N/R	102	189	13
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5421	SIG	2	Digital, Gate	TTL														
					003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	700	INPUT(+) PR. SUPPLY(-)	102	252	13
					004	1175	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	1400	INPUT	102	233	13
5423	TEX	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5425	N/R	2	Digital, Gate	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5427	FSC	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5427	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54273	TEX	1	Digital, Flip-Flop	TTL	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 10 & 20 (+ -)	19	252	13
5430	FSC	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5430	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5437	N/R	2	Digital, Inverter, Buffer	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5437	FSC	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5437	TEX	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5438	N/R	2	Digital, Gate	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5440	FSC	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5440	TEX	2	Digital, Inverter, Buffer	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5442	FSC	2	Digital, Decoder	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5445	N/R	2	Digital, Decoder	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5446	N/R	2	Digital, Line/Bus Driver	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
5450	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5451	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5453	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5454	TEX	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5470	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5472	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5472	NSC	1	Digital, Flip-Flop	TTL	436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1600	INPUT TO GND	5	252	3
5473	NSC	1	Digital, Flip-Flop	TTL	436	0488	SS	1500 Ohms	100E-12 F	12	8726	2	FAILED	1500	INPUT TO OUTPUT	5	252	3
					436	0488	SS	1500 Ohms	100E-12 F	7	8726	2	FAILED	800	INPUT TO COMMON	5	252	3
5473	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5474	FSC	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5474	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5476	NSC	1	Digital, Flip-Flop	TTL	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 5 & 13 (+ -)	19	252	13
5476	TEX	2	Digital, Flip-Flop	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5483	N/R	3	Digital, Error Detect/Correct, Parity/Carry Gen	TTL	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	65	INPUT(+) GND(-)	47	186	21
5483	TEX	2	Digital, Error Detect/Correct, Parity/Carry Gen	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5483	FSC	2	Digital, Error Detect/Correct, Parity/Carry Gen	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
5486	FSC	2	Digital, Gate	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
5486	TEX	2	Digital, Gate	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54C00	NSC	1	Digital, Gate	CMOS														
					393	0485	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	2000	2(INPUT) 7(GND)	102	252	13
54C02	NSC	1	Digital, Gate	CMOS														
					393	0285	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	2000	3(INPUT) 14(VCC)	102	252	13
54C04	NSC	2	Digital, Inverter, Buffer	CMOS														
					393	0285	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	4000	11(INPUT) 10(OUTPUT)	102	252	13
54C08	NSC	2	Digital, Gate	CMOS														
					393	0285	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	4000	1(INPUT) 3(OUTPUT)	102	252	13
54C14	NSC	2	Digital, Inverter, Schmitt Trigger	CMOS														
					393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2250	N/R	102	194	13
54C157	NSC	2	Digital, Multiplexer	CMOS														
					393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2500	2(INPUT) 8(GND)	102	252	13
54C163	NSC	2	Digital, Counter/Divider	CMOS														
					393	0385	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	3000	6(INPUT) 8(GND)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54C164	NSC	2	Digital, Register, Shift	CMOS	393	0984	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2500	8(INPUT) 7(GND)	102	252	13
54C174	NSC	2	Digital, Flip-Flop	CMOS	393	0485	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2500	1(INPUT) 15(VCC)	102	252	13
54C193	NSC	1	Digital, Counter/Divider	CMOS	393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1500	9(INPUT) 16(VCC)	102	252	13
54C30	NSC	2	Digital, Gate	CMOS	393	0285	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	3000	1(INPUT) 7(GND)	102	252	13
54C42	NSC	1	Digital, Decoder	CMOS	393	0984	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1500	12(INPUT) 8(GND)	102	252	13
54C52	NSC	1	Digital, Line/Bus Driver	CMOS	393	0882	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	400	N/R	102	252	13
54C74	NSC	2	Digital, Flip-Flop	CMOS	393	0285	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	3000	12(INPUT) 8(OUTPUT)	102	252	13
54C76	NSC	2	Digital, Flip-Flop	CMOS	393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	4000	4(INPUT) 5(VCC)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology / Failure Criteria	Test Remarks	General Remarks
54C83	NSC	2	Digital, Gate												CMOS		
				393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2500	4(INPUT) 5(VCC)	102	252	13
54C85	NSC	1	Linear, Comparator												CMOS		
				393	0385	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2000	1(INPUT) 8(GND)	102	252	13
54C901	NSC	1	Digital, Inverter, Buffer												CMOS		
				393	0285	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	2000	4(INPUT) 7(GND)	102	252	13
54C902	NSC	1	Digital, Inverter, Buffer												CMOS		
				393	0285	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2000	2(INPUT) 1(OUTPUT)	102	252	13
				436	1186	SS	1500 Ohms	100E-12 F	5	N/R	2	FAILED	600	INPUT TO OUTPUT	5	252	3
54C906	NSC	2	Digital, Inverter, Buffer												CMOS		
				393	0285	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	3000	4(INPUT) 3(OUTPUT)	102	252	13
54C922	NSC	1	Digital, Encoder												CMOS		
				393	0181	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	102	252	13
54F00	SIG	1	Digital, Gate												Advanced STTL		
				436	0688	SS	1500 Ohms	100E-12 F	12	8741	5	FAILED	1500	INPUT TO OUTPUT	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F00	FSC	1	Digital, Gate	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	0788	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GROUND	5	252	3
393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	1(INPUT) 7(GND)	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F02	SIG	1	Digital, Gate	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	0788	SS	1500 Ohms	100E-12 F	7	8737	5	FAILED	800	INPUT TO OUTPUT	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F02	FSC	1	Digital, Gate	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	8(INPUT) 10(OUTPUT)	102	252	13
436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO OUTPUT	5	252	3
							5	FAILED	800	INPUT TO GND	5	252	3
							5	FAILED	800	INPUT TO OUTPUT	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	9(INPUT) 7(GND)	102	252	13
436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	VCC TO INPUT	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F08	FSC	1	Digital, Gate	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0984	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	500	10(INPUT) 7(GND)	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54F11	FSC	1	Digital, Gate	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	10(INPUT) 7(GND)	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology
54F138	FSC	1	Digital, Decoder	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	102	252	13
436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO OUTPUT	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	OUTPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO OUTPUT	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
54F138	SIG	1	Digital, Decoder	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1500	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO GND	5	252	3
							5	FAILED	1000	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO OUTPUT	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
54F153	FSC	2	Digital, Multiplexer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	6(INPUT) 8(GND)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54F163	FSC	1	Digital, Counter/Divider	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
393	0284	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	5(INPUT) 8(GND)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54F132	FSC	1	Digital, Arithmetic, Carry Generator	Advanced STTL														
					393	0284	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	102	147	13
54F194	FSC	2	Digital, Register, Shift	Advanced STTL														
					393	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	1(INPUT) 8(GND)	102	252	13
54F20	FSC	1	Digital, Gate	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
54F21	FSC	3	Digital, Gate	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	18	8617	1	PASSED	4000	N/R	5	252	3
54F240	FSC	2	Digital, Inverter, Buffer	Advanced STTL														
					393	0284	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	15(INPUT) 10(GND)	102	252	13
54F244	FSC	1	Digital, Inverter, Buffer	Advanced STTL														
					393	0784	SS	1500 Ohms	100E-12 F	1	8348	1	FAILED	350	8(INPUT) 10(GND)	102	252	13
54F253	FSC	1	Digital, Multiplexer	Advanced STTL														
					393	0984	SS	1500 Ohms	100E-12 F	1	8338	1	FAILED	750	11(INPUT) 8(GND)	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54F280	FSC	1	Digital, Gate	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	10	8534	1	FAILED	1200	INPUT TO GND	5	252	3
54F32	SIG	1	Digital, Gate	Advanced STTL														
					436	0588	SS	1500 Ohms	100E-12 F	12	8751	4	FAILED	1500	+ INPUT TO - OUTPUT	5	252	3
												4	FAILED	1500	INPUT TO GROUND	5	252	3
54F32	FSC	1	Digital, Gate	Advanced STTL														
					393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	9(INPUT) 7(GND)	102	252	13
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	5	FAILED	1800	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	5	FAILED	1400	INPUT TO GND	5	252	3
54F32	MOT	1	Digital, Gate	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	5	FAILED	1400	INPUT TO GND	5	252	3
54F373	FSC	1	Digital, Latch	Advanced STTL														
					436	0588	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO OUTPUT	5	252	3
					393	0784	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	14(INPUT) 20(GND)	102	252	13
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	5	FAILED	900	INPUT TO GND	5	252	3

Part Number (Cont'd)	Part Mtr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54F373	FSC	1	Digital, Latch	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
												5	FAILED	800	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
54F374	FSC	2	Digital, Flip-Flop	Advanced STTL														
					393	0284	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	4(INPUT) 10(GND)	102	252	13
54F521	FSC	1	Linear, Comparator	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	9	8551	5	FAILED	1000	INPUT TO GND	5	252	3
												1	FAILED	1000	INPUT TO GND	5	252	3
												5	FAILED	1000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	8551	5	FAILED	800	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	8551	1	FAILED	400	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	8551	5	FAILED	1400	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	8551	5	FAILED	1000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	8551	5	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	8551	5	PASSED	4000	N/R	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54F64	FSC	2	Digital, Gate	Advanced STTL														
					393	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	11(INPUT) 7(GND)	102	252	13
54F74	FSC	1	Digital, Flip-Flop	Advanced STTL														
					393	0984	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	400	4(INPUT) 7(GND)	102	252	13
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO OUTPUT	5	252	3
												5	FAILED	700	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO GND	5	252	3
												5	FAILED	1000	INPUT TO GND	5	252	3
54F74	SIG	1	Digital, Flip-Flop	Advanced STTL														
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	5	FAILED	1800	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO OUTPUT	5	252	3

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54F74	SIG	1	Digital, Flip-Flop	Advanced STTL	436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT	5	252	3
54H00	FSC	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H00	N/R	3	Digital, Gate	HTTL	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	93	INPUT(+) GND(-)	47	186	21
54H01	TEX	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H04	TEX	2	Digital, Inverter, Buffer	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H04	FSC	2	Digital, Inverter, Buffer	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H04	RCA	1	Digital, Inverter, Buffer	HTTL	436	1186	SS	1500 Ohms	100E-12 F	14	N/R	2	FAILED	2000	INPUT TO GND	5	252	3
54H10	TEX	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54H10	FSC	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H183	N/R	3	Digital, Arithmetic, Adder, Full	HTTL	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	98	INPUT(+) GND(-)	47	186	21
54H20	TEX	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H20	FSC	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H30	FSC	2	Digital, Gate	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H40	TEX	2	Digital, Inverter, Buffer	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54H76	TEX	2	Digital, Flip-Flop	HTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54HC00	MOT	1	Digital, Gate	HMOS	397	N/R	SS	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1800	INPUT TO GND (+ -)	54	252	7

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54HC00	MOT	1	Digital, Gate	HMOS														
					397	N/R	SS	1500 Ohms	100E-12 F	5	N/R	10	FAILED	3700	OUTPUT TO GND (+ -)	54	252	7
												10	FAILED	2100	INPUT TO OUTPUT (+ -)	54	252	7
												10	PASSED	9000	VCC TO GND (+ -)	102	252	7
												10	PASSED	9000	GND TO VCC (+ -)	102	252	7
54HC00	RCA	2	Digital, Gate	HMOS														
					397	N/R	SS	1500 Ohms	100E-12 F	1	N/R	10	FAILED	2800	INPUT TO GND (+ -)	54	252	7
												10	FAILED	6125	OUTPUT TO GND (+ -)	54	252	7
					397	N/R	SS	1500 Ohms	100E-12 F	5	N/R	10	FAILED	2050	INPUT TO OUTPUT (+ -)	54	252	7
												10	PASSED	9000	VCC TO GND (+ -)	102	252	7
												10	PASSED	9000	GND TO VCC (+ -)	102	252	7
54HC00	NSC	2	Digital, Gate	HMOS														
					397	N/R	SS	1500 Ohms	100E-12 F	5	N/R	10	FAILED	3100	INPUT TO GND (+ -)	54	252	7
												10	FAILED	5300	OUTPUT TO GND (+ -)	54	252	7
												10	FAILED	2500	INPUT TO OUTPUT (+ -)	54	252	7
												10	PASSED	9000	VCC TO GND (+ -)	102	252	7
												10	PASSED	9000	GND TO VCC (+ -)	102	252	7
54HC00	TEX	2	Digital, Gate	HMOS														
					397	N/R	SS	1500 Ohms	100E-12 F	5	N/R	10	PASSED	9000	INPUT TO GND (+ -)	102	252	7
												10	FAILED	5800	OUTPUT TO GND (+ -)	54	252	7
												10	FAILED	2500	INPUT TO OUTPUT (+ -)	54	252	7
												10	PASSED	9000	VCC TO GND (+ -)	102	252	7
												10	PASSED	9000	GND TO VCC (+ -)	102	252	7
54HC04	TEX	1	Digital, Inverter, Buffer	HMOS														
					436	1186	SS	1500 Ohms	100E-12 F	12	8648	2	FAILED	1600	OUTPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54HC14	NSC	1	Digital, Inverter, Buffer	HMOS														
					436	1186	SS	1500 Ohms	100E-12 F	9	8627	1	FAILED	1000	INPUT TO OUTPUT	5	252	3
54HC161	TEX	1	Digital, Counter/Divider	HMOS														
					436	1186	SS	1500 Ohms	100E-12 F	2	8535	2	FAILED	300	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	8535	1	FAILED	2500	INPUT TO OUTPUT	5	252	3
54HC390	MOT	1	Digital, Counter/Divider	HMOS														
					436	1186	SS	1500 Ohms	100E-12 F	10	8703	1	FAILED	1200	INPUT TO GND	5	252	3
54HC42	MOT	1	Digital, Decoder	HMOS														
					436	0588	SS	1500 Ohms	100E-12 F	12	N/R	2	FAILED	1500	INPUT TO COMMON	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	9	N/R	2	FAILED	1000	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	2	FAILED	1000	INPUT TO GND	5	252	3
54L03	NSC	1	Digital, Gate	LTTL														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	2	FAILED	1400	INPUT TO GND	5	252	3
54L04	N/R	2	Digital, Inverter, Buffer	LTTL														
					361	N/R	GN	1500 Ohms	100E-12 F	200	N/R	11	PASSED	2000	GND.(1)(+) IN.(7)(-)	78	252	13
					362	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	2250	GND.(1)(+) IN.(7)(-)	78	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54L04	N/R	2	Digital, Inverter, Buffer	LTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
363	N/R	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2500	GND.(1)(+) IN.(7)(-)	78	252	13
363	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	2500	GND.(1)(+) IN.(7)(-)	78	252	13
364	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	29	77	13
364	N/R	GN	1500 Ohms	100E-12 F	3	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	29	77	13
364	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	42	76	13
364	N/R	GN	1500 Ohms	100E-12 F	8	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	42	76	13
364	N/R	GN	1500 Ohms	100E-12 F	50	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	42	76	13
364	N/R	GN	1500 Ohms	100E-12 F	75	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	29	77	13
364	N/R	GN	1500 Ohms	100E-12 F	125	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	42	76	13
364	N/R	GN	1500 Ohms	100E-12 F	175	N/R	1	FAILED	2750	GND.(1)(+) IN.(7)(-)	42	76	13
							1	PASSED	2750	GND.(1)(+) IN.(7)(-	78	252	13
364	N/R	GN	1500 Ohms	100E-12 F	200	N/R	11	PASSED	2750	GND.(1)(+) IN.(7)(-)	78	252	13
365	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	3000	GND.(1)(+) IN.(7)(-)	78	252	13
365	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	3000	GND.(1)(+) IN.(7)(-)	42	76	13
366	N/R	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	3250	GND.(1)(+) IN.(7)(-)	42	76	13
367	N/R	GN	1500 Ohms	100E-12 F	1	N/R	4	FAILED	3500	GND.(1)(+) IN.(7)(-)	78	252	13
							2	FAILED	3500	GND.(1)(+) IN.(7)(-)	29	77	13
							6	FAILED	3500	GND.(1)(+) IN.(7)(-)	42	76	13
367	N/R	GN	1500 Ohms	100E-12 F	4	N/R	2	FAILED	3500	GND.(1)(+) IN.(7)(-)	42	76	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54L04	N/R	2	Digital, Inverter, Buffer	LTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
367	N/R	GN	1500 Ohms	100E-12 F	8	N/R	1	FAILED	3500	GND.(1)(+) IN.(7)(-)	42	76	13
367	N/R	GN	1500 Ohms	100E-12 F	25	N/R	1	FAILED	3500	GND.(1)(+) IN.(7)(-)	78	252	13
367	N/R	GN	1500 Ohms	100E-12 F	200	N/R	8	PASSED	3500	GND.(1)(+) IN.(7)(-)	78	252	13
368	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	4000	GND.(1)(+) IN.(7)(-)	78	252	13
							4	FAILED	4000	GND.(1)(+) IN.(7)(-)	29	77	13
							7	FAILED	4000	GND.(1)(+) IN.(7)(-)	42	76	13
368	N/R	GN	1500 Ohms	100E-12 F	50	N/R	1	FAILED	4000	GND.(1)(+) IN.(7)(-)	78	252	13
368	N/R	GN	1500 Ohms	100E-12 F	1	N/R	8	PASSED	4000	GND.(1)(+) IN.(7)(-)	78	252	13
369	N/R	GN	1500 Ohms	100E-12 F	1	N/R	10	FAILED	4250	GND.(1)(+) IN.(7)(-)	42	76	13
							2	FAILED	4250	GND.(1)(+) IN.(7)(-)	78	252	13
							5	FAILED	4250	GND.(1)(+) IN.(7)(-)	29	77	13
369	N/R	GN	1500 Ohms	100E-12 F	8	N/R	1	FAILED	4250	GND.(1)(+) IN.(7)(-)	29	77	13
369	N/R	GN	1500 Ohms	100E-12 F	200	N/R	3	PASSED	4250	GND.(1)(+) IN.(7)(-)	78	252	13
370	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	4500	GND.(1)(+) IN.(7)(-)	29	77	13
							7	FAILED	4500	GND.(1)(+) IN.(7)(-)	78	252	13
							8	FAILED	4500	GND.(1)(+) IN.(7)(-)	42	76	13
							3	PASSED	4500	GND.(1)(+) IN.(7)(-)	78	252	13
371	N/R	GN	1500 Ohms	100E-12 F	1	N/R	7	FAILED	5000	GND.(1)(+) IN.(7)(-)	42	76	13
							5	FAILED	5000	GND.(1)(+) IN.(7)(-)	78	252	13
							4	FAILED	5000	GND.(1)(+) IN.(7)(-)	29	77	13
371	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	5000	GND.(1)(+) IN.(7)(-)	78	252	13
371	N/R	GN	1500 Ohms	100E-12 F	6	N/R	1	FAILED	5000	GND.(1)(+) IN.(7)(-)	42	76	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54L04	N/R	2	Digital, Inverter, Buffer	LTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
371	N/R	GN	1500 Ohms	100E-12 F	7	N/R	1	FAILED	5000	GND.(1)(+) IN.(7)(-)	42	76	13
371	N/R	GN	1500 Ohms	100E-12 F	175	N/R	1	FAILED	5000	GND.(1)(+) IN.(7)(-)	42	76	13
371	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	FAILED	5000	GND.(1)(+) IN.(7)(-)	78	252	13
							4	PASSED	5000	GND.(1)(+) IN.(7)(-)	78	252	13
372	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	FAILED	5500	GND.(1)(+) IN.(7)(-)	78	252	13
373	N/R	GN	1500 Ohms	100E-12 F	1	N/R	3	FAILED	5750	GND.(1)(+) IN.(7)(-)	42	76	13
							3	FAILED	5750	GND.(1)(+) IN.(7)(-)	29	77	13
							4	FAILED	5750	GND.(1)(+) IN.(7)(-)	78	252	13
374	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	GND.(1)(+) IN.(7)(-)	78	252	13
374	N/R	GN	1500 Ohms	100E-12 F	25	N/R	1	FAILED	6000	GND.(1)(+) IN.(7)(-)	78	252	13
375	N/R	GN	1500 Ohms	100E-12 F	20	N/R	1	FAILED	6500	GND.(1)(+) IN.(7)(-)	78	252	13
375	N/R	GN	1500 Ohms	100E-12 F	25	N/R	1	FAILED	6500	GND.(1)(+) IN.(7)(-)	78	252	13
376	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7000	GND.(1)(+) IN.(7)(-)	78	252	13
376	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	7000	GND.(1)(+) IN.(7)(-)	78	252	13
376	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	7000	GND.(1)(+) IN.(7)(-)	78	252	13
377	N/R	GN	1500 Ohms	100E-12 F	50	N/R	1	FAILED	7200	GND.(1)(+) IN.(7)(-)	78	252	13
378	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7500	GND.(1)(+) IN.(7)(-)	78	252	13
379	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	8000	GND.(1)(+) IN.(7)(-)	78	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54L74	N/R	3	Digital, Flip-Flop	LTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	77	INPUT(+) GND(-)	47	186	21

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS00	NSC	1	Digital, Gate	LSTTL	383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	8132	IN.(+) APTT(-)	49	188	8
												1	FAILED	771	VCC(+) APTT(-)	49	188	8
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	1	FAILED	366	INPUT(1)(+) GND(7)(-)	6	285	13
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
54LS00	SIG	2	Digital, Gate	LSTTL	026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	513	INPUT(1)(+) GND(7)(-)	6	285	13
54LS00	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	85	INPUT(+) GND(-)	47	186	21
												15	FAILED	83	INPUT(+) GND(-)	47	186	21
												15	FAILED	80	INPUT(+) GND(-)	47	186	21
												15	FAILED	80	INPUT(+) GND(-)	47	186	21
54LS02	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS02	FSC	1	Digital, Gate	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
54LS03	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS04	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS04	FSC	1	Digital, Inverter, Buffer	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3
54LS04	NSC	1	Digital, Inverter, Buffer	LSTTL														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1263	OUT.(+) APTT(-)	49	188	8
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
54LS04	TEX	1	Digital, Inverter, Buffer	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO OUTPUT	5	252	3
54LS05	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	900	EACH PIN(+)	12	99	24
												1	FAILED	800	EACH PIN(+)	9	104	24
												1	FAILED	900	EACH PIN(+)	11	106	24
54LS08	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS08	SIG	1	Digital, Gate	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS09	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS10	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS10	NSC	1	Digital, Gate	LSTTL	435	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
54LS107	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS109	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS11	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS112	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS12	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS123	N/R	1	Digital, Multivibrator	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS123	MOT	1	Digital, Multivibrator	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	5	FAILED	900	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	5	FAILED	400	INPUT TO OUTPUT	5	252	3
54LS123	TEX	1	Digital, Multivibrator	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO GND	5	252	3
54LS125	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS125	MOT	1	Digital, Inverter, Buffer	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND	5	252	3
54LS126	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology											
					Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS138	N/R	1	Digital, Decoder	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS138	FSC	1	Digital, Decoder	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3
54LS139	N/R	1	Digital, Decoder	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS14	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS14	SIG	1	Digital, Inverter, Buffer	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO GND	5	252	3
												5	FAILED	1000	INPUT TO COMMON	5	252	3
54LS148	N/R	1	Digital, Encoder	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS15	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS151	MOT	1	Digital, Multiplexer	LSTTL														
					129	0381	SS	1000 Ohms	200E-12 F	5	N/R	1	FAILED	1117	INPUTS(+) GROUND(-)	109	143	13

Part Number (Cont'd)	Part Mtr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
54LS151	MOT	1	Digital, Multiplexer												LSTTL			
				128	0381	SS	1000 Ohms	200E-12 F	5	N/R	1	FAILED	1133	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	1142	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	973	INPUTS(+) GROUND(-)		109	142	13
											1	FAILED	1045	INPUTS(+) GROUND(-)		109	142	13
54LS151	NSC	1	Digital, Multiplexer												LSTTL			
				128	0381	SS	1000 Ohms	200E-12 F	5	N/R	1	FAILED	1127	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	1033	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	950	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	1042	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	1075	INPUTS(+) GROUND(-)		109	143	13
											1	FAILED	700	INPUT(15)(+) GROUND(-)		109	252	13
											3	FAILED	1000	INPUT(15)(+) GROUND(-)		109	252	13
											1	FAILED	1100	INPUT(15)(GROUND(-)		109	252	13
54LS151	N/R	1	Digital, Multiplexer												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13
54LS153	N/R	1	Digital, Multiplexer												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13
				245	N/P	SS	100 Ohms	N/R	1	N/R	15	FAILED	95	INPUT(+) GND(-)		47	186	21
54LS153	SIG	2	Digital, Multiplexer												LSTTL			
				123	0381	SS	1000 Ohms	200E-12 F	5	N/R	5	PASSED	1500	INPUTS(+) GROUND(-)		109	286	13

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Part Number	Mfr	Part ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS154	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS155	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS157	AMD	2	Digital, Multiplexer	LSTTL	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	433	INPUT(15)(+) GND(8)(-)	50	285	13
54LS157	NSC	1	Digital, Multiplexer	LSTTL	436	0488	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	200	INPUT TO OUTPUT	5	252	3
54LS157	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS160	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS161	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS161	SIG	1	Digital, Counter/Divider	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS161A	MOT	1	Digital, Counter/Divider	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	6	8612	1	FAILED	700	INPUT TO GND	5	252	3
54LS162	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS163	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS164	TEX	2	Digital, Register, Shift	LSTTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54LS164	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS164	SIG	1	Digital, Register, Shift	LSTTL	026	0281	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	228	INPUT(1)(+) OUT(7)(-)	35	285	13
54LS165	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS166	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS166	TEX	1	Digital, Register, Shift	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO GND	5	252	3
54LS166	MOT	1	Digital, Register, Shift	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	200	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	INPUT TO OUTPUT	5	252	3
54LS173	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS174	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS175	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS175	SIG	1	Digital, Flip-Flop	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND	5	252	3
54LS175	FSC	1	Digital, Flip-Flop	LSTTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO GND	5	252	3
54LS181	N/R	1	Digital, Arithmetic, Logic Unit	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS192	N/R	1	Digital, Counter/Divider	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	59	INPUT(+) GND(-)	47	186	21
54LS193	N/R	1	Digital, Counter/Divider	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS194	N/R	1	Digital, Register, Shift	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS196	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS197	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS20	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS20	SIG	1	Digital, Gate	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO INPUT	5	252	3
54LS21	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS221	N/R	1	Digital, Multivibrator	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS240	N/R	1	Digital, Line/Bus Driver	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS244	N/R	1	Digital, Line/Bus Driver	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mf.	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS244	TEX	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO GND	5	252	3
54LS244	SIG	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
54LS245	N/R	1	Digital, Transceiver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS245	TEX	1	Digital, Transceiver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	700	INPUT TO OUTPUT	5	252	3
54LS251	N/R	1	Digital, Multiplexer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS253	N/R	1	Digital, Multiplexer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS253	FSC	1	Digital, Multiplexer	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54LS253	MOT	1	Digital, Multiplexer	LSTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
54LS253	NSC	1	Digital, Multiplexer	LSTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO OUTPUT	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology
54LS257	N/R	1	Digital, Multiplexer	LSTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54LS259	N/R	1	Digital, Latch	LSTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54LS26	MOT	1	Digital, Line/Bus Driver	LSTTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	7	8534	1	FAILED	800	INPUT TO GND	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS266	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS27	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS279	N/R	1	Digital, Latch	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS280	N/R	1	Digital, Error Detect/Correct, Parity/Carry Gen	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS283	N/R	1	Digital, Arithmetic, Adder, Full	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS295	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS298	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS299	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS299	TEX	1	Digital, Register, Shift	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	2	FAILED	500	INPUT TO OUTPUT	5	252	3
54LS30	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS32	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS32	FSC	1	Digital, Gate	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	700	INPUT	5	252	3
54LS353	N/R	1	Digital, Multiplexer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS365	NSC	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	18	8426	1	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	8426	1	FAILED	800	INPUT TO OUTPUT	5	252	3
												5	FAILED	800	INPUT TO OUTPUT	5	252	3
54LS365A	NSC	2	Digital Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	N/R	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS367	N/R	1	Digital, Line/Bus Driver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS368	N/R	1	Digital, Line/Bus Driver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS37	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS37	SIG	1	Digital, Inverter, Buffer	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
54LS373	N/R	1	Digital, Latch	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS373	TEX	1	Digital, Latch	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO GND	5	252	3
54LS374	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS374	MOT	3	Digital, Flip-Flop	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
54LS38	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS390	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS390	TEX	1	Digital, Counter/Divider	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	INPUT TO GND	5	252	3
54LS393	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS393	MOT	1	Digital, Counter/Divider	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO OUTPUT	5	252	3
54LS393	TEX	1	Digital, Counter/Divider	LSTTL	436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO OUTPUT	5	252	3
54LS40	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS40	NSC	1	Digital, Inverter, Buffer	LSTTL														
					436	0588	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO OUTPUT	5	252	3
												5	FAILED	1000	INPUT TO COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	5	FAILED	1400	INPUT TO GND	5	252	3
54LS42	N/R	1	Digital, Decoder	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS51	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS54	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS670	N/R	1	Digital, Register, File	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS688	TEX	1	Linear, Comparator	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	9624	2	FAILED	600	INPUT TO OUTPUT	5	252	3
54LS697	TEX	1	Digital, Counter/Divider	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	2	FAILED	800	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
54LS73	SIG	1	Digital, Flip-Flop												LSTTL			
				436	1186	SS	1500 Ohms	100E-12 F	15	8519	5	FAILED	2500	INPUT TO GND		5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	10	8519	5	FAILED	1200	INPUT TO GND		5	252	3
54LS74	NSC	1	Digital, Flip-Flop												LSTTL			
				383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	133	IN.(+) APTT(-)		49	188	3
											1	FAILED	280	OUT.(+) APTT(-)		49	188	3
											1	FAILED	483	VCC(+) APTT(-)		49	188	8
54LS74	FSC	1	Digital, Flip-Flop												LSTTL			
				436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO OUTPUT		5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	INPUT TO GND		5	252	3
54LS74	SIG	2	Digital, Flip-Flop												LSTTL			
				436	1186	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	2500	INPUT TO GND		5	252	3
54LS74	N/R	1	Digital, Flip-Flop												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13
54LS74A	SIG	2	Digital, Flip-Flop												LSTTL			
				436	1186	SS	1500 Ohms	100E-12 F	15	N/R	5	FAILED	2500	INPUT TO GND		5	252	3
54LS75	N/R	1	Digital, Latch												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS76	MOT	1	Digital, Flip-Flop	LSTTL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1250	EACH PIN TO 5 & 13 (+ -)	19	252	13
54LS85	N/R	1	Linear, Comparator	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS85	MOT	1	Linear, Comparator	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	VCC TO GND	5	252	3
54LS86	TEX	2	Digital, Gate	LSTTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54LS86	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS90	NSC	1	Digital, Counter/Divider	LSTTL														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2692	IN.(-) APTT(+)	49	188	8
												1	FAILED	618	OUT.(-) APTT(+)	49	188	8
												1	FAILED	459716	VCC(-) APTT(-)	49	188	8
54LS90	MOT	1	Digital, Counter/Divider	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	700	INPUT TO GND	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54LS92	N/R	1	Digital, Counter/Divider	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
54LS92	TEX	1	Digital, Counter/Divider	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	INPUT TO GND	5	252	3
54LS93	MOT	1	Digital, Counter/Divider	LSTTL														
					435	1186	SS	1500 Ohms	100E-12 F	3	8535	1	FAILED	400	INPUT TO GND	5	252	3
54S00	TEX	2	Digital, Gate	STTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54S00	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	36	INPUT(+) GND(-)	47	186	21
54S00	SIG	1	Digital, Gate	STTL														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	228	INPUT(1)(+) GND(7)(-)	6	285	13
54S02	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54S03	N/R	1	Digital, Gate	STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54S04	TEX	1	Digital, Inverter, Buffer	STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
238	N/R	GN	1500 Ohms	200E-12 F	200	N/R	1	PASSED	600	VCC(14)(+) IN.(1)(-)	84	252	13
297	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	800	VCC(14)(+) IN.(1)(-)	84	252	13
298	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	PASSED	800	VCC(14)(+) IN.(1)(-)	84	252	13
314	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	900	VCC(14)(+) IN.(1)(-)	84	252	13
319	N/R	GN	1500 Ohms	100E-12 F	200	N/R	1	PASSED	975	VCC(14)(+) IN.(1)(-)	84	252	13
320	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	VCC(14)(+) IN.(1)(-)	77	252	13
320	N/R	GN	1500 Ohms	100E-12 F	200	N/R	2	PASSED	1000	VCC(14)(+) IN.(1)(-)	84	252	13
320	N/R	GN	1500 Ohms	100E-12 F	1	N/R	4	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	2	N/R	3	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	500	N/R	1	PASSED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	2	N/R	2	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
320	N/R	GN	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1000	VCC(14)(+) IN.(1)(-)	121	252	13
321	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	VCC(14)(+) IN.(1)(-)	77	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54S04	TEX	1	Digital, Inverter, Buffer	STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
322	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	1100	VCC(14)(+) IN.(1)(-)	77	252	13
							2	FAILED	1100	VCC(14)(+) IN.(1)(-)	121	252	13
							1	FAILED	1100	VCC(14)(+) IN.(1)(-)	77	252	13
323	N/R	GN	1500 Ohms	100E-12 F	1	N/R	4	FAILED	1125	VCC(14)(+) IN.(1)(-)	121	252	13
323	N/R	GN	1500 Ohms	100E-12 F	2	N/R	2	FAILED	1125	VCC(14)(+) IN.(1)(-)	121	252	13
							2	FAILED	1125	VCC(14)(-) IN.(1)(-)	77	252	13
323	N/R	GN	1500 Ohms	100E-12 F	3	N/R	1	FAILED	1125	VCC(14)(+) IN.(1)(-)	121	252	13
323	N/R	GN	1500 Ohms	100E-12 F	40	N/R	1	FAILED	1125	VCC(14)(+) IN.(1)(-)	121	252	13
324	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1150	VCC(14)(+) IN.(1)(-)	121	252	13
325	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1200	VCC(14)(+) IN.(1)(-)	121	252	13
							4	FAILED	1200	VCC(14)(+) IN.(1)(-)	121	252	13
							6	PASSED	1200	VCC(14)(+) IN.(1)(-)	84	252	13
325	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	1200	VCC(14)(+) IN.(1)(-)	121	252	13
325	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	PASSED	1200	VCC(14)(+) IN.(1)(-)	84	252	13
							2	FAILED	1200	VCC(14)(+) IN.(1)(-)	121	252	13
326	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1250	VCC(14)(+) IN.(1)(-)	77	252	13
							5	FAILED	1250	VCC(14)(+) IN.(1)(-)	121	252	13
							2	FAILED	1250	VCC(14)(+) IN.(1)(-)	77	252	13
326	N/R	GN	1500 Ohms	100E-12 F	2	N/R	2	FAILED	1250	VCC(14)(+) IN.(1)(-)	121	252	13
326	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1250	VCC(14)(+) IN.(1)(-)	77	252	13
327	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1300	VCC(14)(+) IN.(1)(-)	84	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
54S04	TEX	1	Digital, Inverter, Buffer	STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
328	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1350	VCC(14)(+) IN.(1)(-)	121	252	13
							1	FAILED	1350	VCC(14)(+) IN.(1)(-)	77	252	13
329	N/R	GN	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1375	VCC(14)(+) IN.(1)(-)	121	252	13
329	N/R	GN	1500 Ohms	100E-12 F	2	N/R	2	FAILED	1375	VCC(14)(+) IN.(1)(-)	121	252	13
329	N/R	GN	1500 Ohms	100E-12 F	3	N/R	2	FAILED	1375	VCC(14)(+) IN.(1)(-)	121	252	13
329	N/R	GN	1500 Ohms	100E-12 F	4	N/R	1	FAILED	1375	VCC(14)(+) IN.(1)(-)	77	252	13
329	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1375	VCC(14)(+) IN.(1)(-)	121	252	13
							4	FAILED	1375	VCC(14)(+) IN.(1)(-)	77	252	13
							2	PASSED	1375	VCC(14)(+) IN.(1)(-)	84	252	13
330	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1500	VCC(14)(+) IN.(1)(-)	84	252	13
							7	FAILED	1500	VCC(14)(+) IN.(1)(-)	121	252	13
330	N/R	GN	1500 Ohms	100E-12 F	2	N/R	1	FAILED	1500	VCC(14)(+) IN.(1)(-)	121	252	13
330	N/R	GN	1500 Ohms	100E-12 F	3	N/R	1	FAILED	1500	VCC(14)(+) IN.(1)(-)	121	252	13
							1	FAILED	1500	VCC(14)(+) IN.(1)(-)	77	252	13
331	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	1500	VCC(14)(+) IN.(1)(-)	77	252	13
346	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	VCC(14)(+) IN.(1)(-)	77	252	13
347	N/R	GN	1500 Ohms	200E-12 F	1	N/R	1	FAILED	2000	VCC(14)(+) IN.(1)(-)	77	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
54S04	FSC	2	Digital, Inverter, Buffer	STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S04	N/R	1	Digital, Inverter, Buffer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S05	N/R	1	Digital, Inverter, Buffer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S08	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S10	TEX	2	Digital, Gate	STTL														
					004	1175	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	600	INPUT	102	231	13
												1	FAILED	1700	INPUT	102	235	13
												1	FAILED	2200	INPUT	102	234	13
54S10	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S11	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S112	N/R	1	Digital, Flip-Flop	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S133	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S135	N/R	1	Digital, Error Detect/Correct, Parity/Carry Gen	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S138	N/R	1	Digital, Decoder	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	40	INPUT(+) GND(-)	47	186	21
54S140	N/R	1	Digital, Line/Bus Driver	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S151	N/R	1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S153	FSC	2	Digital, Multiplexer	STTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54S153	N/R	1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S157	SIG	1	Digital, Multiplexer	STTL														
					128	0381	SS	1000 Ohms	200E-12 F	5	N/R	2	FAILED	1100	INPUTS(+) GROUND(-)	109	144	13
												1	FAILED	888	INPUTS(+) GROUND(-)	109	144	13
												1	FAILED	1138	INPUTS(+) GROUND(-)	109	144	13
												1	FAILED	988	INPUTS(+) GROUND(-)	109	144	13
54S157	N/R	1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S160	N/R	1	Digital, Counter/Divider	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S161	N/R	1	Digital, Counter/Divider	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S169	TEX	1	Digital, Counter/Divider	STTL														
					592	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	850	EACH PIN TO 8 & 16 (+ -)	19	252	13
54S174	AMD	2	Digital, Flip-Flop	STTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54S174	TEX	2	Digital, Flip-Flop	STTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S174	N/R	1	Digital, Flip-Flop	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S175	N/R	1	Digital, Flip-Flop	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S181	TEX	1	Digital, Arithmetic, Logic Unit	STTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1106	N/R	102	189	13
54S181	N/R	1	Digital, Arithmetic, Logic Unit	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S182	TEX	2	Digital, Arithmetic, Carry Generator	STTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
54S189	N/R	1	Digital, Memory, RAM, Static	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S20	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S200	N/R	1	Digital, Memory, RAM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number	Part Mtr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S22	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S251	N/R	1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S257		1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S258	N/R	1	Digital, Multiplexer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S280	TEX	1	Digital, Gate	STTL														
					436	0688	SS	1500 Ohms	100E-12 F	4	N/R	4	FAILED	500	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO GND	5	252	3
54S287	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S288	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)		Part Mfr	Part ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S283		NSC	1	Digital, Memory, PROM								STTL		
	436	1186	SS	1500 Ohms	100E-12 F	4	N/R	2	FAILED	500	INPUT TO OUTPUT	5	252	3
54S30		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S32		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S32		TEX	1	Digital, Gate								STTL		
	436	1186	SS	1500 Ohms	100E-12 F	3	N/R	2	FAILED	400	INPUT TO OUTPUT	5	252	3
54S471		N/R	1	Digital, Memory, PROM								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S472		N/R	1	Digital, Memory, PROM								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S51		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S573		N/R	1	Digital, Memory, PROM								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
54S64	NSC	1	Digital, Gate	STTL														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	850	EACH PIN TO 7 & 14 (+ -)	19	252	13
54S734	MON	1	Digital, Memory, RAM, Dynamic	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO GND	5	252	3
54S74	N/R	1	Digital, Flip-Flop	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S85	N/R	1	Digital, Arithmetic, Magnitude Comparator	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
54S86	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
55107	N/R	3	Digital, Line/Bus Receiver	Bipolar														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	41	INPUT(+) INPUT(-)	47	186	21
55109	N/R	3	Digital, Line/Bus Driver	Bipolar														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	84	INPUT(+) GND(-)	47	186	21

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
55113	TEX	2	Digital, Line/Bus Driver	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
55114	TEX	3	Digital, Line/Bus Driver	Bipolar														
					390	N/R	CN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
55114	FSC	1	Digital, Line/Bus Driver	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO OUTPUT	5	252	3
55326	TEX	2	Digital, Line/Bus Driver	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
55327	TEX	2	Digital, Line/Bus Driver	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
55454	TEX	1	Digital, Line/Bus Driver	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO GND	5	252	3
55461	N/R	2	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
55462	N/R	2	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
55463	N/R	2	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
55464	N/R	2	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
												1	FAILED	3000	N/R	103	252	13
555	SIG	1	Linear	Bipolar														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	296	N/R	6	285	13
555	N/R	1	Linear	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1700	N/R	103	252	13
												1	FAILED	1700	N/R	103	252	13
556	N/R	1	Linear	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1700	N/R	103	252	13
5710	SIG	3	Linear, Comparator	IIL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6910	N/R	102	188	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
573	VAR	2	Digital, Latch	Bipolar														
					424	0983	SS	1500 Ohms	100E-12 F	8	N/R	3	FAILED	1000	PINS 4,5,6, AND 7	46	149	13
					424	0983	SS	1500 Ohms	100E-12 F	7	N/R	12	FAILED	1000	PINS 4,5,6, AND 7	46	149	13
					423	0983	SS	0 Ohms	0 F	8	N/R	3	FAILED	1000	N/R	111	252	4
					423	0983	SS	0 Ohms	0 F	10	N/R	2	FAILED	1250	N/R	111	252	4
					423	0983	SS	0 Ohms	0 F	12	N/R	10	FAILED	1500	N/R	111	252	4
5845	MOT	1	Linear, Voltage Reference	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO GND	5	252	3
6116	IDT	1	Digital, Memory, RAM, Static	CMOS														
					436	0588	SS	1500 Ohms	100E-12 F	5	8746	1	FAILED	600	INPUT TO OUTPUT	5	252	3
												1	FAILED	600	INPUT TO COMMON	5	252	3
												1	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	10	8746	1	FAILED	1200	INPUT TO COMMON	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	11	8746	1	FAILED	1400	INPUT TO COMMON	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	12	8746	1	FAILED	1500	INPUT TO COMMON	5	252	3
6116590	IDT	1	Digital, Memory, RAM, Static	CMOS														
					393	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	750	N/R	102	252	13
63983	NSC	1	Digital, Memory, RAM	CMOS														
					393	0383	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
6504	VAR	2	Digital, Memory, RAM, Static	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
424	0983	SS	1500 Ohms	100E-12 F	2	N/R	4	FAILED	250	PIN 13	46	149	13
424	0983	SS	1500 Ohms	100E-12 F	1	N/R	4	FAILED	250	PIN 13	46	149	13
424	0983	SS	1500 Ohms	100E-12 F	4	N/R	7	FAILED	500	PIN 13	46	149	13
423	0983	SS	0 Ohms	0 F	6	N/R	5	FAILED	750	PINS 1-3, AND 15-17	46	252	4
423	0983	SS	0 Ohms	0 F	5	N/R	4	FAILED	43000	PINS 1-3 AND 15-17	46	252	4
423	0983	SS	0 Ohms	0 F	7	N/R	6	FAILED	43000	PINS 1-3 AND 15-17	46	252	4

Part Number	Part Mfr	ESD Class	Part Description	Technology
6514	NSC	2	Digital, Memory, RAM, Static	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
055	0681	GN	1000 Ohms	200E-12 F	5	N/R	2	PASSED	250	LID TO ALL PINS	57	60	13
056	0681	GN	1000 Ohms	200E-12 F	5	N/R	2	PASSED	500	LID TO ALL PINS	57	60	13
057	0681	GN	1000 Ohms	200E-12 F	5	N/R	2	PASSED	1000	LID TO ALL PINS	57	60	13
058	0681	GN	1000 Ohms	200E-12 F	5	N/R	2	FAILED	2000	LID TO ALL PINS	57	60	13
059	0681	GN	1000 Ohms	200E-12 F	5	N/R	2	FAILED	4000	LID TO ALL PINS	57	60	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
6514	MON	1	Digital, Memory, RAM, Static	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
002	0679	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	48	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
6514	RCA	1	Digital, Memory, RAM, Static	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
002	0679	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1400	N/R	48	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
6518	N/R	1	Digital, Memory, RAM, Static	CMOS	028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	750	N/R	93	252	13
6561	HAR	1	Digital, Memory, RAM	CMOS	393	0881	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	102	252	13
6654	ISL	1	Digital, Memory, PROM	CMOS	393	1182	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	102	252	13
6800	N/R	1	Digital, Processing Unit, Central	NMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
68000	VAR	3	Digital, Processing Unit, Central	HMOS	424	1283	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	250	PINS 17 AND 18	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	4	N/R	5	FAILED	500	PINS 17 AND 18	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	3	N/R	5	FAILED	500	PINS 17 AND 18	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	750	PINS 17 AND 18	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	5	N/R	3	FAILED	750	PINS 17 AND 18	100	149	13
					423	1283	SS	0 Ohms	0 F	9	N/R	2	FAILED	1250	PINS 10 AND 12	100	252	4

Part Number (Cont'd)		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
68000		VAR	3	Digital, Processing Unit, Central								HMOS		
	423	1283	SS	0 Ohms	0 F	17	N/R	3	FAILED	2250	PINS 10 AND 12	100	252	4
	423	1283	SS	0 Ohms	0 F	19	N/R	1	FAILED	2500	PINS 10 AND 12	100	252	4
	423	1283	SS	0 Ohms	0 F	22	N/R	5	FAILED	2750	PINS 10 AND 12	100	252	4
	423	1283	SS	0 Ohms	0 F	21	N/R	3	FAILED	2750	PINS 10 AND 12	100	252	4
	423	1283	SS	0 Ohms	0 F	24	N/R	1	FAILED	3000	PINS 10 AND 12	100	252	4
68000		TRW	1	Digital, Processing Unit, Central								HMOS		
	436	1186	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	2500	INPUT TO GND	5	252	3
	436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1500	INPUT TO GND	5	252	3
	436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
6802		N/R	1	Digital, Processing Unit, Central								NMOS		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
6821		N/R	1	Digital, Processing Unit, Central								NMOS		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
								1	FAILED	1000	N/R	103	252	13
6828		N/R	1	Digital, Processing Unit, Central								NMOS		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
6844	N/R	1	*Digital, Processing Unit, Central*	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
6845	N/R	1	Digital, Processing Unit, Central	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
6850	N/R	1	Digital, Processing Unit, Central	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
6875	N/R	1	Digital, Processing Unit, Central	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
7040	NIT	2	Digital, Memory, EAROM	MNOS														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2308	D04(10)(+) APTT(-)	49	188	8
												1	FAILED	128398	A0(-) APTT(+)	49	188	8
												1	FAILED	27769	VSS(-) APTT(+)	49	188	8
709	FSC	1	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1984	N/R	102	189	13
												1	FAILED	1565	N/R	102	188	13
70C97	NSC	1	Digital, Inverter, Buffer	CMOS														
					393	0285	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	4(INPUT) 5(OUTPUT)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result						
710	FSC	1	Linear, Comparator															
				026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	[illegible]	[illegible]				
715	FSC	3	Linear, Operational Amplifier												Bipolar			
				029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	15546	N/R		102	188	13
7220	INT	1	Digital, Memory, Bubble												MOS			
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1030	PINS 1,6,AND 7		13	252	13
723	FSC	1	Linear, Voltage Regulator												Bipolar			
				026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	273	V(-)(5)(+) VREF(4)(-)		10	285	13
				392	0986	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1500	PINS 2-6,9,11,13 TO 7,12(+-		19	252	13
723	N/R	1	Linear, Voltage Regulator												Bipolar			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R		103	252	13
											1	FAILED	1000	N/R		103	252	13
				245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	50	INPUT(+) INPUT( )		47	186	21
72709	TEX	N	Linear, Operational Amplifier												[illegible]			
				029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	53665	N/R		[illegible]	[illegible]	13
733	N/R	1	Digital, Multivibrator												Bipolar			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
733	N/R	1	Digital, Multivibrator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
740	FSC	3	Linear, Operational Amplifier	BIFET														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	14270	N/R	102	188	13
7400	FSC	1	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3234	N/R	102	188	13
					426	0986	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
7400	MOT	2	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2460	N/R	102	188	13
7400	TEX	3	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4401	N/R	102	188	13
7400	SIG	3	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	9032	N/R	102	188	13
7400	N/R	1	Digital, Gate	TTL														
					028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	1500	N/R	87	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7402	TEX	3	Digital, Gate	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5485	N/R	102	188	13
7402	FSC	1	Digital, Gate	TTL														
					426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
7404	N/R	2	Digital, Inverter, Buffer	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7404	FSC	1	Digital, Inverter, Buffer	TTL														
					426	0686	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
7406	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7407	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
741	FSC	1	Linear, Operational Amplifier	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5958	N/R	102	188	13
					054	0181	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	EACH PIN	51	171	13

Part Number (Cont'd)	Mfr	Part ESD Class	Part Description	Technology
741	FSC	1	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	315	OFF NULL(5)(+) V(-)(4)	33	285	13
418	0880	SS	1500 Ohms	125E-12 F	1	N/R	100	FAILED	500	NON-INVERTING INPUT	22	252	13
418	0880	SS	1500 Ohms	125E-12 F	2	N/R	100	FAILED	750	INVERTING INPUT	22	252	13
418	0880	SS	1500 Ohms	125E-12 F	4	N/R	100	FAILED	1250	POSITIVE NULL	22	252	13
							100	FAILED	1250	NEGATIVE NULL	22	252	13
418	0880	SS	1500 Ohms	125E-12 F	5	N/R	100	FAILED	5000	NEGATIVE SUPPLY	22	252	13
							100	FAILED	5000	POSITIVE SUPPLY	22	252	13
							100	FAILED	5000	OUTPUT	22	252	13

Part Number (Cont'd)	Mfr	Part ESD Class	Part Description	Technology
741	TEX	1	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
054	0181	SS	1500 Ohms	100E 12 F	1	N/R	2	FAILED	1000	EACH PIN	51	171	13
							2	FAILED	2000	EACH PIN	51	171	13

Part Number (Cont'd)	Mfr	Part ESD Class	Part Description	Technology
741	MOT	1	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
054	0181	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	EACH PIN	51	171	13

Part Number (Cont'd)	Mfr	Part ESD Class	Part Description	Technology
741	N/R	2	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
							1	FAILED	2500	N/R	103	252	13
050	0780	GN	1500 Ohms	125E-12 F	1	N/R	15	FAILED	500	OFFSET(+) APTT(-)	26	252	13
419	0880	SS	1500 Ohms	125E-12 F	1	N/R	23	FAILED	1250	INVERTING INPUT	22	252	13

RAC ESD Database

Part Number (Cont'd)	Mfr	Class	Description	[illegible]
741	N/R	2	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
419	0880	SS	1500 Ohms	125E-12 F	2	N/R	2	FAILED	[illegible]	INVERTING INPUT	22	252	13
419	0880	SS	1500 Ohms	125E-12 F	1	N/R	4	FAILED		NON INVERTING INPUT	[illegible]	252	13
419	0880	SS	1500 Ohms	125E-12 F	[illegible]	N/R	4	FAILED		NON INVERTING INPUT	22	252	13
419	0880	SS	1500 Ohms	125E-12 F	5	N/R	11	FAILED	[illegible]	NON INVERTING INPUT	22	252	13
419	0880	SS	1500 Ohms	125E-12 F	4	N/R	6	FAILED	[illegible]	NON INVERTING INPUT	22	252	13
419	0880	SS	1500 Ohms	125E-12 F	1	N/R	6	FAILED	[illegible]	INVERTING INPUT	22	252	13
							19	FAILED	[illegible]	INVERTING INPUT	22	252	13

Part Number	Mfr	Class	Description	Technology
741	RAY	1	Linear, Operational Amplifier	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
054	0181	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2000	EACH PIN	51	171	13

Part Number	Mfr	Class	Description	Technology
7410	FSC	1	Digital, Gate	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
426	0786	SS	1500 Ohms	100E-12 F	30	8625	3	FAILED	2000	INPUT TO GND.	61	204	13

Part Number	Mfr	Class	Description	Technology
7411	FSC	1	Digital, Gate	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
426	0786	SS	1500 Ohms	100E-12 F	30	8613	3	FAILED	2000	INPUT TO GND.	61	204	13

Part Number	Mfr	Class	Description	Technology
74120	N/R	2	Digital, Line/Bus Driver	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
133	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

Part Number	Mfr	Class	Description	Technology
74123	N/R	2	Digital, Line/Bus Driver	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
133	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7413	TEX	3	Digital, Gate, NAND, Schmitt Trigger	TTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7441	N/R	102	188	13
74132	FSC	1	Digital, Multivibrator	TTL	426	0986	SS	1500 Ohms	100E-12 F	30	8613	3	FAILED	2000	INPUT TO GND.	61	204	13
7414	FSC	1	Digital, Multivibrator	TTL	426	0986	SS	1500 Ohms	100E-12 F	30	8633	3	FAILED	2000	INPUT TO GND.	61	204	13
74151	FSC	1	Digital, Multiplexer	TTL	426	0686	SS	1500 Ohms	100E-12 F	30	8552	3	FAILED	2000	INPUT TO GND.	61	204	13
74153	FSC	1	Digital, Multiplexer	TTL	426	0886	SS	1500 Ohms	100E-12 F	30	8624	3	FAILED	2000	INPUT TO GND.	61	204	13
74154	N/R	2	Digital, Decoder	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
74157	FSC	1	Digital, Multiplexer	TTL	426	0786	SS	1500 Ohms	100E-12 F	30	8621	3	FAILED	2000	INPUT TO GND.	61	204	13
74163	TEX	2	Digital, Counter/Divider	TTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3733	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74163	N/R	1	Digital, Counter/Divider	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
234	N/R	SS	0 Ohms	N/R	1	N/R	1	FAILED	300	IN.(6)(+) GND(8)(-)	108	215	13
							1	FAILED	500	IN.(6)(+) GND(8)(-)	108	252	13
							1	FAILED	300	IN.(6)(+) GND(8)(-)	108	216	13
235	N/R	SS	0 Ohms	120E-12 F	1	N/R	2	FAILED	200	IN.(6)(+) GND(8)(-)	108	214	13
							3	FAILED	200	IN.(6)(+) GND(8)(-)	108	252	13
236	N/R	SS	0 Ohms	510E-12 F	1	N/R	2	FAILED	100	IN.(6)(+) GND(8)(-)	108	213	13
							1	FAILED	200	IN(2,6,10)(+) GND(-)	108	252	13
							1	FAILED	200	IN.(2,6)(+) GND(8)(-)	108	212	13
							1	FAILED	300	IN.(2,6)(+) GND(8)(-)	108	252	13
237	N/R	SS	0 Ohms	.01E-07 F	1	N/R	2	FAILED	100	IN.(10)(+) GND(8)(-)	108	226	13
							1	FAILED	100	IN.(6,10)(+) GND(8)(-)	108	213	13
							1	FAILED	200	IN.(2,6)(+) GND(8)(-)	108	252	13
							1	FAILED	100	IN.(6)(+) GND(8)(-)	108	225	13
238	N/R	SS	0 Ohms	.01E-06 F	1	N/R	4	FAILED	100	IN(2,6,10)(+) GND(-)	108	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74164	FSC	1	Digital, Register, Shift	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
426	0686	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74173	N/R	1	Digital, Flip-Flop	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
234	N/R	SS	0 Ohms	N/R	1	N/R	3	PASSED	500	IN(7,11,15)(+) GND(-)	108	252	13
235	N/R	SS	0 Ohms	120E-12 F	1	N/R	3	PASSED	500	IN(7,11,15)(+) GND(-)	108	252	13
							1	FAILED	400	IN.(7)(+) GND(8)(-)	108	252	13
							1	FAILED	500	IN.(7)(+) GND(8)(-)	108	252	13
236	N/R	SS	0 Ohms	510E-12 F	1	N/R	4	FAILED	300	IN(7,11,15)(+) GND(-)	108	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74173	N/R	1	Digital, Flip-Flop	TTL														
					236	N/R	SS	0 Ohms	510E-12 F	1	N/R	1	FAILED	200	IN.(11)(+) GND(8)(-)	108	228	13
					237	N/R	SS	0 Ohms	.01E-07 F	1	N/R	1	FAILED	400	IN(7,11,15)(+) GND(-)	108	252	13
												2	FAILED	300	IN(7,11,15)(+) GND(-)	108	252	13
												2	FAILED	300	IN.(7)(+) GND(8)(-)	108	252	13
					238	N/R	SS	0 Ohms	.01E-06 F	1	N/R	1	FAILED	100	IN.(11,15)(+) GND(-)	108	217	13
												1	FAILED	100	IN.(11)(+) GND(8)(-)	108	252	13
												1	FAILED	100	IN.(7)(+) GND(8)(-)	108	224	13
												1	FAILED	200	IN.(7)(+) GND(8)(-)	108	252	13
74175	NSC	2	Digital, Flip-Flop	TTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	2	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
74175	TEX	2	Digital, Flip-Flop	TTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1500	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	1500	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
74175	FSC	1	Digital, Flip-Flop	TTL														
					426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74182	N/R	2	Digital, Arithmetic, Carry Generator	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology														
					Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74191	FSC	1	Digital, Counter/Divider	TTL														
					426	1086	SS	1500 Ohms	100E-12 F	30	8634	3	FAILED	2000	INPUT TO GND.	61	204	13
7420	FSC	1	Digital, Gate	TTL														
					426	0686	SS	1500 Ohms	100E-12 F	30	8613	3	FAILED	2000	INPUT TO GND.	61	204	13
7425	N/R	2	Digital, Gate	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7432	FSC	1	Digital, Gate	TTL														
					425	0786	SS	1500 Ohms	100E-12 F	30	8621	3	FAILED	2000	INPUT TO GND.	61	204	13
7437	N/R	2	Digital, Gate	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
					067	N/R	N/R	0 Ohms	N/R	1	N/R	1	FAILED	750	INPUT	102	252	9
					068	N/R	N/R	0 Ohms	100E-12 F	1	N/R	1	FAILED	475	INPUT	102	252	9
					069	N/R	N/R	0 Ohms	150E-12 F	1	N/R	1	FAILED	400	INPUT	102	252	9
					070	N/R	N/R	0 Ohms	200E-12 F	1	N/R	1	FAILED	300	INPUT	102	252	9
7438	N/R	2	Digital, Gate	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7440	FSC	1	Digital, Inverter, Buffer	TTL	426	0786	SS	1500 Ohms	100E-12 F	30	8606	3	FAILED	2000	INPUT TO GND.	61	204	13
7445	N/R	2	Digital, Decoder	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7446	N/R	2	Digital, Decoder	TTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
747	FSC	3	Linear, Operational Amplifier	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	13675	N/R	102	188	13
747	N/R	2	Linear, Operational Amplifier	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7474	FSC	1	Digital, Flip-Flop	TTL	426	0986	SS	1500 Ohms	100E-12 F	30	8626	3	FAILED	2000	INPUT TO GND.	61	204	13
747A	RAY	2	Linear, Operational Amplifier	Bipolar	392	0986	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2750	PINS 1,2 & 10,12 TO 4,9,13	19	145	13
7486	FSC	1	Digital, Gate	TTL	426	0886	SS	1500 Ohms	100E-12 F	30	8619	3	FAILED	2000	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology
7490	TEX	3	Digital, Counter/Divider	TTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4987	N/R	102	188	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74AC00	FSC	2	Digital, Gate	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	4000	INPUT TO OUTPUT	100	275	13
							3	FAILED	3500	INPUT TO OUTPUT	100	275	13
427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND.	100	275	13
							3	FAILED	5000	VCC TO GND.	100	275	13
426	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3500	VCC TO OUTPUT	100	275	13
							3	FAILED	3500	OUTPUT TO GND.	100	275	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74AC109	FSC	3	Digital, Flip-Flop	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND.	100	275	13
427	0587	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND.	100	275	13
426	0587	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4850	INPUT TO VCC	100	275	13
427	0587	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	4850	INPUT TO OUTPUT.	100	275	13
							3	FAILED	5000	VCC TO GND.	100	275	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74AC153	FSC	2	Digital, Multiplexer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4250	INPUT TO GND.	100	275	13
							3	FAILED	4950	OUTPUT TO GND.	100	275	13
427	1186	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3950	INPUT TO VCC	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74AC153	FSC	2	Digital, Multiplexer	CMOS														
					427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4450	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC163	FSC	2	Digital, Counter/Divider	CMOS														
					427	0387	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	4000	INPUT TO GND	100	275	13
					427	0387	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4800	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND.	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND.	100	275	13
74AC169	FSC	2	Digital, Counter/Divider	CMOS														
					427	0786	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3700	INPUT TO GND	100	275	13
					427	0786	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4800	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4800	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC191	FSC	3	Digital, Counter/Divider	CMOS														
					427	0287	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4800	INPUT TO VCC	100	275	13
												3	FAILED	4875	INPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74AC191	FSC	3	Digital, Counter/Divider	CMOS														
					427	0287	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4825	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC245	FSC	3	Digital, Transceiver	CMOS														
					427	1286	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	I-O TO GND	100	275	13
												3	FAILED	5000	I-O TO VCC	100	275	13
												3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	4600	INPUT TO VCC	100	275	13
												3	FAILED	4800	VCC TO GND	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC251	FSC	2	Digital, Multiplexer	CMOS														
					427	0586	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3800	INPUT TO OUTPUT	100	275	13
												3	FAILED	3500	INPUT TO GND	100	275	13
												3	FAILED	3500	INPUT TO VCC	100	275	13
												3	FAILED	3500	OUTPUT TO GND	100	275	13
					427	0586	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4800	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC253	FSC	2	Digital, Multiplexer	CMOS														
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4750	INPUT TO GND	100	275	13
					427	0986	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	4000	INPUT TO VCC	100	275	13
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Sou	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74AC253	FSC	2	Digital, Multiplexer	CMOS														
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC258	FSC	2	Digital, Multiplexer	CMOS														
					427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
					427	1186	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3650	INPUT TO VCC	100	275	13
					427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	4500	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC299	FSC	3	Digital, Register, Shift	CMOS														
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	INPUT TO VCC	100	275	13
												3	FAILED	4800	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	4600	GND TO VCC	100	275	13
74AC323	FSC	3	Digital, Register, Shift	CMOS														
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	INPUT TO VCC	100	275	13
												3	FAILED	4700	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	INPUT TO OUTPUT	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74AC323	FSC	3	Digital, Register, Shift	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4600	GND TO VCC	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74AC521	FSC	1	Linear, Comparator	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	1086	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	1890	INPUT TO GND	100	275	13
427	1086	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	2850	INPUT TO VCC	100	275	13
427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	OUTPUT TO GND	100	275	13
427	1086	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3800	OUTPUT TO VCC	100	275	13
							3	FAILED	3100	INPUT TO OUTPUT	100	275	13
							3	FAILED	2150	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74AC540	FSC	3	Digital, Line/Bus Driver	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
							3	FAILED	4900	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	4600	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74AC541	FSC	3	Digital, Line/Bus Driver	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4999	INPUT TO GND	100	275	13
							3	FAILED	4550	INPUT TO VCC	100	275	13
							3	FAILED	4950	OUTPUT TO GND	100	275	13
							3	FAILED	4999	OUTPUT TO VCC	100	275	13
							3	FAILED	4950	INPUT TP OUTPUT	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74AC541	FSC	3	Digital, Line/Bus Driver	CMOS														
					427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4999	OUTPUT TO VCC	100	275	13
74AC646	FSC	2	Digital, Trarsceiver	CMOS														
					427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	4000	INPUT TO VCC	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	I-O TO GND	100	275	13
												3	FAILED	5000	I-O TO VCC	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3750	I TO I-O	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	VCC TO GND	100	275	13
74AC708	FSC	3	Digital, Memory	CMOS														
					427	0687	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	4950	INPUT TO VCC	100	275	13
												3	FAILED	4950	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74AC74	FSC	3	Digital, Flip-Flop	CMOS														
					426	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	INPUT TO GND.	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND.	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74AC74	FSC	3	Digital, Flip-Flop	CMOS														
					426	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND.	100	275	13
												3	FAILED	5000	VCC TO GND.	100	275	13
					427	0886	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO OUTPUT	100	275	13
74ACT00	FSC	2	Digital, Gate	CMOS														
					427	0187	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	2600	INPUT TO GND	100	275	13
												3	FAILED	3100	OUTPUT TO GND	100	275	13
					427	0187	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4250	INPUT TO VCC	100	275	13
												3	FAILED	4950	OUTPUT TO VCC	100	275	13
					427	0187	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	2700	INPUT TO OUTPUT	100	275	13
					427	0187	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	VCC TO GND	100	275	13
74ACT08	FSC	3	Digital, Gate	CMOS														
					427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4500	INPUT TO GND	100	275	13
												3	FAILED	4250	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4500	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74ACT109	FSC	3	Digital, Flip-Flop	CMOS														
					427	0487	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74ACT109	FSC	3	Digital, Flip-Flop	CMOS														
					427	0487	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4950	INPUT TO OUTPUT	100	275	13
												3	FAILED	4950	VCC TO GND	100	275	13
74ACT151	FSC	3	Digital, Multiplexer	CMOS														
					427	0487	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	4900	VCC TO GND	100	275	13
74ACT153	FSC	3	Digital, Multiplexer	CMOS														
					427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4150	INPUT TO VCC	100	275	13
												3	FAILED	4950	INPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4900	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74ACT157	FSC	2	Digital, Multiplexer	CMOS														
					427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4550	INPUT TO GND	100	275	13
					427	1086	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3400	INPUT TO VCC	100	275	13
					427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks	Technology
74ACT157	FSC	2	Digital, Multiplexer															CMOS
				427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO VCC	100	275	13	
											3	FAILED	4450	INPUT TO OUTPUT	100	275	13	
											3	FAILED	4800	VCC TO GND	100	275	13	
74ACT158	FSC	2	Digital, Multiplexer															CMOS
				427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4450	INPUT TO GND	100	275	13	
				427	0986	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3800	INPUT TO VCC	100	275	13	
				427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND	100	275	13	
											3	FAILED	5000	OUTPUT TO VCC	100	275	13	
											3	FAILED	5000	INPUT TO OUTPUT	100	275	13	
											3	FAILED	4950	VCC TO GND	100	275	13	
74ACT175	FSC	3	Digital, Flip-Flop															CMOS
				427	0587	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4900	INPUT TO VCC	100	275	13	
											3	FAILED	5000	INPUT TO GND	100	275	13	
											3	FAILED	50000	OUTPUT TO VCC	100	275	13	
											3	FAILED	5000	OUTPUT TO GND	100	275	13	
											3	FAILED	5000	INPUT TO OUTPUT	100	275	13	
											3	FAILED	5000	VCC TO GND	100	275	13	
74ACT245	FSC	3	Digital, Transceiver															CMOS
				427	1286	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13	
											3	FAILED	4550	INPUT TO VCC	100	275	13	
											3	FAILED	5000	I-O TO GND	100	275	13	
											3	FAILED	5000	I-O TO VCC	100	275	13	

RAC ESD Database

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74ACT245	FSC	3	Digital, Transceiver	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	1286	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO I-O	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74ACT253	FSC	3	Digital, Multiplexer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0286	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4900	INPUT TO GND	100	275	13
							3	FAILED	4400	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	5000	INPUT TO OUTPUT	100	275	13
							3	FAILED	4900	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74ACT257	FSC	3	Digital, Multiplexer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
							3	FAILED	4550	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	4900	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74ACT258	FSC	3	Digital, Multiplexer	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	INPUT TO GND	100	275	13
							3	FAILED	4200	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74ACT510	FSC	2	Digital	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
427	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3500	X14 TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74ACT510	FSC	2	Digital	CMOS														
					427	0886	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	3500	X14 TO VCC	100	275	13
												3	FAILED	3500	ACC TO GND	100	275	13
												3	FAILED	3500	ACC TO VCC	100	275	13
												3	FAILED	3500	P11 TO GND	100	275	13
												3	FAILED	3500	P11 TO VCC	100	275	13
												3	FAILED	3500	P34 TO GND	100	275	13
												3	FAILED	3500	P34 TO VCC	100	275	13
74ACT534	FSC	2	Digital, Flip-Flop, D	CMOS														
					427	0687	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO VCC	100	275	13
												3	FAILED	4500	INPUT TO GND	100	275	13
												3	FAILED	4200	OUTPUT TO VCC	100	275	13
					427	0687	SS	1500 Ohms	100E-12 F	40	N/R	3	FAILED	4000	OUTPUT TO GND	100	275	13
					427	0687	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	4700	VCC TO GND	100	275	13
74ACT540	FSC	3	Digital, Line/Bus Driver	CMOS														
					427	0687	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	4950	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4850	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74ACT563	FSC	3	Digital, Latch	CMOS														
					427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4900	INPUT TO GND	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description								Technology		
Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74ACT563	FSC	3	Digital, Latch								CMOS		
427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	4850	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	4550	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13
74ACT564	FSC	3	Digital, Flip-Flop								CMOS		
427	1186	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	INPUT TO VCC	100	275	13
							3	FAILED	4300	INPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	4450	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13
74ACT573	FSC	3	Digital, Latch								CMOS		
427	0986	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
							3	FAILED	4873	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13
							3	FAILED	4750	INPUT TO OUTPUT	100	275	13
							3	FAILED	5000	VCC TO GND	100	275	13
74ACT574	FSC	3	Digital, Latch								CMOS		
427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
							3	FAILED	5000	INPUT TO VCC	100	275	13
							3	FAILED	5000	OUTPUT TO GND	100	275	13
							3	FAILED	5000	OUTPUT TO VCC	100	275	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74ACT574	FSC	3	Digital, Latch	CMOS														
					427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74ACT708	FSC	3	Digital, Memory	CMOS														
					427	0387	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	INPUT TO GND	100	275	13
												3	FAILED	4950	INPUT TO VCC	100	275	13
					427	1087	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	OUTPUT TO VCC	100	275	13
					427	1086	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	4950	OUTPUT TO GND	100	275	13
					427	0387	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74ACT74	FSC	3	Digital, Flip-Flop	CMOS														
					427	0487	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	5000	INPUT TO GND	100	275	13
												3	FAILED	5000	OUTPUT TO GND	100	275	13
												3	FAILED	4950	INPUT TO VCC	100	275	13
												3	FAILED	5000	OUTPUT TO VCC	100	275	13
												3	FAILED	4900	INPUT TO OUTPUT	100	275	13
												3	FAILED	5000	VCC TO GND	100	275	13
74F00	FSC	1	Digital, Gate	Advanced STTL														
					049	0681	GN	1500 Ohms	100E-12 F	1	N/R	3	FAILED	500	INPUT(+) INPUT(-)	51	252	13
					426	0986	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74F02	FSC	1	Digital, Gate	Advanced STTL														
					426	0786	SS	1500 Ohms	100E-12 F	20	8624	3	FAILED	1000	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
170	0881	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	INPUT(1)(+) COM.(7)(-)	51	252	13
							1	FAILED	1250	INPUT(3)(+) COM.(7)(-)	51	252	13
							1	PASSED	1250	INPUT(3)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	INPUT(5)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	INPUT(9)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	INPUT(11)(+) COM(7)(-)	51	252	13
							2	FAILED	1250	INPUT(13)(+) COM(7)(-)	51	252	13
							1	PASSED	1250	COM(7)(+) OUT.(4)(-)	51	252	13
							1	PASSED	1250	COM(7)(+) OUT.(6)(-)	51	252	13
							1	PASSED	1250	COM(7)(+) OUT.(8)(-)	51	252	13
							1	PASSED	1250	COM(7)(+) OUT.(10)(-)	51	252	13
							1	PASSED	1250	COM(7)(+) OUT.(12)(-)	51	252	13
							2	FAILED	1250	INPUT(1)(+) OUT.(2)(-)	51	252	13
							2	FAILED	1250	INPUT(3)(+) OUT.(4)(-)	51	252	13
							2	FAILED	1250	INPUT(5)(+) OUT.(6)(-)	51	252	13
							1	PASSED	1250	INPUT(9)(+) OUT.(8)(-)	51	252	13
							2	FAILED	1250	IN.(11)(+) OUT.(10)(-)	51	252	13
							2	FAILED	1250	IN.(13)(+) OUT.(12)(-)	51	252	13
							1	PASSED	1250	VCC(-) COM.(7)(+)	51	252	13
171	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	INPUT(1)(+) COM.(7)(-)	4	252	13
							2	FAILED	1250	INPUT(3)(+) COM.(7)(-)	4	252	13
							2	FAILED	1250	INPUT(5)(+) COM.(7)(-)	4	252	13
							2	FAILED	1250	INPUT(9)(+) COM.(7)(-)	4	252	13
							2	FAILED	1250	IN.(11)(+) COM.(7)(-)	4	252	13
							2	FAILED	1250	IN.(13)(+) COM.(7)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) OUT.(2)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) OUT.(4)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) OUT.(6)(-)	4	252	13
							1	PASSED	1250	COM.(7)(-) OUT.(8)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) OUT.(10)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) OUT.(12)(-)	4	252	13
							2	FAILED	1250	IN.(1)(+) OUT.(2)(-)	4	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
171	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	IN.(3)(+) OUT.(4)(-)	4	252	13
							2	FAILED	1250	IN.(5)(+) OUT.(6)(-)	4	252	13
							2	FAILED	1250	IN.(9)(+) OUT.(8)(-)	4	252	13
							2	FAILED	1250	IN.(11)(+) OUT.(10)(-)	4	252	13
							2	FAILED	1250	IN.(13)(+) OUT.(12)(-)	4	252	13
							1	PASSED	1250	COM.(7)(+) VCC(-)	4	252	13
172	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	COM.(7)(+) OUT.(2)(-)	4	252	13
							1	PASSED	5000	COM.(7)(+) OUT.(4)(-)	4	252	13
							1	PASSED	5000	COM.(7)(+) OUT.(6)(-)	4	252	13
							1	PASSED	5000	COM.(7)(+) OUT.(8)(-)	4	252	13
							1	PASSED	5000	COM.(7)(+) OUT.(10)(-)	4	252	13
							2	FAILED	1250	COM.(7)(+) OUT.(12)(-)	4	252	13
							1	PASSED	5000	COM.(7)(+) VCC(-)	4	252	13
173	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	IN.(1)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	IN.(3)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	IN.(5)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	IN.(9)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	IN.(11)(+) COM.(7)(-)	51	252	13
							2	FAILED	1250	IN.(13)(+) COM.(7)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(2)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(4)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(6)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(8)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(10)(-)	51	252	13
							2	PASSED	1250	COM.(7)(+) OUT.(12)(-)	51	252	13
							2	FAILED	1250	IN.(1)(+) OUT.(2)(-)	51	252	13
							2	FAILED	1250	IN.(3)(+) OUT.(4)(-)	51	252	13
							2	FAILED	1250	IN.(5)(+) OUT.(6)(-)	51	252	13
							2	FAILED	1250	IN.(9)(+) OUT.(8)(-)	51	252	13
							2	FAILED	1250	IN.(11)(+) OUT.(10)(-)	51	252	13
							2	FAILED	1250	IN.(13)(+) OUT.(12)(-)	51	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
173	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	1250	COM.(7)(+) VCC(-)	51	252	13
174	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	PASSED	5000	COM.(7)(+) OUT.(2)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) OUT.(4)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) OUT.(6)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) OUT.(8)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) OUT.(10)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) OUT.(12)(-)	51	252	13
							2	PASSED	5000	COM.(7)(+) VCC(-)	51	252	13
175	0881	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	IN.(1)(+) COM.(7)(-)	51	252	13
176	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	IN.(1)(+) COM.(7)(-)	51	252	13
177	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	IN.(1)(+) COM.(7)(-)	51	252	13
178	0981	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	400	IN.(1)(+) APTT(-)	51	252	13
							1	FAILED	300	IN.(3)(+) APTT(-)	51	252	13
							1	FAILED	400	IN.(5)(+) APTT(-)	51	252	13
							1	FAILED	300	IN.(9)(+) APTT(-)	51	252	13
							1	FAILED	100	IN.(11)(+) APTT(-)	51	252	13
							1	FAILED	400	IN.(13)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(2)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(4)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(6)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(8)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(10)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(12)(+) APTT(-)	51	252	13
							1	PASSED	1250	VCC(14)(+) APTT(-)	51	252	13
179	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	IN.(1)(+) APTT(-)	4	252	27
							1	FAILED	200	IN.(3)(+) APTT(-)	4	252	27
							1	FAILED	200	IN.(5)(+) APTT(-)	4	252	27

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
179	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	400	IN.(9)(+) APTT(-)	4	252	27
							1	FAILED	600	IN.(11)(+) APTT(-)	4	252	27
							1	FAILED	500	IN.(13)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(2)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(4)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(6)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(8)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(10)(+) APTT(-)	4	252	27
							1	PASSED	5000	OUT.(12)(+) APTT(-)	4	252	27
							1	PASSED	5000	VCC(14)(+) APTT(-)	4	252	27
180	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	400	IN.(1)(+) APTT(-)	51	252	27
							1	FAILED	400	IN.(3)(+) APTT(-)	51	252	27
							1	FAILED	400	IN.(5)(+) APTT(-)	51	252	27
							1	FAILED	300	IN.(9)(+) APTT(-)	51	252	27
							1	FAILED	400	IN.(11)(+) APTT(-)	51	252	27
							1	FAILED	400	IN.(13)(+) APTT(-)	51	252	27
							2	PASSED	5000	OUT.(2)(+) APTT(-)	51	252	27
							1	PASSED	5000	OUT.(6)(+) APTT(-)	51	252	27
							1	PASSED	5000	OUT.(8)(+) APTT(-)	51	252	27
							1	PASSED	5000	OUT.(10)(+) APTT(-)	51	252	27
							1	PASSED	5000	OUT.(12)(+) APTT(-)	51	252	27
							1	PASSED	5000	VCC(14)(+) APTT(-)	51	252	27
181	0981	SS	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	IN.(1)(+)	51	262	0
							1	PASSED	1250	IN.(3)(+)	51	262	0
							1	FAILED	800	IN.(5)(+)	51	262	0
							1	PASSED	1250	IN.(9)(+)	51	262	0
							1	PASSED	1250	IN.(11)(+)	51	262	0
							1	FAILED	1250	IN.(13)(+)	51	262	0
							1	PASSED	1250	OUT.(2)(+)	51	262	0
							1	PASSED	1250	OUT.(4)(+)	51	262	0
							1	PASSED	1250	OUT.(6)(+)	51	262	0

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F04	FSC	1	Digital, Inverter, Buffer	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
181	0981	SS	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	OUT.(8)(+)	51	262	0
							1	PASSED	1250	OUT.(10)(+)	51	262	0
							1	PASSED	1250	OUT.(12)(+)	51	262	0
							1	PASSED	1250	VCC(14)(+)	51	262	0
182	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1800	IN.(1)(+)	4	262	0
							1	FAILED	800	IN.(3)(+)	4	262	0
							1	FAILED	700	IN.(5)(+)	4	262	0
							1	FAILED	1800	IN.(9)(+)	4	262	0
							1	FAILED	1400	IN.(11)(+)	4	262	0
							1	FAILED	1400	IN.(13)(+)	4	262	0
							1	FAILED	5000	OUT.(2)(+)	4	262	0
							1	FAILED	5000	OUT.(4)(+)	4	262	0
							1	PASSED	5000	OUT.(6)(+)	4	262	0
							1	PASSED	5000	OUT.(8)(+)	4	262	0
							1	PASSED	5000	OUT.(10)(+)	4	262	0
							1	PASSED	5000	OUT.(12)(+)	4	262	0
							1	PASSED	5000	VCC(14)(+)	4	262	0
183	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	IN.(1)(+)	51	262	0
							1	FAILED	2200	IN.(3)(+)	51	262	0
							1	FAILED	2200	IN.(5)(+)	51	262	0
							1	FAILED	1400	IN.(9)(+)	51	262	0
							1	FAILED	900	IN.(11)(+)	51	262	0
							1	FAILED	900	IN.(13)(+)	51	262	0
							1	PASSED	5000	OUT.(2)(+)	51	262	0
							1	PASSED	5000	OUT.(4)(+)	51	262	0
							1	PASSED	5000	OUT.(6)(+)	51	262	0
							1	PASSED	5000	OUT.(8)(+)	51	262	0
							1	PASSED	5000	OUT.(10)(+)	51	262	0
							1	PASSED	5000	OUT.(12)(+)	51	262	0
							1	PASSED	5000	VCC(14)(+)	51	262	0
184	0981	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	60	IN.(11)(+) APTT(-)	51	252	13

RAC ESD Database

Technology
Advanced STTL

[illegible]	Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
184	0981	SS	1500 Ohms	100E-12 F	300	N/R	3	FAILED	60	IN.(11)(+) APTT(-)	51	252	13
184	0981	SS	1500 Ohms	100E-12 F	100	N/R	1	PASSED	60	IN.(11)(+) APTT(-)	51	252	13
185	N/R	GN	1500 Ohms	100E-12 F	30	N/R	5	FAILED	60	IN.(1)(+) APTT(-)	4	252	13
186	N/R	GN	1500 Ohms	100E-12 F	10	N/R	7	FAILED	120	IN.(1)(+) APTT(-)	4	252	13
186	N/R	GN	1500 Ohms	100E-12 F	100	N/R	1	FAILED	120	IN.(1)(+) APTT(-)	4	252	13
187	N/R	SS	1500 Ohms	100E-12 F	300	N/R	1	PASSED	160	IN.(1)(+) APTT(-)	4	252	13
188	N/R	GN	1500 Ohms	100E-12 F	10	N/R	4	FAILED	160	IN.(1)(+) APTT(-)	4	252	13
189	N/R	SS	1500 Ohms	100E-12 F	30	N/R	1	FAILED	240	IN.(9)(+) APTT(-)	51	252	13
189	N/R	SS	1500 Ohms	100E-12 F	300	N/R	1	FAILED	240	IN.(9)(+) APTT(-)	51	252	13
							3	PASSED	240	IN.(9)(+) APTT(-)	51	252	13
190	0981	SS	1500 Ohms	100E-12 F	300	N/R	2	FAILED	480	IN.(5)(+)	51	262	0
190	0981	SS	1500 Ohms	100E-12 F	30	N/R	1	PASSED	480	IN.(5)(+)	51	262	0
191	0981	SS	1500 Ohms	100E-12 F	300	N/R	1	PASSED	640	IN.(5)(+)	51	262	0
192	0981	GN	1500 Ohms	100E-12 F	300	N/R	1	PASSED	240	IN.(5)(+)	51	262	0
193	0981	GN	1500 Ohms	100E-12 F	100	N/R	1	PASSED	480	IN.(5)(+)	51	262	0
194	0981	GN	1500 Ohms	100E-12 F	10	N/R	3	PASSED	640	IN.(5)(+)	51	262	0
194	0981	GN	1500 Ohms	100E-12 F	30	N/R	1	PASSED	640	IN.(5)(+)	51	262	0
195	N/R	SS	1500 Ohms	100E-12 F	300	N/R	4	PASSED	560	IN.(5)(+)	4	262	15

RAC ESD Database

Part [illegible] Part ESD Part
Number [illegible] Mfr Class Description Technology
[illegible] FSC 1 Digital, Inverter, Buffer Advanced STTL

	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
	196	N/R	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	420	IN.(5)(+)	4	262	0
	197	N/R	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	560	IN.(5)(+)	4	262	0
	170	0881	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	COM(7)(+) OUT.(2)(-)	51	252	13
	426	0612	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74F04		N/R	3	Digital, Inverter, Buffer								Advanced STTL		
	180	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	PASSED	5000	OUT.(4)(+) APTT(-)	51	252	27
74F08		FSC	1	Digital, Gate								Advanced STTL		
	426	1286	SS	1500 Ohms	100E-12 F	10	8624	3	FAILED	600	INPUT TO GND.	61	204	13
74F10		FSC	1	Digital, Gate								Advanced STTL		
	426	0786	SS	1500 Ohms	100E-12 F	20	8622	3	FAILED	1000	INPUT TO GND.	61	204	13
74F109		FSC	1	Digital, Flip-Flop								Advanced STTL		
	426	0986	SS	1500 Ohms	100E-12 F	10	8632	3	FAILED	600	INPUT TO GND.	61	204	13
74F11		FSC	1	Digital, Gate								Advanced STTL		
	426	0786	SS	1500 Ohms	100E-12 F	10	8622	3	FAILED	600	INPUT TO GND.	61	204	13
74F112		FSC	1	Digital, Flip-Flop								Advanced STTL		
	426	0686	SS	1500 Ohms	100E-12 F	30	8617	3	FAILED	2000	INPUT TO GND.	61	204	13

RAC ESD Database

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F113	FSC	1	Digital, Flip-Flop	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8635	3	FAILED	1000	INPUT TO GND.	61	204	13
74F138	FSC	1	Digital, Decoder	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	20	8614	3	FAILED	1000	INPUT TO GND.	61	204	13
74F139	FSC	1	Digital, Decoder	Advanced STTL	426	0786	SS	1500 Ohms	100E-12 F	20	8621	3	FAILED	1000	INPUT TO GND.	61	204	13
74F151	FSC	1	Digital, Multiplexer	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	20	8620	3	FAILED	1000	INPUT TO GND.	61	204	13
74F153	FSC	1	Digital, Multiplexer	Advanced STTL	426	0886	SS	1500 Ohms	100E-12 F	30	8630	3	FAILED	2000	INPUT TO GND.	61	204	13
74F157	FSC	1	Digital, Multiplexer	Advanced STTL	426	0786	SS	1500 Ohms	100E-12 F	20	8622	3	FAILED	1000	INPUT TO GND.	61	204	13
74F158	FSC	1	Digital, Multiplexer	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	20	8623	3	FAILED	1000	INPUT TO GND.	61	204	13
74F160	FSC	1	Digital, Counter/Divider	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	30	8425	3	FAILED	2000	INPUT TO GND.	61	204	13

RAC ESD Database

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F161	FSC	1	Digital, Counter/Divider	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	30	8637	3	FAILED	2000	INPUT TO GND.	61	204	13
74F163	FSC	1	Digital, Counter/Divider	Advanced STTL	426	1286	SS	1500 Ohms	100E-12 F	30	8637	3	FAILED	2000	INPUT TO GND.	61	204	13
74F164	FSC	1	Digital, Register, Shift	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	30	8619	3	FAILED	2000	INPUT TO GND.	61	204	13
74F168	FSC	1	Digital, Counter/Divider	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	20	8636	3	FAILED	1000	INPUT TO GND.	61	204	13
74F169	FSC	1	Digital, Counter/Divider	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8634	3	FAILED	1000	INPUT TO GND.	61	204	13
74F174	FSC	1	Digital, Flip-Flop	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8636	3	FAILED	1000	INPUT TO GND.	61	204	13
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL	198	0881	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	IN.(1)(+) COM.(8)(-)	51	252	13
												1	PASSED	1250	IN.(4)(+) COM.(8)(-)	51	252	13
												2	FAILED	1250	IN.(5)(+) COM.(8)(-)	51	252	13

RAC ESD Database

Description
Digital, Flip Flop

Technology
Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
[illegible]	[illegible]	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	IN.(9)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	IN.(12)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	IN.(13)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(2)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(3)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(6)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(7)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(10)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(11)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT(14)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	OUT.(15)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	IN.(4)(+) OUT.(2)(-)	51	252	13
							1	PASSED	1250	IN.(4)(+) OUT.(3)(-)	51	252	13
							2	FAILED	1250	IN.(5)(+) OUT.(6)(-)	51	252	13
							1	PASSED	1250	IN.(5)(+) OUT.(7)(-)	51	252	13
							2	FAILED	1250	IN.(12)(+) OUT.(10)(-)	51	252	13
							1	FAILED	1250	IN.(12)(+) OUT.(11)(-)	51	252	13
							1	PASSED	1250	IN.(12)(+) OUT.(11)(-)	51	252	13
							1	PASSED	1250	IN.(13)(+) OUT.(14)(-)	51	252	13
							1	FAILED	1250	IN.(13)(+) OUT.(15)(-)	51	252	13
							1	PASSED	1250	IN.(13)(+) OUT.(15)(-)	51	252	13
							2	PASSED	1250	VCC(16)(+) COM.(8)(-)	51	252	13
199	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	IN.(4)(+) COM.(8)(-)	4	252	13
							2	FAILED	1250	IN.(1)(+) OUT.(2)(-)	4	252	13
200	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	5000	IN.(1)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(4)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(5)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(9)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(12)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(13)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(2)(+) COM.(8)(-)	4	252	13

RAC ESD Database

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
200	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	5000	OUT.(3)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(6)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(7)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(10)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(11)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(14)(+) COM.(8)(-)	4	252	13
							1	PASSED	5000	OUT.(15)(+) COM.(8)(-)	4	252	13
							2	FAILED	5000	IN.(4)(+) OUT.(2)(-)	4	252	13
							2	FAILED	5000	IN.(5)(+) OUT.(7)(-)	4	252	13
							2	FAILED	5000	IN.(9)(+) OUT.(2)(-)	4	252	13
							2	FAILED	5000	IN.(12)(+) OUT.(11)(-)	4	252	13
							2	FAILED	5000	IN.(13)(+) OUT.(14)(-)	4	252	13
							1	PASSED	5000	VCC(16)(+) COM.(8)(-)	4	252	13
201	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1250	IN.(2)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	IN.(4)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	IN.(5)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	IN.(9)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	IN.(12)(+) COM.(8)(-)	51	252	13
							1	PASSED	1250	IN.(13)(+) COM.(8)(-)	51	252	13
							1	FAILED	1250	IN.(13)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(2)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(3)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(6)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(7)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(10)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(11)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(14)(+) COM.(8)(-)	51	252	13
							2	PASSED	1250	OUT.(15)(+) COM.(8)(-)	51	252	13
							2	FAILED	1250	IN.(1)(+) OUT.(2)(-)	51	252	13
							2	PASSED	1250	IN.(4)(+) OUT.(2)(-)	51	252	13
							2	PASSED	1250	IN.(5)(+) OUT.(7)(-)	51	252	13
							1	FAILED	1250	IN.(9)(+) OUT.(7)(-)	51	252	13

Part Number (Cont'd)	Part Mtr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
201	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	IN.(9)(+) OUT.(7)(-)	51	252	13
							2	PASSED	1250	IN.(12)(+) OUT.(10)(-)	51	252	13
							2	PASSED	1250	IN.(13)(+) OUT.(15)(-)	51	252	13
							2	PASSED	1250	VCC(16)(+) COM.(8)(-)	51	252	13
202	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	5000	IN.(4)(+) COM.(8)(-)	51	252	13
							2	FAILED	5000	IN.(5)(+) COM.(8)(-)	51	252	13
							2	FAILED	5000	IN.(9)(+) COM.(8)(-)	51	252	13
							2	FAILED	5000	IN.(12)(+) COM.(8)(-)	51	252	13
							1	FAILED	5000	IN.(13)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(2)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(3)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(6)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(7)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(10)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(11)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(14)(+) COM.(8)(-)	51	252	13
							2	PASSED	5000	OUT.(15)(+) COM.(8)(-)	51	252	13
							2	FAILED	5000	IN.(4)(+) OUT.(2)(-)	51	252	13
							2	FAILED	5000	IN.(5)(+) OUT.(7)(-)	51	252	13
							1	FAILED	5000	IN.(9)(+) OUT.(7)(-)	51	252	13
							2	FAILED	5000	IN.(12)(+) OUT.(10)(-)	51	252	13
							2	FAILED	5000	IN.(13)(+) OUT.(15)(-)	51	252	13
							2	PASSED	5000	VCC(16)(+) COM.(8)(-)	51	252	13
203	0881	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	IN.(5)(+) COM.(8)(-)	51	252	13
							8	PASSED	1000	IN.(5)(+) COM.(8)(-)	51	252	13
204	N/R	GN	1500 Ohms	100E-12 F	1	N/R	10	PASSED	1000	IN.(1)(+) OUT.(2)(-)	4	252	13
205	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	4000	IN.(4)(+) COM.(8)(-)	4	252	13
206	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	IN.(1)(+) COM.(8)(-)	51	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
207	0981	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	IN.(1)(+) APTT(-)	51	252	13
							1	FAILED	800	IN.(4)(+) APTT(-)	51	252	13
							1	FAILED	700	IN.(5)(+) APTT(-)	51	252	13
							1	FAILED	600	IN.(9)(+) APTT(-)	51	252	13
							1	FAILED	1250	IN.(12)(+) APTT(-)	51	252	13
							1	FAILED	1000	IN.(13)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(2)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(3)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(6)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(7)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(10)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(11)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(14)(+) APTT(-)	51	252	13
							1	PASSED	1250	OUT.(15)(+) APTT(-)	51	252	13
							1	PASSED	1250	VCC(16)(+) APTT(-)	51	252	13
208	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1800	IN.(1)(+) APTT(-)	4	252	13
							4	FAILED	700	IN.(4)(+) APTT(-)	4	252	13
							1	FAILED	500	IN.(5)(+) APTT(-)	4	252	13
							1	FAILED	1800	IN.(9)(+) APTT(-)	4	252	13
							1	FAILED	2200	IN.(12)(+) APTT(-)	4	252	13
							1	FAILED	2600	IN.(13)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(2)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(3)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(6)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(7)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(10)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(11)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(14)(+) APTT(-)	4	252	13
							1	PASSED	5000	OUT.(15)(+) APTT(-)	4	252	13
							1	PASSED	5000	VCC(16)(+) APTT(-)	4	252	13
209	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	IN.(1)(+) APTT(-)	51	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
209	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	700	IN.(4)(+) APTT(-)	51	252	13
							1	FAILED	3400	IN.(5)(+) APTT(-)	51	252	13
							1	FAILED	300	IN.(9)(+) APTT(-)	51	252	13
							1	FAILED	400	IN.(12)(+) APTT(-)	51	252	13
							1	FAILED	800	IN.(13)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(2)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(3)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(6)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(7)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(10)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(11)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(14)(+) APTT(-)	51	252	13
							1	PASSED	5000	OUT.(15)(+) APTT(-)	51	252	13
							1	PASSED	5000	VCC(16)(+) APTT(-)	51	252	13
210	0981	SS	1500 Ohms	100E-12 F	1	N/R	1	PASSED	1250	IN.(1)(+)	51	262	0
							1	PASSED	1250	IN.(4)(+)	51	262	0
							1	PASSED	1250	IN.(5)(+)	51	262	0
							1	FAILED	1000	IN.(9)(+)	51	262	0
							1	PASSED	1250	INPUT(12)(+)	51	262	0
							1	PASSED	1250	IN.(13)(+)	51	262	0
							1	PASSED	1250	OUT.(2)(+)	51	262	0
							1	PASSED	1250	OUT.(3)(+)	51	262	0
							1	PASSED	1250	OUT.(6)(+)	51	262	0
							1	PASSED	1250	OUT.(7)(+)	51	262	0
							1	PASSED	1250	OUT.(10)(+)	51	262	0
							1	PASSED	1250	OUT.(11)(+)	51	262	0
							1	PASSED	1250	OUT.(14)(+)	51	262	0
							1	PASSED	1250	OUT.(15)(+)	51	262	0
							1	PASSED	1250	VCC(16)(+)	51	262	0
211	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2200	IN.(1)(+)	4	262	0
							1	FAILED	1400	IN.(4)(+)	4	262	0

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
211	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2200	IN.(5)(+)	4	262	0
							1	FAILED	2200	IN.(9)(+)	4	262	0
							1	FAILED	3000	IN.(12)(+)	4	262	0
							1	FAILED	2200	IN.(13)(+)	4	262	0
							1	PASSED	5000	OUT.(2)(+)	4	262	0
							1	PASSED	5000	OUT.(3)(+)	4	262	0
							1	PASSED	5000	OUT.(6)(+)	4	262	0
							1	PASSED	5000	OUT.(7)(+)	4	262	0
							1	PASSED	5000	OUT.(10)(+)	4	262	0
							1	PASSED	5000	OUT.(11)(+)	4	262	0
							1	PASSED	5000	OUT.(14)(+)	4	262	0
							1	PASSED	5000	OUT.(15)(+)	4	262	0
							1	PASSED	5000	VCC(16)(+)	4	262	0
212	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4700	IN.(1)(+)	51	262	0
							1	FAILED	4600	IN.(4)(+)	51	262	0
							1	FAILED	4600	IN.(5)(+)	51	262	0
							1	FAILED	2200	IN.(9)(+)	51	262	0
							1	FAILED	3000	IN.(12)(+)	51	262	0
							1	FAILED	4600	IN.(13)(+)	51	262	0
							1	PASSED	5000	OUT.(2)(+)	51	262	0
							1	PASSED	5000	OUT.(3)(+)	51	262	0
							1	PASSED	5000	OUT.(6)(+)	51	262	0
							1	PASSED	5000	OUT.(7)(+)	51	262	0
							1	PASSED	5000	OUT.(10)(+)	51	262	0
							1	PASSED	5000	OUT.(11)(+)	51	262	0
							1	PASSED	5000	OUT.(14)(+)	51	262	0
							1	PASSED	5000	OUT.(15)(+)	51	262	0
							1	PASSED	5000	VCC(16)(+)	51	262	0
213	0981	SS	1500 Ohms	100E-12 F	100	N/R	1	FAILED	360	IN.(9)(+) APTT(-)	51	252	13
214	0981	SS	1500 Ohms	100E-12 F	100	N/R	1	FAILED	480	IN.(9)(+) APTT(-)	51	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
215	0981	GN	1500 Ohms	100E-12 F	30	N/R	1	PASSED	180	IN.(9)(+) APTT(-)	51	252	13
215	0981	GN	1500 Ohms	100E-12 F	100	N/R	1	PASSED	180	IN.(9)(+) APTT(-)	51	252	13
215	0981	GN	1500 Ohms	100E-12 F	300	N/R	1	PASSED	180	IN.(9)(+) APTT(-)	51	252	13
216	0981	SS	1500 Ohms	100E-12 F	30	N/R	1	FAILED	480	IN.(9)(+) APTT(-)	51	252	13
217	0981	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	600	IN.(9)(+) APTT(-)	51	252	13
217	0981	GN	1500 Ohms	100E-12 F	100	N/R	1	FAILED	360	IN.(9)(+) APTT(-)	51	252	13
218	0981	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	480	IN.(9)(+) APTT(-)	51	252	13
							1	PASSED	480	IN.(9)(+) APTT(-)	51	252	13
218	0981	GN	1500 Ohms	100E-12 F	300	N/R	1	PASSED	480	IN.(9)(+) APTT(-)	51	252	13
219	N/R	SS	1500 Ohms	100E-12 F	100	N/R	2	FAILED	300	IN.(5)(+) APTT(-)	4	252	13
220	N/R	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	150	IN.(5)(+) APTT(-)	4	252	13
220	N/R	GN	1500 Ohms	100E-12 F	100	N/R	1	FAILED	150	IN.(5)(+) APTT(-)	4	252	13
221	N/R	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	300	IN.(5)(+) APTT(-)	4	252	13
222	N/R	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	300	IN.(5)(+) APTT(-)	4	252	13
222	N/R	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	300	IN.(5)(+) APTT(-)	4	252	13
223	N/R	GN	1500 Ohms	100E-12 F	30	N/R	1	FAILED	400	IN.(5)(+) APTT(-)	4	252	13
223	N/R	GN	1500 Ohms	100E-12 F	100	N/R	4	FAILED	400	IN.(5)(+) APTT(-)	4	252	13
224	N/R	SS	1500 Ohms	100E-12 F	300	N/R	2	FAILED	320	IN.(9)(+) APTT(-)	51	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F175	FSC	1	Digital, Flip-Flop	Advanced STTL														
					224	N/R	SS	1500 Ohms	100E-12 F	300	N/R	3	PASSED	320	IN.(9)(+) APTT(-)	51	252	13
					225	0981	SS	1500 Ohms	100F-12 F	300	N/R	5	PASSED	800	IN.(9)(+)	51	262	0
					226	N/R	SS	1500 Ohms	100E-12 F	30	N/R	1	FAILED	1120	IN.(4)(+)	4	262	15
					226	N/R	SS	1500 Ohms	100E-12 F	300	N/R	2	PASSED	1120	IN.(4)(+)	4	262	15
					227	N/R	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	840	IN.(4)(+)	4	262	0
					228	N/R	SS	1500 Ohms	100E-12 F	300	N/R	1	PASSED	1120	IN.(4)(+)	4	262	0
					229	N/R	GN	1500 Ohms	100E-12 F	300	N/R	1	FAILED	420	IN.(4)(+)	4	262	16
					230	N/R	GN	1500 Ohms	100E-12 F	300	N/R	1	PASSED	1120	IN.(4)(+)	4	262	0
					426	0786	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74F190	FSC	1	Digital, Counter/Divider	Advanced STTL														
					426	0986	SS	1500 Ohms	100E-12 F	20	8503	3	FAILED	1000	INPUT TO GND.	61	204	13
74F191	FSC	1	Digital, Counter/Divider	Advanced STTL														
					426	1086	SS	1500 Ohms	100E-12 F	20	8637	3	FAILED	1000	INPUT TO GND.	61	204	13
74F192	FSC	1	Digital, Counter/Divider	Advanced STTL														
					426	0986	SS	1500 Ohms	100E-12 F	30	8446	3	FAILED	2000	INPUT TO GND.	61	204	13
74F193	FSC	1	Digital, Counter/Divider	Advanced STTL														
					426	1086	SS	1500 Ohms	100E-12 F	30	8635	3	FAILED	2000	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F20	FSC	1	Digital, Gate	Advanced STTL	049	0681	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	INPUT(4)(+) VCC(14)(-)	51	252	13
					426	0786	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
					426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74F240	FSC	1	Digital, Line/Bus Driver	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	10	8616	3	FAILED	600	INPUT TO GND.	61	204	13
74F241	FSC	1	Digital, Line/Bus Driver	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	10	8637	3	FAILED	600	INPUT TO GND.	61	204	13
74F243	FSC	1	Digital, Transceiver	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8450	3	FAILED	1000	INPUT TO GND.	61	204	13
74F244	FSC	1	Digital, Line/Bus Driver	Advanced STTL	426	0886	SS	1500 Ohms	100E-12 F	20	8629	3	FAILED	1000	INPUT TO GND.	61	204	13
74F245	FSC	1	Digital, Transceiver	Advanced STTL	426	0886	SS	1500 Ohms	100E-12 F	30	8629	3	FAILED	2000	INPUT TO GND.	61	204	13
74F251	FSC	1	Digital, Multiplexer	Advanced STTL	426	1186	SS	1500 Ohms	100E-12 F	10	8414	3	FAILED	600	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F253	FSC	1	Digital, Multiplexer	Advanced STTL	426	1186	SS	1500 Ohms	100E-12 F	20	8637	3	FAILED	1000	INPUT TO GND.	61	204	13
74F257	FSC	1	Digital, Multiplexer	Advanced STTL	426	1186	SS	1500 Ohms	100E-12 F	20	8621	3	FAILED	1000	INPUT TO GND.	61	204	13
74F258	FSC	1	Digital, Multiplexer	Advanced STTL	426	1186	SS	1500 Ohms	100E-12 F	10	8631	3	FAILED	600	INPUT TO GND.	61	204	13
74F283	FSC	1	Digital, Counter/Divider	Advanced STTL	426	1286	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74F299	FSC	1	Digital, Register, Shift	Advanced STTL	426	0786	SS	1500 Ohms	100E-12 F	20	8622	3	FAILED	1000	INPUT TO GND.	61	204	13
74F32	FSC	1	Digital, Gate	Advanced STTL	426	0786	SS	1500 Ohms	100E-12 F	30	8624	3	FAILED	2000	INPUT TO GND.	61	204	13
74F322	FSC	1	Digital, Arithmetic, Logic Unit	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8612	3	FAILED	1000	INPUT TO GND.	61	204	13
74F323	FSC	1	Digital, Register, Shift	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	20	8627	3	FAILED	1000	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	[illegible] Remark
74F350	FSC	1	Digital, Register, Shift	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	10	8604	3	FAILED	600	INPUT TO GND.	61	204	13
74F352	FSC	1	Digital, Multiplexer	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	20	8452	3	FAILED	1000	INPUT TO GND.	61	204	13
74F353	FSC	1	Digital, Multiplexer	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	20	8616	3	FAILED	1000	INPUT TO GND.	61	204	13
74F373	FSC	1	Digital, Latch	Advanced STTL	426	0886	SS	1500 Ohms	100E-12 F	20	8628	3	FAILED	1000	INPUT TO GND.	61	204	13
74F374	FSC	1	Digital, Flip-Flop	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	10	8635	3	FAILED	600	INPUT TO GND.	61	204	13
74F378	FSC	1	Digital, Flip-Flop, D	Advanced STTL	426	0986	SS	1500 Ohms	100E-12 F	30	8636	3	FAILED	2000	INPUT TO GND.	61	204	13
74F379	FSC	1	Digital, Flip-Flop, D	Advanced STTL	426	1086	SS	1500 Ohms	100E-12 F	10	8634	3	FAILED	600	INPUT TO GND.	61	204	13
74F398	FSC	1	Digital, Multiplexer	Advanced STTL	426	0686	SS	1500 Ohms	100E-12 F	10	8408	3	FAILED	600	INPUT TO GND.	61	204	13

Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F399		FSC	1	Digital, Multiplexer								Advanced STTL		
	426	1086	SS	1500 Ohms	100E-12 F	10	8637	3	FAILED	600	INPUT TO GND.	61	204	13
74F533		FSC	1	Digital, Latch								Advanced STTL		
	426	0786	SS	1500 Ohms	100E-12 F	20	8616	3	FAILED	1000	INPUT TO GND.	61	204	13
74F534		FSC	1	Digital, Flip-Flop								Advanced STTL		
	426	1086	SS	1500 Ohms	100E-12 F	20	8632	3	FAILED	1000	INPUT TO GND.	61	204	13
74F543		FSC	1	Digital, Transceiver								Advanced STTL		
	426	0686	SS	1500 Ohms	100E-12 F	30	8610	3	FAILED	2000	INPUT TO GND.	61	204	13
74F547		FSC	1	Digital, Decoder								Advanced STTL		
	426	0986	SS	1500 Ohms	100E-12 F	10	8502	3	FAILED	600	INPUT TO GND.	61	204	13
74F548		FSC	1	Digital, Decoder								Advanced STTL		
	426	0986	SS	1500 Ohms	100E-12 F	20	8630	3	FAILED	1000	INPUT TO GND.	61	204	13
74F569		FSC	1	Digital, Counter/Divider								Advanced STTL		
	426	0986	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74F64		FSC	1	Digital, Gate								Advanced STTL		
	426	0886	SS	1500 Ohms	100E-12 F	20	8629	3	FAILED	1000	INPUT MTO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74F74	FSC	1	Digital, Flip-Flop	Advanced STTL														
					426	0986	SS	1500 Ohms	100E-12 F	10	8635	3	FAILED	600	INPUT TO GND.	61	204	13
74F86	FSC	1	Digital, Gate	Advanced STTL														
					426	0886	SS	1500 Ohms	100E-12 F	20	8625	3	FAILED	1000	INPUT TO GND.	61	204	13
74H00	TEX	2	Digital, Gate	HTTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3205	N/R	102	188	13
74H05	TEX	N	Digital, Inverter, Buffer	HTTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	21697	N/R	102	188	13
74H106	N/R	1	Digital, Flip-Flop	HTTL														
					234	N/R	SS	0 Ohms	N/R	1	N/R	1	FAILED	300	IN.(9)(+) GND(13)(-)	108	222	13
												1	FAILED	300	IN.(9)(+) GND(13)(-)	108	211	13
												1	FAILED	300	IN.(9)(+) GND(13)(-)	108	210	13
					235	N/R	SS	0 Ohms	120E-12 F	1	N/R	3	FAILED	200	IN.(9)(+) GND(8)(-)	108	220	13
												1	FAILED	200	IN.(9)(+) GND(8)(-)	108	218	13
												1	FAILED	200	IN.(9)(+) GND(8)(-)	108	221	13
					236	N/R	SS	0 Ohms	510E-12 F	1	N/R	1	FAILED	100	IN.(8)(+) GND(13)(-)	108	223	13
												1	FAILED	100	IN.(9)(+) GND(13)(-)	108	209	13
												1	FAILED	100	IN.(9)(+) GND(13)(-)	108	206	13
												2	FAILED	100	IN.(8,9)(+) GND(13)(-)	108	208	13
					237	N/R	SS	0 Ohms	.01E-07 F	1	N/R	1	FAILED	200	IN.(8)(+) GND(13)(-)	108	219	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74H106	N/R	1	Digital, Flip-Flop	HTTL														
					237	N/R	SS	0 Ohms	.01E-07 F	1	N/R	1	FAILED	200	IN.(8,9)(+) GND(13)(-)	108	209	13
												1	FAILED	100	IN.(9)(+) GND(13)(-)	108	207	13
												1	FAILED	100	IN.(8,9)(+) GND(13)(-)	108	209	13
												1	FAILED	100	IN(1,8,9)(+) GND(-)	108	252	13
					238	N/R	SS	0 Ohms	.01E-06 F	1	N/R	2	FAILED	100	IN(1,8,9)(+) GND(-)	108	252	13
												2	FAILED	100	IN(8,9)(+) GND(13)(-)	108	252	13
74HC00	MOT	1	Digital, Gate	HMOS														
					399	0883	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	2000	N/R	102	252	13
												2	FAILED	1100	N/R	102	252	13
74HC00	NSC	2	Digital, Gate	HMOS														
					399	0883	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	2000	N/R	102	252	13
												10	PASSED	2000	N/R	102	252	13
74HC00	RCA	3	Digital, Gate	HMOS														
					399	0684	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13
												6	FAILED	4120	PINS 4-7 & 1-3	102	252	13
74HC00	TEX	3	Digital, Gate	HMOS														
					399	0684	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13
												1	FAILED	4120	PINS 7-8	102	252	13
74HC00	SIG	2	Digital, Gate	HMOS														
					399	0185	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
74HC04	SIG	1	Digital, Inverter, Buffer	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
391	0886	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2150	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2150	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2150	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2175	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2225	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2225	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2250	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2275	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2275	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2300	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2350	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2425	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2425	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2450	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2475	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2550	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2575	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2600	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2675	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2675	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2775	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2775	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2850	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3950	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3050	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3600	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3850	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3925	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	4150	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	1975	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2100	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2300	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2325	INPUT(13)(+) GND(7)(-)	44	252	19

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74HC04	SIG	1	Digital, Inverter, Buffer	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
391	0886	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2350	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2425	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2475	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2500	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2525	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2575	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2575	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2675	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2675	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2675	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2700	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2775	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2850	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2900	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2925	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2925	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2950	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2975	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	2975	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3050	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3225	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3225	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3400	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3450	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3750	INPUT(13)(+) GND(7)(-)	44	252	19
							1	FAILED	3800	INPUT(13)(+) GND(7)(-)	44	252	19

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
74HC161	MOT	1	Digital, Counter/Divider	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
399	0883	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	2000	N/R	102	252	13
399	0886	GN	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1100	N/R	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74HC161	NSC	2	Digital, Counter/Divider	HMOS														
					399	0883	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	2000	N/R	102	252	13
												10	PASSED	2000	N/R	102	252	13
74HC161	TEX	3	Digital, Counter/Divider	HMOS														
					399	0684	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13
												9	FAILED	4120	PINS 8-9, 8-12, & 4-13	102	252	13
74HC195	RCA	3	Digital, Register, Shift	HMOS														
					399	0684	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13
												6	FAILED	4120	PINS 8-9 & 4-15	102	252	13
74HC195	SIG	2	Digital, Register, Shift	HMOS														
					399	0185	GN	1500 Ohms	100E-12 F	5	N/R	15	PASSED	2000	N/R	102	252	13
74L00	TEX	3	Digital, Gate	LTTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4031	N/R	102	188	13
74L71	TEX	3	Digital, Flip-Flop	LTTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4692	N/R	102	188	13
74L73	TEX	2	Digital, Flip-Flop	LTTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2139	N/R	102	188	13

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Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
74L95	TEX	3	Digital, Register, Shift												LTTL			
				029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4642	N/R		102	188	13
74LS00	MOT	1	Digital, Gate												LSTTL			
				027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1000	N/R		47	252	12
											13	PASSED	1000	N/R		47	252	12
74LS00	FSC	1	Digital, Gate												LSTTL			
				426	0986	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.		61	204	13
74LS00	N/R	1	Digital, Gate												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13
				384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	400	EACH PIN(+)		52	99	24
											1	FAILED	400	EACH PIN(+)		52	137	24
											1	FAILED	950	EACH PIN(+)		52	110	24
				028	N/R	SS	1500 Ohms	117E 12 F	30	N/R	5	FAILED	1000	N/R		28	252	13
74LS02	N/R	1	Digital, Gate												LSTTL			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R		103	252	13
74LS02	FSC	1	Digital, Gate												LSTTL			
				426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.		61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS03	N,R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1000	EACH PIN(+)	52	110	24
74LS04	FSC	1	Digital, Inverter, Buffer	LSTTL														
					426	0686	SS	1500 Ohms	100E-12 F	20	8620	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS05	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS08	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS09	FSC	1	Digital, Gate	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1200	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
74LS09	TEX	1	Digital, Gate	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1500	INPUTS(+) GROUND(-)	3	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS09	TEX	1	Digital, Gate	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	400	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
74LS09	SIG	2	Digital, Gate	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
74LS09	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS10	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS10	FSC	1	Digital, Gate	LSTTL														
					426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS107	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS109	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS11	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS11	FSC	1	Digital, Gate	LSTTL														
					426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS112	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	EACH PIN(+)	52	101	24
74LS112	FSC	1	Digital, Flip-Flop	LSTTL														
					426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS12	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS123	N/R	1	Digital, Multivibrator	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS125	N/R	1	Digital, Inverter, Buffer	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS126	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS132	FSC	1	Digital, Multivibrator	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	20	8631	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS138	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS138	FSC	1	Digital, Decoder	LSTTL	426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS139	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS139	FSC	1	Digital, Decoder	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS14	N/R	1	Digital, Inverter, Schmitt Trigger	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS148	N/R	1	Digital, Encoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS15	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS151	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS151	FSC	1	Digital, Multiplexer	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS153	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS154	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS155	N/R	1	Digital, Decoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS157	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS157	FSC	1	Digital, Multiplexer	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS158	FSC	1	Digital, Multiplexer	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	8636	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS160	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS160	FSC	1	Digital, Counter/Divider	LSTTL	426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS161	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS161	FSC	1	Digital, Counter/Divider	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS162	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS163	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					239	N/R	SS	0 Ohms	N/R	1	N/R	1	FAILED	400	IN.(2)(+) GND(8)(-)	108	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS163	N/R	1	Digital, Counter/Divider	LSTTL														
					239	N/R	SS	0 Ohms	N/R	1	N/R	1	FAILED	400	IN.(6,10)(+) GND(8)(-)	108	252	13
												1	FAILED	400	IN.(2,6,10)(+) GND(-)	108	252	13
					240	N/R	SS	0 Ohms	120E-12 F	1	N/R	1	FAILED	300	IN.(2,6)(+) GND(8)(-)	108	252	13
												1	FAILED	100	IN.(10)(+) GND(8)(-)	108	227	13
												3	FAILED	200	IN.(10)(+) GND(8)(-)	108	227	13
					241	N/R	SS	0 Ohms	510E-12 F	1	N/R	2	FAILED	200	IN.(2,6,10)(+) GND(-)	108	252	13
												3	FAILED	100	IN.(10)(+) GND(8)(-)	108	226	13
					242	N/R	SS	0 Ohms	.01E-07 F	1	N/R	1	FAILED	100	IN.(10)(+) GND(8)(-)	108	226	13
												2	FAILED	100	IN.(2,10)(+) GND(8)(-)	108	252	13
												1	FAILED	100	IN.(6,10)(+) GND(8)(-)	108	252	13
												1	FAILED	100	IN.(10)(+) GND(8)(-)	108	252	13
					243	N/R	SS	0 Ohms	.01E-06 F	1	N/R	1	PASSED	400	IN.(2,6,10)(+) GND(-)	108	252	13
												1	FAILED	75	IN.(6,10)(+) GND(8)(-)	108	252	13
												2	FAILED	100	IN.(2,6,10)(+) GND(-)	108	252	13
74LS164	N/R	1	Digital, Register, Shift	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS164	FSC	1	Digital, Register, Shift	LSTTL														
					426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS165	N/R	1	Digital, Register, Shift	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS166	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS169	FSC	1	Digital, Counter/Divider	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74LS173	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS174	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS174	FSC	1	Digital, Flip-Flop	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS175	AMD	1	Digital, Flip-Flop	LSTTL	127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
74LS175	SIG	1	Digital, Flip-Flop	LSTTL	127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS175	SIG	1	Digital, Flip-Flop	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
74LS175	FSC	1	Digital, Flip-Flop	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	600	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
					426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS175	N/R	1	Digital, Flip-Flop	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS175	MOT	1	Digital, Flip-Flop	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	2	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	2	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
74LS181	N/R	1	Digital, Arithmetic, Logic Unit	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS191	FSC	1	Digital, Counter/Divider	LSTTL														
					426	1086	SS	1500 Ohms	100E-12 F	10	8634	3	FAILED	600	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS192	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS192	FSC	1	Digital, Counter/Divider	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS193	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS193	FSC	1	Digital, Counter/Divider	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS194	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS194	FSC	1	Digital, Register, Shift	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS195	FSC	1	Digital, Register, Shift	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	8635	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS196	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS197	N/R	1	Digital, Counter/Divider	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS20	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS20	FSC	1	Digital, Gate	LSTTL														
					426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS21	N/R	1	Digital, Gate	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS221	N/R	1	Digital, Multivibrator	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS240	SIG	1	Digital, Line/Bus Driver	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1500	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	800	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
74LS240	TEX	1	Digital, Line/Bus Driver	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS240	TEX	1	Digital, Line/Bus Driver	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1500	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	1	FAILED	1000	INPUTS(+) GROUND(-)	3	252	13
												1	PASSED	1500	INPUTS(+) GROUND(-)	3	252	13
74LS240	MOT	2	Digital, Line/Bus Driver	LSTTL														
					127	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1200	INPUTS(+) GROUND(-)	3	252	13
												1	FAILED	1400	INPUTS(+) GROUND(-)	3	252	13
					127	N/R	SS	1000 Ohms	200E-12 F	10	N/R	2	FAILED	1200	INPUTS(+) GROUND(-)	3	252	13
74LS240	FSC	1	Digital, Line/Bus Driver	LSTTL														
					426	0786	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS240	N/R	1	Digital, Line/Bus Driver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS241	FSC	1	Digital, Line/Bus Driver	LSTTL														
					426	1086	SS	1500 Ohms	100E-12 F	10	8632	3	FAILED	600	INPUT TO GND.	61	204	13
74LS244	N/R	1	Digital, Line/Bus Driver	LSTTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS244	MOT	1	Digital, Line/Bus Driver	LSTTL														
					027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	15	PASSED	1000	N/R	47	252	12

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS245	N/R	1	Digital, Transceiver	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS245	FSC	1	Digital, Transceiver	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS251	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/P	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	550	EACH PIN(+)	52	139	24
												1	FAILED	1150	EACH PIN(+)	52	113	24
												1	FAILED	1100	EACH PIN(+)	52	111	24
74LS251	FSC	1	Digital, Multiplexer	LSTTL	426	1186	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74LS253	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS253	FSC	1	Digital, Multiplexer	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS257	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS259	N/R	1	Digital, Latch	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS266	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS27	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS279	N/R	1	Digital, Latch	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS280	N/R	1	Digital, Error Detect/Correct, Parity/Carry Gen	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS283	N/R	1	Digital, Arithmetic, Adder, Full	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS295	N/R	1	Digital, Register, Shift	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS298	N/R	1	Digital, Latch	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS298	FSC	1	Digital, Latch	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74LS299	N/R	1	Digital, Register, Shift	LSTTL	384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	600	EACH PIN(+)	52	141	24
74LS299	FSC	1	Digital, Register, Shift	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS30	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS32	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS32	FSC	1	Digital, Gate	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS323	FSC	1	Digital, Register, Shift	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	8633	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS352	FSC	1	Digital, Multiplexer	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	20	8514	3	FAILED	1000	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Rerarks
74LS353	N/R	1	Digital, Multiplexer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS353	FSC	1	Digital, Multiplexer	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS365	FSC	1	Digital, Inverter, Buffer	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	10	8623	3	FAILED	600	INPUT TO GND.	61	204	13
74LS366	FSC	1	Digital, Inverter, Buffer	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	10	8614	3	FAILED	600	INPUT TO GND.	61	204	13
74LS367	N/R	1	Digital, Line/Bus Driver	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS368	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS37	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS373	N/R	1	Digital, Latch	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS373	FSC	1	Digital, Latch	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS374	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS374	FSC	1	Digital, Flip-Flop	LSTTL	426	0986	SS	1500 Ohms	100E-12 F	10	N/R	3	FAILED	600	INPUT TO GND.	61	204	13
74LS379	FSC	1	Digital, Flip-Flop	LSTTL	426	1086	SS	1500 Ohms	100E-12 F	20	8613	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS38	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS390	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS393	N/R	1	Digital, Counter/Divider	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS395	FSC	1	Digital, Register, Shift	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	10	8449	3	FAILED	600	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74LS40	N/R	1	Digital, Inverter, Buffer	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS40	FSC	1	Digital, Inverter, Buffer	LSTTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS42	N/R	1	Digital, Encoder	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS51	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS54	N/R	1	Digital, Gate	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS574	FSC	1	Digital, Flip-Flop	LSTTL	426	0886	SS	1500 Ohms	100E-12 F	20	8626	3	FAILED	1000	INPUT TO GND.	61	204	13
74LS670	N/R	1	Digital, Register, File	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
74LS74	N/R	1	Digital, Flip-Flop	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology													
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks			
74LS74	N/R	1	Digital, Flip-Flop	LSTTL													
	384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	700	EACH PIN(+)	12	109	24			
								1	FAILED	900	EACH PIN(+)	9	112	24			
								1	FAILED	1200	EACH PIN(+)	11	114	24			
								1	FAILED	3700	EACH PIN(+)	8	133	24			
74LS75	N/R	1	Digital, Latch	LSTTL													
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13			
74LS86	N/R	1	Digital, Gate	LSTTL													
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13			
74LS86	FSC	1	Digital, Gate	LSTTL													
	426	0886	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13			
74LS92	N/R	1	Digital, Counter/Divider	LSTTL													
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13			
74S00	TEX	1	Digital, Gate	STTL													
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2144	N/R	102	188	13			
	003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	250	INPUT(+) PR. SUPPLY(-)	102	252	13			
74S0	FSC	1	Digital, Gate	STTL													
	426	0986	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13			

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S00	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
					067	N/R	N/R	0 Ohms	N/R	1	N/R	1	FAILED	375	INPUT	102	252	9
					068	N/R	N/R	0 Ohms	100E-12 F	1	N/R	1	FAILED	250	INPUT	102	252	9
					069	N/R	N/R	0 Ohms	150E-12 F	1	N/R	1	FAILED	200	INPUT	102	252	9
					070	N/R	N/R	0 Ohms	200E-12 F	1	N/R	1	FAILED	175	INPUT	102	252	9
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	800	EACH PIN(+)	52	105	24
												1	FAILED	650	EACH PIN(+)	52	141	24
												1	FAILED	850	EACH PIN(+)	52	101	24
												1	FAILED	650	EACH PIN(+)	52	138	24
					028	N/R	SS	1500 Ohms	117E-12 F	30	N/R	5	FAILED	1000	N/R	86	252	13
74S02	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S02	FSC	1	Digital, Gate	STTL														
					426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S03	N/R	1	Digital, Gate	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S04	N/R	1	Digital, Inverter, Buffer	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S04	FSC	1	Digital, Inverter, Buffer	STTL	426	0686	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S05	N/R	1	Digital, Inverter, Buffer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S08	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S10	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S10	FSC	1	Digital, Gate	STTL	426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S109	FSC	1	Digital, Flip-Flop	STTL	426	1086	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S11	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S11	FSC	1	Digital, Gate	STTL	426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13

Part Number	Part Mfr	ESD Class	Part Description	Part Pkg	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S112	N/R	1	Digital, Flip-Flop	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S112	FSC	1	Digital, Flip-Flop	STTL	426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S133	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S135	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S138	FSC	1	Digital, Decoder	STTL	426	0686	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S139	FSC	1	Digital, Decoder	STTL	426	1086	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S140	N/R	1	Digital, Line/Bus Driver	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S151	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S151	FSC	1	Digital, Multiplexer	STTL	426	0686	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S153	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S153	FSC	1	Digital, Multiplexer	STTL	426	0886	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S157	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S157	FSC	1	Digital, Multiplexer	STTL	426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	[illegible]	INPUT TO GND.	61	204	13
74S158	FSC	1	Digital, Multiplexer	STTL	426	1086	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S160	N/R	1	Digital, Counter/Divider	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S161	N/R	1	Digital, Counter/Divider	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S174	N/R	1	Digital, Flip-Flop	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S175	N/R	1	Digital, Flip-Flop	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S175	FSC	1	Digital, Flip-Flop	STTL	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S181	N/R	1	Digital, Arithmetic, Logic Unit	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S182	N/R	1	Digital, Arithmetic, Carry Generator	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S189	N/R	1	Digital, Memory, RAM, Static	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S20	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S20	FSC	1	Digital, Gate	STTL	426	0686	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S200	N/R	1	Digital, Memory, RAM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S22	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S251	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S257	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S257	FSC	1	Digital, Multiplexer	STTL	426	1086	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S258	N/R	1	Digital, Multiplexer	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S258	FSC	1	Digital, Multiplexer	STTL	426	1086	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S30	N/R	1	Digital, Gate	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S32		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S32		FSC	1	Digital, Gate								STTL		
	426	0786	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
74S40		FSC	1	Digital, Inverter, Buffer								STTL		
	426	0786	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	1000	INPUT TO GND.	61	204	13
74S472		N/R	1	Digital, Memory, PROM								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S51		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S74		N/R	1	Digital, Flip-Flop								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S85		N/R	1	Digital, Arithmetic, Magnitude Comparator								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
74S86		N/R	1	Digital, Gate								STTL		
	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
74S86	FSC	1	Digital, Gate	STTL														
					426	0886	SS	1500 Ohms	100E-12 F	30	N/R	3	FAILED	2000	INPUT TO GND.	61	204	13
75107	TEX	3	Digital, Line/Bus Receiver	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4907	N/R	102	188	13
7520	ANA	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	INPUT(4)(+) VSS(3)(-)	104	180	13
												1	FAILED	500	INPUT(4)(+) VSS(3)(-)	104	179	13
												1	FAILED	500	INPUT(4)(+) VDD(14)(-)	104	86	13
												1	FAILED	800	INPUT(4)(+) VSS(3)(-)	104	80	13
												1	FAILED	500	INPUT(4)(+) VSS(3)(-)	104	178	13
												1	FAILED	500	INPUT(4)(+) VSS(3)(-)	104	181	13
7520	ISL	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	RREF(15)(+) VSS(3)(-)	104	94	13
												1	FAILED	500	INPUT(8)(+) VDD(14)(-)	104	176	13
												1	FAILED	500	RFB(16)(+) VDD(14)(-)	104	93	13
												1	FAILED	500	RFB(16)(+) VSS(3)(-)	104	173	13
												1	FAILED	800	INPUT(4)(-) VSS(3)(-)	104	182	13
												1	FAILED	500	RFB(16)(+) VSS(3)(-)	104	175	13
7520	MIT	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	INPUT(+) VSS(-)	104	75	13
												1	FAILED	800	INPUT(4)(+) VSS(3)(-)	104	75	13
												1	FAILED	500	INPUT(9)(+) VSS(3)(-)	104	81	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7520	MIT	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	INPUT(4)(+) VSS(3)(-)	104	82	13
												1	FAILED	500	INPUT(9)(+) VSS(3)(-)	104	84	13
												1	FAILED	800	INPUT(6)(+) VSS(3)(-)	104	87	13
7520	N/R	1	Digital, Converter, A/D-D/A	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
7521	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	800	INPUT(6)(+) VSS(-)	104	264	13
												1	FAILED	800	INPUT(6)(+) VSS(-)	104	265	13
												1	FAILED	800	INPUT(6)(+) VDD(-)	104	177	13
												1	FAILED	800	RFB(18)(+) OUTPUT(-)	104	91	13
												1	FAILED	800	INPUT(7)(+) OUTPUT(-)	104	252	13
												1	FAILED	800	INPUT(4)(+) VDD(-)	104	90	13
7521	RAY	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	500	RFB(818)(+) VSS(-)	104	88	13
												1	FAILED	500	INPUT(7)(+) VSS(-)	104	267	13
												1	FAILED	500	RREF(17)(+) VSS(-)	104	92	13
												1	FAILED	500	RFB(18)(+) VSS(-)	104	252	13
												1	FAILED	500	RREF(17)(+) VSS(-)	104	252	13
7521	N/R	1	Digital, Converter, A/D-D/A	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7522	N/R	1	Digital, Converter, A/D-D/A	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
												1	FAILED	1000	N/R	103	252	13
7533	ANA	1	Digital, Converter, A/D-D/A	CMOS														
					005	0980	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	INPUT(4)(+) VDD(14)(-)	104	252	13
												1	FAILED	1000	INPUT(7)(+) VDD(14)(-)	104	252	13
												1	PASSED	1000	N/R	104	252	13
												1	FAILED	800	INPUT(10)(+) OUTPUT(-)	104	83	13
												1	FAILED	1000	INPUT(6)(+) VDD(14)(-)	104	252	13
												1	FAILED	1000	INPUT(4)(+) VSS(-)	104	85	13
75461	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
75462	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
75463	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
75464	N/R	2	Digital, Line/Bus Driver	TTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
7552	ISL	1	Digital, Memory, RAM, Static	MOS														
					003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	400	INPUT(+) PR. SUPPLY(-)	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
75LS85	N/R	1	Digital, Arithmetic, Magnitude Comparator	LSTTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1500	N/R	103	252	13
76161	HAR	1	Digital, Memory, PROM	STTL	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1050	EACH PIN TO 12 & 24 (+ -)	19	252	13
76161	N/R	2	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3000	N/R	103	252	13
7620	N/R	3	Digital, Memory, PROM	STTL	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	83	INPUT(+) GND(-)	47	186	21
76321	HAR	1	Digital, Memory, PROM	STTL	392	0886	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	1000	EACH PIN TO GND,VCC (+ -)	19	252	13
776	FSC	3	Linear, Operational Amplifier	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5932	N/R	102	188	13
776	N/R	2	Linear, Operational Amplifier	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2500	N/R	103	252	13
7805	N/R	3	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
7812	FSC	2	Linear, Voltage Regulator	Bipolar	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
7812	N/R	3	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
7815	N/R	3	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
78H05	N/R	3	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
78M05	FSC	2	Linear, Voltage Regulator	Bipolar	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
78M05	N/R	3	Linear, Voltage Regulator	Bipolar	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
78M12	FSC	2	Linear, Voltage Regulator	Bipolar	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
78M12	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
78M15	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
7905	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
7912	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
7915	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
												1	FAILED	10000	N/R	103	252	13
7924	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
79M12	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
79M12	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
79M15	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
79M15	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
7M853S65	IDT	3	Digital, Memory, RAM, Static	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	INPUT TO GND	5	252	3
80186	INT	1	Digital, Processing Unit, Central	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
80188	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
80286	INT	1	Digital, Processing Unit, Central												HMOS			
				429	n/r	GN	0 Ohms	50E-12 F	3	N/R	10	FASSED	600	N/R		13	237	13
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R		13	252	13
80287	INT	1	Digital, Processing Unit, Central												HMOS			
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R		13	252	13
				430	N/R	GN	10M Ohms	N/R F	3	N/R	10	FAILED	1800	PIN 39		13	149	13
											10	PASSED	1500	N/R		13	149	13
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	PIN 39		13	237	13
8031	INT	1	Digital, Processing Unit, Central												HMOS			
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R		13	252	13
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	300	N/R		13	237	13
											10	FAILED	350	N/R		13	237	13
8032	INT	1	Digital, Processing Unit, Central												HMOS			
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R		13	252	13
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	400	N/R		13	237	13
											10	FAILED	450	N/R		13	237	13
8039	N/R	1	Digital, Micro Computer												NMOS			
				384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1700	EACH PIN(+)		52	116	24

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8039	N/R	1	Digital, Micro Computer	NMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	900	EACH PIN(+)	52	128	24
												1	FAILED	1400	EACH PIN(+)	52	131	24
												1	FAILED	400	EACH PIN(+)	52	107	24
8039	INT	1	Digital, Micro Computer	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8048	N/R	1	Digital, Micro Computer	NMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1200	EACH PIN(+)	52	124	24
												1	FAILED	1000	EACH PIN(+)	52	127	24
												1	FAILED	600	EACH PIN(+)	52	118	24
												1	FAILED	600	EACH PIN(+)	52	115	24
8051	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	400	N/R	13	237	13
												10	FAILED	450	N/R	13	237	13
8080	N/R	1	Digital, Processing Unit, Central	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
8085	N/R	1	Digital, Processing Unit, Central	NMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8085	INT	1	Digital, Processing Unit, Central	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	220	N/R	13	237	13
												10	PASSED	600	N/R	13	237	13
8086	VAR	3	Digital, Processing Unit, Central	HMOS														
					424	1283	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1500	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	1750	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	16	N/R	2	FAILED	2000	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	15	N/R	2	FAILED	2000	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	2250	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	17	N/R	4	FAILED	2250	PINS 5,21, AND 32	100	149	13
					424	1283	SS	1500 Ohms	100E-12 F	20	N/R	3	FAILED	2500	PINS 5,21, AND 32	100	149	13
					423	1283	SS	0 Ohms	0 F	22	N/R	1	FAILED	2750	PIN21	100	252	4
					423	1283	SS	0 Ohms	0 F	30	N/R	1	FAILED	4500	PIN 21	100	252	4
					423	1283	SS	0 Ohms	0 F	32	N/R	1	FAILED	5000	PIN 21	100	252	4
8086	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1000	PIN 2	13	252	13
												10	FAILED	950	PIN 4	13	252	13
												10	FAILED	1050	PIN 11	13	252	13
												10	FAILED	1000	PIN 34	13	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8086	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	PIN 39	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8087	INT	1	Digital, Processing Unit, Central	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8088	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8089	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
80C86	HAR	3	Digital, Processing Unit, Central	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	8706	2	PASSED	4000	INPUT TO GND	5	252	3
810	VAR	2	Digital, Multifunction, RAM, I/O, Timer	CMOS														
					424	0983	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	750	PINS 9 AND 3	46	149	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
810	VAP	2	Digital, Multifunction, RAM, I/O, Timer	CMOS														
					424	0983	SS	1500 Ohms	100E-12 F	5	N/R	10	FAILED	750	PINS 9 AND 3	46	149	13
					423	0983	SS	0 Ohms	0 F	5	N/R	1	FAILED	750	PINS 9 AND 3	46	252	4
					423	0983	SS	0 Ohms	0 F	8	N/R	1	FAILED	1000	PINS 9 AND 3	46	252	4
					423	0983	SS	0 Ohms	0 F	9	N/R	2	FAILED	1250	PINS 9 AND 3	46	252	4
					423	0983	SS	0 Ohms	0 F	12	N/R	1	FAILED	1500	PINS 9 AND 3	46	252	4
					423	0983	SS	0 Ohms	0 F	11	N/R	10	FAILED	1500	PINS 9 AND 3	46	252	4
8155	N/R	1	Digital, Memory, RAM	NMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	700	EACH PIN(+)	52	123	24
												1	FAILED	900	EACH PIN(+)	52	123	24
												1	FAILED	600	EACH PIN(+)	52	120	24
												1	FAILED	500	EACH PIN(+)	52	108	24
8155	VAR	3	Digital, Memory, RAM	NMOS														
					424	1083	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	1750	PINS 4,7,9, AND 10	46	149	13
					424	1083	SS	1500 Ohms	100E-12 F	13	N/R	3	FAILED	1750	PINS 4,7,9, AND 10	46	149	13
					424	1083	SS	1500 Ohms	100E-12 F	16	N/R	10	FAILED	2000	PINS 4,7,9, AND 10	46	149	13
					423	1083	SS	0 Ohms	0 F	16	N/R	1	FAILED	2000	PINS 1,2,12, AND 37	100	252	4
					423	1083	SS	0 Ohms	0 F	26	N/R	1	FAILED	3250	PINS 1,2,12, AND 37	100	252	4
					423	1083	SS	0 Ohms	0 F	30	N/R	1	FAILED	3750	PINS 1,2,12, AND 37	100	252	4

RAC ESD Database

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
8155	VAR	3	Digital, Memory, RAM	NMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
423	1083	SS	0 Ohms	0 F	29	N/R	2	FAILED	3750	PINS 1,2,12, AND 37	100	252	4
423	1083	SS	0 Ohms	0 F	32	N/R	2	FAILED	4000	PINS 1,2,12, AND 37	100	252	4
423	1083	SS	0 Ohms	0 F	33	N/R	1	FAILED	4250	PINS 1,2,12, AND 37	100	252	4
423	1083	SS	0 Ohms	0 F	35	N/R	1	FAILED	4500	PINS 1,2,12, AND 37	100	252	4
423	1083	SS	0 Ohms	0 F	37	N/R	2	FAILED	4750	PINS 1,2,12, AND 37	100	252	4

Part Number	Part Mfr	ESD Class	Part Description	Technology
8155	INT	1	Digital, Memory, RAM	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	PINS 8,9,AND 11	13	237	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
8156	INT	1	Digital, Memory, RAM	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
8185	INT	1	Digital, Memory, RAM	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	PINS 13,15,16,AND 17	13	252	13
429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	PINS 10,11,12,15,16,AND 17	13	237	13
428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
8202	INT	1	Digital, Memory, RAM, Dynamic	HMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8202	INT	1	Digital, Memory, RAM, Dynamic	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8203	INT	1	Digital, Memory, RAM, Dynamic	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
8206	INT	1	Digital, Error Detect/Correct	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	3	N/R	10	PASSED	1200	N/R	13	252	13
8207	INT	1	Digital, Memory, RAM, Dynamic	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	500	N/R	13	237	13
					429	N/R	GN	0 Ohms	50E-12 F	5	N/R	10	FAILED	1100	N/R	13	252	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	450	N/R	13	237	13
												10	FAILED	550	N/R	13	237	13
8208	INT	1	Digital, Memory, RAM, Dynamic	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	450	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8212	INT	1	Digital, Transceiver, Input-Output Port	STTL	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	560	PIN 11	13	252	13
8214	INT	1	Digital, Controller	Bipolar	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	775	PINS 2,6,7,AND 20	13	252	13
8224	INT	1	Digital, Multivibrator	HMOS	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	620	PINS 2 AND 5	13	252	13
8228	INT	1	Digital, Line/Bus Driver	HMOS	428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	512	PINS 1,6, AND 7	13	252	13
82284	INT	1	Digital, Multivibrator	HMOS	429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	ALL INPUT PINS	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	2,3,4,6,7,11,12,13,16,17	13	252	13
82288	SIG	1	Digital, Controller	HMOS	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1576	N/R	102	189	13
82288	INT	1	Digital, Controller	HMOS	429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	PIN 19	13	237	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
82288	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
82289	INT	1	Digital	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					430	N/R	GN	10M Ohms	N/R F	3	N/R	10	PASSED	1500	N/R	13	149	13
8237	INT	1	Digital, Controller	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	400	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					428	N/R	GN	1500 Ohms	100E-12 F	3	N/R	10	PASSED	1200	PIN 5	13	149	13
												10	PASSED	1200	PINS 11,12,13,16,17,AND 18	13	149	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8238	INT	1	Digital, Line/Bus Driver	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	512	PINS 2,3, AND 22	13	252	13
8243	INT	1	Digital, Expander, Input-Output	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks	Technology
8243	INT	1	Digital, Expander, Input-Output															HMOS
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13	
82501	INT	1	Digital, Transceiver, Eithernet															Bipolar
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	350	N/R	13	237	13	
											10	FAILED	350	N/R	13	237	13	
8251	INT	1	Digital, Controller, Communications, Programmable															HMOS
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	550	N/R	13	237	13	
											10	FAILED	550	N/R	13	237	13	
8253	INT	1	Digital, Timer, Programmable Interval															NMOS
				393	0984	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2000	15(INPUT) 24(VCC)	102	271	13	
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13	
											10	FAILED	550	N/R	13	237	13	
				428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1100	N/R	13	252	13	
8253	N/R	1	Digital, Timer, Programmable Interval															NMOS
				384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1400	EACH PIN(+)	52	121	24	
											1	FAILED	800	EACH PIN(+)	52	129	24	
8254	INT	1	Digital, Counter/Divider															HMOS
				429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	500	N/R	13	237	13	

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8254	INT	1	Digital, Counter/Divider	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	550	N/R	13	237	13
												10	PASSED	600	N/R	13	237	13
												10	PASSED	600	N/R	13	237	13
8255	INT	1	Digital, Buffer, Schmitt Trigger	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	550	N/R	13	237	13
8256	INT	1	Digital, Transceiver	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8257	INT	1	Digital, Controller	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	380	N/R	13	237	13
82586	INT	1	Digital, Processing Unit, Central	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	400	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	400	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	400	N/R	13	237	13
82588	INT	1	Digital, Controller	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	450	N/R	13	237	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
82588	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8259	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	950	PINS 3,26,AND 27	13	252	13
												10	PASSED	1200	N/R	13	252	13
												10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8259A	AMD	1	Digital, Processing Unit, Central	MOS														
					392	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	450	EACH PIN TO 14 & 28 (+ -)	19	252	13
8272	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8274	INT	1	Digital, Controller	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	550	N/R	13	237	13
												10	FAILED	550	N/R	13	237	13
8276	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8279	INT	1	Digital, Controller, Keyboard	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
8282	INT	1	Digital, Latch	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8283	INT	1	Digital, Latch	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	669	PINS 1,2,AND 19	13	252	13
												10	PASSED	1200	N/R	13	252	13
8284	INT	1	Digital, Multivibrator	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	325	PIN 11	13	252	13
												10	FAILED	887	PIN 11	13	252	13
												10	PASSED	1200	N/R	13	252	13
												10	FAILED	300	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	150	N/R	13	237	13
8286	INT	1	Digital, Transceiver	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8287	INT	1	Digital, Transceiver	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8288	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1193	PINS 1,2,AND 19	13	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8288	INT	1	Digital, Controller	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	FAILED	550	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	150	N/R	13	237	13
8289	INT	1	Digital, Controller, Bus Arbitrator	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	887	PINS 4,5,AND 6	13	252	13
8291	INT	1	Digital, Controller, Bus Arbitrator	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	25	N/R	10	PASSED	600	N/R	13	237	13
8293	INT	1	Digital, Transceiver	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
82C52	HAR	1	Digital, Transceiver	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	OUTPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO OUTPUT	5	252	3
												1	FAILED	600	VCC TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
82C59A	HAR	1	Digital, Controller	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	3	8709	2	FAILED	400	VCC TO OUTPUT	5	252	3
82C82	HAR	1	Digital, Line/Bus Driver	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	8720	2	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	8720	2	FAILED	700	INPUT TO GND	5	252	3
82C84A	HAR	1	Digital, Line/Bus Driver	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	6	8710	2	FAILED	700	INPUT TO GND	5	252	3
												2	FAILED	700	INPUT TO GNC	5	252	3
82C88	INT	1	Digital, Controller	CMOS														
					430	N/R	GN	10M Ohms	N/R F	5	N/R	10	PASSED	1500	PIN 11	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	149	13
					428	N/R	GN	1500 Ohms	100E-12 F	3	N/R	10	PASSED	1200	PINS 1,2,3,6,15,18,AND 19	13	237	13
82C88	HAR	1	Digital, Controller	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	2	FAILED	800	INPUT TO GND	5	252	3
												2	FAILED	800	INPUT TO GND	5	252	3
												2	FAILED	800	INPUT TO GND	5	252	3
82S114	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
82S123	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S123	SIG	1	Digital, Memory, PROM	STTL	436	1186	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	700	INPUT TO OUTPUT	5	252	3
82S129	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S129	SIG	1	Digital, Memory, PROM	STTL	436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO GND	5	252	3
82S131	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S137	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S141	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S181	N/R	1	Digital, Memory, PROM	STTL	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13

Part Number	Part Mtr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
82S185	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S191	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]
82S191	SIG	1	Digital, Memory, PROM	STTL														
					36	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO GND	5	252	3
												5	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO GND	5	252	3
												5	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO GND	5	252	3
82S2708	N/R	1	Digital, Memory, PROM	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
82S34	N/R	2	Digital, Multiplexer	STTL														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	31	INPUT(+) GND(-)	47	186	21
82S67	N/R	3	Digital, Multiplexer	STTL														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	41	INPUT(+) GND(-)	47	186	21

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8481	SIG	N	Digital, Gate	DTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	164722	N/R	102	188	13
8656	PLE	1	Digital, Line/Bus Driver	Bipolar														
					393	0385	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	8(INPUT) 2(VCC)	102	252	13
8685	PLE	1	Digital, Counter/Divider	ECL														
					393	1184	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	1500	15(INPUT) 8(VEE)	102	252	13
8741	INT	1	Digital, Transceiver, Input-Output, RAM	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	500	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1050	N/R	13	252	13
												10	FAILED	1100	N/R	13	252	13
												10	FAILED	900	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	550	N/R	13	237	13
												10	FAILED	500	N/R	13	237	13
8742	INT	1	Digital, Controller, Peripheral Interface	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8744	INT	1	Digital, Memory, EPROM	HMOS														
					429	N/R	GN	0 Ohms	50E 12 F	3	N/R	10	PASSED	600	N/R	13	237	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
8744	INT	1	Digital, Memory, EPROM	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
8748	INT	1	Digital, Processing Unit, Central	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
												10	FAILED	700	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	500	N/R	13	237	13
												10	FAILED	400	N/R	13	237	13
8755	N/R	1	Digital, Memory, EPROM	NMOS														
					384	N/R	SS	1000 Ohms	200E-12 F	1	N/R	1	FAILED	1900	EACH PIN(+)	52	125	24
												1	FAILED	500	EACH PIN(+)	52	113	24
8T26	N/R	1	Digital, Transceiver	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
8T26C	N/R	1	Digital, Transceiver	STTL														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	103	252	13
8X01	SIG	1	Digital	IIL														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1728	IN.(+) APTT(-)	49	188	8
												1	FAILED	507	OUT.(+) APTT(-)	49	188	8
												1	FAILED	459	VCC(+) APTT(-)	49	188	8

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Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9093		FSC	3	Digital, Flip-Flop								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6123	N/R	102	188	13
9102		AMD	1	Digital, Memory, RAM, Static								NMOS		
	003	1175	SS	0 Ohms	100E-12 F	1	N/R	1	FAILED	300	INPUT(+) PR. SUPPLY(-)	102	252	13
914		MOT	3	Digital, Gate								RTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5848	N/R	102	189	13
930		RAY	3	Digital, Gate								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4283	N/R	102	188	13
9309		FSC	2	Digital, Multiplexer								TTL		
	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
93415		MOT	1	Digital, Memory, RAM, Static								TTL		
	027	N/R	GN	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1000	N/R	47	252	12
								13	PASSED	1000	N/R	47	252	12
93449		FSC	3	Digital								TTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	8060	N/R	102	189	13
935		FSC	2	Digital, Inverter, Buffer								DTL		
	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9383	FSC	2	Digital	TTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
940	FSC	2	Digital, Inverter, Buffer	DTL														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
9428-037	AM	2	Digital, Array, PAL	CMOS														
					392	0986	SS	1500 Ohms	100E-12 F	1	N/R	3	FAILED	2500	EACH PIN TO 10 & 20 (+ -)	19	273	13
												3	FAILED	2500	EACH PIN TO 10 & 20 (+ -)	19	46	13
94459	FSC	3	Digital, Gate	DTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	13426	N/R	102	188	13
946	NSC	3	Digital, Gate	DTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5237	N/R	102	188	13
												1	FAILED	4192	N/R	102	188	13
946	N/R	3	Digital, Gate	DTL														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	58	INPUT(+) GND(-)	47	186	21
948	NSC	3	Digital, Flip-Flop	DTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	5227	N/R	102	188	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9601	FSC	2	Digital, Multivibrator	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
9602	FSC	1	Digital, Multivibrator	TTL	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					392	0886	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	1050	PINS 3-5,11-13 TO GND,VCC	19	145	13
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1125	EACH PIN TO 8 & 16 (+ -)	19	252	13
												5	FAILED	1250	EACH PIN TO 8 & 16 (+ -)	19	252	13
					392	0886	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1050	INPUT PINS TO GND & VCC	19	155	13
9614	FSC	1	Digital, Line/Bus Driver	Bipolar	026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	963	INPUT(5)(+) GND(8)(-)	6	285	13
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	5	FAILED	1000	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	5	FAILED	1800	INPUT TO GND	5	252	3
9614	TEX	2	Digital, Line/Bus Driver	Bipolar	390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
9614	MOT	3	Digital, Line/Bus Driver	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9614	N/R	1	Digital, Line/Bus Driver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13
												1	FAILED	2000	N/R	103	252	13
9615	FSC	1	Digital, Line/Bus Receiver	Bipolar														
					026	0178	SS	100 Ohms	200E-12 F	1	N/R	4	FAILED	230	N/R	6	285	13
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO GND	5	252	3
9615	TEX	1	Digital, Line/Bus Receiver	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	5	FAILED	900	INPUT TO OUTPUT	5	252	3
9615	N/R	3	Digital, Line/Bus Receiver	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	12000	N/R	103	252	13
												1	FAILED	12000	N/R	103	252	13
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	90	INPUT(+) INPUT(-)	47	186	21
9616	N/R	3	Digital, Line/Bus Driver	Bipolar														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	112	INPUT(+) INPUT(-)	47	186	21
9900	TEX	1	Digital, Processing Unit, Central	IIL														
					383	N/R	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	113	INJ.(-) APTT(+)	49	188	8
9908	FSC	3	Digital, Encoder, Octal/Binary	DTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	9561	N/R	102	188	13

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Part Number		Part Mfr	ESD Class	Part Description								Technology		
	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9909		FSC	3	Digital, Gate								RTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7342	N/R	102	188	13
9910		FSC	3	Digital, Gate								RTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4595	N/R	102	188	13
9911		FSC	3	Digital, Gate								RTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6371	N/R	102	188	13
9912		FSC	3	Digital								RTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	14260	N/R	102	188	13
9930		FSC	2	Digital, Gate								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3514	N/R	102	188	13
9932		FSC	2	Digital, Gate								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3883	N/R	102	188	13
9944		NSC	2	Digital, Gate								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3444	N/R	102	188	13
9945		NSC	2	Digital, Flip-Flop								DTL		
	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	3708	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
9945	FSC	3	Digital, Flip-Flop	DTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4481	N/R	102	188	13
9946	FSC	3	Digital, Gate	DTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	7970	N/R	102	188	13
9948	FSC	3	Digital, Flip-Flop	DTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	4774	N/R	102	188	13
AD5216	ITE	1	Digital, Converter, A/D-D/A	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	9	N/R	2	FAILED	1000	INPUT TO GND	5	252	3
AD558T	ANA	1	Digital, Converter, A/D-D/A	Bipolar	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	450	EACH PIN TO 11 & 12 (+ -)	19	252	13
AD574	ANA	3	Digital, Converter, A/D-D/A	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	18	8633	1	PASSED	4000	N/R	5	252	3
AD581	ANA	1	Linear, Voltage Reference	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	10	8644	2	FAILED	1200	INPUT TO GND	5	252	3
AD584SH	ANA	1	Linear, Voltage Reference	Bipolar	392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1050	EACH PIN TO 8 (+ -)	19	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
AD584TH	ANA	3	Linear, Voltage Reference	Bipolar														
					436	0788	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
AD590	ANA	1	Digital, Converter, A/D-D/A	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	2	FAILED	1600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO INPUT	5	252	3
												2	FAILED	1400	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	1	FAILED	1600	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	3	FAILED	2500	OUTPUT TO INPUT	5	252	3
ADC0800	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	PINS 5,6,AND 7	102	252	13
ADC0808CJ	NSC	1	Digital, Converter, A/D-D/A	Bipolar														
					392	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	1050	EACH PIN TO 11 & 13 (+ -)	19	252	13
ADC0811	NSC	2	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	11	8436	1	FAILED	2500	PINS 11,15,AND 17-19	102	252	13
ADC0819	NSC	2	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	PINS 4,9,23,24,AND 26	102	252	13

Part Number (Cont'd)	Part Mfr	Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
ADC0819	NSC	2	Digital, Converter, A/D-D/A	CMOS														
					422	0184	SS	0 Ohms	125E-12 F	3	N/R	1	FAILED	500	PINS 4,9,23,24, AND 26	102	289	13
ADC0820	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	PINS 6-8, 11-13	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	2	N/R	1	FAILED	350	PINS 6-8, 11-13	102	289	13
ADC0838	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	700	PINS 13,16,17,AND 18	102	252	13
					421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	N/R	102	252	13
AM111	AMD	1	Linear, Comparator	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	611	N/R	102	188	13
AM111	N/R	3	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13
												1	FAILED	11000	N/R	103	252	13
AM26LS29	AMD	2	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
												1	FAILED	3000	INPUT TO OUTPUT	5	252	3
AM26LS31	AMD	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	5	FAILED	1400	INPUT TO GND	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
AM26LS31	AMD	1	Digital, Line/Bus Driver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO OUTPUT	5	252	3
AM26LS32	AMD	1	Digital, Line/Bus Receiver	LSTTL														
					436	0588	SS	1500 Ohms	100E-12 F	16	N/R	3	FAILED	3000	OUTPUT TO GROUND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO GND	5	252	3
AM26LS33	AMD	1	Digital, Line/Bus Receiver	LSTTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	8622	1	FAILED	600	INPUT TO GND	5	252	3
AM687	AMD	1	Linear, Comparator	Bipolar														
					392	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	850	EACH PIN TO 6, 11 THEN 3,14	19	145	13
AT27C256	ATM	2	Digital, Memory, EPROM	CMOS														
					401	0187	SS	1500 Ohms	100E-12 F	5	N/R	1	PASSED	6200	PIN # 01 (Vpp),(+V)	60	288	1
												1	PASSED	6200	PIN # 02 (A12),(+V)	60	288	1
												1	PASSED	6200	PIN # 03 (A7),(+V)	60	288	1
												1	FAILED	3000	PIN # 04 (A6),(+V)	60	288	1
												1	PASSED	6200	PIN # 07 (A3),(+V)	60	288	1
												1	PASSED	6200	PIN # 08 (A2),(+V)	60	288	1
												1	PASSED	6200	PIN # (09),(+V)	60	288	1
												1	PASSED	6200	PIN # 10 (A0),(+V)	60	288	1
												1	PASSED	6200	PIN # 11 (O0),(+V)	60	288	1

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
AT27C256	ATM	2	Digital, Memory, EPROM	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
401	0187	SS	1500 Ohms	100E-12 F	5	N/R	1	PASSED	6200	PIN # 12 (01),(+V)	60	288	1
							1	PASSED	6200	PIN 13 (02),(+V)	60	288	1
							1	PASSED	6200	PIN # 15 (03),(+V)	60	288	1
							1	PASSED	6200	PIN # 16 (04),(+V)	60	288	1
							1	PASSED	6200	PIN # 17 (05),(+V)	60	288	1
							1	PASSED	6200	PIN # 18 (06),(+V)	60	288	1
							1	PASSED	6200	PIN # 19 (07),(+V)	60	288	1
							1	PASSED	6200	PIN # 20 (CE),(+V)	60	288	1
							1	PASSED	6200	PIN # 21 (A10),(+V)	60	288	1
							1	FAILED	3000	PIN # 22 (CE),(+V)	60	288	1
							1	FAILED	2800	PIN # 23 (A11),(+V)	60	288	1
							1	PASSED	6200	PIN # 24 (A9),(+V)	60	288	1
							1	FAILED	2400	PIN # 25 (A8),(+V)	60	288	1
							1	FAILED	2400	PIN # 26 (A13),(+V)	60	288	1
							1	FAILED	2800	PIN # 27 (A14),(+V)	60	288	1
							1	PASSED	6200	PIN # 28 (Vcc),(+V)	60	288	1
							1	PASSED	6200	PIN # 01 (Vpp),(-V)	60	288	1
							1	PASSED	6200	PIN # 02 (A12),(-V)	60	288	1
							1	PASSED	6200	PIN # 03 (A7),(-V)	60	288	1
							1	PASSED	6200	PIN # 04 (A6),(-V)	60	288	1
							1	PASSED	6200	PIN # 05 (A5),(-V)	60	288	1
							1	PASSED	6200	PIN # 06 (A4),(-V)	60	288	1
							1	PASSED	6200	PIN # 07 (A3),(-V)	60	288	1
							1	PASSED	6200	PIN # 08 (A2),(-V)	60	288	1
							1	PASSED	6200	PIN # 09 (A1),(-V)	60	288	1
							1	PASSED	6200	PIN # 10 (A0),(-V)	60	288	1
							1	PASSED	6200	PIN # 11 (00),(-V)	60	288	1
							1	PASSED	6200	PIN # 12 (01),(-V)	60	288	1
							1	PASSED	6200	PIN # 13 (02),(-V)	60	288	1
							1	PASSED	6200	PIN # 15 (03),(-V)	60	288	1
							1	PASSED	6200	PIN # 16 (04),(-V)	60	288	1
							1	PASSED	6200	PIN # 17 (05),(-V)	60	288	1
							1	PASSED	6200	PIN # 18 (06),(-V)	60	288	1

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
AT27C256	ATM	2	Digital, Memory, EPROM	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
401	0187	SS	1500 Ohms	100E-12 F	5	N/R	1	PASSED	6200	PIN # 19 (O7),(-V)	60	288	1
							1	FAILED	3000	PIN # 20 (CE),(-V)	60	288	1
							1	FAILED	3000	PIN # 21 (A10),(-V)	60	288	1
							1	PASSED	6200	PIN # 22 (OE),(-V)	60	288	1
							1	PASSED	6200	PIN # 23 (A11),(-V)	60	288	1
							1	PASSED	6200	PIN # 24 (A9),(-V)	60	288	1
							1	PASSED	6200	PIN # 25 (A8),(-V)	60	288	1
							1	PASSED	6200	PIN # 26 (A13),(-V)	60	288	1
							1	PASSED	6200	PIN # 27 (A14),(-V)	60	288	1

Part Number	Part Mfr	ESD Class	Part Description	Technology
AT27C512	ATM	2	Digital, Memory, EPROM	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
401	0187	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	2600	PIN # 01 (A15),(+V)	60	287	1
							1	FAILED	2800	PIN # 02 (A12),(+V)	60	287	1
							1	FAILED	3000	PIN # 03 (A7),(+V)	60	287	1
							1	FAILED	2800	PIN # 04 (A6),(+V)	60	287	1
							1	PASSED	6200	PIN # 05 (A5),(+V)	60	287	1
							1	PASSED	6200	PIN # 06 (A4),(+V)	60	287	1
							1	PASSED	6200	PIN # 07 (A3),(+V)	60	287	1
							1	PASSED	6200	PIN # 08 (A2),(+V)	60	287	1
							1	FAILED	2800	PIN # 09 (A1),(+V)	60	287	1
							1	FAILED	2600	PIN # 10 (A0),(+V)	60	287	1
							1	PASSED	6200	PIN # 11 (O0),(+V)	60	287	1
							1	PASSED	6200	PIN # 12 (O1),(+V)	60	287	1
							1	PASSED	6200	PIN # 13 (O2),(+V)	60	287	1
							1	PASSED	6200	PIN # 15 (O3),(+V)	60	287	1
							1	PASSED	6200	PIN # 16 (O4),(+V)	60	287	1
							1	PASSED	6200	PIN # 17 (O5),(+V)	60	287	1
							1	PASSED	6200	PIN # 18 (O6),(+V)	60	287	1
							1	PASSED	6200	PIN # 19 (O7),(+V)	60	287	1
							1	FAILED	2400	PIN # 20 (CE),(+V)	60	287	1
							1	PASSED	6200	PIN # 21 (A10),(+V)	60	287	1

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology
AT27C512	ATM	2	Digital, Memory, EPROM	CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
401	0187	SS	1500 Ohms	100E-12 F	5	N/R	1	PASSED	6200	PIN # 22 (OE/Vpp),(+V)	60	287	1
							1	FAILED	2600	PIN # 23 (A11),(+V)	60	287	1
							1	FAILED	3000	PIN # 24 (A9),(+V)	60	287	1
							1	FAILED	2600	PIN # 25 (A8),(+V)	60	287	1
							1	FAILED	2600	PIN # 26 (A13),(+V)	60	287	1
							1	FAILED	2400	PIN # 27 (A14),(+V)	60	287	1
							1	FAILED	4200	PIN # 01 (A15),(-V)	60	287	1
							1	PASSED	6200	PIN # 02 (A12),(-V)	60	287	1
							1	PASSED	6200	PIN # 03 (A7),(-V)	60	287	1
							1	PASSED	6200	PIN # 04 (A6),(-V)	60	287	1
							1	PASSED	6200	PIN # 05 (A5),(-V)	60	287	1
							1	PASSED	6200	PIN # 06 (A4),(-V)	60	287	1
							1	PASSED	6200	PIN # 07 (A3),(-V)	60	287	1
							1	PASSED	6200	PIN # 08 (A2),(-V)	60	287	1
							1	PASSED	6200	PIN # 09 (A1),(-V)	60	287	1
							1	FAILED	4200	PIN # 10 (A0),(-V)	60	287	1
							1	PASSED	6200	PIN # 11 (O0),(-V)	60	287	1
							1	PASSED	6200	PIN # 13 (O2),(-V)	60	287	1
							1	PASSED	6200	PIN # 13 (O2),(-V)	60	287	1
							1	PASSED	6200	PIN # 15 (O3),(-V)	60	287	1
							1	PASSED	6200	PIN # 16 (O4),(-V)	60	287	1
							1	PASSED	6200	PIN # 17 (O5),(-V)	60	287	1
							1	PASSED	6200	PIN # 18 (O6),(-V)	60	287	1
							1	PASSED	6200	PIN # 19 (O7),(-V)	60	287	1
							1	PASSED	6200	PIN # 20 (CE),(-V)	60	287	1
							1	PASSED	6200	PIN # 21 (A10),(-V)	60	287	1
							1	PASSED	6200	PIN # 22 (OE/V),(-V)	60	287	1
							1	PASSED	6200	PIN # 23 (A11),(-V)	60	287	1
							1	PASSED	6200	PIN # 24 (A9),(-V)	60	287	1
							1	PASSED	6200	PIN # 25 (A8),(-V)	60	287	1
							1	PASSED	6200	PIN # 26 (A13),(-V)	60	287	1
							1	PASSED	6200	PIN # 27 (A14),(-V)	60	287	1
							1	PASSED	6200	PIN # 27 (A14),(-V)	60	287	1

RAC ESD Database

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
CD4000A	RCA	3	Digital, Gate	CMOS	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6985	N/R	102	188	13
												1	FAILED	8010	N/R	102	188	13
												1	FAILED	10533	N/R	102	188	13
CD4001	RCA	2	Digital, Gate	CMOS	436	0788	SS	1500 Ohms	100E-12 F	16	8739	8	FAILED	3000	INPUT TO COMMON	5	252	3
CD4002BE	RCA	1	Digital, Gate	CMOS	416	0586	SS	1500 Ohms	100E-12 F	1	8610	10	FAILED	1000	N/R	25	252	13
CD4006B	RCA	1	Digital, Register, Shift	CMOS	436	1186	SS	1500 Ohms	100E-12 F	7	8720	1	FAILED	800	INPUT TO OUTPUT	5	252	3
CD4011	RCA	1	Digital, Gate	CMOS	414	0783	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	700	NEG INPUT,POS OUTPUT	102	259	26
												16	FAILED	900	NEG INPUT,POS OUTPUT	102	259	26
												12	FAILED	1000	NEG INPUT,POS OUTPUT	102	259	26
												5	FAILED	1100	NEG INPUT,POS OUTPUT	102	259	26
												1	FAILED	1200	NEG INPUT,POS OUTPUT	102	259	26
												1	FAILED	700	ALL	102	260	26
												9	FAILED	800	ALL	102	260	26
												12	FAILED	900	ALL	102	260	26
												13	FAILED	1000	ALL	102	260	26
												5	FAILED	1100	ALL	102	260	26
CD4011	N/R	1	Digital, Gate	CMOS	414	0783	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	800	NEG INPUT,POS OUTPUT	102	259	26

RAC ESD Database

[illegible] Digital, Gate

Technology
CMOS

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
414	0783	SS	1500 Ohms	100E-12	5	N/R	1	FAILED	500	NEG INPUT, POS OUTPUT	102	259	26
414	0683	SS	1500 Ohms	100E-12 F	5	N/R	11	FAILED	600	NEG INPUT,POS OUTPUT	102	259	26
							15	FAILED	700	NEG INPUT,POS OUTPUT	102	259	26
							24	FAILED	800	NEG INPUT,POS OUTPUT	102	259	26
							20	FAILED	900	NEG INPUT,POS OUTPUT	102	259	26
							8	FAILED	1000	NEG INPUT,POS OUTPUT	102	259	26
							1	FAILED	1100	NEG INPUT,POS OUTPUT	102	259	26
							25	FAILED	500	ALL	102	260	26
							29	FAILED	600	ALL	102	260	26
							14	FAILED	700	ALL	102	260	26
							9	FAILED	800	ALL	102	260	26
							3	FAILED	900	ALL	102	260	26
							1	FAILED	500	NEG INPUT,POS OUTPUT	102	259	26
							11	FAILED	600	NEG INPUT, POS OUTPUT	102	259	26
							15	FAILED	700	NEG INPUT,POS OUTPUT	102	259	26
							24	FAILED	800	NEG INPUT,POS OUTPUT	102	259	26
							8	FAILED	1000	NEG INPUT,POS OUTPUT	102	259	26
							1	FAILED	1100	NEG INPUT,POS OUTPUT	102	259	26
							20	FAILED	900	NEG INPUT,POS OUTPUT	102	259	26
							24	FAILED	500	ALL	102	260	26
							29	FAILED	600	ALL	102	260	26
							13	FAILED	700	ALL	102	260	26
							8	FAILED	800	ALL	102	260	26
							3	FAILED	900	ALL	102	260	26

CD4011UB RCA 1 Digital, Gate CMOS

436	0788	SS	1500 Ohms	100E-12 F	12	8742	2	FAILED	1500	OUTPUT TO COMMON	5	252	3

CD4012UBF RCA 1 Digital, Gate CMOS

436	0788	SS	1500 Ohms	100E-12 F	5	8742	5	FAILED	600	INPUT TO OUTPUT	5	252	3

RAC ESD Database

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
CD4012UBF	RCA	1	Digital, Gate	CMOS														
					436	0788	SS	1500 Ohms	100E-12 F	15	8742	5	FAILED	2500	INPUT TO GROUND	5	252	3
CD4015B	RCA	1	Digital, Register, Shift	CMOS														
					416	0284	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
CD4017B[illegible]X	RCA	1	Digital, Counter/Divider	CMOS														
					416	0185	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	2000	N/R	25	252	13
CD4024	RCA	2	Digital, Counter/Divider, Binary	CMOS														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	36281	N/R	102	189	13
					436	0488	SS	1500 Ohms	100E-12 F	17	N/R	5	FAILED	3500	INPUT TO COMMON	5	252	3
CD4024BCN	NSC	1	Digital, Counter/Divider, Binary	CMOS														
					416	1285	SS	1500 Ohms	100E-12 F	1	N/R	10	FAILED	400	N/R	25	252	13
					417	0386	SS	0 Ohms	200E-12 F	4	N/R	5	FAILED	1000	N/R	25	252	13
					416	0486	SS	1500 Ohms	100E-12 F	4	N/R	10	FAILED	1000	N/R	25	252	13
CD4024BEX	RCA	1	Digital, Counter/Divider, Binary	CMOS														
					416	0386	SS	1500 Ohms	100E-12 F	1	N/R	10	FAILED	1000	N/R	25	252	13
CD4030B	RCA	3	Digital, Gate	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	8633	1	PASSED	4000	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
CD4050B	RCA	1	Digital, Inverter, Buffer												CMOS			
				436	1186	SS	1500 Ohms	100E-12 F	13	8633	1	FAILED	1800	INPUT TO GND		5	252	3
CD4051BCN	NSC	1	Digital, Multiplexer												CMOS			
				416	0384	SS	1500 Ohms	100E-12 F	3	8312	5	FAILED	400	N/R		25	252	13
CD4066	RCA	2	Linear, Switch												CMOS			
				436	1186	SS	1500 Ohms	100E-12 F	15	8625	1	FAILED	2500	INPUT TO GND		5	252	3
CD4069UB	RCA	2	Digital, Inverter, Buffer												CMOS			
				436	1186	SS	1500 Ohms	100E-12 F	15	8651	1	FAILED	2500	INPUT TO OUTPUT		5	252	3
CD4072BEX	RCA	1	Digital, Gate												CMOS			
				417	0385	SS	0 Ohms	200E-12 F	3	N/R	5	FAILED	1800	N/R		25	252	13
				416	0485	SS	1500 Ohms	100E-12 F	3	N/R	5	FAILED	1800	N/R		25	252	13
CD4072BEX	N/R	1	Digital, Gate												CMOS			
				416	0584	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	1800	N/R		25	252	13
CD4081BEX	RCA	1	Digital, Gate												CMOS			
				416	0185	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	2000	N/R		25	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
CD4081BEX	PLE	2	Digital, Gate	CMOS														
					393	1184	SS	1500 Ohms	100E-12 F	1	N/R	2	FAILED	2500	12(INPUT) 14(VDD)	102	252	13
COP370	NSC	1	Digital, Line/Bus Driver	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
COP409	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13
COP411	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1000	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
COP420	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1100	N/R	102	252	13
COP420L	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	N/R	102	252	13
COP420W	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1000	N/R	102	252	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
COP420W	NSC	1	Digital, Processing Unit, Central	CMOS														
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	100	N/R	102	289	13
COP444C	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13
COP470	NSC	1	Digital, Line/Bus Driver	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1100	N/R	102	252	13
COP484	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	400	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	150	N/R	102	289	13
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	N/R	102	252	13
COP498	NSC	1	Digital, Memory, RAM	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1000	N/R	102	252	13
COP920	NSC	1	Digital, Gate	NMOS														
					421	0184	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1800	N/R	102	252	13
COP944	NSC	1	Digital, Gate	NMOS														
					421	0184	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1700	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
CY7C401	CYP	2	Digital, Memory	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	16	8701	2	FAILED	3000	GND TO OUTPUT	5	252	3
CY7C403	CYP	2	Digital, Memory	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	17	8637	1	FAILED	3500	INPUT TO GND	5	252	3
D2817A	INT	1	Digital, Memory, EAROM, EEPROM	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
DAC-08	PRE	1	Digital, Converter, A/D-D/A	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO GND	5	252	3
DAC0830	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	PINS 17 AND 19	102	252	13
DAC10	RAY	1	Linear, Operational Amplifier	Bipolar														
					437	1083	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	PINS 2 TO 4	100	252	13
												3	FAILED	2000	PINS 5 TO 3	100	252	13
												3	FAILED	2000	PINS 15 TO 3	100	252	13
												8	PASSED	2000	N/R	100	252	13
DAC1006	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PIN 16	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
DAC1230	NSC	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	1000	N/R	102	252	13
DG140	SIX	1	Linear, Switch	BIFET														
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	GND TO OUTPUT	5	252	3
DG184	SIX	2	Linear, Switch	JFET														
					436	1186	SS	1500 Ohms	100E-12 F	17	8722	5	FAILED	3500	SOURCE TO GATE	5	252	3
DG184A	INT	1	Linear, Switch	JFET														
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	VGS TO GND	5	252	3
DG184A	SIL	3	Linear, Switch	JFET														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
DG187A	SIX	1	Linear, Switch	JFET														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 4 & 7 (+ -)	19	252	13
DG201	SIX	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO COMMON AND OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO GND	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
DG201	SIX	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	5	FAILED	700	INPUT TO GND	5	252	3
DG201	SIL	1	Linear, Switch	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	600	INPUT TO V(-)	5	252	3
DG201	N/R	1	Linear, Switch	CMOS														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1100	N/R	103	252	13
DG403	SIX	1	Linear, Switch	FET														
					436	1186	SS	1500 Ohms	100E-12 F	6	8548	2	FAILED	700	INPUT TO GND	5	252	3
DLZ-5	GEN	3	Linear, Voltage Regulator	TTL														
					412	1286	SS	1500 Ohms	100E-12 F	15	N/R	5	PASSED	15000	PIN 1 (GND) +/-	20	252	13
DM28C256	SEQ	2	Digital, Memory, PROM	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO OUTPUT	5	252	3
DM74ALS00	NSC	1	Digital, Gate	Advanced LSTTL														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	INPUTS	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
DM74ALS138	NSC	2	Digital, Decoder	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3200	N/R	102	252	13
DM74ALS14	NSC	2	Digital, Inverter, Buffer	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	N/R	102	252	13
DM74ALS157	NSC	2	Digital, Multiplexer	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13
DM74ALS245	NSC	2	Digital, Transceiver	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	N/R	102	252	13
DM74ALS258	NSC	2	Digital, Multiplexer	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13
DM74ALS373	NSC	3	Digital, Latch	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	25	N/R	1	FAILED	5000	N/R	102	252	13
DM74ALS541	NSC	2	Digital, Line/Bus Driver	Advanced LSTTL	421	0184	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	2500	N/R	102	252	13
DM74AS174	NSC	2	Digital, Flip-Flop	Advanced STTL	421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
DM74AS282	NSC	2	Digital	Advanced STTL	421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	N/R	102	252	13
DM74AS640	NSC	3	Digital, Transceiver	Advanced STTL	421	0184	SS	1500 Ohms	100E-12 F	25	N/R	1	FAILED	5000	N/R	102	252	13
DM74LS00	NSC	1	Digital, Gate	LSTTL	421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	N/R	102	252	13
DM74S195	NSC	1	Digital, Register, Shift	STTL	421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	N/R	102	252	13
DM8820AJ	NSC	1	Digital, Line/Bus Receiver	Bipolar	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	1707	N/R	102	188	13
DM933N	NSC	3	Digital, Timer, Programmable Interval	DTL	029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6748	N/R	102	188	13
DMPAL16L8ANC	NSC	1	Digital, Array, PAL	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1600	N/R	102	252	13
DMPAL16L8B2	NSC	2	Digital, Array, PAL	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	PASSED	2000	N/R	102	252	13

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DP8340	NSC	1	Digital, Encoder	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
DP8341	NSC	1	Digital, Decoder	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	N/R	102	252	13
DP8464BN	NSC	1	Digital, Controller, Fixed Disk Pulse Det	MOS	421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	350	PINS 2,3 AND 10	102	252	13
DP8466	NSC	1	Digital, Controller, Disk Drive Data	MOS	421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1000	N/R	102	252	13
DS3896	NSC	1	Digital, Line/Bus Driver	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
DS3897	NSC	1	Digital, Transceiver	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
DS8908	NSC	1	Linear, Phase Lock Loop	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	400	N/R	102	193	13
DS8921	NSC	2	Digital, Line/Bus Receiver	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	2500	PIN 8	102	168	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Resul.	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
HEF4001BTB	SGS	1	Digital, Gate	CMOS	416	0685	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
HEF4002BP	SGS	1	Digital, Gate	CMOS	416	0586	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
[illegible]	SGS	1	Digital, Gate, NAND	CMOS	416	0685	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
[illegible]	SGS	1	Digital, Flip-Flop	CMOS	416	0486	SS	1500 Ohms	100E-12 F	3	N/R	3	FAILED	400	N/R	25	252	13
HEF4040BTB	SGS	1	Digital, Counter/Divider	CMOS	416	0785	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
HEF4081BT	SGS	1	Digital, Gate	CMOS	416	0485	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
HEF4520BP	SGS	1	Digital, Counter/Divider	CMOS	416	0986	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
HI201	HAR	1	Linear, Switch	CMOS	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	2000	N/R	103	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
HI508A-B	HAR	1	Digital, Multiplexer												CMO			
				436	1186	SS	1500 Ohms	100E-12 F	4	8616	1	FAILED	500	INPUT TO GND		5	252	3
[illegible]	HAR	[illegible]	Digital, Converter, A/D-D/A												CMOS			
				[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]	[illegible]		5	252	3
[illegible]	HAR	[illegible]	Digital, Transceiver, Bus												CMOS			
				436	0787	SS	1500 Ohms	100E-12 F	6	N/R	2	FAILED	700	INPUT TO OUTPUT		5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	6	N/R	2	FAILED	700	INPUT TO OUTPUT		5	252	3
IDL6116	IDT	1	Digital, Memory, RAM, Static												CMOS			
				436	1186	SS	1500 Ohms	100E-12 F	6	8548	1	FAILED	700	INPUT TO GND		5	252	3
IDL720150DB	IDT	1	Digital, Memory												CMOS			
				436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND		5	252	3
IDT6116	IDT	1	Digital, Memory, RAM, Static												CMOS			
				436	0788	SS	1500 Ohms	100E-12 F	7	8745	1	FAILED	800	INPUT TO OUTPUT		5	252	3
				436	0788	SS	1500 Ohms	100E-12 F	5	8745	1	FAILED	600	INPUT TO GROUND		5	252	3
				436	0788	SS	1500 Ohms	100E-12 F	7	8745	1	FAILED	800	INPUT TO GROUND		5	252	3
				436	0788	SS	1500 Ohms	100E-12 F	5	8745	1	FAILED	600	INPUT TO GROUND		5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
IDT6116	IDT	1	Digital, Memory, RAM, Static	CMOS														
					436	0788	SS	1500 Ohms	100E-12 F	7	8745	1	FAILED	300	OUTPUT TO GROUND	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	5	8745	1	FAILED	600	INPUT TO GROUND	5	252	3
												1	FAILED	600	INPUT TO GROUND	5	252	3
												1	FAILED	600	INPUT TO GROUND	5	252	3
												1	FAILED	600	INPUT TO GROUND	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	7	8745	1	FAILED	800	INPUT TO OUTPUT	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	5	8745	1	FAILED	600	INPUT TO GROUND	5	252	3
					436	0788	SS	1500 Ohms	100E-12 F	9	8745	1	FAILED	1000	INPUT TO GROUND	5	252	3
IH5216	ISL	1	Digital, Multiplexer	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	1	8625	1	FAILED	200	INPUT TO OUTPUT	5	252	3
												1	FAILED	200	INPUT TO OUTPUT	5	252	3
IMS-1203	INM	1	Digital, Memory, RAM, Static	CMOS														
					425	0487	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1250	PINS 5 AND 17	53	252	17
IMS-1223	INM	2	Digital, Memory, RAM, Static	CMOS														
					425	0487	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	PIN 7	53	252	17
IMS-1400	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	0887	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1100	PINS 1 AND 3	53	252	17

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
IMS-1400	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	0887	SS	1500 Ohms	100E-12 F	140	N/R	3	FAILED	2000	N/R	53	252	17
IMS-1403	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	N/R	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	500	N/R	53	252	17
IMS-1420	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	1086	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1250	PINS 17 AND 18	53	252	17
					425	1086	SS	1500 Ohms	100E-12 F	140	N/R	3	FAILED	2000	N/R	53	252	17
IMS-1423	INM	1	Digital, Memory, RAM, Static	CMOS														
					425	0887	SS	1500 Ohms	100E-12 F	80	N/R	3	FAILED	800	PINS 2,4,6,9, AND 11	53	252	17
					425	0887	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	PINS 12,13 AND 14	53	252	17
IMS-1600	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	0587	SS	1500 Ohms	100E-12 F	50	N/R	3	FAILED	500	PINS 3,6,8,9,10 AND 19	53	252	17
IMS-1601	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	0187	SS	1500 Ohms	100E-12 F	70	N/R	3	FAILED	700	1,3,5,6,10, AND 19	53	252	17
					425	0187	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	PIN 9	53	252	17
IMS-1620	INM	1	Digital, Memory, RAM, Static	NMOS														
					425	0187	SS	1500 Ohms	100E-12 F	90	N/R	3	FAILED	900	PINS 3 AND 13	53	252	17

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
IMS-1624	INM	1	Digital, Memory, RAM, Static	NMOS	425	1187	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1250	PINS 4,5,6,7,9,10,13,19,23	53	252	17
IMS-1625	INM	1	Digital, Memory, RAM, Static	NMOS	425	1187	SS	1500 Ohms	100E-12 F	100	N/R	3	FAILED	1000	PINS 3,12, AND 20	53	252	17
IMS-1630	INM	1	Digital, Memory, RAM, Static	NMOS	425	1187	SS	1500 Ohms	100E-12 F	100	N/R	3	FAILED	1000	PINS 7,23,25, AND 27	53	252	17
					425	1187	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	PINS 11,12,13,16,17,18,19	53	252	17
IMS-1800	INM	1	Digital, Memory, RAM, Static	NMOS	425	1087	SS	1500 Ohms	100E-12 F	120	N/R	3	FAILED	1500	SEE REMARKS	53	268	17
IMS-2600	INM	2	Digital, Memory, RAM, Dynamic	NMOS	425	1187	SS	1500 Ohms	100E-12 F	180	N/R	3	FAILED	3000	PIN 12	53	252	17
IMS-A100	INM	1	Digital	CMOS	425	0487	SS	1500 Ohms	100E-12 F	100	N/R	3	FAILED	1000	ALL	53	252	17
IMS-C004	INM	1	Digital	CMOS	425	0487	SS	1500 Ohms	100E-12 F	120	N/R	3	FAILED	1500	PIN 26 AND 58	53	252	17

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IMS-C011	INM	1	Digital	CMOS														
					425	0887	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1250	PIN 4	53	252	17
					425	0887	SS	1500 Ohms	100E-12 F	120	N/R	3	FAILED	1500	PINS 15-20	53	252	17
					425	0887	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	N/R	53	252	17
IMS-C012	INM	1	Digital	MOS														
					425	0887	SS	1500 Ohms	100E-12 F	110	N/R	3	FAILED	1250	PIN 4	53	252	17
					425	0887	SS	1500 Ohms	100E-12 F	120	N/R	3	FAILED	1500	PINS 15-20	53	252	17
					425	0887	SS	1500 Ohms	100E-12 F	220	N/R	3	FAILED	4000	N/R	53	252	17
IMS-G171	INM	2	Digital	CMOS														
					425	0188	SS	1500 Ohms	100E-12 F	150	N/R	3	FAILED	2250	PIN 16	53	252	17
IMS-T800	INM	3	Digital, Processing Unit, Central	NMOS														
					425	0287	SS	1500 Ohms	100E-12 F	220	N/R	3	PASSED	4000	N/R	53	252	17
INS8050	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
INS82C50	NSC	1	Digital, Processing Unit, Central	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1500	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LF11202	NSC	1	Linear, Switch	FET														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	1400	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO GND	5	252	3
LF11202D	NSC	2	Linear, Switch	FET														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	5	FAILED	3000	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	5	FAILED	2500	INPUT TO GND	5	252	3
LF155	LTC	1	Linear, Operational Amplifier	BIFET														
					438	0587	GN	1500 Ohms	100E-12 F	10	N/R	8	FAILED	2000	IN TO V(-)	55	252	13
LF155A	LTC	1	Linear, Operational Amplifier	BIFET														
					438	0587	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	IN TO V(-)	55	252	13
LF156	LTC	N	Linear, Operational Amplifier	BIFET														
					245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	169	INPUT(+) INPUT(-)	47	186	21
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
LF156A	LTC	1	Linear, Operational Amplifier	BIFET														
					438	1185	GN	1500 Ohms	100E-12 F	10	N/R	8	FAILED	2000	INPUT TO V(-)	55	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LF157	N/R	3	Linear, Operational Amplifier	BIFET	030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6000	N/R	103	252	13
LF198	NSC	2	Linear, Operational Amplifier, Sample and Hold	BIFET	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	PIN 8	102	252	13
LF198A	LTC	1	Linear, Operational Amplifier, Sample and Hold	BIFET	436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	N/R	5	252	3
LF198AH	LTC	1	Linear, Operational Amplifier, Sample and Hold	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	5	FAILED	2000	IN TO V(-), CH TO V(-)	55	252	13
LF298	NSC	2	Linear, Operational Amplifier, Sample and Hold	BIFET	421	0184	SS	1500 Ohms	100E-12 F	20	N/R	1	FAILED	4000	PIN 8	102	252	13
LF353	NSC	1	Linear, Operational Amplifier	JFET	421	0184	SS	1500 Ohms	100E-12 F	7	8424	1	FAILED	1400	PINS 2,3,5, AND 6	102	252	13
LF356	N/R	1	Linear	JFET	421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	PINS 2 AND 3	102	252	13
LF357	NSC	1	Linear	JFET	421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	PINS 2 AND 3	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LF398	NSC	2	Linear, Operational Amplifier, Sample and Hold	JFET	421	0184	SS	1500 Ohms	100E-12 F	20	8512	1	FAILED	4000	PIN 8	102	252	13
LF412	NSC	1	Linear, Operational Amplifier	JFET	421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	PINS 2,3,5, AND 6	102	252	13
LF441	NSC	1	Linear, Operational Amplifier	JFET	421	0184	SS	1500 Ohms	100E-12 F	3	8416	1	FAILED	600	PINS 2 AND 3	102	252	13
LF442	NSC	1	Linear, Operational Amplifier	JFET	421	0184	SS	1500 Ohms	100E-12 F	5	8440	1	FAILED	1000	PINS 2,3,5, AND 6	102	252	13
LH0033	DCC	1	Digital, Multivibrator	Bipolar	392	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	650	EACH PIN TESTED TO 10 & 12	19	145	13
LH0070-2H	LTC	2	Linear, Voltage Reference	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LH2101A	SIG	1	Linear, Operational Amplifier	Bipolar	392	0986	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 1,6 & 9 (+ -)	19	252	13
LH2108A	LTC	2	Linear, Operational Amplifier	Bipolar	438	1185	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LH2108AD	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM101A	FSC	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	5	FAILED	2500	INPUT TO OUTPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
												5	PASSED	4000	N/R	5	252	3
LM101A	NSC	3	Linear, Operational Amplifier	Bipolar														
					436	0788	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					436	0588	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
												5	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	3	PASSED	4000	N/R	5	252	3
LM101AH	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	IN TO V(-), IN TO OUT	55	252	13
LM103	NSC	3	Linear, Voltage Regulator	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	6152	N/R	102	188	13

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM103	NSC	3	Linear, Voltage Regulator	Bipolar														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11040	N/R	102	188	13
LM105H	NSC	2	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	16	8707	2	FAILED	3000	INPUT TO COMMON	5	252	3
LM108	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	PIN 1	102	252	13
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
LM108	LTC	3	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
LM108	FSC	2	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO GND	5	252	3
LM108A	FSC	2	Linear, Operational Amplifier	Bipolar														
					436	0788	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	18	FAILED	2500	INPUT	5	205	3
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
LM108A	FSC	2	Linear, Operational Amplifier												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO INPUT		5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R		5	252	3
											5	PASSED	4000	N/R		5	252	3
				436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO INPUT		5	252	3
											5	FAILED	3000	INPUT TO GND		5	252	3
											1	FAILED	3000	+/- INPUT		5	252	3
LM108A	NSC	2	Linear, Operational Amplifier												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	18	N/R	4	PASSED	4000	N/R		5	252	3
											1	FAILED	4000	INPUT TO INPUT		5	252	3
											1	FAILED	4000	INPUT TO COMMON		5	252	3
											5	PASSED	4000	N/R		5	252	3
											9	PASSED	4000	N/R		5	252	3
LM10H	LTC	1	Linear, Operational Amplifier												Bipolar			
				438	0285	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	REF. F/B TO REF. OUT		55	252	13
LM11	NSC	1	Linear, Operational Amplifier												Bipolar			
				421	0184	SS	1500 Ohms	100E-12 F	10	8420	1	FAILED	2000	PINS 1 AND 8		102	252	13
LM110H	NSC	3	Linear, Voltage Follower												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R		5	252	3
											5	PASSED	4000	N/R		5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM110H	NSC	3	Linear, Voltage Follower	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
LM111	FSC	1	Linear, Comparator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	5	FAILED	800	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
												5	PASSED	4000	N/R	5	252	3
LM111	NSC	1	Linear, Comparator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	10	N/R	5	FAILED	1200	INPUT TO INPUT	5	252	3
LM111	RAY	3	Linear, Comparator	Bipolar														
					436	0588	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
LM111	N/R	3	Linear, Comparator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	11000	N/R	103	252	13
LM117	NSC	2	Linear, Voltage Regulator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM117H	NSC	1	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	INPUT TO INPUT	5	252	3
LM117H	LTC	1	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	INPUT TO INPUT	5	252	3
					438	0986	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	ADJ. TO VOUT,ADJ. TO VIN	55	252	13
LM117K	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	1286	GN	1500 Ohms	100E-12 F	10	N/R	8	FAILED	2000	ADJ. TO VIN, ADJ. TO VOUT	55	252	13
LM118	NSC	1	Linear, Operational Amplifier	Bipolar														
					414	0883	SS	1500 Ohms	100E-12 F	5	N/R	25	FAILED	2000	NEG INPUT,POS OUTPUT	102	259	26
												16	FAILED	2250	NEG INPUT,POS OUTPUT	102	259	26
												16	FAILED	2750	NEG INPUT,POS OUTPUT	102	260	26
												25	FAILED	3000	NEG INPUT,POS OUTPUT	102	260	26
					421	0184	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	2100	PINS 2 AND 3	102	252	13
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
												5	PASSED	4000	N/R	5	252	3
LM118	LTC	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	5	FAILED	2500	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	200	OUTPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM119H	LTC	3	Linear, Comparator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
LM120H	FSC	3	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	8447	1	PASSED	4000	N/R	5	252	3
												1	PASSED	4000	N/R	5	252	3
LM120H-12	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM120H-15	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM120K-05	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM120K-12	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM1211	NSC	1	Linear	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	PINS 9 AND 10	102	252	13
LM123K	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM124	FSC	1	Linear, Operational Amplifier	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	7	8620	5	FAILED	800	INPUT TO COMMON	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	8620	5	FAILED	500	INPUT TO INPUT	5	252	3
LM129AH	LTC	2	Linear, Voltage Regulator	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM134H	LTC	2	Linear	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM137H	LTC	2	Linear, Voltage Regulator	Bipolar	438	0587	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM137K	LTC	1	Linear, Voltage Regulator	Bipolar	438	0587	GN	1500 Ohms	100E-12 F	10	N/R	5	FAILED	2000	ADJ. TO VIN,ADJ. TO VOUT	55	252	13
LM139	RAY	1	Linear, Comparator	Bipolar	436	1186	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2000	OUTPUT TO GND	5	252	3
LM139	FSC	1	Linear, Comparator	Bipolar	436	0788	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Technology	Failure Criteria	Test Remarks	General Remarks
LM139	FSC	1	Linear, Comparator												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO GND		5	252	3
LM139A	NSC	1	Linear, Comparator												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	6	8712	5	FAILED	700	INPUT TO COMMON		5	254	3
				436	1186	SS	1500 Ohms	100E-12 F	7	8712	5	FAILED	800	INPUT TO COMMON		5	98	3
LM140H	FSC	3	Linear, Voltage Regulator												Bipolar			
				436	1186	SS	1500 Ohms	100E-12 F	18	8632	1	PASSED	4000	N/R		5	252	3
LM140H-05	FSC	3	Linear, Voltage Regulator												Bipolar			
				436	0788	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R		5	252	3
LM140H-05	N/R	3	Linear, Voltage Regulator												Bipolar			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R		103	252	13
LM140K-05	FSC	2	Linear, Voltage Regulator												Bipolar			
				390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R		105	247	11
LM140K-05	N/R	3	Linear, Voltage Regulator												Bipolar			
				030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R		103	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM140K-12	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM140K-12	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
LM140K-15	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
LM140K-24	FSC	2	Linear, Voltage Regulator	Bipolar														
					390	N/R	GN	1500 Ohms	100E-12 F	5	N/R	1	PASSED	2000	S/R	105	247	11
LM140K-24	N/R	3	Linear, Voltage Regulator	Bipolar														
					030	N/R	[illegible]	1500 Ohms	100E-12 F	1	N/R	1	FAILED	10000	N/R	103	252	13
LM148	FSC	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
LM1822	NSC	1	Linear	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	400	PIN 12	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
LM1823	NSC	1	Linear	Bipolar
LM1844-2.5	LTC	2	Linear, Operational Amplifier	Bipolar
LM1875	NSC	1	Digital, Multivibrator	Bipolar
LM1884	NSC	1	Linear	Bipolar
LM1893	NSC	1	Digital, Transceiver	Bipolar
LM1894	NSC	3	Linear	Bipolar
LM193	NSC	1	Linear, Comparator	Bipolar
LM199	NSC	2	Linear, Voltage Reference	Bipolar

Part Number	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM1823	421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	PIN 12,14,17, AND 22	102	252	13
LM1844-2.5	439	1585	SN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM1875	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PINS 1 AND 2	102	252	13
LM1884	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PIN 9	102	251	13
LM1893	421	0184	SS	1500 Ohms	100E-12 F	4	8424	1	FAILED	800	PIN 5 AND 17	102	252	13
LM1894	421	0184	SS	1500 Ohms	100E-12 F	58	N/R	1	FAILED	11500	PIN 9	102	252	13
LM193	392	1286	SS	1500 Ohms	100E-12 F	1	N/R	8	FAILED	1250	EACH PIN TO 4 & 8 (+ -)	19	252	13
LM199	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	PIN 1	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM199AH	LTC	2	Linear, Comparator	Bipolar														
					438	0385	GV	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LM199H	NSC	3	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	8609	2	PASSED	4000	N/R	5	252	3
LM285	NSC	1	Linear, Voltage Reference	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
LM2889	NSC	1	Linear	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	PINS 10 AND 11	102	251	13
LM2900	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
LM2930	NSC	3	Linear, Voltage Regulator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	40	8421	1	FAILED	8000	N/R	102	252	13
LM2931	NSC	2	Linear, Voltage Regulator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	PIN 1	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM2935	NSC	1	Linear, Voltage Regulator	Bipolar	422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
LM305	NSC	1	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	6	8344	1	FAILED	1200	PIN 6	102	252	13
LM309	NSC	2	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	18	8524	1	FAILED	3500	N/R	102	252	13
LM311	NSC	1	Linear, Comparator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	2	8540	1	FAILED	300	PINS 2 AND 3	102	252	13
LM317	NSC	2	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13
LM318	NSC	2	Linear, Operational Amplifier	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	11	N/R	1	FAILED	2100	N/R	102	252	13
LM319	NSC	1	Linear, Comparator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	4	8608	1	FAILED	800	PINS 4,5,98, AND 10	102	252	13
LM320	NSC	2	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	18	8344	1	FAILED	3500	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM323	NSC	2	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	18	8616	1	FAILED	3500	N/R	102	252	13
LM324	NSC	1	Linear, Operational Amplifier	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	2	8504	1	FAILED	250	INPUTS	102	252	13
LM32800	NSC	2	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13
LM339	NSC	1	Linear, Comparator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	3	8428	1	FAILED	600	INPUTS	102	252	13
LM340	NSC	3	Linear, Voltage Regulator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	40	8416	1	FAILED	8000	N/R	102	252	13
												1	FAILED	8000	N/R	102	252	13
LM3524	NSC	1	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PINS 1,2,4,5, AND 16	102	251	13
LM358	NSC	1	Linear, Operational Amplifier	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	250	PINS 2,3,5, AND 6	102	252	13
LM365	NSC	2	Linear, Comparator	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	20	8404	1	FAILED	4000	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM393	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	7	8604	1	FAILED	1300	PINS 2,3,5, AND 6	102	252	13
LM398	NSC	2	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	20	8512	1	FAILED	4000	PIN 8	102	252	13
LM4250	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	PINS 2 AND 3	102	252	13
LM567	NSC	1	Digital, Decoder	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	4	8404	1	FAILED	750	PIN 6	102	252	13
LM592	NSC	1	Digital, Multivibrator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PIN 1 AND 14	102	252	13
LM628	NSC	1	Linear	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	100	PIN 26	102	269	13
LM723	FSC	1	Linear, Voltage Regulator	Bipolar														
					436	0788	SS	1500 Ohms	100E-12 F	7	N/R	2	FAILED	800	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3

Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM723	FSC	1	Linear, Voltage Regulator	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	12	N/R	2	FAILED	1600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	700	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	2	FAILED	500	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1000	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
												2	PASSED	4000	N/R	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	17	N/R	2	FAILED	3500	OUTPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	11	N/R	2	FAILED	1400	INPUT TO INPUT	5	252	3
LM723	NSC	1	Linear, Voltage Regulator	Bipolar														
					436	0688	SS	1500 Ohms	100E-12 F	18	N/R	5	PASSED	4000	N/R	5	252	3
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	PIN 4 AND 5	102	252	13
LM733	NSC	1	Digital, Multivibrator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	5	8520	1	FAILED	900	PIN 1 AND 14	102	252	13
LM741A	RAY	2	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO INPUT	5	252	3
LM741CN	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	2	8420	1	FAILED	400	PINS 2 AND 3	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LM747A	FSC	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO INPUT	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	2	FAILED	1800	INPUT TO INPUT	5	252	3
												6	FAILED	1800	INPUT TO GND	5	252	3
LM747A	RAY	3	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	1	PASSED	4000	N/R	5	252	3
LM747A	NSC	1	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	14	N/R	5	FAILED	2000	INPUT TO INPUT	5	252	3
LM747CN	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	PINS 1,2,6, AND 7	102	252	13
LM78L05	NSC	2	Linear, Voltage Regulator	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	12	8444	1	FAILED	2300	N/R	102	252	13
LM833	NSC	1	Linear, Operational Amplifier	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1600	PIN 2 AND 6	102	252	13
LM835	NSC	1	Linear	Bipolar														
					421	0185	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	400	PINS 2 AND 3	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LMC13421	NSC	2	Linear, Switch	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	2500	N/R	102	252	13
LMC628	NSC	1	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	100	PIN 26	102	252	13
LMC660	NSC	1	Linear, Operational Amplifier	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	INPUTS	102	252	13
LMC668	NSC	1	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1500	PINS 1,2, AND 12-14	102	252	13
LMC669	NSC	1	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	PIN 2	102	252	13
LMC7660	NSC	2	Linear	Bipolar	412	0184	SS	1500 Ohms	100E-12 F	18	N/R	1	FAILED	3500	PINS 2-8	102	252	13
LMF100	NSC	1	Linear, Switch	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	PINS 1-3,19, AND 20	102	252	13
LSI29681	RAY	1	Digital, Memory, PROM	STTL	431	N/R	SS	1500 Ohms	100E-12 F	20	N/R	12	FAILED	900	PIN 23	110	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LS129681	RAY	1	Digital, Memory, PROM	STTL														
					431	N/R	SS	1500 Ohms	100E-12 F	40	N/R	12	FAILED	1100	PINS 1 AND 2	110	263	13
					431	N/R	SS	1500 Ohms	100E-12 F	50	N/R	12	FAILED	1200	PINS 3,4,5,AND 22	110	266	13
					431	N/R	SS	1500 Ohms	100E-12 F	60	N/R	12	FAILED	1300	PIN 7	110	252	13
					431	N/R	SS	1500 Ohms	100E-12 F	70	N/R	12	FAILED	1400	PIN 6	110	252	13
					431	N/R	SS	1500 Ohms	100E-12 F	160	N/R	12	PASSED	2248	PINS 9,10,11,12,AND 13	110	252	13
LT1001MJ8	LTC	1	Linear	Bipolar														
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	5	FAILED	2000	IN TO V(-), IN(-) TO IN(+)	55	252	13
LT1002MJ	LTC	1	Linear	Bipolar														
					438	0585	GN	1500 Ohms	100E-12 F	10	N/R	5	FAILED	2000	IN(A),IN(B),IN(A) TO V-A	55	252	13
LT1004MH-1.2	LTC	2	Linear	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT1005MK	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	4	FAILED	2000	VIN TO VEN, VEN TO GND.	55	252	13
												4	FAILED	2000	VIN TO VEN, VEN TO GND.	55	252	13
LT1007AMJ8	LTC	2	Linear, Voltage Regulator	Bipolar														
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LT1009CZ	LTC	1	Linear, Operational Amplifier	Bipolar	438	0386	GN	1500 Ohms	100E-12 F	10	N/R	10	FAILED	2000	ADJ. TO V(-), ADJ. TO V(+)	55	252	13
LT1009MH	LTC	1	Linear	Bipolar	438	0585	GN	1500 Ohms	100E-12 F	10	N/R	15	FAILED	2000	ADJ. TO V(-),V(+),V(-)-V(+)	55	252	13
LT1010MH	LTC	2	Linear, Voltage Regulator	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT1011MH	LTC	1	Linear, Operational Amplifier	Bipolar	438	0585	GN	1500 Ohms	100E-12 F	10	N/R	15	FAILED	2000	ALL PINS	55	252	13
LT1012MH	LTC	1	Linear, Voltage Regulator	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	2	FAILED	2000	IN TO V(-)	55	252	13
LT1013MH	LTC	1	Linear, Voltage Regulator	Bipolar	438	0585	GN	1500 Ohms	100E-12 F	10	N/R	12	FAILED	2000	IN +/-,V-A,V-B,IN A AND B	55	252	13
LT1014ACJ	LTC	1	Linear, Voltage Regulator	Bipolar	438	0485	GN	1500 Ohms	100E-12 F	10	N/R	15	FAILED	2000	ALL PINS	55	252	13
LT1024ACN	LTC	1	Linear, Voltage Regulator	Bipolar	438	0585	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	IN TO V(-)	55	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LT1032CJ	LTC	1	Linear, Operational Amplifier	Bipolar	438	0585	GN	1500 Ohms	100E-12 F	10	N/R	8	FAILED	2000	IN,STRB.,RESP. TO V(-)	55	252	13
LT1033MK	LTC	2	Linear, Operational Amplifier	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT1037MJ8	LTC	2	Linear	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT1055AMH	LTC	1	Linear	Bipolar	438	0485	GN	1500 Ohms	100E-12 F	10	N/R	7	FAILED	2000	IN TO V(-)	55	252	13
LT1055H8	LTC	1	Linear	Bipolar	438	0387	GN	1500 Ohms	100E-12 F	10	N/R	6	FAILED	2000	IN TO V(-), IN TO V(+)	55	252	13
LT107J8	LTC	1	Linear, Operational Amplifier	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	IN TO V(-), IN TO OUT	55	252	13
LT108H8	LTC	2	Linear, Operational Amplifier	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT111AJ8	LTC	1	Linear, Comparator	Bipolar	438	0785	GN	1500 Ohms	100E-12 F	10	N/R	6	FAILED	2000	IN TO V(-)	55	252	13

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LT117AH	LTC	1	Linear, Voltage Regulator	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	2	FAILED	2000	PINS 1-2 AND 3-2	55	252	13
LT118H8	LTC	1	Linear, Operational Amplifier	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	IN TO V(-),IN TO IN	55	252	13
LT118J8	LTC	1	Linear, Operational Amplifier	Bipolar	438	1286	GN	1500 Ohms	100E-12 F	10	N/R	9	FAILED	2000	IN TO V(-),IN(-) TO IN(+)	55	252	13
LT119AH	LTC	2	Linear, Comparator	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT137AH	LTC	2	Linear, Voltage Regulator	Bipolar	438	0285	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT138AK	LTC	2	Linear, Operational Amplifier	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT15CAK	LTC	2	Linear, Voltage Regulator	Bipolar	438	0385	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
LT1526J	LTC	1	Linear, Voltage Regulator	TTL	436	1186	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	1200	INPUT TO GND	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
LT317AK	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	0585	GN	1500 Ohms	100E-12 F	10	N/R	10	FAILED	2000	ADJ. TO VIN,ADJ. TO VOUT	55	252	13
LT3525AJ	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	0585	GN	1500 Ohms	100E-12 F	10	N/R	4	FAILED	2000	IN-GND,IN(-)-IN(+),OSC-GND	55	252	13
LT3527AJ	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	0585	GN	1500 Ohms	100E-12 F	10	N/R	4	FAILED	2000	IN-GND,IN(-)-IN(+),OSC-GND	55	252	13
LTC1044CH	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	18	FAILED	2000	N/R	55	252	13
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	7	FAILED	2000	PINS 1-3,7-3,1-7,AND 6-3	55	252	13
MC14029B	MOT	1	Digital, Flip-Flop	CMOS														
					416	1086	SS	1500 Ohms	100E-12 F	1	N/R	10	FAILED	800	N/R	25	252	13
MC14520BCP	MOT	1	Digital, Counter/Divider	CMOS														
					416	0986	SS	1500 Ohms	100E-12 F	1	N/R	10	FAILED	800	N/R	25	252	13
MC14557B	MOT	1	Digital, Register, Shift	CMOS														
					416	1083	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
MC6850	MOT	2	Digital, Transceiver, ACIA	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	15	8003	1	FAILED	2500	INPUT TO GND	5	252	3
MC8087	INT	2	Digital, Processing Unit, Central	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	2500	INPUT TO GND	5	252	3
												2	FAILED	2500	INPUT TO OUTPUT	5	252	3
MCA1300PSJ	NSC	1	Digital, Array, PGA	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	N/R	102	252	13
MCC4011BF	SGS	1	Digital, Gate	CMOS														
					416	0184	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
MCC4069UBF	SGS	1	Digital, Inverter, Buffer	CMOS														
					416	0284	SS	1500 Ohms	100E-12 F	3	N/R	10	FAILED	400	N/R	25	252	13
MD82C55A	HAR	3	Digital, Transceiver, Input-Output Port	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	18	8709	2	PASSED	4000	N/R	5	252	3
MD82C55A	MOT	2	Digital, Transceiver, Input-Output Port	CMOS														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	2	FAILED	3000	GND TO OUTPUT	5	252	3
MF10	NSC	2	Linear	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	15	N/R	1	FAILED	3000	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
[illegible]	NSC	1	Linear	MOS	421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	PIN 19	102	252	13
[illegible]	NSC	1	Linear	MOS	421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	PINS 1,7,13, AND 14	102	252	13
MF8	NSC	1	Linear	Bipolar	421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	PINS 5 AND 6	102	270	13
MK359-1	NSC	1	Digital, Memory, EPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	102	252	13
MK359-2	NSC	1	Digital, Memory, EPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	102	252	13
MK359-3	NSC	1	Digital, Memory, EPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	102	252	13
MK359-4	NSC	1	Digital, Memory, EPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	400	N/R	102	252	13
MK359-5	NSC	1	Digital, Memory, EPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
MK359-6	NSC	1	Digital, Memory, EPROM	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	102	252	13
MM5020	NSC	1	Digital	CMOS														
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
MM5034	[illegible]	1	Digital, Converter, A/D-D/A	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	N/R	102	252	13
MM5051	NSC	1	Digital	CMOS														
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
MM5066	NSC	1	Digital	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
MM5081	NSC	1	Digital	CMOS														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
MM5387	NSC	1	Digital	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology													
MM5437	NSC	1	Digital	MOS													
Test Source	**Test Date**	**Test Type**	**Test Resistance**	**Test Capacitance**	**Number Pulses**	**Date Code**	**Number Devices**	**Test Result**	**Test Voltage**	**Pin Combination**	**Failure Criteria**	**Test Remarks**	**General Remarks**				
421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	350	N/R	102	252	13				
MM5450	NSC	1	Digital	MOS													
421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13				
422	0184	SS	0 Ohms	175E-12 F	1	N/R	1	FAILED	50	N/R	102	289	13				
MM5453	NSC	1	Digital	MOS													
421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	N/R	102	252	13				
421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	N/R	102	252	13				
MM57408D	NSC	1	Digital, Micro Computer	CMOS													
392	0886	SS	1500 Ohms	100E-12 F	5	N/R	5	FAILED	500	INPUT PINS AND GND & VCC	19	249	13				
							5	FAILED	700	INPUT PINS TO GND & VCC	19	153	13				
MM58538	NSC	1	Digital	MOS													
421	0184	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	300	N/R	102	252	13				
MM58539	NSC	1	Digital	MOS													
421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	N/R	102	252	13				
MM58540	NSC	1	Digital	MOS													
421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	100	N/R	102	252	13				

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
MM58548	NSC	1	Digital	MOS	421	0184	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	100	N/R	102	252	13
MM74HC4020	NSC	1	Digital, Memory	HMOS	422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
MM74HC4538	NSC	1	Digital, Memory	HMOS	422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
NMC27C32	NSC	2	Digital, Memory, EPROM	CMOS	421	0184	SS	1500 Ohms	100E-12 F	20	N/R	1	FAILED	4000	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	3	N/R	1	FAILED	600	N/R	102	289	13
NMC61642	NSC	1	Digital, Memory	MOS	421	0184	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1800	N/R	102	252	13
NMC9346N	NSC	1	Digital, Memory, EAROM, EEPROM	MOS	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
NS32082	NSC	1	Digital, Processing Unit, Central	MOS	421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
NS455	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
NS8040	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	900	N/R	102	252	13
NS8049	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1600	N/R	102	252	13
NS8050	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	N/R	102	252	13
NS87P50	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	1500	N/R	102	252	13
					421	0184	SS	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	N/R	102	252	13
NS913	NSC	1	Digital, Processing Unit, Central	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	6	N/R	1	FAILED	1200	N/R	102	252	13
					421	0184	SS	1500 Ohms	100E-12 F	9	N/R	1	FAILED	1800	N/R	102	252	13
OP-07	RAY	1	Linear, Operational Amplifier	Bipolar														
					437	1083	GN	1500 Ohms	100E-12 F	10	N/R	12	FAILED	2000	PINS 2-4,3-4,2-3,6-4, & 7-4	100	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
OP07A	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	N/R	GN	1500 Ohms	100E-12 F	10	N/R	2	FAILED	2000	IN(+) TO IN(-)	55	252	13
												1	FAILED	2000	IN(+) TO IN(-)	55	252	13
OP07AH8	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	1286	GN	1500 Ohms	100E-12 F	10	N/R	1	FAILED	2000	IN(-) TO IN(+)	55	252	13
OP07H	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	IN(+) TO IN(-)	55	252	13
OP16CH	LTC	1	Linear, Operational Amplifier	Bipolar														
					438	0385	GN	1500 Ohms	100E-12 F	10	N/R	10	FAILED	2000	IN TO V(-)	55	252	13
OP227EJ	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0485	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
OP237AJ	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0485	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
OP27A	PRE	2	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	16	N/R	1	FAILED	3000	INPUT TO GND	5	252	3
OP27A	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0587	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13

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Part Number (Cont'd)	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
OP27A	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	0687	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
OP27AH8	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	1286	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
OP[illegible]H8	LTC	2	Linear, Operational Amplifier	Bipolar														
					438	1286	GN	1500 Ohms	100E-12 F	10	N/R	15	PASSED	2000	N/R	55	252	13
P51C56	INT	1	Digital, Memory, EAROM, EEPROM	HMOS														
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	FAILED	1000	N/R	13	252	13
P8751H	INT	1	Digital, Processing Unit, Central	HMOS														
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	FAILED	300	N/R	13	237	13
					428	N/R	GN	1500 Ohms	100E-12 F	5	N/R	10	PASSED	1200	N/R	13	252	13
					429	N/R	GN	0 Ohms	50E-12 F	3	N/R	10	PASSED	600	N/R	13	237	13
PAL10H8	PRE	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
PA[illegible]10H8	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO GND	5	252	3

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
PAL12L10	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	3	N/R	2	FAILED	400	INPUT TO OUTPUT	5	252	3
PAL16H2MJ	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	INPUT TO OUTPUT	5	252	3
PAL16L2	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	2	N/R	1	FAILED	300	INPUT TO OUTPUT	5	252	3
PAL16L8	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND	5	252	3
PAL16L8A	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
					436	1186	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	VCC TO GND	5	252	3
PAL16L8B	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	800	INPUT TO GND	5	252	3
PAL16R4	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	4	8623	1	FAILED	500	INPUT TO GND	5	252	3

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
PAL16R6A	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	5	N/R	1	FAILED	600	INPUT TO GND	5	252	3
PAL20RA10	MON	1	Linear, Array	STTL														
					436	1186	SS	1500 Ohms	100E-12 F	12	8643	1	FAILED	1600	INPUT TO OUTPUT	5	97	3
RC139	RAY	1	Linear, Comparator	Bipolar														
					432	0783	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	INPUT TO GND	100	252	13
												3	FAILED	2000	INPUT TO INPUT	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	12	N/R	5	FAILED	1000	PINS 6 TO 7	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	20	N/R	1	FAILED	2000	PINS 4 TO 12	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	24	N/R	2	FAILED	2250	PINS 4 TO 12	100	252	13
					432	0783	GN	1500 Ohms	100E-12 F	10	N/R	6	PASSED	2000	N/R	100	252	13
RC148	RAY	1	Linear, Operational Amplifier	Bipolar														
					432	0783	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	INPUT TO V(-)	100	252	13
												3	FAILED	2000	INPUT TO INPUT	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	500	PINS 5 TO 6	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	8	N/R	6	FAILED	750	PINS 3 TO 11,AND 5 TO 6	100	252	13
					433	0783	SS	1500 Ohms	100E-12 F	12	N/R	3	FAILED	1000	PINS 3 TO 11,AND 5 TO 6	100	252	13
REF01CH	LTC	1	Linear	Bipolar														
					438	0485	GN	1500 Ohms	100E-12 F	10	N/R	10	FAILED	2000	IN TO GND,TRIM, AND OUT	55	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
REF02CH	LTC	1	Linear	Bipolar														
					438	0485	GN	1500 Ohms	100E-12 F	10	N/R	10	FAILED	2000	IN TO GND,TRIM,TEMP,& OUT	55	252	13
RF9601	RAY	2	Digital, Register, Shift	Bipolar														
					437	1083	GN	1500 Ohms	100E-12 F	10	N/R	12	PASSED	2000	N/R	100	252	13
RM4153	RAY	1	Linear, Operational Amplifier	Bipolar														
					437	1083	GN	1500 Ohms	100E-12 F	10	N/R	2	FAILED	2000	PINS 11 TO 1	100	252	13
												13	PASSED	2000	N/R	100	252	13
RM951DC	RAY	2	Digital, Register, Shift	TTL														
					437	1083	GN	1500 Ohms	100E-12 F	10	N/R	12	PASSED	2000	N/R	100	252	13
SCX6212QFU/N5	NSC	1	Digital, Array, PGA	MOS														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13
SE140	N/R	N	Linear, Voltage Regulator	TTL														
					029	N/R	N/R	1500 Ohms	100E-12 F	1	N/R	1	FAILED	177676	N/R	102	188	13
SG1524J	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	0285	GN	1500 Ohms	100E-12 F	10	N/R	12	FAILED	2000	CL-GND,IN-IN,CL-CL,OSC-GND	55	252	13
SG1525AJ	LTC	1	Linear, Voltage Regulator	Bipolar														
					438	1286	GN	1500 Ohms	100E-12 F	10	N/R	3	FAILED	2000	IN TO GND., IN(-) TO IN(+)	55	252	13

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Part Number	Part Mfr	ESD Class	Part Description	Technology	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
SG1526J	SIL	1	Linear, Voltage Regulator	MOS														
					436	1186	SS	1500 Ohms	100E-12 F	13	N/R	1	FAILED	1800	INPUT TO GND	5	252	3
TIL-24	TEX	3	Linear, Operational Amplifier	Bipolar														
					436	1186	SS	1500 Ohms	100E-12 F	18	N/R	2	PASSED	4000	N/R	5	252	3
TL084	TEX	1	Linear, Operational Amplifier	Bipolar														
					392	1086	SS	1500 Ohms	100E-12 F	1	N/R	5	FAILED	2000	EACH PIN TO 4 & 11 (+ -)	19	252	13
TP3020	NSC	1	Linear, Communications, Auto Dialer	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	N/R	102	252	13
TP3040	NSC	1	Linear, Operational Amplifier, General Purpose	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13
TP3054	NSC	1	Linear, Operational Amplifier, General Purpose	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	4	N/R	1	FAILED	800	N/R	102	252	13
					422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	200	N/R	102	289	13
TP3120	NSC	1	Linear, Communications, Digital Interface	Bipolar														
					421	0184	SS	1500 Ohms	100E-12 F	7	N/R	1	FAILED	1400	N/R	102	252	13

Part Number	Part Mfr	ESD Class	Part Description	Technology
TP3155	NSC	1	Digital, Controller, Time Slot Assigner	Bipolar
TP3320	NSC	1	Linear, Communications, Telecom	Bipolar
TP5088	NSC	2	Linear, Communications, Telecom	Bipolar
TP5116	NSC	1	Linear, Communications, Telecom	Bipolar
X28256	XIC	2	Digital, Memory, PROM	MOS
XC401	N/R	3	Digital, Gate	IIL
XC402	N/R	3	Digital, Gate	IIL

Part Number	Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
TP3155	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	N/R	102	252	
TP3155	422	0184	SS	0 Ohms	125E-12 F	1	N/R	1	FAILED	50	N/R	102	289	13
TP3320	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	500	N/R	102	252	13
TP5088	421	0184	SS	1500 Ohms	100E-12 F	14	N/R	1	FAILED	2800	N/R	102	252	13
TP5116	421	0184	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	600	N/R	102	252	13
X28256	436	1186	SS	1500 Ohms	100E-12 F	17	N/R	1	FAILED	3500	INPUT TO GND	5	252	3
XC401	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	52	OUTPUT(+) GND(-)	47	186	21
XC402	245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	62	INJECTOR(+) INPUT(-)	47	186	21

Part Number	Part Mfr	ESD Class	Part Description	Technology
XC404	N/R	3	Digital, Flip-Flop	IIL

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
245	N/R	SS	100 Ohms	N/R	1	N/R	15	FAILED	49	INJECTOR(+) INPUT(-)	47	186	21

Part Number	Part Mfr	ESD Class	Part Description	Technology
Z8581-10CMB	ZIL	1	Digital, Peripheral Driver, Clock	Bipolar

Test Source	Test Date	Test Type	Test Resistance	Test Capacitance	Number Pulses	Date Code	Number Devices	Test Result	Test Voltage	Pin Combination	Failure Criteria	Test Remarks	General Remarks
436	1186	SS	1500 Ohms	100E-12 F	1	N/R	1	FAILED	200	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	8	N/R	1	FAILED	900	INPUT TO GND	5	252	3
436	1186	SS	1500 Ohms	100E-12 F	3	N/R	1	FAILED	400	INPUT TO GND	5	252	3

RAC ESD Database

END